Radiation Report

TPS7H4010-SEP Total Ionizing Dose (TID) Radiation Report

ABSTRACT

This report discusses the results of the Total Ionizing Dose (TID) testing for the Texas Instruments 3.5V to 32V, 6A synchronous step-down voltage converter TPS7H4010-SEP. The study was done to determine TID effects under low dose rate (LDR) and high dose rate (HDR) up to 30krad(Si). The results show that all samples passed within the specified limits up to 30krad(Si) and Radiation Lot Acceptance Testing (RLAT) will be performed using 22 units at 30krad(Si) for future wafer lots.

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Trademarks

1 Device Information

1.1 Product Description

The TPS7H4010-SEP is a 3.5V to 32V, 6A synchronous step-down voltage converter capable of driving up to 6A of load current. The TPS7H4010-SEP provides exceptional efficiency and output accuracy in a very small solution size.

1.2 Device Details

Table 1-1 lists the device information used in the TID HDR and LDR characterization.

Table 1-1. Device and Exposure Details

TID HDR and LDR Details: 20krad(Si) and 30krad(Si)	
Package	30-pin WQFN (RNP)
Quantity Tested	HDR and LDR: 22 bias and 5 unbiased units at 20krad(Si) levels; 5 bias and 5 unbiased units at 30krad(Si) levels
HDR and LDR Radiation Facility	Radiation Test Solutions, Colorado Springs, Colorado
HDR and LDR Dose Level	20krad(Si), 30krad(Si)
HDR Dose Rate	59.16rad(Si)/s ionizing radiation with increments
LDR Dose Rate	10mrad(Si)/s ionizing radiation with increments
HDR Radiation Source	Gamma rays provided by JLSA 81-24 Co60 source. Dosimetry performed by Air Ionization Chamber (AIC) traceable to NIST.
LDR Radiation Source	Gamma rays provided by JLSA 81-22 or JLSA 81-23 Co60 LDR source. Dosimetry performed by AIC traceable to NIST.
Irradiation and Test Temperature	Ambient, room temperature controlled to 24°C±6°C per MIL-STD-883 and MIL-STD-750.

Figure 1-1. TPS7H4010-SEP Devices Used in Exposure

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H4010-SEP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Conditions A and D were used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H4010-SEP HDR and LDR exposures were performed on biased and unbiased devices in gamma rays provided by JLSA 81-24 Co60 source and by JLSA 81-22 or JLSA 81-23 Co60 LDR source, respectively, at *Radiation Test Solutions, Inc.* facility in Colorado Springs, Colorado. Dosimetry performed by Air Ionization Chamber (AIC) traceable to NIST. Radiation Test Solutions's dosimetry has been audited by DLA. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post-radiation electrical evaluation using Texas Instruments Automated Test Equipment (ATE). ATE guard band test limits are set within VID electrical limits to ensure robust Cpk and test error margin based on qualification and characterization data. Post-radiation measurements were taken on the same test setup where initial, pre-exposure testing done, within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR and LDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR and LDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 shows the diagram for HDR and LDR exposure with biased condition.

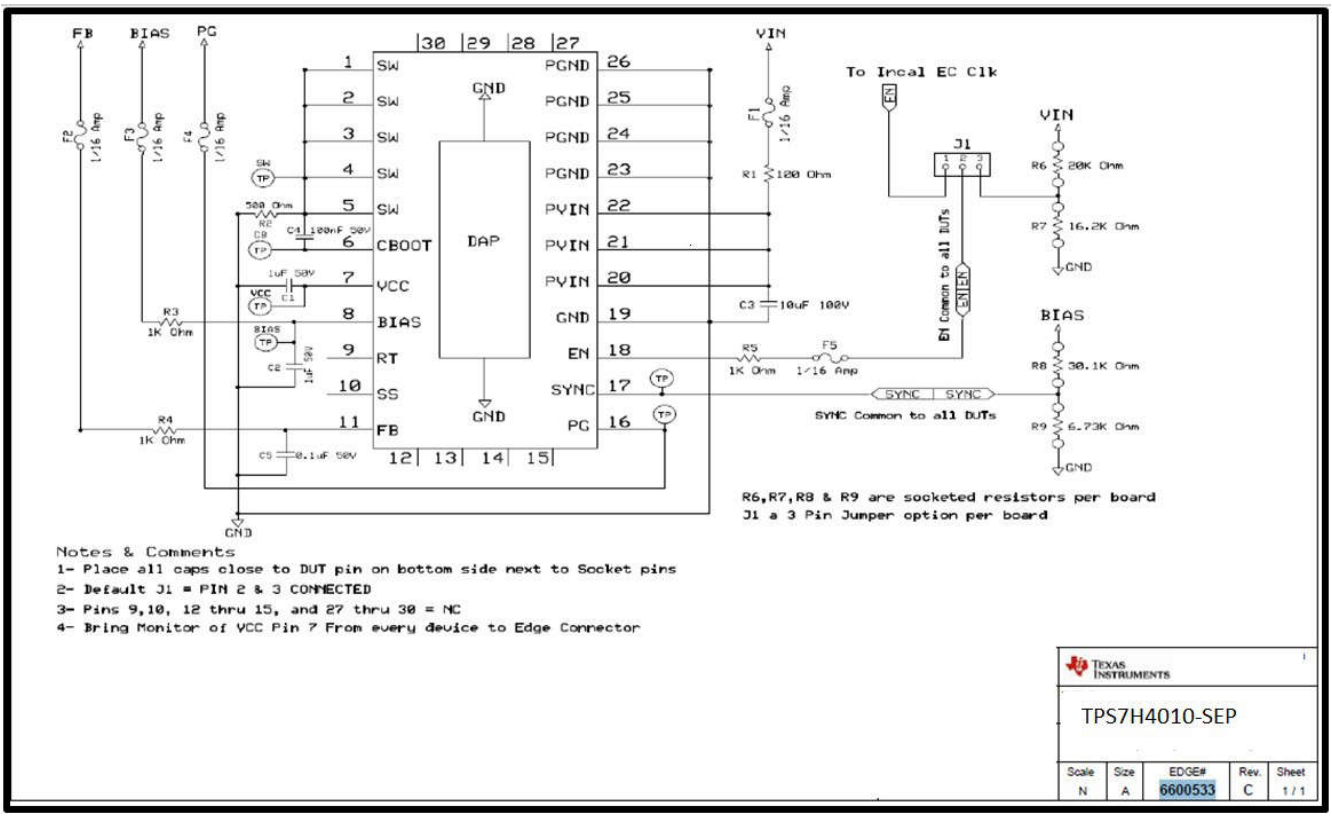


Figure 2-1. Bias Diagram Used in TID Exposure

2.4 Test Configuration and Condition

HDR and LDR devices were stressed at 20krad(Si) and 30krad(Si) for biased and unbiased conditions.

Table 2-1. HDR ≥ 50–300rad(Si)/s Biased Device Information (HDR)

Total Samples: 27	
Exposure Levels:	
20krad(Si) (22 samples)	30krad(Si) (5 samples)
61, 62, 63, 64, 65, 67, 68, 69, 70, 71, 72, 73, 74, 75, 76, 77, 78, 79, 80, 81, 82, 83	89, 90, 91, 92, 93

Table 2-2. HDR ≥ 50–300rad(Si)/s Unbiased Device Information (HDR)

Total Samples: 10	
Exposure Levels:	
20krad(Si) (5 samples)	30krad(Si) (5 samples)
84, 85, 86, 87, 88	94, 95, 96, 97, 98

Table 2-3. LDR ≤ 10 mrad(Si)/s Biased Device Information (LDR)

Total Samples: 27	
Exposure Levels:	
20krad(Si) (22 samples)	30krad(Si) (5 samples)
6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16, 17, 18, 19, 20, 21, 22, 23, 24, 25, 26, 27	33, 34, 35, 36, 37

Table 2-4. LDR ≤ 10 mrad(Si)/s Unbiased Device Information (LDR)

Total Samples: 10	
Exposure Levels:	
20krad(Si) (5 samples)	30krad(Si) (5 samples)
1, 2, 3, 4, 5	28, 29, 30, 31, 32

3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the TPS7H4010-SEP passes up to 30krad(Si) HDR and LDR TID. The drift of VID electrical parameters through HDR and LDR were within the pre-radiation limits.

Overall, the TPS7H4010-SEP showed a strong degree of hardness to HDR and LDR TID irradiation up to 30krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the data sheet electrical specifications (see Section 3.2 for Specification Compliance Matrix).

Please see Appendix A for HDR report up to 30krad(Si).

Please see Appendix B for LDR report up to 30krad(Si).

3.2 Specification Compliance Matrix

The TPS7H4010-SEP Specification Compliance Matrix is comprised of electrical, timing, and switching characteristics lists as shown in the following tables.

Table 3-1. Electrical Characteristics

PARAMETER		TEST CONDITIONS	TPS7H4010-SEP Data Sheet				Test#
			MIN	TYP	MAX	UNIT	
SUPPLY VOLTAGE (PVIN PINS)							
PVIN	Operating input voltage		3.5		32	V	
I_{SD}	Shutdown quiescent current; measured at PVIN pin(1)	V_{EN} = AGND, T_J = 25°C		0.8	10	µA	2.1, 2.2, 2.3, 2.4
I_{Q_NONSW}	Operating quiescent current from PVIN (non-switching)	V_{EN} = 2V, V_{FB} = 1.5V, V_{BIAS} = 3.3V external		0.6	12	µA	25.5
ENABLE (EN PIN)							
$V_{EN\_VCC\_H}$	Enable input high-level for VCC output	V_{EN} rising			1.15	V	30.1
$V_{EN\_VCC\_L}$	Enable input low-level for VCC output	V_{EN} falling	0.3			V	30.2
$V_{EN\_VOUT\_H}$	Enable input high-level for VOUT	V_{EN} rising	1.14	1.196	1.25	V	30.4
$V_{EN\_VOUT\_HYS}$	Enable input hysteresis for VOUT	V_{EN} falling hysteresis		100		mV	30.6
I_{LKG_EN}	Enable input leakage current	V_{EN} = 2V		1.4	200	nA	25.3
INTERNAL LDO (VCC PIN, BIAS PIN)							
VCC	Internal VCC voltage	PWM operation		3.27		V	12.6, 12.7, 12.8
		PFM operation		3.1		V	29.4, 29.5, 29.6
V_{CC_UVLO}	Internal VCC undervoltage lockout	VCC rising	2.96	3.14	3.27	V	29.2
		VCC falling hysteresis		605		mV	29.3
V_{BIAS_ON}	Input changeover	VBIAS rising		3.09	3.25	V	29.9
		VBIAS falling hysteresis		63		mV	29.10
I_{BIAS_NONSW}	Operating quiescent current from external VBIAS (non-switching)	VEN = 2V, VFB = 1.5V, VBIAS = 3.3V external		21	50	µA	29.16
VOLTAGE REFERENCE (FB PIN)							
V_{FB}	Feedback voltage	PWM mode	0.987	1.006	1.017	V	28.1, 28.3, 28.5
I_{LKG_FB}	Input leakage current at FB pin	VFB = 1V		0.2	60	nA	25.4
HIGH SIDE DRIVER (CBOOT PIN)							
V_{CBOOT_UVLO}	CBOOT - SW undervoltage lockout		1.6	2.2	2.7	V	38.2
CURRENT LIMITS AND HICCUP							
I_{HS_LIMIT}	Short-circuit, high-side current limit(2)		7.4	8.7	9.85	A	20.5
I_{LS_LIMIT}	Low-side current limit(2)		5.8	6.6	7.25	A	22.5
I_{NEG_LIMIT}	Negative current limit			–6		A	22.7

Table 3-1. Electrical Characteristics (continued)

PARAMETER		TEST CONDITIONS	TPS7H4010-SEP Data Sheet				Test#
			MIN	TYP	MAX	UNIT	
V_{HICCUP}	Hiccup threshold on FB pin		0.36	0.4	0.44	V	37.17, 37.18
I_{L_ZC}	Zero cross-current limit			0.06		A	22.6
SOFT START (SS/TRK PIN)							
I_{SSC}	Soft-start charge current		1.8	2	2.2	µA	25.6, 32.4
R_{SSD}	Soft-start discharge resistance	UVLO, TSD, OCP, or EN = AGND		1		kΩ	32.3
POWER GOOD (PGOOD PIN) and OVERVOLTAGE PROTECTION							
V_{PGOOD_OV}	Power-good overvoltage threshold	% of FB voltage	106%	110%	113%		37.5,37.6
V_{PGOOD_UV}	Power-good undervoltage threshold	% of FB voltage	86%	90%	93%		37.8, 37.9
V_{PGOOD_HYS}	Power-good hysteresis	% of FB voltage		1.2%			37.7, 37.10
V_{PGOOD_VALID}	Minimum input voltage for proper PGOOD function	50µA pullup to PGOOD pin, V_{EN} = AGND, T_J = 25℃		1.3	2	V	37.1
R_{PGOOD}	Power-good ON-resistance	VEN = 2.5V		40	100	Ω	37.2, 37.4
		VEN = AGND		30	90		37.3
MOSFETS							
$R_{DS\_ON\_HS}$ (3)	High-side MOSFET ON-resistance	IOUT = 1A, VBIAS = VOUT = 3.3V		53	90	mΩ	18.1
$R_{DS\_ON\_LS}$ (3)	Low-side MOSFET ON-resistance	IOUT = 1A, VBIAS = VOUT = 3.3V		31	55	mΩ	18.2

(1) Shutdown current includes leakage current of the switching transistors.
(2) This current limit was measured as the internal comparator trip point. Due to inherent delays in the current limit comparator and drivers, the peak current limit measured in closed loop with faster slew rate will be larger, and valley current limit will be lower.
(3) Measured at pins.

Table 3-2. Timing Characteristics

PARAMETER		TEST CONDITIONS	TPS7H4010-SEP Data Sheet				Test #
			MIN	TYP	MAX	UNIT	
CURRENT LIMITS AND HICCUP							
t_{OC}	Overcurrent hiccup retry delay time			46		ms	32.2
SOFT START (SS/TRK PIN)							
t_{SS}	Internal soft-start time	CSS = OPEN, from EN rising edge to PGOOD rising edge	3.5	6.3		ms	32.1, 32.5
POWER GOOD (PGOOD PIN) and OVERVOLTAGE PROTECTION							
t_{PGOOD_RISE}	PGOOD rising edge deglitch delay		80	140	200	µs	37.15
t_{PGOOD_FALL}	PGOOD falling edge deglitch delay		80	140	200	µs	37.16

Table 3-3. Switching Characteristics

PARAMETER		TEST CONDITIONS	TPS7H4010-SEP Data Sheet				Test #
			MIN	TYP	MAX	UNIT	
PWM LIMITS (SW PINS)							
$t_{ON\text{-}MIN}$	Minimum switch on-time			60	82	ns	36.2
$t_{OFF\text{-}MIN}$	Minimum switch off-time			70	120	ns	36.5
$t_{ON\text{-}MAX}$	Maximum switch on-time	HS timeout in dropout	3	6	9	µs	36.7
OSCILLATOR (RT and SYNC PINS)							
f_{OSC}	Internal oscillator frequency	RT = Open	440	500	560	kHz	36.1
f_{ADJ}	Minimum adjustable frequency by RT or SYNC	RT = 115kΩ, 0.1%	315	350	385	kHz	36.9
	Maximum adjustable frequency by RT or SYNC	RT = 17.4kΩ, 0.1%	1980	2200	2420		36.3, 36.4
V_{SYNC_HIGH}	Sync input high-level threshold				2	V	34.1
V_{SYNC_LOW}	Sync input low-level threshold		0.4			V	34.2
V_{MODE_HIGH}	Mode input high-level threshold for FPWM			0.42		V	34.7
V_{MODE_LOW}	Mode input low-level threshold for AUTO mode			0.4		V	34.8
t_{SYNC_MIN}	Sync input minimum ON and OFF time			80		ns	34.5, 34.6

4 Applicable and Reference Documents

4.1 Applicable Documents

- *TPS7H4010-SEP Radiation Hardened 3.5-V to 32-V, 6-A Synchronous Step-Down Voltage Converter in Space Enhanced Plastic* data sheet
- *TPS7H4010-SEP Production Flow and Reliability Report*
- *TPS7H4010-SEP EVM User's Guide*

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

5 Revision History

Changes from Revision * (November 2020) to Revision A (June 2024)	Page
• Updated the production flow from 20krad RLAT to 30krad RLAT and added RLAT statement	1

A Appendix A: HDR TID Report

This appendix contains the HDR TID report data.

HDR TID Report
TPS7H4010-SEP

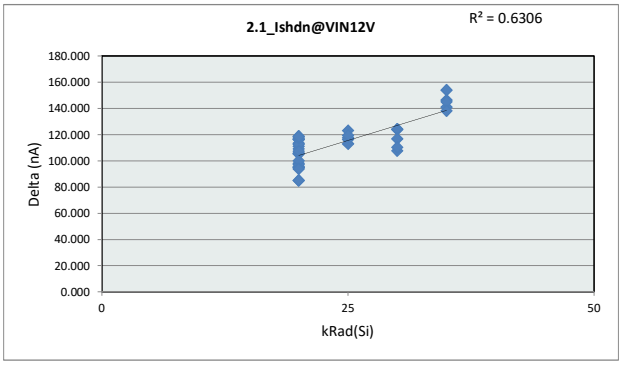
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

HDR TID Report
TPS7H4010-SEP

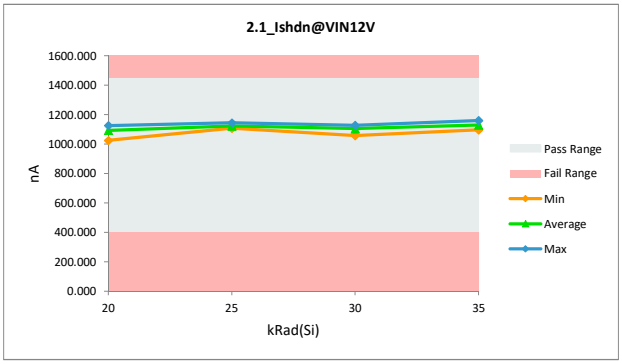
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.1_Ishdn@VIN12V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	1445	1445
Min Limit	400	400

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1007.360	1120.760	113.400
20	62	908.500	1024.920	116.420
20	63	942.080	1047.330	105.250
20	64	1010.950	1116.600	105.650
20	65	1015.130	1100.180	85.050
20	67	988.480	1097.720	109.240
20	68	1012.430	1108.040	95.610
20	69	1008.900	1103.890	94.990
20	70	982.810	1080.980	98.170
20	71	988.920	1105.270	116.350
20	72	1014.630	1125.800	111.170
20	73	1029.740	1124.790	95.050
20	74	967.170	1079.690	112.520
20	75	992.880	1098.820	105.940
20	76	944.570	1063.380	118.810
20	77	924.680	1032.190	107.510
20	78	997.320	1114.690	117.370
20	79	1008.020	1105.270	97.250
20	80	1011.330	1111.440	100.110
20	81	1009.440	1103.390	93.950
20	82	982.280	1100.680	118.400
20	83	1003.520	1088.690	85.170
25	84	983.820	1107.010	123.190
25	85	993.580	1111.290	117.710
25	86	1028.100	1144.490	116.390
25	87	1020.330	1133.290	112.960
25	88	1003.360	1122.770	119.410
30	89	932.670	1056.710	124.040
30	90	999.490	1123.750	124.260
30	91	1019.380	1127.050	107.670
30	92	980.040	1096.870	116.830
30	93	1008.620	1119.000	110.380
35	94	1010.290	1151.320	141.030
35	95	942.080	1096.150	154.070
35	96	957.410	1103.860	146.450
35	97	1014.760	1159.820	145.060
35	98	995.620	1133.790	138.170
	Max	1029.740	1159.820	154.070
	Average	990.289	1103.829	113.541
	Min	908.500	1024.920	85.050
	Std Dev	30.470	29.770	16.277



	2.1_Ishdn@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	1445	nA		
Min Limit	400	nA		
kRad(Si)	20	25	30	35
LL	400.000	400.000	400.000	400.000
Min	1024.920	1107.010	1056.710	1096.150
Average	1093.387	1123.770	1104.676	1128.988
Max	1125.800	1144.490	1127.050	1159.820
UL	1445.000	1445.000	1445.000	1445.000

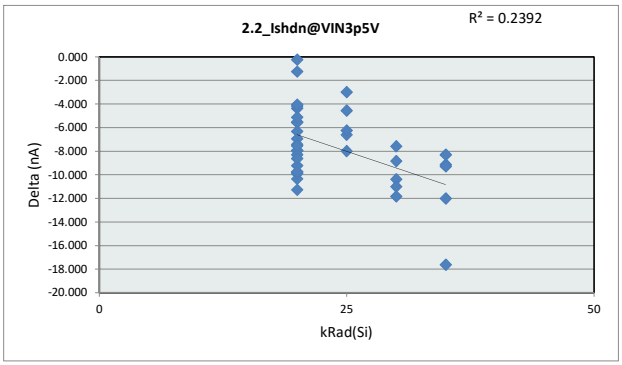


HDR TID Report
TPS7H4010-SEP

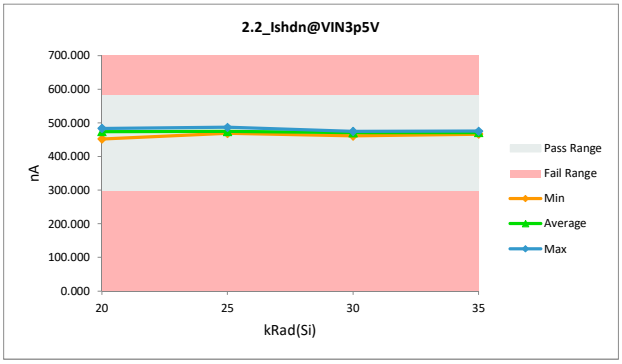
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.2_Ishdn@VIN3p5V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	580	580
Min Limit	295	295

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	490.410	482.450	-7.960
20	62	478.610	474.230	-4.380
20	63	475.990	470.420	-5.570
20	64	489.780	479.430	-10.350
20	65	461.270	452.040	-9.230
20	67	486.880	478.920	-7.960
20	68	472.910	472.660	-0.250
20	69	480.370	472.060	-8.310
20	70	478.100	472.560	-5.540
20	71	487.610	483.420	-4.190
20	72	489.650	478.360	-11.290
20	73	474.040	468.910	-5.130
20	74	481.570	475.240	-6.330
20	75	482.510	475.550	-6.960
20	76	481.600	480.340	-1.260
20	77	479.520	472.090	-7.430
20	78	491.130	483.580	-7.550
20	79	465.360	455.540	-9.820
20	80	478.450	474.390	-4.060
20	81	477.030	467.120	-9.910
20	82	491.100	481.350	-9.750
20	83	479.020	470.390	-8.630
25	84	476.720	470.110	-6.610
25	85	484.240	477.980	-6.260
25	86	472.600	469.610	-2.990
25	87	476.530	468.540	-7.990
25	88	491.350	486.790	-4.560
30	89	481.470	471.080	-10.390
30	90	485.340	474.330	-11.010
30	91	478.580	470.990	-7.590
30	92	483.580	474.740	-8.840
30	93	472.750	460.920	-11.830
35	94	479.490	470.360	-9.130
35	95	492.050	474.420	-17.630
35	96	481.060	469.040	-12.020
35	97	475.680	466.400	-9.280
35	98	483.640	475.330	-8.310
Max		492.050	486.790	-0.250
Average		480.756	473.019	-7.738
Min		461.270	452.040	-17.630
Std Dev		7.121	7.171	3.262



	2.2_Ishdn@VIN3p5V			
Test Site				
Tester				
Test Number				
Max Limit	580	nA		
Min Limit	295	nA		
kRad(Si)	20	25	30	35
LL	295.000	295.000	295.000	295.000
Min	452.040	468.540	460.920	466.400
Average	473.684	474.606	470.412	471.110
Max	483.580	486.790	474.740	475.330
UL	580.000	580.000	580.000	580.000

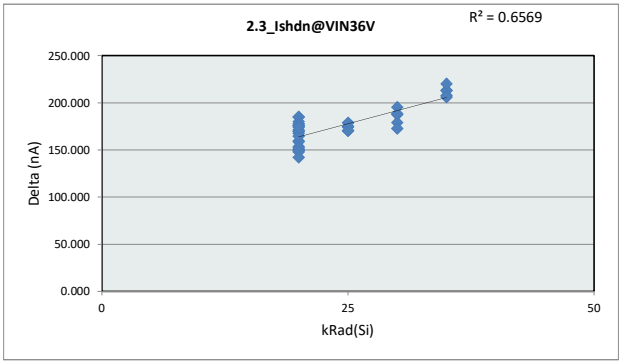


HDR TID Report
TPS7H4010-SEP

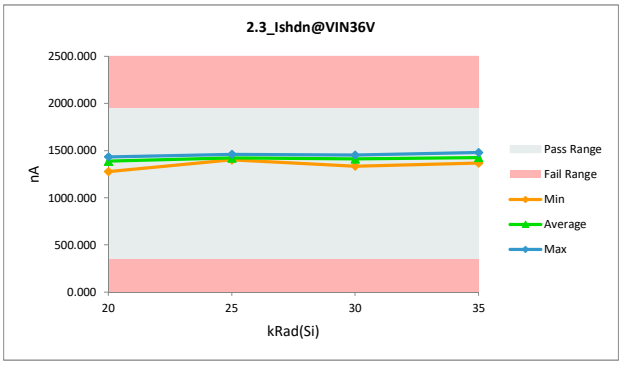
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.3_Ishdn@VIN36V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	1940	1940
Min Limit	345	345

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1252.980	1428.030	175.050
20	62	1109.590	1277.180	167.590
20	63	1146.030	1317.090	171.060
20	64	1249.200	1419.030	169.830
20	65	1258.640	1408.740	150.100
20	67	1211.910	1396.720	184.810
20	68	1260.940	1410.250	149.310
20	69	1254.620	1414.090	159.470
20	70	1224.750	1383.410	158.660
20	71	1222.540	1407.320	184.780
20	72	1254.020	1433.980	179.960
20	73	1274.260	1427.750	153.490
20	74	1189.150	1366.910	177.760
20	75	1217.950	1387.620	169.670
20	76	1164.890	1340.980	176.090
20	77	1128.850	1293.390	164.540
20	78	1235.570	1411.640	176.070
20	79	1263.370	1414.250	150.880
20	80	1253.200	1405.560	152.360
20	81	1257.860	1405.850	147.990
20	82	1218.040	1391.870	173.830
20	83	1251.440	1393.570	142.130
25	84	1226.230	1400.430	174.200
25	85	1228.340	1403.300	174.960
25	86	1290.460	1460.670	170.210
25	87	1262.260	1432.600	170.340
25	88	1242.030	1420.890	178.860
30	89	1146.600	1334.090	187.490
30	90	1249.640	1444.970	195.330
30	91	1274.950	1453.910	178.960
30	92	1209.800	1398.130	188.330
30	93	1257.890	1430.460	172.570
35	94	1250.520	1463.500	212.980
35	95	1154.660	1367.760	213.100
35	96	1180.280	1387.840	207.560
35	97	1259.710	1479.840	220.130
35	98	1230.540	1436.560	206.020
Max		1290.460	1479.840	220.130
Average		1226.046	1401.356	175.310
Min		1109.590	1277.180	142.130
Std Dev		44.535	44.290	19.290



	2.3_Ishdn@VIN36V			
Test Site				
Tester				
Test Number				
Max Limit	1940	nA		
Min Limit	345	nA		
kRad(Si)	20	25	30	35
LL	345.000	345.000	345.000	345.000
Min	1277.180	1400.430	1334.090	1367.760
Average	1387.965	1423.578	1412.312	1427.100
Max	1433.980	1460.670	1453.910	1479.840
UL	1940.000	1940.000	1940.000	1940.000

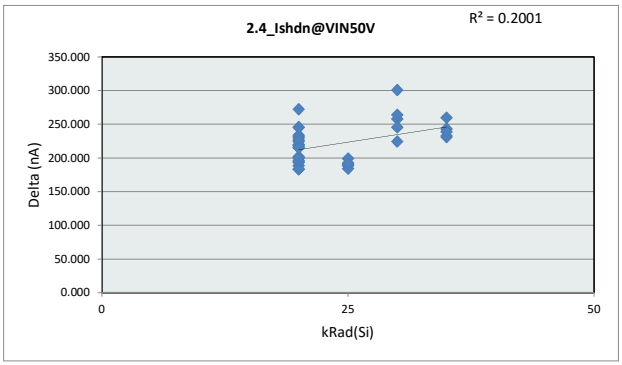


HDR TID Report
TPS7H4010-SEP

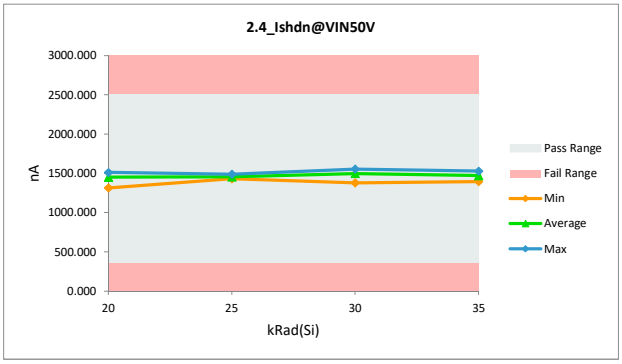
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.4_Ishdn@VIN50V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	2500	2500
Min Limit	345	345

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1264.490	1482.700	218.210
20	62	1117.960	1313.570	195.610
20	63	1155.930	1344.320	188.390
20	64	1265.210	1510.410	245.200
20	65	1269.140	1452.360	183.220
20	67	1227.440	1445.700	218.260
20	68	1270.960	1472.780	201.820
20	69	1270.230	1499.960	229.730
20	70	1239.410	1459.330	219.920
20	71	1237.970	1471.850	233.880
20	72	1271.080	1495.490	224.410
20	73	1289.070	1482.310	193.240
20	74	1201.530	1400.950	199.420
20	75	1231.310	1447.090	215.780
20	76	1180.900	1453.030	272.130
20	77	1138.490	1333.710	195.220
20	78	1249.780	1495.350	245.570
20	79	1276.390	1459.670	183.280
20	80	1273.910	1505.990	232.080
20	81	1269.860	1469.860	200.000
20	82	1229.280	1455.480	226.200
20	83	1265.810	1480.790	214.980
25	84	1239.840	1438.860	199.020
25	85	1240.110	1430.440	190.330
25	86	1300.350	1488.390	188.040
25	87	1277.640	1461.400	183.760
25	88	1257.930	1450.140	192.210
30	89	1152.700	1377.170	224.470
30	90	1258.200	1515.750	257.550
30	91	1290.020	1554.020	264.000
30	92	1223.230	1523.810	300.580
30	93	1270.940	1516.340	245.400
35	94	1267.970	1527.700	259.730
35	95	1164.050	1395.000	230.950
35	96	1198.010	1430.480	232.470
35	97	1280.150	1523.220	243.070
35	98	1243.970	1482.720	238.750
	Max	1300.350	1554.020	300.580
	Average	1239.494	1460.761	221.267
	Min	1117.960	1313.570	183.220
	Std Dev	45.963	54.726	28.351



	2.4_Ishdn@VIN50V			
Test Site				
Tester				
Test Number				
Max Limit	2500	nA		
Min Limit	345	nA		
kRad(Si)	20	25	30	35
LL	345.000	345.000	345.000	345.000
Min	1313.570	1430.440	1377.170	1395.000
Average	1451.486	1453.846	1497.418	1471.824
Max	1510.410	1488.390	1554.020	1527.700
UL	2500.000	2500.000	2500.000	2500.000

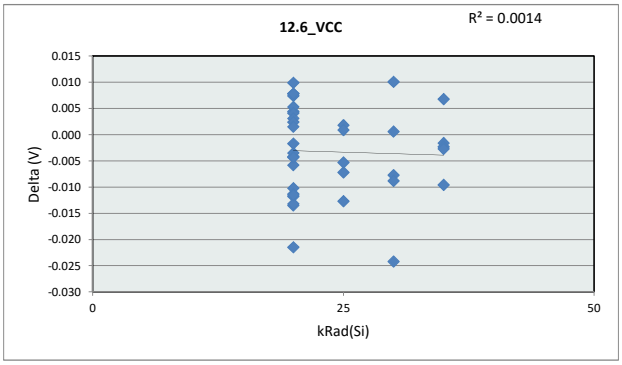


HDR TID Report
TPS7H4010-SEP

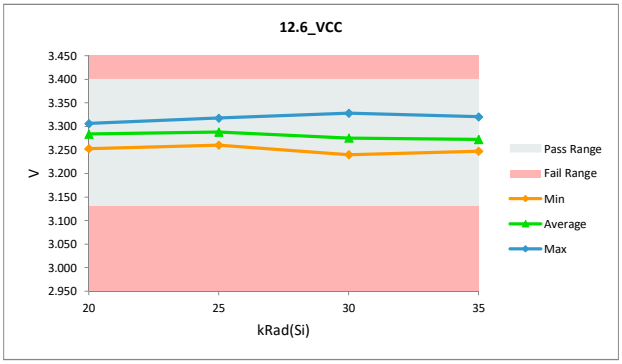
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	12.6_VCC	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.4	3.4
Min Limit	3.13	3.13

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.273	3.278	0.004
20	62	3.301	3.291	-0.010
20	63	3.278	3.286	0.008
20	64	3.312	3.306	-0.006
20	65	3.267	3.263	-0.004
20	67	3.272	3.268	-0.004
20	68	3.317	3.306	-0.011
20	69	3.285	3.291	0.005
20	70	3.269	3.273	0.004
20	71	3.262	3.265	0.003
20	72	3.293	3.303	0.010
20	73	3.287	3.289	0.002
20	74	3.300	3.279	-0.021
20	75	3.288	3.274	-0.013
20	76	3.304	3.300	-0.004
20	77	3.255	3.253	-0.002
20	78	3.300	3.301	0.002
20	79	3.282	3.271	-0.012
20	80	3.272	3.279	0.007
20	81	3.279	3.266	-0.013
20	82	3.288	3.296	0.008
20	83	3.315	3.303	-0.011
25	84	3.325	3.318	-0.007
25	85	3.273	3.260	-0.013
25	86	3.279	3.280	0.002
25	87	3.313	3.314	0.001
25	88	3.272	3.267	-0.005
30	89	3.240	3.240	0.001
30	90	3.303	3.279	-0.024
30	91	3.318	3.328	0.010
30	92	3.259	3.251	-0.008
30	93	3.287	3.278	-0.009
35	94	3.249	3.247	-0.002
35	95	3.257	3.255	-0.002
35	96	3.252	3.249	-0.003
35	97	3.314	3.320	0.007
35	98	3.300	3.291	-0.010
Max		3.325	3.328	0.010
Average		3.285	3.282	-0.003
Min		3.240	3.240	-0.024
Std Dev		0.022	0.022	0.008



	12.6_VCC			
Test Site				
Tester				
Test Number				
Max Limit	3.4	V		
Min Limit	3.13	V		
kRad(Si)	20	25	30	35
LL	3.130	3.130	3.130	3.130
Min	3.253	3.260	3.240	3.247
Average	3.284	3.288	3.275	3.272
Max	3.306	3.318	3.328	3.320
UL	3.400	3.400	3.400	3.400

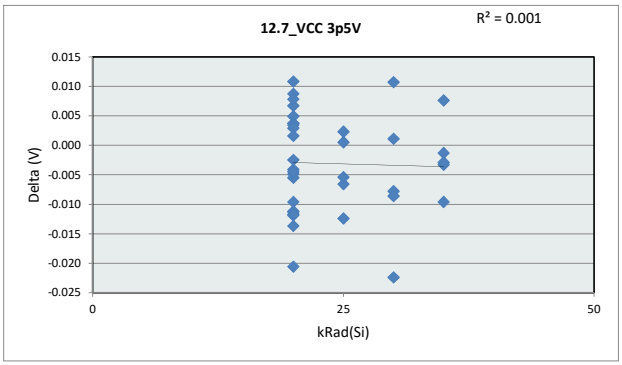


HDR TID Report
TPS7H4010-SEP

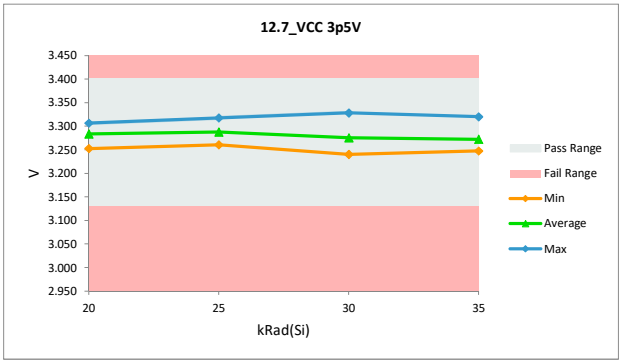
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	12.7_VCC 3p5V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.4	3.4
Min Limit	3.13	3.13

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.273	3.277	0.004
20	62	3.300	3.291	-0.010
20	63	3.277	3.286	0.009
20	64	3.312	3.306	-0.005
20	65	3.267	3.263	-0.005
20	67	3.272	3.268	-0.004
20	68	3.317	3.305	-0.012
20	69	3.285	3.290	0.005
20	70	3.270	3.273	0.004
20	71	3.262	3.265	0.003
20	72	3.293	3.303	0.011
20	73	3.287	3.290	0.003
20	74	3.300	3.279	-0.021
20	75	3.288	3.274	-0.014
20	76	3.304	3.300	-0.004
20	77	3.255	3.253	-0.003
20	78	3.300	3.301	0.002
20	79	3.282	3.271	-0.011
20	80	3.272	3.279	0.007
20	81	3.277	3.266	-0.011
20	82	3.288	3.296	0.008
20	83	3.315	3.303	-0.012
25	84	3.324	3.318	-0.007
25	85	3.273	3.261	-0.012
25	86	3.278	3.280	0.002
25	87	3.313	3.314	0.001
25	88	3.272	3.266	-0.005
30	89	3.239	3.240	0.001
30	90	3.303	3.280	-0.022
30	91	3.317	3.328	0.011
30	92	3.259	3.251	-0.008
30	93	3.287	3.278	-0.009
35	94	3.249	3.247	-0.001
35	95	3.257	3.254	-0.003
35	96	3.252	3.249	-0.003
35	97	3.312	3.320	0.008
35	98	3.300	3.291	-0.010
Max		3.324	3.328	0.011
Average		3.285	3.282	-0.003
Min		3.239	3.240	-0.022
Std Dev		0.022	0.022	0.008



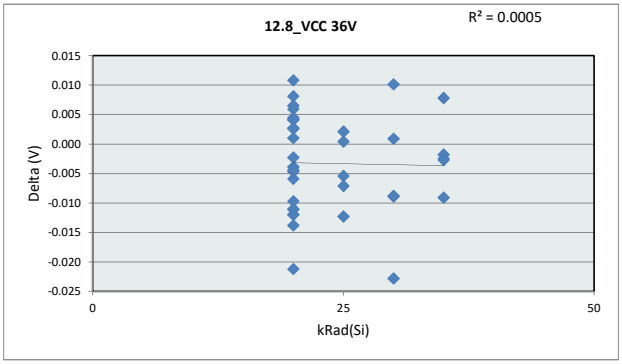
	12.7_VCC 3p5V			
Test Site				
Tester				
Test Number				
Max Limit	3.4	V		
Min Limit	3.13	V		
kRad(Si)	20	25	30	35
LL	3.130	3.130	3.130	3.130
Min	3.253	3.261	3.240	3.247
Average	3.284	3.288	3.276	3.272
Max	3.306	3.318	3.328	3.320
UL	3.400	3.400	3.400	3.400



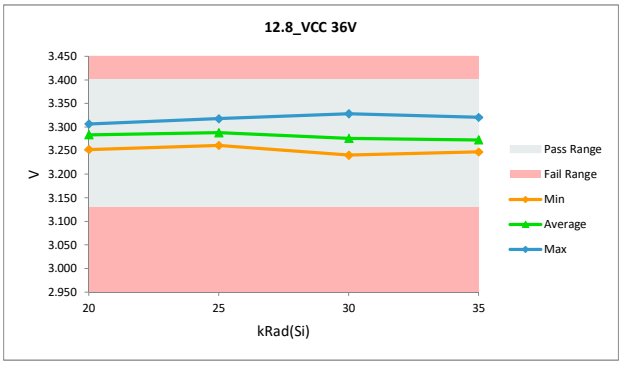
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	12.8_VCC 36V		
Test Site			
Tester			
Test Number			
Unit	V	V	
Max Limit	3.4	3.4	
Min Limit	3.13	3.13	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.273	3.277	0.004
20	62	3.301	3.291	-0.010
20	63	3.277	3.285	0.008
20	64	3.313	3.307	-0.006
20	65	3.267	3.263	-0.005
20	67	3.272	3.268	-0.004
20	68	3.317	3.306	-0.011
20	69	3.286	3.290	0.004
20	70	3.269	3.273	0.004
20	71	3.262	3.265	0.003
20	72	3.293	3.303	0.011
20	73	3.287	3.290	0.003
20	74	3.300	3.279	-0.021
20	75	3.288	3.274	-0.014
20	76	3.304	3.300	-0.004
20	77	3.255	3.252	-0.002
20	78	3.300	3.301	0.001
20	79	3.282	3.271	-0.011
20	80	3.272	3.278	0.006
20	81	3.277	3.265	-0.012
20	82	3.289	3.296	0.007
20	83	3.315	3.303	-0.012
25	84	3.325	3.318	-0.007
25	85	3.273	3.261	-0.012
25	86	3.278	3.280	0.002
25	87	3.313	3.314	0.000
25	88	3.272	3.266	-0.005
30	89	3.240	3.240	0.001
30	90	3.303	3.281	-0.023
30	91	3.318	3.328	0.010
30	92	3.261	3.252	-0.009
30	93	3.287	3.279	-0.009
35	94	3.249	3.247	-0.002
35	95	3.257	3.255	-0.003
35	96	3.253	3.250	-0.003
35	97	3.313	3.321	0.008
35	98	3.300	3.291	-0.009
	Max	3.325	3.328	0.011
	Average	3.285	3.282	-0.003
	Min	3.240	3.240	-0.023
	Std Dev	0.022	0.022	0.008



	12.8_VCC 36V			
Test Site				
Tester				
Test Number				
Max Limit	3.4	V		
Min Limit	3.13	V		
kRad(Si)	20	25	30	35
LL	3.130	3.130	3.130	3.130
Min	3.252	3.261	3.240	3.247
Average	3.284	3.288	3.276	3.273
Max	3.307	3.318	3.328	3.321
UL	3.400	3.400	3.400	3.400

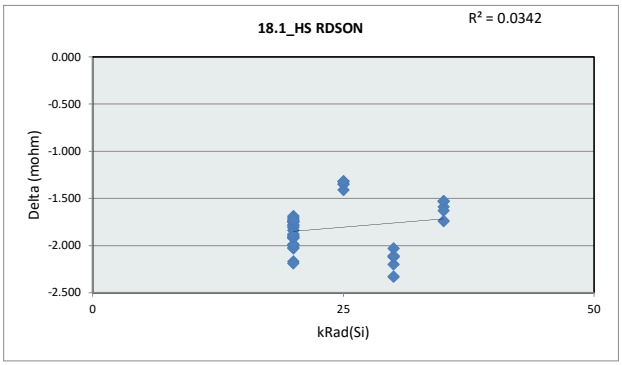


HDR TID Report
TPS7H4010-SEP

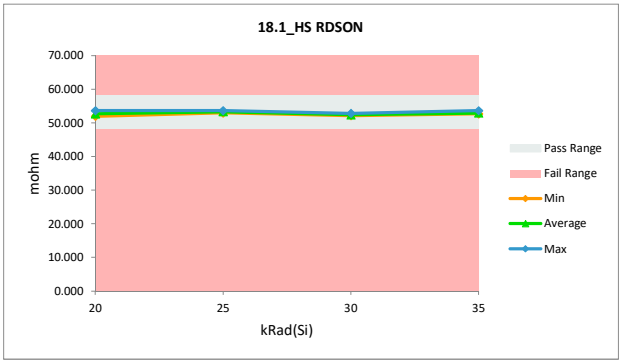
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	18.1_HS RDSON	
Test Site		
Tester		
Test Number		
Unit	mohm	mohm
Max Limit	58	58
Min Limit	48	48

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	53.980	51.980	-2.000
20	62	55.080	52.910	-2.170
20	63	55.220	53.030	-2.190
20	64	54.230	52.240	-1.990
20	65	54.820	52.790	-2.030
20	67	54.590	52.570	-2.020
20	68	54.180	52.430	-1.750
20	69	54.070	52.330	-1.740
20	70	54.350	52.660	-1.690
20	71	54.670	52.830	-1.840
20	72	53.960	52.250	-1.710
20	73	54.840	53.050	-1.790
20	74	54.700	52.800	-1.900
20	75	54.170	52.360	-1.810
20	76	54.800	52.880	-1.920
20	77	55.050	53.060	-1.990
20	78	54.210	52.430	-1.780
20	79	55.520	53.600	-1.920
20	80	54.270	52.520	-1.750
20	81	54.190	52.460	-1.730
20	82	54.620	52.720	-1.900
20	83	54.310	52.430	-1.880
25	84	54.520	53.170	-1.350
25	85	54.730	53.320	-1.410
25	86	54.930	53.610	-1.320
25	87	54.830	53.480	-1.350
25	88	54.270	52.950	-1.320
30	89	55.120	52.790	-2.330
30	90	54.330	52.130	-2.200
30	91	54.460	52.340	-2.120
30	92	54.360	52.250	-2.110
30	93	54.360	52.330	-2.030
35	94	54.270	52.740	-1.530
35	95	55.350	53.610	-1.740
35	96	54.360	52.770	-1.590
35	97	54.180	52.650	-1.530
35	98	54.490	52.860	-1.630
Max		55.520	53.610	-1.320
Average		54.551	52.739	-1.812
Min		53.960	51.980	-2.330
Std Dev		0.394	0.425	0.265



	18.1_HS RDSON			
Test Site				
Tester				
Test Number				
Max Limit	58	mohm		
Min Limit	48	mohm		
kRad(Si)	20	25	30	35
LL	48.000	48.000	48.000	48.000
Min	51.980	52.950	52.130	52.650
Average	52.651	53.306	52.368	52.926
Max	53.600	53.610	52.790	53.610
UL	58.000	58.000	58.000	58.000

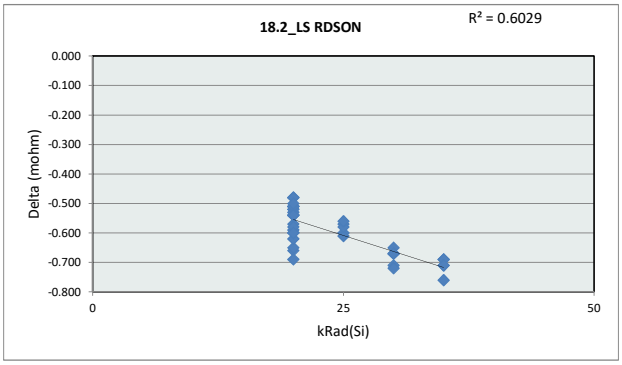


HDR TID Report
TPS7H4010-SEP

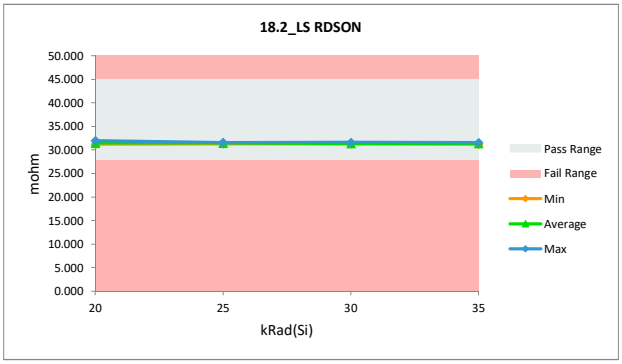
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	18.2_LS RDSON	
Test Site		
Tester		
Test Number		
Unit	mohm	mohm
Max Limit	45	45
Min Limit	27.8	27.8

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	31.900	31.240	-0.660
20	62	32.150	31.500	-0.650
20	63	32.270	31.580	-0.690
20	64	31.810	31.190	-0.620
20	65	32.110	31.510	-0.600
20	67	32.100	31.510	-0.590
20	68	31.840	31.330	-0.510
20	69	31.880	31.310	-0.570
20	70	31.940	31.400	-0.540
20	71	32.060	31.530	-0.530
20	72	31.850	31.340	-0.510
20	73	32.090	31.570	-0.520
20	74	32.010	31.530	-0.480
20	75	31.910	31.430	-0.480
20	76	32.050	31.530	-0.520
20	77	32.240	31.660	-0.580
20	78	31.830	31.320	-0.510
20	79	32.470	31.960	-0.510
20	80	31.950	31.410	-0.540
20	81	31.980	31.480	-0.500
20	82	32.030	31.490	-0.540
20	83	31.910	31.310	-0.600
25	84	31.900	31.300	-0.600
25	85	32.140	31.530	-0.610
25	86	32.160	31.590	-0.570
25	87	32.040	31.460	-0.580
25	88	31.990	31.430	-0.560
30	89	32.310	31.600	-0.710
30	90	31.980	31.330	-0.650
30	91	31.990	31.270	-0.720
30	92	32.020	31.350	-0.670
30	93	32.010	31.340	-0.670
35	94	32.020	31.330	-0.690
35	95	32.340	31.580	-0.760
35	96	32.070	31.380	-0.690
35	97	31.920	31.210	-0.710
35	98	32.050	31.340	-0.710
	Max	32.470	31.960	-0.480
	Average	32.036	31.437	-0.599
	Min	31.810	31.190	-0.760
	Std Dev	0.150	0.150	0.079



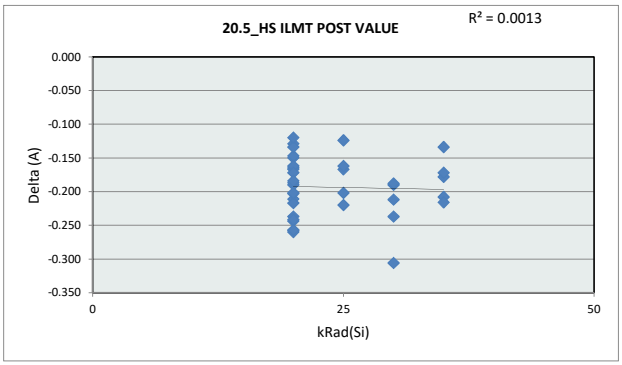
	18.2_LS RDSON			
Test Site				
Tester				
Test Number				
Max Limit	45	mohm		
Min Limit	27.8	mohm		
kRad(Si)	20	25	30	35
LL	27.800	27.800	27.800	27.800
Min	31.190	31.300	31.270	31.210
Average	31.460	31.462	31.378	31.368
Max	31.960	31.590	31.600	31.580
UL	45.000	45.000	45.000	45.000



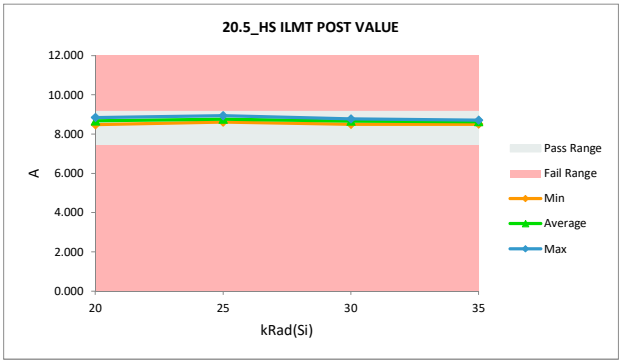
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	20.5_HS ILMT POST VALUE		
Test Site			
Tester			
Test Number			
Unit	A	A	
Max Limit	9.15	9.15	
Min Limit	7.4	7.4	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	8.873	8.723	-0.150
20	62	8.975	8.717	-0.258
20	63	8.882	8.622	-0.260
20	64	8.955	8.790	-0.165
20	65	8.881	8.637	-0.244
20	67	8.711	8.474	-0.237
20	68	8.862	8.715	-0.147
20	69	8.817	8.650	-0.167
20	70	8.727	8.598	-0.129
20	71	8.845	8.634	-0.211
20	72	8.877	8.687	-0.190
20	73	8.992	8.830	-0.162
20	74	8.806	8.589	-0.217
20	75	8.797	8.663	-0.134
20	76	8.952	8.710	-0.242
20	77	9.048	8.845	-0.203
20	78	8.942	8.770	-0.172
20	79	8.883	8.626	-0.257
20	80	8.794	8.592	-0.202
20	81	8.810	8.623	-0.187
20	82	8.788	8.604	-0.184
20	83	8.889	8.769	-0.120
25	84	9.062	8.938	-0.124
25	85	8.834	8.614	-0.220
25	86	8.891	8.724	-0.167
25	87	8.880	8.718	-0.162
25	88	8.998	8.796	-0.202
30	89	8.737	8.500	-0.237
30	90	8.901	8.711	-0.190
30	91	9.025	8.719	-0.306
30	92	8.960	8.772	-0.188
30	93	8.825	8.613	-0.212
35	94	8.861	8.683	-0.178
35	95	8.789	8.655	-0.134
35	96	8.710	8.502	-0.208
35	97	8.831	8.615	-0.216
35	98	8.884	8.712	-0.172
	Max	9.062	8.938	-0.120
	Average	8.873	8.679	-0.193
	Min	8.710	8.474	-0.306
	Std Dev	0.090	0.097	0.043



	20.5_HS ILMT POST VALUE			
Test Site				
Tester				
Test Number				
Max Limit	9.15	A		
Min Limit	7.4	A		
kRad(Si)	20	25	30	35
LL	7.400	7.400	7.400	7.400
Min	8.474	8.614	8.500	8.502
Average	8.676	8.758	8.663	8.633
Max	8.845	8.938	8.772	8.712
UL	9.150	9.150	9.150	9.150

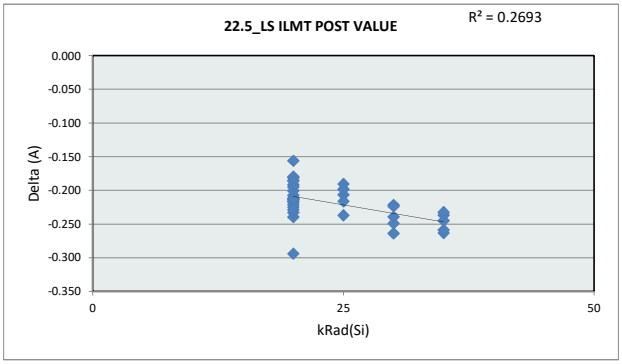


HDR TID Report
TPS7H4010-SEP

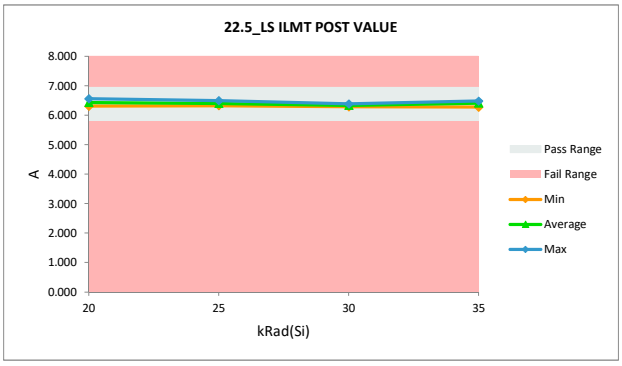
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	22.5_LS ILMT POST VALUE	
Test Site		
Tester		
Test Number		
Unit	A	A
Max Limit	6.95	6.95
Min Limit	5.8	5.8

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	6.635	6.454	-0.181
20	62	6.674	6.463	-0.211
20	63	6.676	6.382	-0.294
20	64	6.568	6.377	-0.192
20	65	6.588	6.376	-0.213
20	67	6.586	6.346	-0.240
20	68	6.710	6.493	-0.217
20	69	6.691	6.505	-0.185
20	70	6.688	6.532	-0.156
20	71	6.758	6.558	-0.201
20	72	6.735	6.539	-0.195
20	73	6.725	6.518	-0.207
20	74	6.541	6.308	-0.233
20	75	6.604	6.387	-0.216
20	76	6.698	6.473	-0.225
20	77	6.578	6.364	-0.214
20	78	6.557	6.336	-0.221
20	79	6.573	6.358	-0.214
20	80	6.572	6.393	-0.180
20	81	6.689	6.460	-0.229
20	82	6.651	6.438	-0.213
20	83	6.649	6.463	-0.186
25	84	6.686	6.495	-0.191
25	85	6.593	6.387	-0.207
25	86	6.643	6.427	-0.216
25	87	6.520	6.322	-0.198
25	88	6.608	6.371	-0.237
30	89	6.510	6.288	-0.222
30	90	6.583	6.359	-0.224
30	91	6.647	6.383	-0.264
30	92	6.565	6.316	-0.249
30	93	6.576	6.337	-0.239
35	94	6.716	6.479	-0.237
35	95	6.712	6.479	-0.232
35	96	6.618	6.354	-0.263
35	97	6.738	6.479	-0.259
35	98	6.519	6.274	-0.245
	Max	6.758	6.558	-0.156
	Average	6.632	6.413	-0.219
	Min	6.510	6.274	-0.294
	Std Dev	0.069	0.076	0.028



	22.5_LS ILMT POST VALUE			
Test Site				
Tester				
Test Number				
Max Limit	6.95	A		
Min Limit	5.8	A		
kRad(Si)	20	25	30	35
LL	5.800	5.800	5.800	5.800
Min	6.308	6.322	6.288	6.274
Average	6.433	6.400	6.337	6.413
Max	6.558	6.495	6.383	6.479
UL	6.950	6.950	6.950	6.950

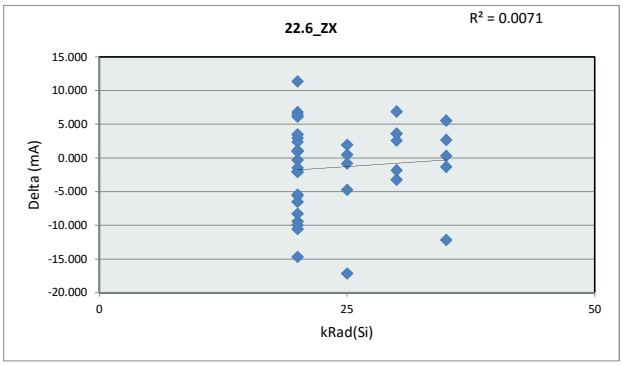


HDR TID Report
TPS7H4010-SEP

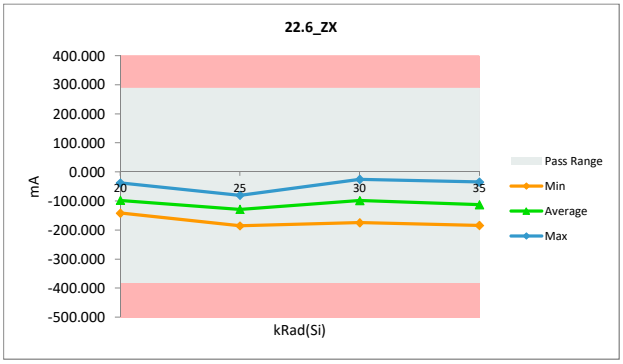
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	22.6_ZX	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	288	288
Min Limit	-380	-380

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	-32.770	-38.230	-5.460
20	62	-128.790	-127.840	0.950
20	63	-129.320	-131.410	-2.090
20	64	-46.280	-51.880	-5.600
20	65	-112.650	-122.060	-9.410
20	67	-69.490	-69.800	-0.310
20	68	-99.060	-98.030	1.030
20	69	-99.070	-107.340	-8.270
20	70	-32.720	-47.410	-14.690
20	71	-110.550	-112.540	-1.990
20	72	-99.030	-96.090	2.940
20	73	-131.580	-129.190	2.390
20	74	-54.900	-48.120	6.780
20	75	-114.990	-121.500	-6.510
20	76	-64.300	-63.190	1.110
20	77	-88.030	-84.530	3.500
20	78	-102.520	-112.480	-9.960
20	79	-135.960	-124.610	11.350
20	80	-113.620	-107.190	6.430
20	81	-106.880	-108.340	-1.460
20	82	-131.210	-141.770	-10.560
20	83	-115.600	-109.500	6.100
25	84	-80.750	-80.290	0.460
25	85	-108.520	-106.600	1.920
25	86	-114.490	-131.650	-17.160
25	87	-184.990	-185.820	-0.830
25	88	-134.550	-139.280	-4.730
30	89	-172.950	-174.780	-1.830
30	90	-50.470	-53.690	-3.220
30	91	-28.330	-25.740	2.590
30	92	-73.490	-69.890	3.600
30	93	-174.530	-167.660	6.870
35	94	-121.260	-122.580	-1.320
35	95	-40.400	-34.860	5.540
35	96	-83.650	-83.340	0.310
35	97	-142.890	-140.220	2.670
35	98	-172.270	-184.450	-12.180
	Max	-28.330	-25.740	11.350
	Average	-102.780	-104.159	-1.379
	Min	-184.990	-185.820	-17.160
	Std Dev	41.344	41.774	6.456



	22.6_ZX			
Test Site				
Tester				
Test Number				
Max Limit	288	mA		
Min Limit	-380	mA		
kRad(Si)	20	25	30	35
LL	-380.000	-380.000	-380.000	-380.000
Min	-141.770	-185.820	-174.780	-184.450
Average	-97.866	-128.728	-98.352	-113.090
Max	-38.230	-80.290	-25.740	-34.860
UL	288.000	288.000	288.000	288.000

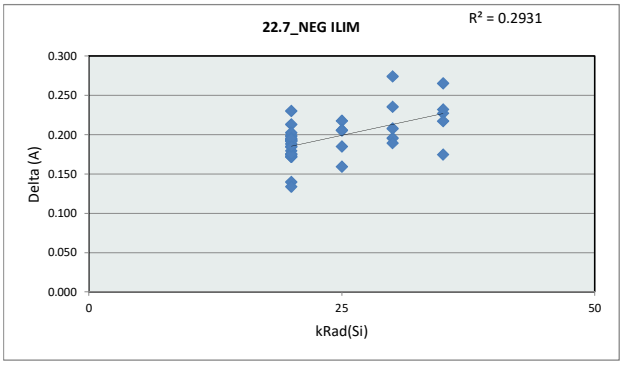


HDR TID Report
TPS7H4010-SEP

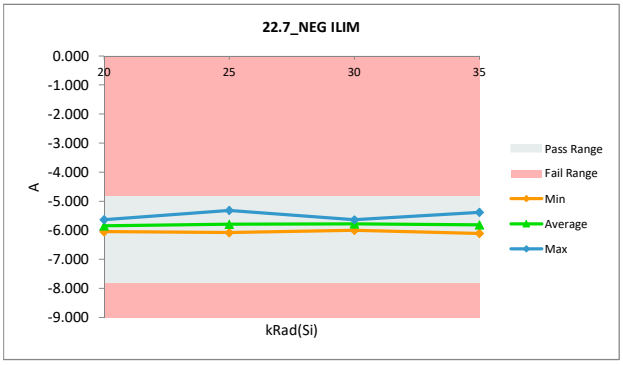
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	22.7_NEG ILIM	
Test Site		
Tester		
Test Number		
Unit	A	A
Max Limit	-4.8	-4.8
Min Limit	-7.8	-7.8

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	-5.943	-5.803	0.140
20	62	-6.019	-5.839	0.180
20	63	-5.987	-5.757	0.230
20	64	-6.156	-5.984	0.172
20	65	-6.152	-5.939	0.213
20	67	-5.997	-5.799	0.198
20	68	-6.182	-5.989	0.193
20	69	-6.078	-5.903	0.175
20	70	-6.026	-5.833	0.193
20	71	-6.063	-5.871	0.192
20	72	-6.232	-6.047	0.184
20	73	-6.197	-6.008	0.188
20	74	-5.863	-5.668	0.194
20	75	-6.164	-5.990	0.174
20	76	-6.105	-5.906	0.199
20	77	-5.807	-5.635	0.172
20	78	-5.942	-5.739	0.203
20	79	-5.813	-5.679	0.134
20	80	-6.198	-6.006	0.192
20	81	-5.858	-5.682	0.175
20	82	-5.916	-5.721	0.195
20	83	-6.082	-5.898	0.185
25	84	-6.160	-5.975	0.185
25	85	-6.053	-5.835	0.218
25	86	-6.290	-6.084	0.206
25	87	-5.473	-5.314	0.159
25	88	-5.983	-5.778	0.205
30	89	-5.876	-5.640	0.236
30	90	-5.850	-5.655	0.196
30	91	-6.246	-5.972	0.274
30	92	-5.827	-5.638	0.189
30	93	-6.210	-6.002	0.208
35	94	-6.138	-5.911	0.227
35	95	-5.991	-5.817	0.175
35	96	-6.110	-5.845	0.265
35	97	-6.328	-6.111	0.217
35	98	-5.612	-5.380	0.232
	Max	-5.473	-5.314	0.274
	Average	-6.025	-5.828	0.197
	Min	-6.328	-6.111	0.134
	Std Dev	0.184	0.178	0.029



	22.7_NEG ILIM			
Test Site				
Tester				
Test Number				
Max Limit	-4.8	A		
Min Limit	-7.8	A		
kRad(Si)	20	25	30	35
LL	-7.800	-7.800	-7.800	-7.800
Min	-6.047	-6.084	-6.002	-6.111
Average	-5.850	-5.797	-5.781	-5.813
Max	-5.635	-5.314	-5.638	-5.380
UL	-4.800	-4.800	-4.800	-4.800

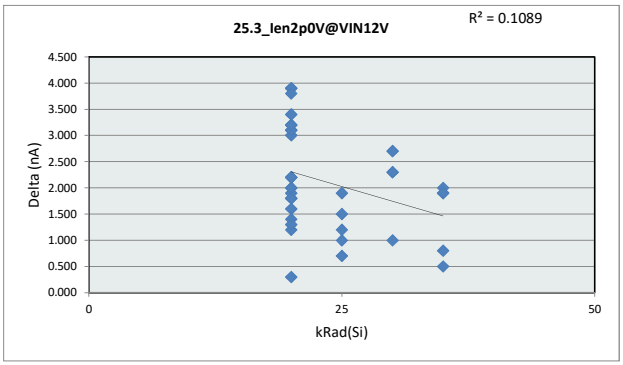


HDR TID Report
TPS7H4010-SEP

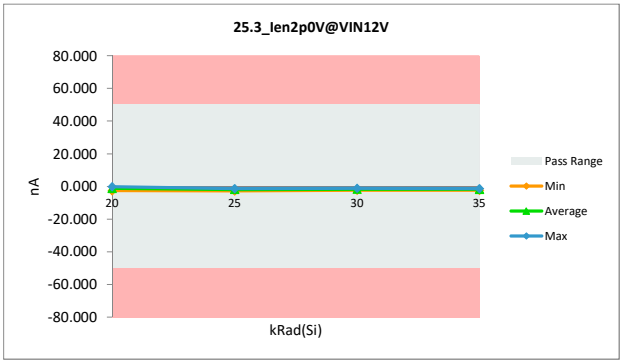
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.3_Ien2p0V@VIN12V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	50	50
Min Limit	-50	-50

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	-4.300	-1.100	3.200
20	62	-3.600	-1.800	1.800
20	63	-3.800	-0.700	3.100
20	64	-4.000	-0.100	3.900
20	65	-4.200	-1.200	3.000
20	67	-3.100	-0.900	2.200
20	68	-3.900	-0.500	3.400
20	69	-3.100	-1.900	1.200
20	70	-2.700	-0.800	1.900
20	71	-3.500	-1.300	2.200
20	72	-2.700	-1.300	1.400
20	73	-4.200	-0.300	3.900
20	74	-4.000	-0.900	3.100
20	75	-3.500	-1.500	2.000
20	76	-3.600	-1.400	2.200
20	77	-2.900	-1.600	1.300
20	78	-4.800	-1.600	3.200
20	79	-3.100	-1.500	1.600
20	80	-2.900	-2.600	0.300
20	81	-4.300	-0.500	3.800
20	82	-2.700	-0.700	2.000
20	83	-3.600	-1.800	1.800
25	84	-3.400	-1.500	1.900
25	85	-2.700	-1.700	1.000
25	86	-2.800	-1.300	1.500
25	87	-3.400	-2.700	0.700
25	88	-3.200	-2.000	1.200
30	89	-3.400	-2.400	1.000
30	90	-4.000	-1.700	2.300
30	91	-4.000	-1.700	2.300
30	92	-4.200	-1.500	2.700
30	93	-3.800	-1.100	2.700
35	94	-3.200	-1.300	1.900
35	95	-2.500	-1.700	0.800
35	96	-3.600	-1.600	2.000
35	97	-2.900	-2.400	0.500
35	98	-3.600	-1.700	1.900
	Max	-2.500	-0.100	3.900
	Average	-3.492	-1.414	2.078
	Min	-4.800	-2.700	0.300
	Std Dev	0.569	0.607	0.953



	25.3_Ien2p0V@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	50	nA		
Min Limit	-50	nA		
kRad(Si)	20	25	30	35
LL	-50.000	-50.000	-50.000	-50.000
Min	-2.600	-2.700	-2.400	-2.400
Average	-1.182	-1.840	-1.680	-1.740
Max	-0.100	-1.300	-1.100	-1.300
UL	50.000	50.000	50.000	50.000

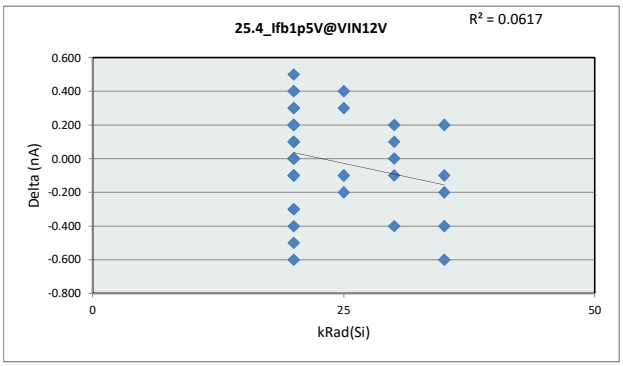


HDR TID Report
TPS7H4010-SEP

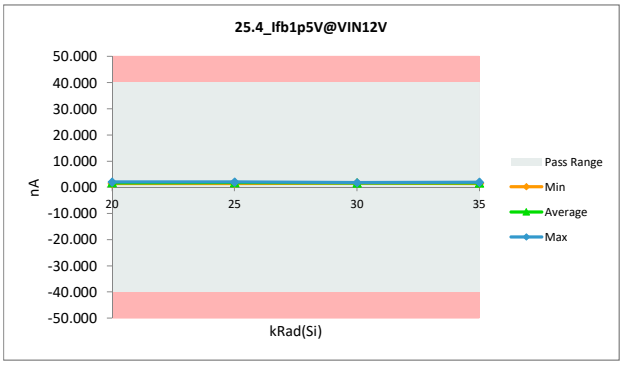
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.4_Ifb1p5V@VIN12V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	40	40
Min Limit	-40	-40

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.800	2.000	0.200
20	62	2.000	1.400	-0.600
20	63	1.800	1.400	-0.400
20	64	1.600	1.600	0.000
20	65	1.500	1.400	-0.100
20	67	1.900	1.900	0.000
20	68	1.600	1.700	0.100
20	69	1.500	1.900	0.400
20	70	1.700	1.800	0.100
20	71	1.800	1.800	0.000
20	72	2.000	1.700	-0.300
20	73	1.500	1.800	0.300
20	74	1.500	1.900	0.400
20	75	1.800	1.500	-0.300
20	76	1.900	1.800	-0.100
20	77	1.700	1.900	0.200
20	78	1.600	1.900	0.300
20	79	1.700	1.900	0.200
20	80	1.500	2.000	0.500
20	81	1.900	1.400	-0.500
20	82	2.000	1.900	-0.100
20	83	1.900	2.000	0.100
25	84	1.800	1.700	-0.100
25	85	1.600	1.500	-0.100
25	86	1.600	2.000	0.400
25	87	2.000	1.800	-0.200
25	88	1.600	1.900	0.300
30	89	2.100	1.700	-0.400
30	90	1.500	1.600	0.100
30	91	1.600	1.800	0.200
30	92	1.800	1.700	-0.100
30	93	1.600	1.600	0.000
35	94	1.900	1.500	-0.400
35	95	1.700	1.900	0.200
35	96	2.000	1.900	-0.100
35	97	2.000	1.400	-0.600
35	98	1.700	1.500	-0.200
Max		2.100	2.000	0.500
Average		1.749	1.732	-0.016
Min		1.500	1.400	-0.600
Std Dev		0.182	0.199	0.289



	25.4_Ifb1p5V@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	40	nA		
Min Limit	-40	nA		
kRad(Si)	20	25	30	35
LL	-40.000	-40.000	-40.000	-40.000
Min	1.400	1.500	1.600	1.400
Average	1.755	1.780	1.680	1.640
Max	2.000	2.000	1.800	1.900
UL	40.000	40.000	40.000	40.000

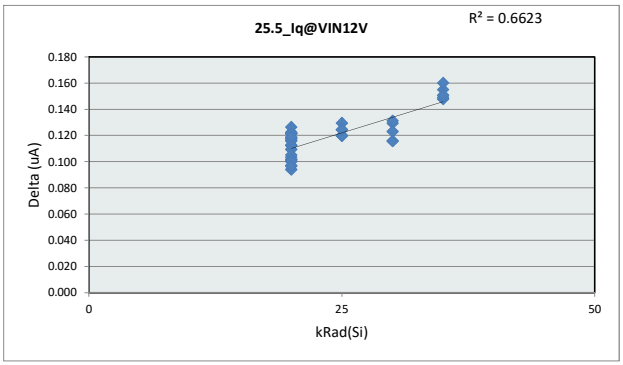


HDR TID Report
TPS7H4010-SEP

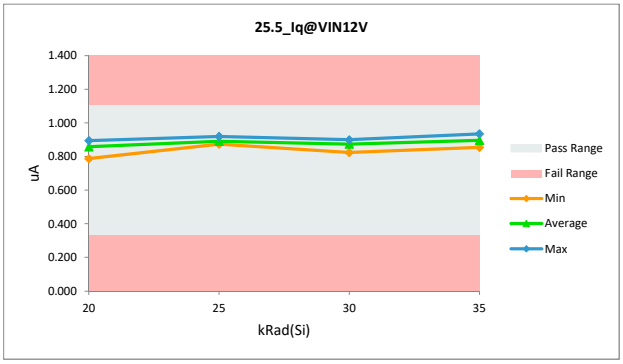
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.5_Iq@VIN12V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	1.1	1.1
Min Limit	0.33	0.33

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.763	0.873	0.109
20	62	0.669	0.787	0.118
20	63	0.702	0.814	0.113
20	64	0.762	0.874	0.113
20	65	0.784	0.881	0.097
20	67	0.742	0.865	0.122
20	68	0.775	0.876	0.101
20	69	0.766	0.869	0.103
20	70	0.747	0.852	0.105
20	71	0.744	0.866	0.121
20	72	0.767	0.886	0.118
20	73	0.793	0.894	0.101
20	74	0.726	0.848	0.122
20	75	0.746	0.862	0.116
20	76	0.698	0.824	0.126
20	77	0.683	0.799	0.116
20	78	0.743	0.864	0.122
20	79	0.782	0.876	0.094
20	80	0.770	0.872	0.102
20	81	0.773	0.873	0.100
20	82	0.738	0.857	0.119
20	83	0.761	0.858	0.097
25	84	0.744	0.874	0.130
25	85	0.749	0.873	0.124
25	86	0.799	0.919	0.120
25	87	0.785	0.905	0.120
25	88	0.756	0.880	0.124
30	89	0.694	0.824	0.129
30	90	0.762	0.893	0.131
30	91	0.784	0.899	0.116
30	92	0.737	0.860	0.123
30	93	0.777	0.892	0.116
35	94	0.763	0.918	0.155
35	95	0.695	0.855	0.160
35	96	0.719	0.867	0.148
35	97	0.786	0.935	0.149
35	98	0.750	0.901	0.151
	Max	0.799	0.935	0.160
	Average	0.750	0.869	0.120
	Min	0.669	0.787	0.094
	Std Dev	0.032	0.031	0.016



	25.5_Iq@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	1.1	uA		
Min Limit	0.33	uA		
kRad(Si)	20	25	30	35
LL	0.330	0.330	0.330	0.330
Min	0.787	0.874	0.824	0.855
Average	0.858	0.890	0.874	0.895
Max	0.894	0.919	0.899	0.935
UL	1.100	1.100	1.100	1.100

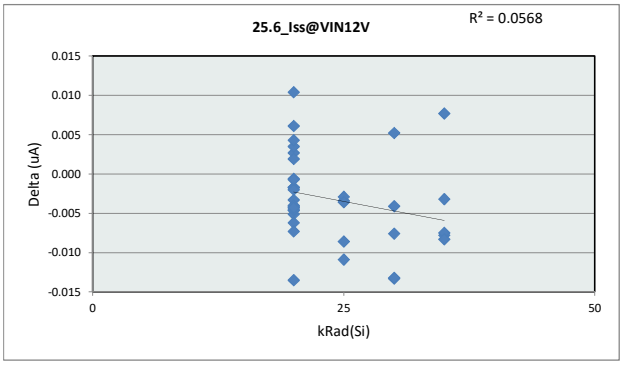


HDR TID Report
TPS7H4010-SEP

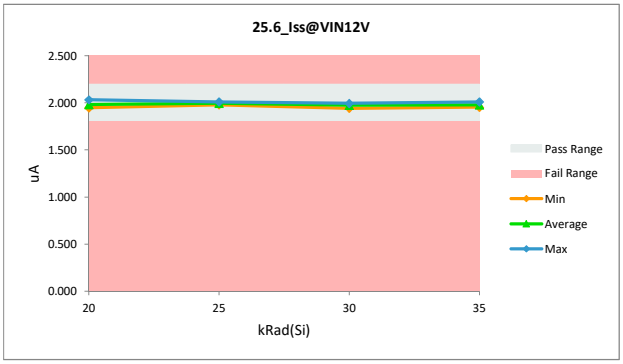
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.6_Iss@VIN12V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	2.199	2.199
Min Limit	1.8	1.8

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.950	1.948	-0.002
20	62	1.972	1.967	-0.005
20	63	2.019	2.015	-0.004
20	64	1.971	1.957	-0.013
20	65	2.014	2.009	-0.005
20	67	1.954	1.948	-0.006
20	68	2.009	2.012	0.003
20	69	1.965	1.969	0.003
20	70	1.974	1.975	0.002
20	71	2.011	2.016	0.004
20	72	1.959	1.956	-0.003
20	73	1.958	1.956	-0.002
20	74	1.983	1.979	-0.004
20	75	1.998	1.996	-0.002
20	76	1.964	1.970	0.006
20	77	1.974	1.967	-0.007
20	78	1.997	1.993	-0.004
20	79	2.023	2.033	0.010
20	80	2.000	1.995	-0.005
20	81	1.987	1.982	-0.004
20	82	1.963	1.962	-0.001
20	83	2.017	2.016	-0.001
25	84	1.982	1.979	-0.003
25	85	2.019	2.010	-0.009
25	86	2.000	1.997	-0.003
25	87	2.013	2.002	-0.011
25	88	1.998	1.994	-0.004
30	89	1.989	1.995	0.005
30	90	1.988	1.984	-0.004
30	91	1.973	1.960	-0.013
30	92	2.005	1.992	-0.013
30	93	1.950	1.943	-0.008
35	94	1.962	1.954	-0.008
35	95	1.961	1.969	0.008
35	96	1.999	1.991	-0.008
35	97	2.013	2.010	-0.003
35	98	1.976	1.968	-0.008
Max		2.023	2.033	0.010
Average		1.986	1.983	-0.003
Min		1.950	1.943	-0.013
Std Dev		0.022	0.023	0.006



	25.6_Iss@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	2.199	uA		
Min Limit	1.8	uA		
kRad(Si)	20	25	30	35
LL	1.800	1.800	1.800	1.800
Min	1.948	1.979	1.943	1.954
Average	1.983	1.997	1.975	1.978
Max	2.033	2.010	1.995	2.010
UL	2.199	2.199	2.199	2.199

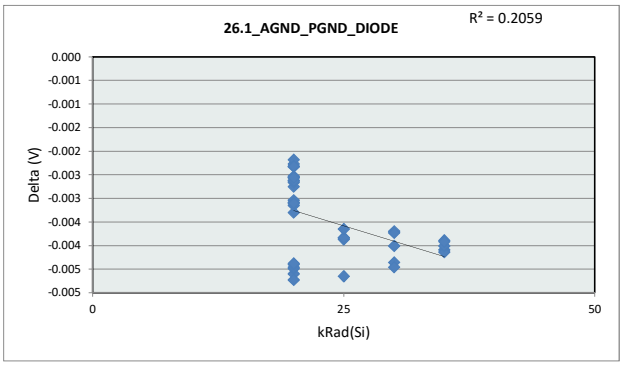


HDR TID Report
TPS7H4010-SEP

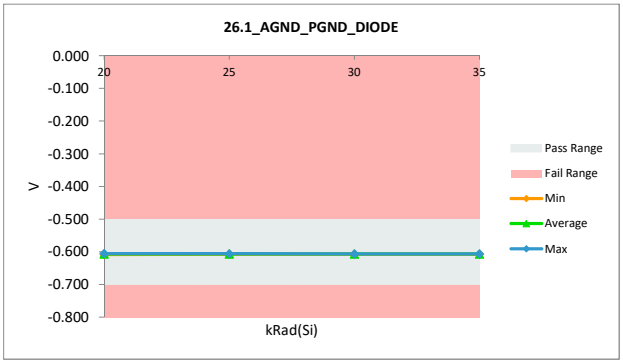
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.1_AGND_PGND_DIODE	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	-0.5	-0.5
Min Limit	-0.7	-0.7

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	-0.603	-0.607	-0.005
20	62	-0.604	-0.608	-0.004
20	63	-0.603	-0.608	-0.004
20	64	-0.603	-0.607	-0.004
20	65	-0.603	-0.608	-0.005
20	67	-0.605	-0.608	-0.003
20	68	-0.603	-0.606	-0.003
20	69	-0.603	-0.606	-0.003
20	70	-0.602	-0.605	-0.003
20	71	-0.604	-0.607	-0.002
20	72	-0.603	-0.605	-0.002
20	73	-0.603	-0.606	-0.002
20	74	-0.604	-0.606	-0.002
20	75	-0.603	-0.605	-0.003
20	76	-0.604	-0.606	-0.003
20	77	-0.604	-0.606	-0.003
20	78	-0.603	-0.605	-0.003
20	79	-0.603	-0.605	-0.003
20	80	-0.602	-0.605	-0.003
20	81	-0.603	-0.606	-0.003
20	82	-0.604	-0.607	-0.003
20	83	-0.601	-0.605	-0.004
25	84	-0.601	-0.606	-0.005
25	85	-0.604	-0.608	-0.004
25	86	-0.602	-0.606	-0.004
25	87	-0.603	-0.607	-0.004
25	88	-0.602	-0.606	-0.004
30	89	-0.603	-0.607	-0.004
30	90	-0.603	-0.607	-0.004
30	91	-0.603	-0.607	-0.004
30	92	-0.603	-0.607	-0.004
30	93	-0.602	-0.606	-0.004
35	94	-0.602	-0.606	-0.004
35	95	-0.603	-0.608	-0.004
35	96	-0.603	-0.607	-0.004
35	97	-0.602	-0.606	-0.004
35	98	-0.604	-0.607	-0.004
Max		-0.601	-0.605	-0.002
Average		-0.603	-0.607	-0.004
Min		-0.605	-0.608	-0.005
Std Dev		0.001	0.001	0.001



	26.1_AGND_PGND_DIODE			
Test Site				
Tester				
Test Number				
Max Limit	-0.5	V		
Min Limit	-0.7	V		
kRad(Si)	20	25	30	35
LL	-0.700	-0.700	-0.700	-0.700
Min	-0.608	-0.608	-0.607	-0.608
Average	-0.606	-0.606	-0.607	-0.607
Max	-0.605	-0.606	-0.606	-0.606
UL	-0.500	-0.500	-0.500	-0.500

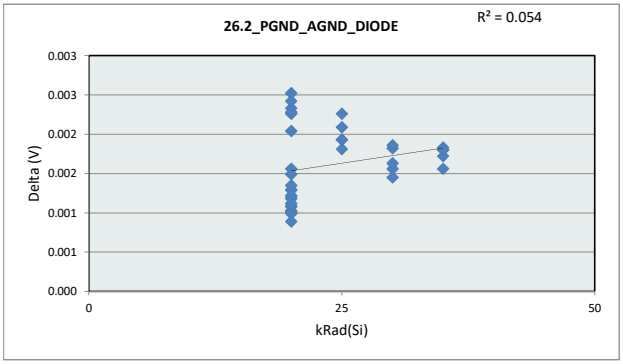


HDR TID Report
TPS7H4010-SEP

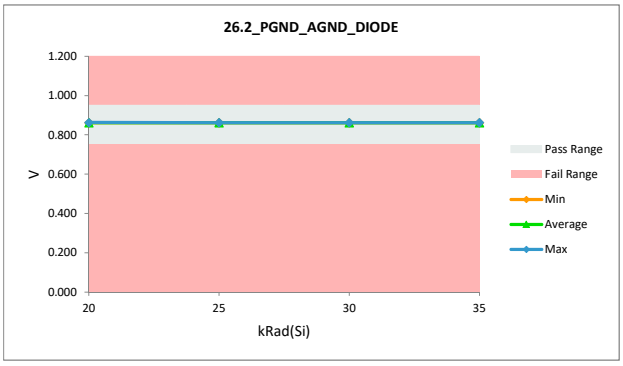
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.2_PGND_AGND_DIODE	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.95	0.95
Min Limit	0.75	0.75

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.860	0.863	0.003
20	62	0.860	0.863	0.002
20	63	0.860	0.862	0.002
20	64	0.860	0.863	0.002
20	65	0.860	0.862	0.002
20	67	0.861	0.862	0.002
20	68	0.861	0.862	0.001
20	69	0.861	0.862	0.001
20	70	0.861	0.862	0.001
20	71	0.861	0.862	0.001
20	72	0.861	0.862	0.001
20	73	0.860	0.862	0.001
20	74	0.860	0.861	0.001
20	75	0.861	0.862	0.001
20	76	0.861	0.862	0.001
20	77	0.861	0.862	0.001
20	78	0.861	0.862	0.001
20	79	0.861	0.862	0.001
20	80	0.861	0.862	0.001
20	81	0.861	0.862	0.001
20	82	0.861	0.862	0.001
20	83	0.860	0.862	0.002
25	84	0.860	0.862	0.002
25	85	0.860	0.862	0.002
25	86	0.860	0.862	0.002
25	87	0.860	0.862	0.002
25	88	0.860	0.862	0.002
30	89	0.860	0.862	0.002
30	90	0.860	0.862	0.002
30	91	0.860	0.862	0.002
30	92	0.860	0.862	0.001
30	93	0.860	0.862	0.002
35	94	0.861	0.862	0.002
35	95	0.860	0.862	0.002
35	96	0.860	0.862	0.002
35	97	0.860	0.862	0.002
35	98	0.860	0.862	0.002
Max		0.861	0.863	0.003
Average		0.860	0.862	0.002
Min		0.860	0.861	0.001
Std Dev		0.000	0.000	0.000



	26.2_PGND_AGND_DIODE			
Test Site				
Tester				
Test Number				
Max Limit	0.95	V		
Min Limit	0.75	V		
kRad(Si)	20	25	30	35
LL	0.750	0.750	0.750	0.750
Min	0.861	0.862	0.862	0.862
Average	0.862	0.862	0.862	0.862
Max	0.863	0.862	0.862	0.862
UL	0.950	0.950	0.950	0.950

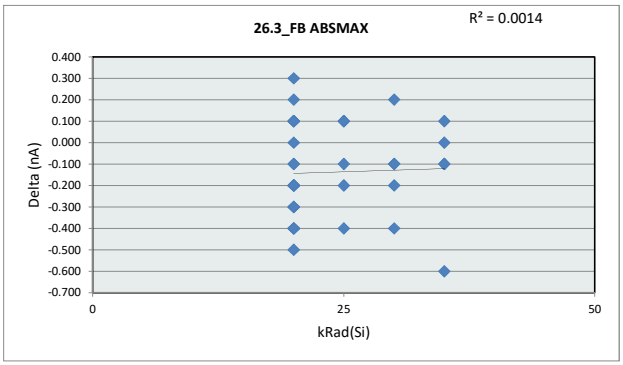


HDR TID Report
TPS7H4010-SEP

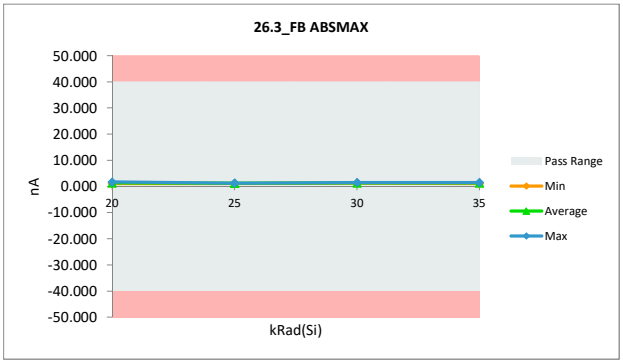
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.3_FB ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	40	40
Min Limit	-40	-40

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.500	1.100	-0.400
20	62	1.300	1.100	-0.200
20	63	1.300	1.400	0.100
20	64	1.700	1.300	-0.400
20	65	1.200	1.500	0.300
20	67	1.700	1.700	0.000
20	68	1.600	1.500	-0.100
20	69	1.300	1.400	0.100
20	70	1.400	1.200	-0.200
20	71	1.300	1.400	0.100
20	72	1.300	1.200	-0.100
20	73	1.600	1.100	-0.500
20	74	1.500	1.200	-0.300
20	75	1.700	1.300	-0.400
20	76	1.600	1.400	-0.200
20	77	1.600	1.200	-0.400
20	78	1.400	1.200	-0.200
20	79	1.700	1.400	-0.300
20	80	1.600	1.300	-0.300
20	81	1.400	1.500	0.100
20	82	1.300	1.500	0.200
20	83	1.500	1.300	-0.200
25	84	1.500	1.100	-0.400
25	85	1.200	1.300	0.100
25	86	1.300	1.200	-0.100
25	87	1.100	1.200	0.100
25	88	1.500	1.300	-0.200
30	89	1.600	1.500	-0.100
30	90	1.300	1.500	0.200
30	91	1.400	1.300	-0.100
30	92	1.400	1.200	-0.200
30	93	1.800	1.400	-0.400
35	94	1.700	1.100	-0.600
35	95	1.400	1.500	0.100
35	96	1.300	1.200	-0.100
35	97	1.400	1.300	-0.100
35	98	1.500	1.500	0.000
	Max	1.800	1.700	0.300
	Average	1.457	1.319	-0.138
	Min	1.100	1.100	-0.600
	Std Dev	0.171	0.151	0.219



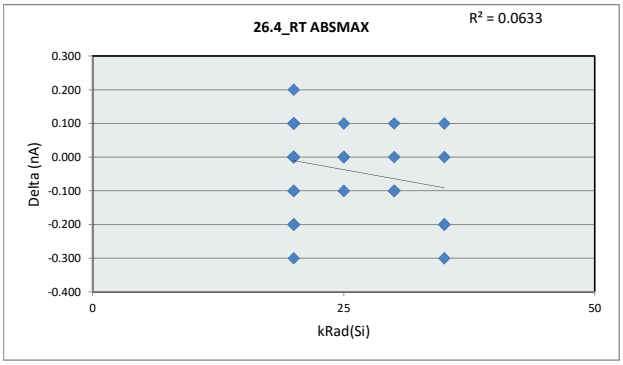
	26.3_FB ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	40	nA		
Min Limit	-40	nA		
kRad(Si)	20	25	30	35
LL	-40.000	-40.000	-40.000	-40.000
Min	1.100	1.100	1.200	1.100
Average	1.327	1.220	1.380	1.320
Max	1.700	1.300	1.500	1.500
UL	40.000	40.000	40.000	40.000



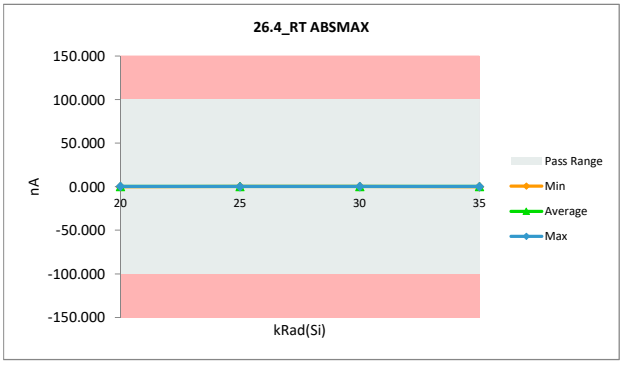
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.4_RT ABSMAX		
Test Site			
Tester			
Test Number			
Unit	nA	nA	
Max Limit	100	100	
Min Limit	-100	-100	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.100	0.100	0.000
20	62	0.100	0.100	0.000
20	63	0.300	0.300	0.000
20	64	0.200	0.000	-0.200
20	65	0.300	0.300	0.000
20	67	0.100	0.300	0.200
20	68	0.200	0.100	-0.100
20	69	0.200	-0.100	-0.300
20	70	0.000	0.000	0.000
20	71	0.200	0.200	0.000
20	72	0.100	0.100	0.000
20	73	0.300	0.200	-0.100
20	74	0.100	0.100	0.000
20	75	0.100	0.200	0.100
20	76	0.100	0.200	0.100
20	77	0.200	0.000	-0.200
20	78	0.200	0.200	0.000
20	79	0.400	0.400	0.000
20	80	0.000	0.100	0.100
20	81	0.200	0.000	-0.200
20	82	0.200	0.300	0.100
20	83	0.100	0.200	0.100
25	84	0.200	0.100	-0.100
25	85	0.100	0.100	0.000
25	86	0.100	0.200	0.100
25	87	0.200	0.200	0.000
25	88	0.100	0.100	0.000
30	89	0.200	0.300	0.100
30	90	0.200	0.100	-0.100
30	91	0.100	0.000	-0.100
30	92	0.100	0.000	-0.100
30	93	0.100	0.100	0.000
35	94	0.200	0.000	-0.200
35	95	0.300	0.000	-0.300
35	96	0.200	0.000	-0.200
35	97	0.100	0.200	0.100
35	98	0.100	0.100	0.000
Max		0.400	0.400	0.200
Average		0.162	0.130	-0.032
Min		0.000	-0.100	-0.300
Std Dev		0.086	0.115	0.120



	26.4_RT ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	100	nA		
Min Limit	-100	nA		
kRad(Si)	20	25	30	35
LL	-100.000	-100.000	-100.000	-100.000
Min	-0.100	0.100	0.100	0.000
Average	0.150	0.140	0.100	0.060
Max	0.400	0.200	0.300	0.200
UL	100.000	100.000	100.000	100.000

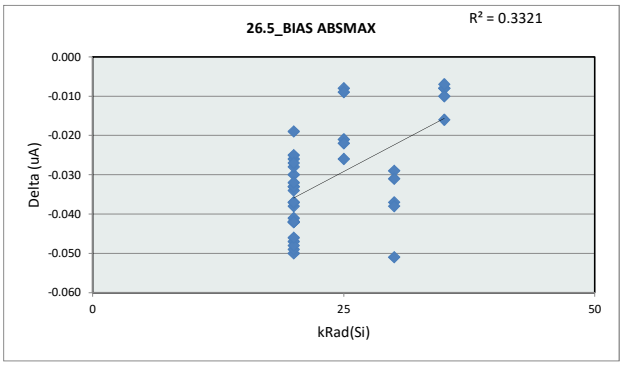


HDR TID Report
TPS7H4010-SEP

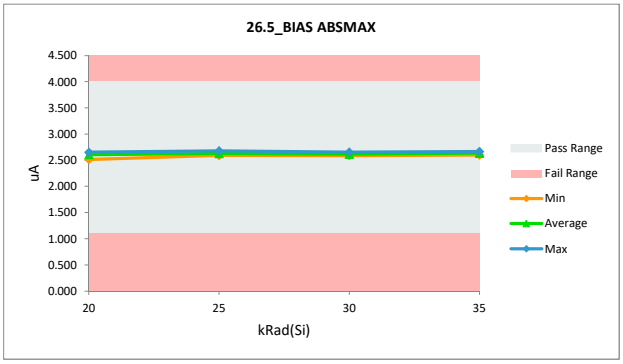
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.5_BIAS ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	4	4
Min Limit	1.1	1.1

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	2.673	2.631	-0.042
20	62	2.650	2.608	-0.042
20	63	2.635	2.594	-0.041
20	64	2.675	2.633	-0.042
20	65	2.573	2.523	-0.050
20	67	2.680	2.642	-0.038
20	68	2.603	2.570	-0.033
20	69	2.627	2.578	-0.049
20	70	2.628	2.591	-0.037
20	71	2.698	2.651	-0.047
20	72	2.668	2.634	-0.034
20	73	2.603	2.573	-0.030
20	74	2.666	2.618	-0.048
20	75	2.664	2.645	-0.019
20	76	2.664	2.636	-0.028
20	77	2.656	2.630	-0.026
20	78	2.672	2.647	-0.025
20	79	2.553	2.516	-0.037
20	80	2.627	2.581	-0.046
20	81	2.614	2.581	-0.033
20	82	2.683	2.651	-0.032
20	83	2.615	2.588	-0.027
25	84	2.631	2.605	-0.026
25	85	2.688	2.680	-0.008
25	86	2.620	2.611	-0.009
25	87	2.614	2.593	-0.021
25	88	2.681	2.659	-0.022
30	89	2.635	2.598	-0.037
30	90	2.693	2.655	-0.038
30	91	2.623	2.594	-0.029
30	92	2.682	2.651	-0.031
30	93	2.640	2.589	-0.051
35	94	2.613	2.605	-0.008
35	95	2.663	2.655	-0.008
35	96	2.662	2.652	-0.010
35	97	2.605	2.598	-0.007
35	98	2.683	2.667	-0.016
Max		2.698	2.680	-0.007
Average		2.645	2.614	-0.030
Min		2.553	2.516	-0.051
Std Dev		0.035	0.038	0.013



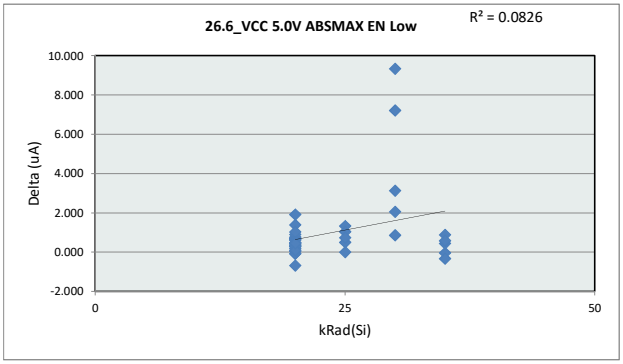
	26.5_BIAS ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	4	uA		
Min Limit	1.1	uA		
kRad(Si)	20	25	30	35
LL	1.100	1.100	1.100	1.100
Min	2.516	2.593	2.589	2.598
Average	2.606	2.630	2.617	2.635
Max	2.651	2.680	2.655	2.667
UL	4.000	4.000	4.000	4.000



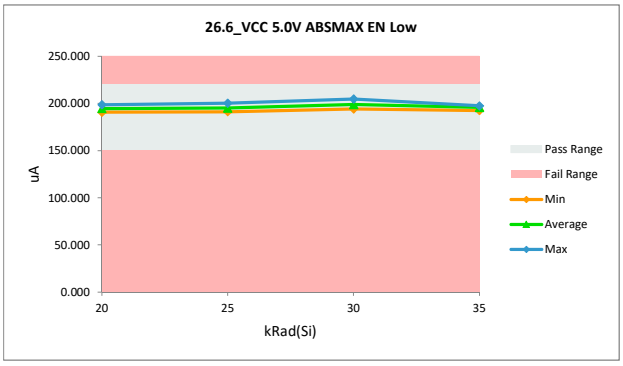
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.6_VCC 5.0V ABSMAX EN Low		
Test Site			
Tester			
Test Number			
Unit	uA	uA	
Max Limit	220	220	
Min Limit	150	150	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	193.147	193.848	0.701
20	62	192.920	193.598	0.678
20	63	193.216	193.523	0.307
20	64	196.089	196.846	0.757
20	65	194.645	195.290	0.645
20	67	192.507	193.890	1.383
20	68	192.905	193.798	0.893
20	69	195.074	195.675	0.601
20	70	191.838	191.755	-0.083
20	71	196.133	198.050	1.917
20	72	194.212	194.581	0.369
20	73	194.345	195.368	1.023
20	74	194.167	193.483	-0.684
20	75	194.758	194.800	0.042
20	76	191.804	192.282	0.478
20	77	190.884	190.801	-0.083
20	78	198.152	198.613	0.461
20	79	192.730	193.038	0.308
20	80	195.978	196.166	0.188
20	81	195.661	195.942	0.281
20	82	191.982	192.065	0.083
20	83	195.862	196.310	0.448
25	84	193.975	193.973	-0.002
25	85	196.393	197.719	1.326
25	86	190.207	191.239	1.032
25	87	192.068	192.565	0.497
25	88	199.588	200.314	0.726
30	89	196.859	198.911	2.052
30	90	193.415	194.276	0.861
30	91	195.381	204.702	9.321
30	92	197.600	200.722	3.122
30	93	188.291	195.493	7.202
35	94	191.691	192.564	0.873
35	95	194.153	194.114	-0.039
35	96	197.081	197.514	0.433
35	97	196.952	197.531	0.579
35	98	197.719	197.390	-0.329
	Max	199.588	204.702	9.321
	Average	194.335	195.372	1.037
	Min	188.291	190.801	-0.684
	Std Dev	2.437	2.929	1.900



	26.6_VCC 5.0V ABSMAX EN Low			
Test Site				
Tester				
Test Number				
Max Limit	220	uA		
Min Limit	150	uA		
kRad(Si)	20	25	30	35
LL	150.000	150.000	150.000	150.000
Min	190.801	191.239	194.276	192.564
Average	194.533	195.162	198.821	195.823
Max	198.613	200.314	204.702	197.531
UL	220.000	220.000	220.000	220.000

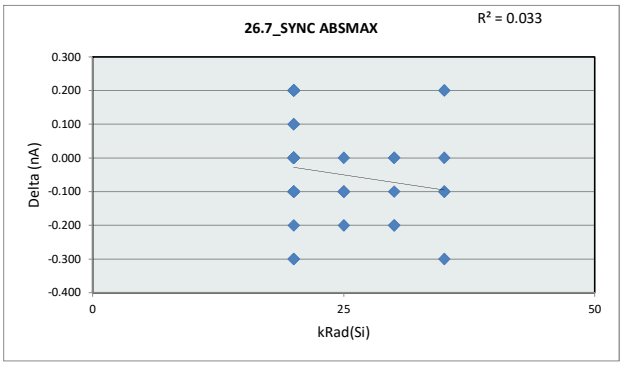


HDR TID Report
TPS7H4010-SEP

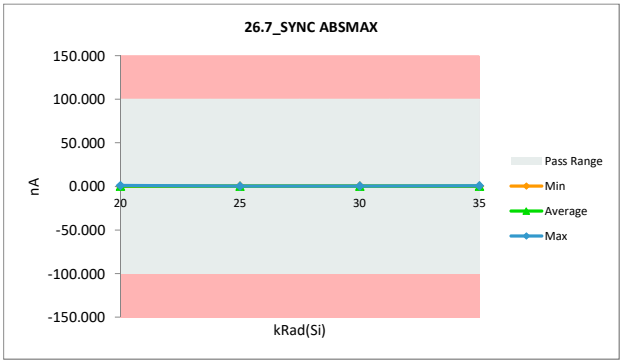
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.7_SYNC ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	100	100
Min Limit	-100	-100

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.400	0.300	-0.100
20	62	0.400	0.400	0.000
20	63	0.600	0.800	0.200
20	64	0.300	0.500	0.200
20	65	0.600	0.800	0.200
20	67	0.500	0.200	-0.300
20	68	0.500	0.500	0.000
20	69	0.400	0.300	-0.100
20	70	0.300	0.300	0.000
20	71	0.300	0.200	-0.100
20	72	0.300	0.300	0.000
20	73	0.600	0.400	-0.200
20	74	0.400	0.300	-0.100
20	75	0.300	0.400	0.100
20	76	0.500	0.500	0.000
20	77	0.500	0.200	-0.300
20	78	0.300	0.300	0.000
20	79	0.800	1.000	0.200
20	80	0.400	0.500	0.100
20	81	0.400	0.300	-0.100
20	82	0.500	0.400	-0.100
20	83	0.400	0.400	0.000
25	84	0.300	0.300	0.000
25	85	0.500	0.400	-0.100
25	86	0.500	0.300	-0.200
25	87	0.500	0.400	-0.100
25	88	0.400	0.300	-0.100
30	89	0.600	0.600	0.000
30	90	0.500	0.300	-0.200
30	91	0.500	0.400	-0.100
30	92	0.600	0.600	0.000
30	93	0.600	0.400	-0.200
35	94	0.500	0.400	-0.100
35	95	0.600	0.800	0.200
35	96	0.500	0.500	0.000
35	97	0.600	0.500	-0.100
35	98	0.500	0.200	-0.300
	Max	0.800	1.000	0.200
	Average	0.470	0.424	-0.046
	Min	0.300	0.200	-0.300
	Std Dev	0.118	0.185	0.139



	26.7_SYNC ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	100	nA		
Min Limit	-100	nA		
kRad(Si)	20	25	30	35
LL	-100.000	-100.000	-100.000	-100.000
Min	0.200	0.300	0.300	0.200
Average	0.423	0.340	0.460	0.480
Max	1.000	0.400	0.600	0.800
UL	100.000	100.000	100.000	100.000

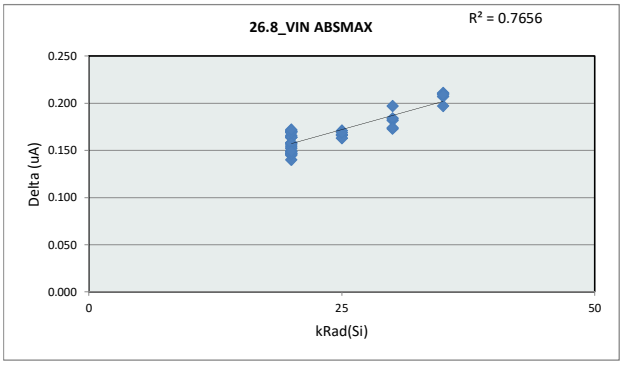


HDR TID Report
TPS7H4010-SEP

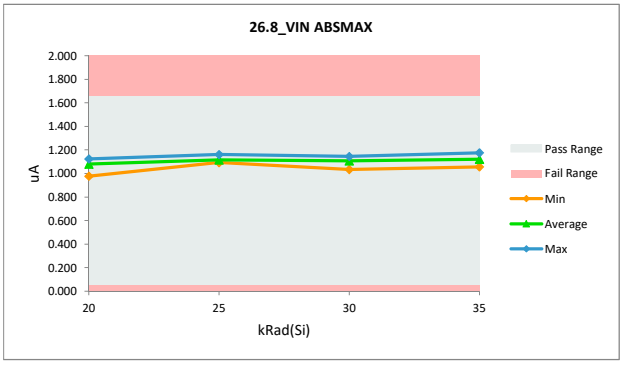
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.8_VIN ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	1.65	1.65
Min Limit	0.05	0.05

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.942	1.108	0.166
20	62	0.819	0.977	0.158
20	63	0.857	1.013	0.156
20	64	0.941	1.105	0.164
20	65	0.968	1.113	0.145
20	67	0.914	1.084	0.170
20	68	0.960	1.109	0.149
20	69	0.949	1.103	0.154
20	70	0.925	1.077	0.152
20	71	0.918	1.089	0.171
20	72	0.946	1.116	0.170
20	73	0.977	1.124	0.147
20	74	0.893	1.057	0.164
20	75	0.913	1.077	0.164
20	76	0.864	1.034	0.170
20	77	0.838	0.996	0.158
20	78	0.923	1.092	0.169
20	79	0.973	1.113	0.140
20	80	0.951	1.098	0.147
20	81	0.957	1.103	0.146
20	82	0.911	1.083	0.172
20	83	0.945	1.094	0.149
25	84	0.923	1.094	0.171
25	85	0.926	1.093	0.167
25	86	0.995	1.161	0.166
25	87	0.971	1.134	0.163
25	88	0.932	1.101	0.169
30	89	0.852	1.034	0.182
30	90	0.943	1.140	0.197
30	91	0.972	1.145	0.173
30	92	0.906	1.090	0.184
30	93	0.958	1.132	0.174
35	94	0.947	1.158	0.211
35	95	0.850	1.057	0.207
35	96	0.885	1.082	0.197
35	97	0.966	1.176	0.210
35	98	0.923	1.132	0.209
Max		0.995	1.176	0.211
Average		0.925	1.094	0.169
Min		0.819	0.977	0.140
Std Dev		0.043	0.044	0.019



	26.8_VIN ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	1.65	uA		
Min Limit	0.05	uA		
kRad(Si)	20	25	30	35
LL	0.050	0.050	0.050	0.050
Min	0.977	1.093	1.034	1.057
Average	1.080	1.117	1.108	1.121
Max	1.124	1.161	1.145	1.176
UL	1.650	1.650	1.650	1.650

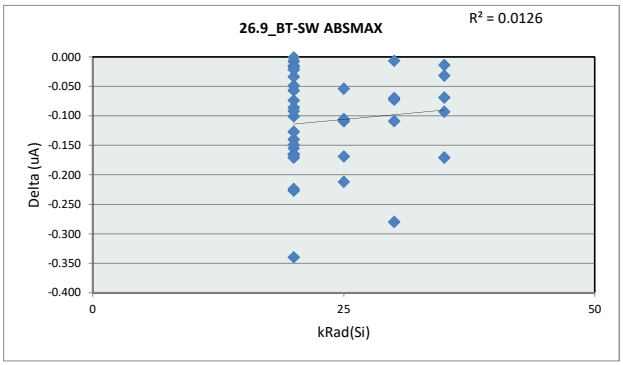


HDR TID Report
TPS7H4010-SEP

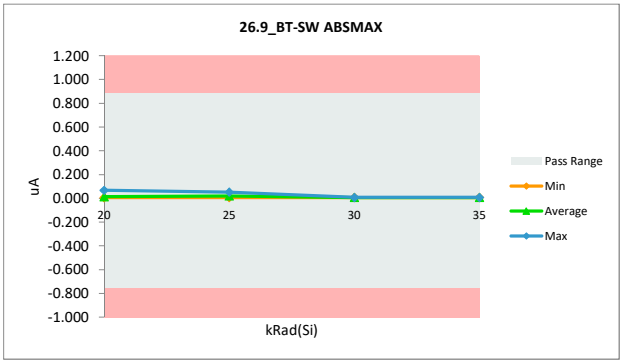
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.9_BT-SW ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	0.88	0.88
Min Limit	-0.75	-0.75

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.266	0.039	-0.227
20	62	0.022	0.007	-0.015
20	63	0.016	0.008	-0.008
20	64	0.055	0.006	-0.049
20	65	0.041	0.007	-0.034
20	67	0.154	0.014	-0.140
20	68	0.177	0.011	-0.166
20	69	0.385	0.045	-0.340
20	70	0.291	0.067	-0.224
20	71	0.135	0.008	-0.127
20	72	0.165	0.010	-0.155
20	73	0.064	0.007	-0.057
20	74	0.024	0.007	-0.017
20	75	0.093	0.007	-0.086
20	76	0.080	0.006	-0.074
20	77	0.029	0.007	-0.022
20	78	0.111	0.010	-0.101
20	79	0.008	0.007	-0.001
20	80	0.175	0.010	-0.165
20	81	0.187	0.016	-0.171
20	82	0.101	0.009	-0.092
20	83	0.158	0.009	-0.149
25	84	0.183	0.014	-0.169
25	85	0.061	0.007	-0.054
25	86	0.120	0.011	-0.109
25	87	0.121	0.015	-0.106
25	88	0.264	0.052	-0.212
30	89	0.015	0.008	-0.007
30	90	0.080	0.007	-0.073
30	91	0.077	0.007	-0.070
30	92	0.117	0.008	-0.109
30	93	0.287	0.007	-0.280
35	94	0.179	0.008	-0.171
35	95	0.022	0.008	-0.014
35	96	0.100	0.007	-0.093
35	97	0.076	0.007	-0.069
35	98	0.039	0.007	-0.032
Max		0.385	0.067	-0.001
Average		0.121	0.013	-0.108
Min		0.008	0.006	-0.340
Std Dev		0.091	0.014	0.081



	26.9_BT-SW ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	0.88	uA		
Min Limit	-0.75	uA		
kRad(Si)	20	25	30	35
LL	-0.750	-0.750	-0.750	-0.750
Min	0.006	0.007	0.007	0.007
Average	0.014	0.020	0.007	0.007
Max	0.067	0.052	0.008	0.008
UL	0.880	0.880	0.880	0.880

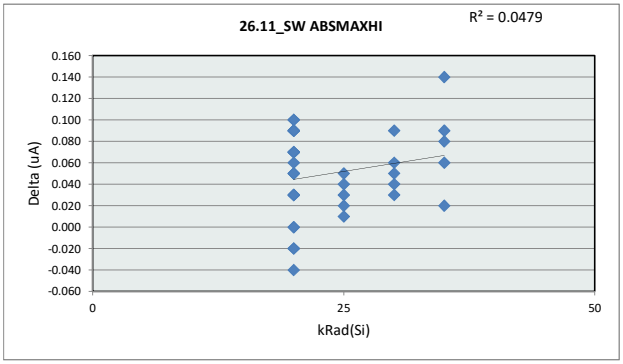


HDR TID Report
TPS7H4010-SEP

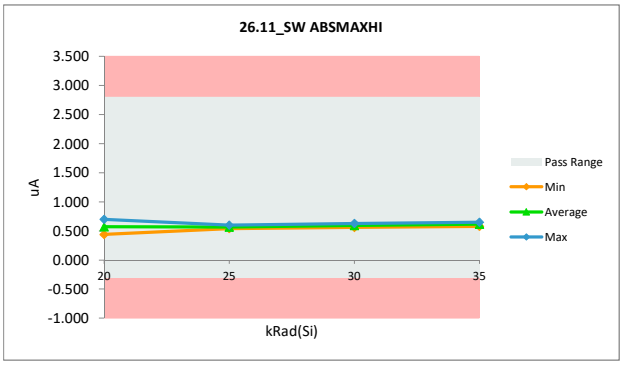
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.11_SW ABSMAXHI	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	2.8	2.8
Min Limit	-0.3	-0.3

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.620	0.600	-0.020
20	62	0.490	0.520	0.030
20	63	0.540	0.500	-0.040
20	64	0.440	0.440	0.000
20	65	0.590	0.620	0.030
20	67	0.510	0.580	0.070
20	68	0.480	0.550	0.070
20	69	0.540	0.610	0.070
20	70	0.470	0.540	0.070
20	71	0.470	0.560	0.090
20	72	0.570	0.620	0.050
20	73	0.540	0.520	-0.020
20	74	0.610	0.700	0.090
20	75	0.550	0.650	0.100
20	76	0.470	0.560	0.090
20	77	0.510	0.570	0.060
20	78	0.490	0.540	0.050
20	79	0.540	0.640	0.100
20	80	0.510	0.560	0.050
20	81	0.490	0.580	0.090
20	82	0.510	0.540	0.030
20	83	0.570	0.570	0.000
25	84	0.530	0.540	0.010
25	85	0.510	0.540	0.030
25	86	0.520	0.570	0.050
25	87	0.540	0.580	0.040
25	88	0.580	0.600	0.020
30	89	0.570	0.610	0.040
30	90	0.600	0.630	0.030
30	91	0.530	0.580	0.050
30	92	0.470	0.560	0.090
30	93	0.530	0.590	0.060
35	94	0.470	0.610	0.140
35	95	0.520	0.610	0.090
35	96	0.580	0.640	0.060
35	97	0.570	0.650	0.080
35	98	0.560	0.580	0.020
Max		0.620	0.700	0.140
Average		0.529	0.580	0.051
Min		0.440	0.440	-0.040
Std Dev		0.045	0.049	0.039



	26.11_SW ABSMAXHI			
Test Site				
Tester				
Test Number				
Max Limit	2.8	uA		
Min Limit	-0.3	uA		
kRad(Si)	20	25	30	35
LL	-0.300	-0.300	-0.300	-0.300
Min	0.440	0.540	0.560	0.580
Average	0.571	0.566	0.594	0.618
Max	0.700	0.600	0.630	0.650
UL	2.800	2.800	2.800	2.800

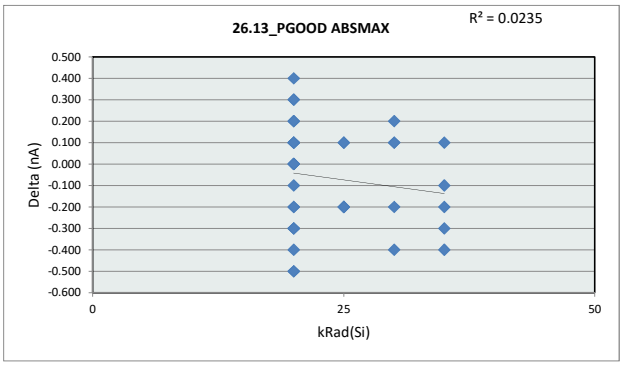


HDR TID Report
TPS7H4010-SEP

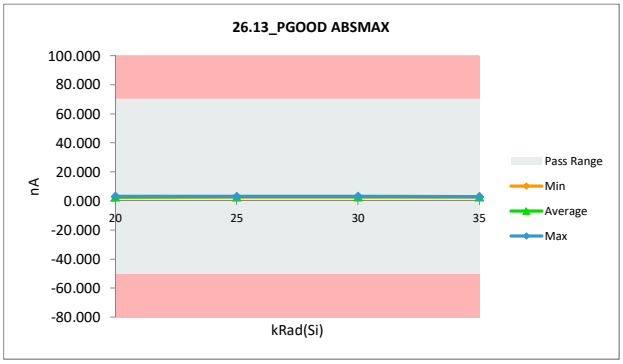
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.13_PGOOD ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	70	70
Min Limit	-50	-50

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	2.700	2.700	0.000
20	62	3.000	2.800	-0.200
20	63	3.100	2.800	-0.300
20	64	3.000	2.700	-0.300
20	65	3.000	2.700	-0.300
20	67	2.800	3.000	0.200
20	68	3.000	3.000	0.000
20	69	3.100	3.000	-0.100
20	70	2.700	2.700	0.000
20	71	3.000	2.800	-0.200
20	72	2.700	2.900	0.200
20	73	3.100	2.600	-0.500
20	74	3.000	3.100	0.100
20	75	2.800	2.900	0.100
20	76	2.900	3.000	0.100
20	77	3.000	2.600	-0.400
20	78	2.900	3.000	0.100
20	79	2.600	2.600	0.000
20	80	2.700	3.100	0.400
20	81	2.900	3.200	0.300
20	82	2.700	3.000	0.300
20	83	3.100	2.600	-0.500
25	84	2.900	2.700	-0.200
25	85	3.200	3.000	-0.200
25	86	2.800	2.900	0.100
25	87	2.900	2.700	-0.200
25	88	3.000	3.100	0.100
30	89	3.100	3.200	0.100
30	90	3.100	2.900	-0.200
30	91	2.900	3.100	0.200
30	92	2.800	2.900	0.100
30	93	3.200	2.800	-0.400
35	94	2.800	2.900	0.100
35	95	3.100	2.900	-0.200
35	96	3.100	2.700	-0.400
35	97	3.100	3.000	-0.100
35	98	3.200	2.900	-0.300
	Max	3.200	3.200	0.400
	Average	2.946	2.878	-0.068
	Min	2.600	2.600	-0.500
	Std Dev	0.164	0.173	0.237



	26.13_PGOOD ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	70	nA		
Min Limit	-50	nA		
kRad(Si)	20	25	30	35
LL	-50.000	-50.000	-50.000	-50.000
Min	2.600	2.700	2.800	2.700
Average	2.855	2.880	2.980	2.880
Max	3.200	3.100	3.200	3.000
UL	70.000	70.000	70.000	70.000

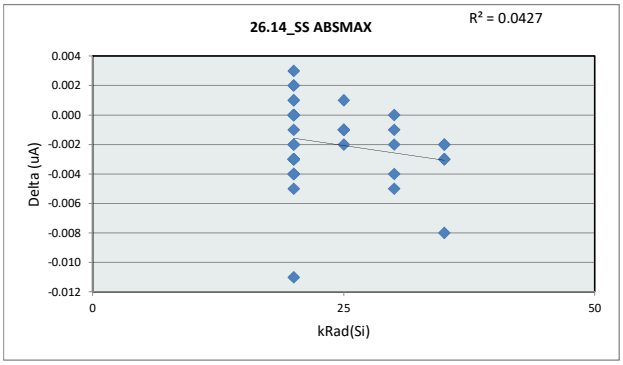


HDR TID Report
TPS7H4010-SEP

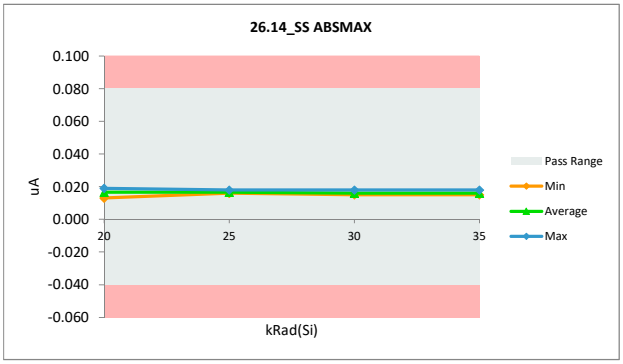
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.14_SS ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	0.08	0.08
Min Limit	-0.04	-0.04

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.017	0.017	0.000
20	62	0.028	0.017	-0.011
20	63	0.019	0.017	-0.002
20	64	0.018	0.016	-0.002
20	65	0.019	0.016	-0.003
20	67	0.019	0.018	-0.001
20	68	0.019	0.015	-0.004
20	69	0.014	0.015	0.001
20	70	0.018	0.018	0.000
20	71	0.016	0.019	0.003
20	72	0.019	0.015	-0.004
20	73	0.020	0.017	-0.003
20	74	0.016	0.018	0.002
20	75	0.017	0.019	0.002
20	76	0.016	0.016	0.000
20	77	0.017	0.017	0.000
20	78	0.020	0.017	-0.003
20	79	0.020	0.017	-0.003
20	80	0.016	0.013	-0.003
20	81	0.019	0.015	-0.004
20	82	0.020	0.015	-0.005
20	83	0.017	0.018	0.001
25	84	0.017	0.018	0.001
25	85	0.018	0.016	-0.002
25	86	0.017	0.016	-0.001
25	87	0.018	0.017	-0.001
25	88	0.017	0.016	-0.001
30	89	0.020	0.015	-0.005
30	90	0.020	0.016	-0.004
30	91	0.020	0.018	-0.002
30	92	0.017	0.016	-0.001
30	93	0.015	0.015	0.000
35	94	0.017	0.015	-0.002
35	95	0.024	0.016	-0.008
35	96	0.018	0.015	-0.003
35	97	0.020	0.018	-0.002
35	98	0.019	0.016	-0.003
Max		0.028	0.019	0.003
Average		0.018	0.016	-0.002
Min		0.014	0.013	-0.011
Std Dev		0.002	0.001	0.003



	26.14_SS ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	0.08	uA		
Min Limit	-0.04	uA		
kRad(Si)	20	25	30	35
LL	-0.040	-0.040	-0.040	-0.040
Min	0.013	0.016	0.015	0.015
Average	0.017	0.017	0.016	0.016
Max	0.019	0.018	0.018	0.018
UL	0.080	0.080	0.080	0.080

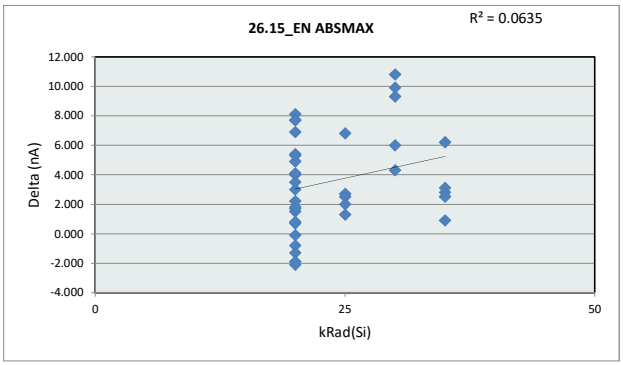


HDR TID Report
TPS7H4010-SEP

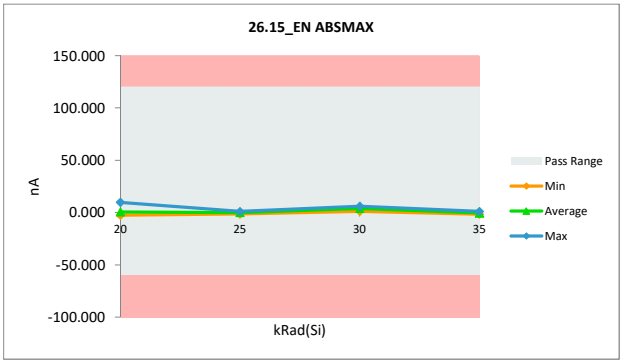
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.15_EN ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	120	120
Min Limit	-60	-60

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	-3.500	1.900	5.400
20	62	-1.300	-0.600	0.700
20	63	-3.100	0.400	3.500
20	64	-3.100	-0.900	2.200
20	65	-2.900	4.000	6.900
20	67	-0.600	-0.700	-0.100
20	68	-3.200	1.700	4.900
20	69	-3.700	-0.700	3.000
20	70	-3.600	0.400	4.000
20	71	-4.000	-2.500	1.500
20	72	-3.300	-1.600	1.700
20	73	0.100	-0.700	-0.800
20	74	-1.400	0.400	1.800
20	75	-0.300	-1.600	-1.300
20	76	-2.000	3.300	5.300
20	77	-4.000	3.700	7.700
20	78	0.300	-1.800	-2.100
20	79	1.800	9.900	8.100
20	80	-3.600	0.500	4.100
20	81	-3.400	4.300	7.700
20	82	0.100	-1.800	-1.900
20	83	-2.700	-1.900	0.800
25	84	-6.000	0.800	6.800
25	85	-2.000	-0.700	1.300
25	86	-1.600	1.100	2.700
25	87	-3.400	-1.400	2.000
25	88	-1.800	0.700	2.500
30	89	-5.100	5.700	10.800
30	90	-4.000	5.300	9.300
30	91	-4.000	2.000	6.000
30	92	-3.100	1.200	4.300
30	93	-3.900	6.000	9.900
35	94	-5.100	1.100	6.200
35	95	-3.700	-0.900	2.800
35	96	-2.900	0.200	3.100
35	97	-4.000	-1.500	2.500
35	98	-1.700	-0.800	0.900
	Max	1.800	9.900	10.800
	Average	-2.695	0.932	3.627
	Min	-6.000	-2.500	-2.100
	Std Dev	1.679	2.728	3.288



	26.15_EN ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	120	nA		
Min Limit	-60	nA		
kRad(Si)	20	25	30	35
LL	-60.000	-60.000	-60.000	-60.000
Min	-2.500	-1.400	1.200	-1.500
Average	0.714	0.100	4.040	-0.380
Max	9.900	1.100	6.000	1.100
UL	120.000	120.000	120.000	120.000

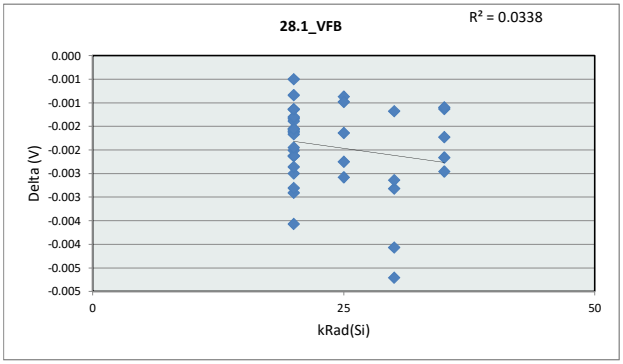


HDR TID Report
TPS7H4010-SEP

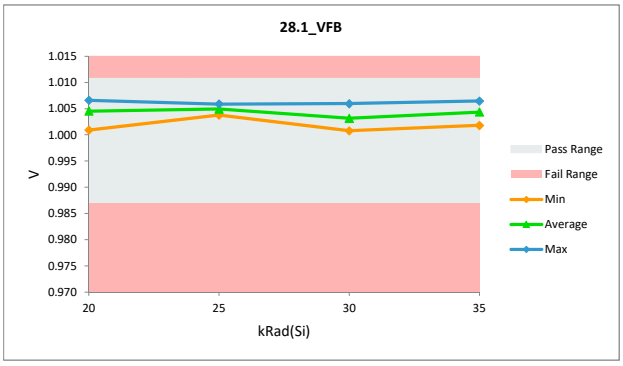
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	28.1_VFB	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.0108	1.0108
Min Limit	0.987	0.987

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.007	1.005	-0.002
20	62	1.006	1.003	-0.003
20	63	1.006	1.005	-0.001
20	64	1.004	1.002	-0.002
20	65	1.007	1.006	0.000
20	67	1.007	1.005	-0.002
20	68	1.007	1.005	-0.002
20	69	1.007	1.006	-0.001
20	70	1.005	1.004	-0.001
20	71	1.007	1.005	-0.002
20	72	1.006	1.004	-0.002
20	73	1.005	1.004	-0.001
20	74	1.005	1.001	-0.004
20	75	1.008	1.005	-0.003
20	76	1.007	1.005	-0.002
20	77	1.006	1.004	-0.002
20	78	1.007	1.005	-0.001
20	79	1.006	1.003	-0.003
20	80	1.007	1.006	-0.001
20	81	1.008	1.007	-0.002
20	82	1.005	1.003	-0.002
20	83	1.007	1.006	-0.001
25	84	1.007	1.006	-0.001
25	85	1.007	1.005	-0.003
25	86	1.005	1.004	-0.001
25	87	1.007	1.006	-0.002
25	88	1.007	1.005	-0.002
30	89	1.007	1.005	-0.003
30	90	1.005	1.001	-0.004
30	91	1.006	1.004	-0.003
30	92	1.006	1.001	-0.005
30	93	1.007	1.006	-0.001
35	94	1.004	1.002	-0.002
35	95	1.007	1.006	-0.001
35	96	1.008	1.006	-0.001
35	97	1.005	1.004	-0.002
35	98	1.006	1.004	-0.002
Max		1.008	1.007	0.000
Average		1.006	1.004	-0.002
Min		1.004	1.001	-0.005
Std Dev		0.001	0.002	0.001



	28.1_VFB			
Test Site				
Tester				
Test Number				
Max Limit	1.0108	V		
Min Limit	0.987	V		
kRad(Si)	20	25	30	35
LL	0.987	0.987	0.987	0.987
Min	1.001	1.004	1.001	1.002
Average	1.005	1.005	1.003	1.004
Max	1.007	1.006	1.006	1.006
UL	1.011	1.011	1.011	1.011

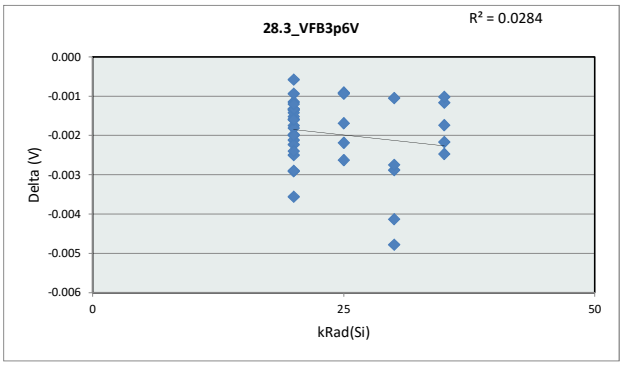


HDR TID Report
TPS7H4010-SEP

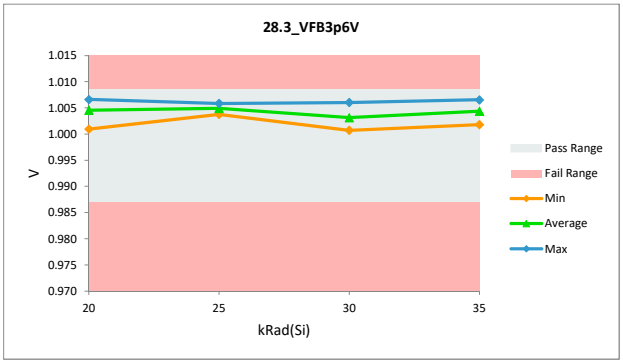
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	28.3_VFB3p6V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.0085	1.0085
Min Limit	0.987	0.987

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.007	1.005	-0.002
20	62	1.006	1.003	-0.002
20	63	1.006	1.005	-0.001
20	64	1.004	1.002	-0.002
20	65	1.007	1.006	-0.001
20	67	1.007	1.005	-0.002
20	68	1.007	1.005	-0.002
20	69	1.007	1.006	-0.001
20	70	1.005	1.004	-0.001
20	71	1.007	1.005	-0.002
20	72	1.006	1.004	-0.002
20	73	1.005	1.004	-0.001
20	74	1.005	1.001	-0.004
20	75	1.008	1.005	-0.003
20	76	1.007	1.005	-0.002
20	77	1.006	1.004	-0.002
20	78	1.007	1.005	-0.001
20	79	1.006	1.003	-0.003
20	80	1.007	1.006	-0.001
20	81	1.008	1.007	-0.002
20	82	1.005	1.003	-0.002
20	83	1.007	1.006	-0.001
25	84	1.007	1.006	-0.001
25	85	1.007	1.005	-0.003
25	86	1.005	1.004	-0.001
25	87	1.007	1.006	-0.002
25	88	1.007	1.005	-0.002
30	89	1.007	1.005	-0.003
30	90	1.005	1.001	-0.004
30	91	1.006	1.003	-0.003
30	92	1.006	1.001	-0.005
30	93	1.007	1.006	-0.001
35	94	1.004	1.002	-0.002
35	95	1.007	1.006	-0.001
35	96	1.008	1.007	-0.001
35	97	1.005	1.004	-0.002
35	98	1.006	1.004	-0.002
Max		1.008	1.007	-0.001
Average		1.006	1.004	-0.002
Min		1.004	1.001	-0.005
Std Dev		0.001	0.002	0.001



	28.3_VFB3p6V			
Test Site				
Tester				
Test Number				
Max Limit	1.0085	V		
Min Limit	0.987	V		
kRad(Si)	20	25	30	35
LL	0.987	0.987	0.987	0.987
Min	1.001	1.004	1.001	1.002
Average	1.005	1.005	1.003	1.004
Max	1.007	1.006	1.006	1.007
UL	1.009	1.009	1.009	1.009

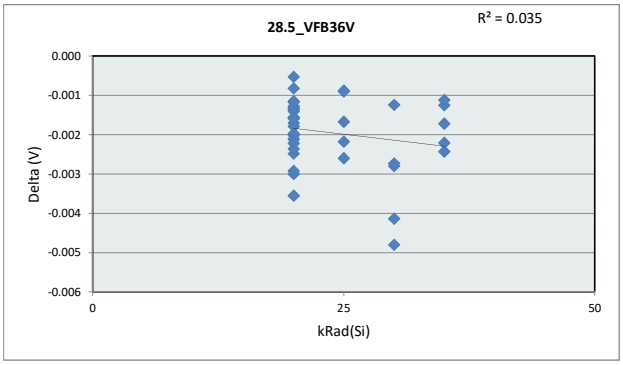


HDR TID Report
TPS7H4010-SEP

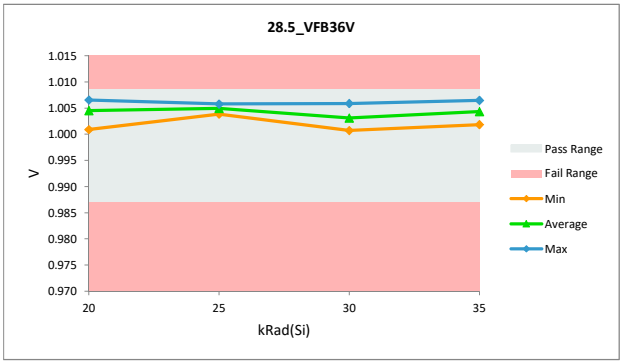
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	28.5_VFB36V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.0085	1.0085
Min Limit	0.987	0.987

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.007	1.005	-0.002
20	62	1.006	1.003	-0.002
20	63	1.006	1.005	-0.001
20	64	1.004	1.002	-0.002
20	65	1.007	1.006	-0.001
20	67	1.007	1.005	-0.002
20	68	1.007	1.005	-0.002
20	69	1.007	1.006	-0.001
20	70	1.005	1.004	-0.001
20	71	1.007	1.005	-0.002
20	72	1.006	1.004	-0.002
20	73	1.005	1.004	-0.001
20	74	1.004	1.001	-0.004
20	75	1.008	1.005	-0.003
20	76	1.007	1.005	-0.002
20	77	1.006	1.004	-0.002
20	78	1.007	1.005	-0.001
20	79	1.006	1.003	-0.003
20	80	1.006	1.006	-0.001
20	81	1.008	1.007	-0.002
20	82	1.005	1.003	-0.002
20	83	1.007	1.006	-0.001
25	84	1.007	1.006	-0.001
25	85	1.007	1.005	-0.003
25	86	1.005	1.004	-0.001
25	87	1.007	1.006	-0.002
25	88	1.007	1.005	-0.002
30	89	1.007	1.005	-0.003
30	90	1.005	1.001	-0.004
30	91	1.006	1.004	-0.003
30	92	1.006	1.001	-0.005
30	93	1.007	1.006	-0.001
35	94	1.004	1.002	-0.002
35	95	1.007	1.006	-0.001
35	96	1.008	1.006	-0.001
35	97	1.005	1.004	-0.002
35	98	1.006	1.004	-0.002
Max		1.008	1.007	-0.001
Average		1.006	1.004	-0.002
Min		1.004	1.001	-0.005
Std Dev		0.001	0.002	0.001



	28.5_VFB36V			
Test Site				
Tester				
Test Number				
Max Limit	1.0085	V		
Min Limit	0.987	V		
kRad(Si)	20	25	30	35
LL	0.987	0.987	0.987	0.987
Min	1.001	1.004	1.001	1.002
Average	1.005	1.005	1.003	1.004
Max	1.007	1.006	1.006	1.006
UL	1.009	1.009	1.009	1.009

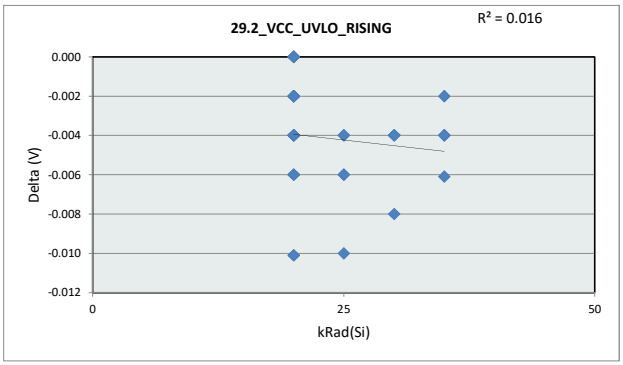


HDR TID Report
TPS7H4010-SEP

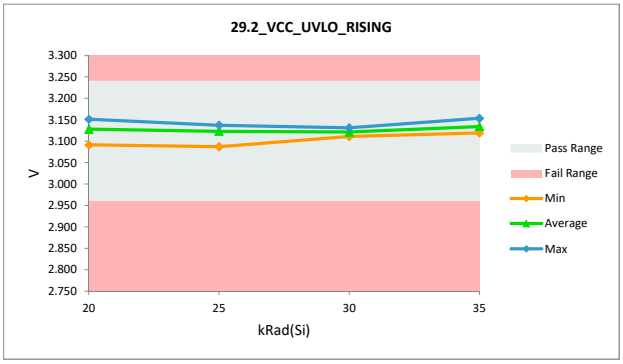
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.2_VCC_UVLO_RISING	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.24	3.24
Min Limit	2.96	2.96

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.131	3.129	-0.002
20	62	3.121	3.117	-0.004
20	63	3.125	3.125	0.000
20	64	3.151	3.147	-0.004
20	65	3.137	3.137	0.000
20	67	3.127	3.117	-0.010
20	68	3.145	3.141	-0.004
20	69	3.145	3.141	-0.004
20	70	3.151	3.151	0.000
20	71	3.115	3.111	-0.004
20	72	3.133	3.131	-0.002
20	73	3.151	3.145	-0.006
20	74	3.129	3.119	-0.010
20	75	3.135	3.129	-0.006
20	76	3.123	3.123	0.000
20	77	3.109	3.105	-0.004
20	78	3.139	3.137	-0.002
20	79	3.147	3.143	-0.004
20	80	3.133	3.131	-0.002
20	81	3.097	3.091	-0.006
20	82	3.117	3.113	-0.004
20	83	3.137	3.135	-0.002
25	84	3.133	3.127	-0.006
25	85	3.093	3.087	-0.006
25	86	3.133	3.129	-0.004
25	87	3.141	3.137	-0.004
25	88	3.145	3.135	-0.010
30	89	3.115	3.111	-0.004
30	90	3.129	3.125	-0.004
30	91	3.129	3.125	-0.004
30	92	3.121	3.113	-0.008
30	93	3.135	3.131	-0.004
35	94	3.157	3.153	-0.004
35	95	3.129	3.125	-0.004
35	96	3.125	3.119	-0.006
35	97	3.145	3.143	-0.002
35	98	3.135	3.131	-0.004
Max		3.157	3.153	0.000
Average		3.132	3.128	-0.004
Min		3.093	3.087	-0.010
Std Dev		0.014	0.015	0.003



	29.2_VCC_UVLO_RISING			
Test Site				
Tester				
Test Number				
Max Limit	3.24	V		
Min Limit	2.96	V		
kRad(Si)	20	25	30	35
LL	2.960	2.960	2.960	2.960
Min	3.091	3.087	3.111	3.119
Average	3.128	3.123	3.121	3.134
Max	3.151	3.137	3.131	3.153
UL	3.240	3.240	3.240	3.240

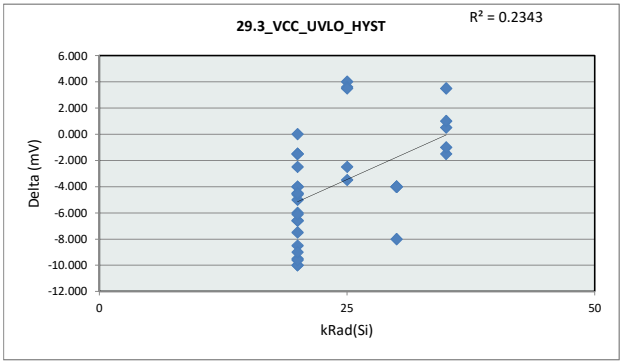


HDR TID Report
TPS7H4010-SEP

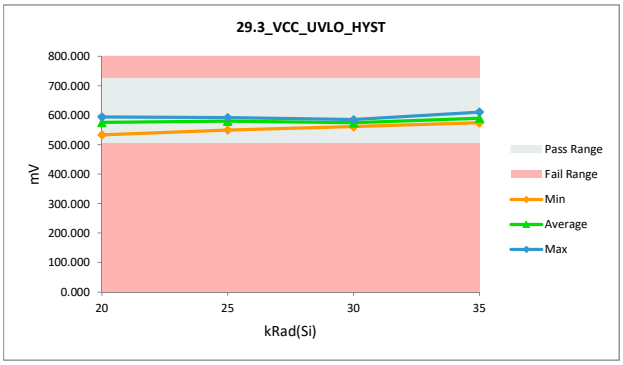
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.3_VCC_UVLO_HYST	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	725	725
Min Limit	505	505

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	576.100	571.600	-4.500
20	62	571.100	569.600	-1.500
20	63	572.600	572.600	0.000
20	64	593.700	592.200	-1.500
20	65	587.100	584.600	-2.500
20	67	574.600	564.600	-10.000
20	68	592.700	586.100	-6.600
20	69	592.700	586.100	-6.600
20	70	601.200	593.700	-7.500
20	71	567.600	563.600	-4.000
20	72	583.100	573.600	-9.500
20	73	598.700	592.700	-6.000
20	74	584.100	574.100	-10.000
20	75	582.600	574.100	-8.500
20	76	575.600	570.600	-5.000
20	77	559.100	557.600	-1.500
20	78	591.700	582.100	-9.600
20	79	599.700	590.700	-9.000
20	80	590.700	586.100	-4.600
20	81	539.600	533.500	-6.100
20	82	567.100	563.100	-4.000
20	83	579.600	575.100	-4.500
25	84	583.100	579.600	-3.500
25	85	545.600	549.600	4.000
25	86	585.600	589.200	3.600
25	87	588.700	592.200	3.500
25	88	590.200	587.700	-2.500
30	89	565.100	561.100	-4.000
30	90	589.200	585.200	-4.000
30	91	579.100	575.100	-4.000
30	92	576.100	568.100	-8.000
30	93	585.100	581.100	-4.000
35	94	607.200	610.700	3.500
35	95	579.100	577.600	-1.500
35	96	575.100	574.100	-1.000
35	97	595.200	595.700	0.500
35	98	590.200	591.200	1.000
	Max	607.200	610.700	4.000
	Average	581.503	577.735	-3.768
	Min	539.600	533.500	-10.000
	Std Dev	14.326	14.525	3.955



	29.3_VCC_UVLO_HYST			
Test Site				
Tester				
Test Number				
Max Limit	725	mV		
Min Limit	505	mV		
kRad(Si)	20	25	30	35
LL	505.000	505.000	505.000	505.000
Min	533.500	549.600	561.100	574.100
Average	575.364	579.660	574.120	589.860
Max	593.700	592.200	585.200	610.700
UL	725.000	725.000	725.000	725.000

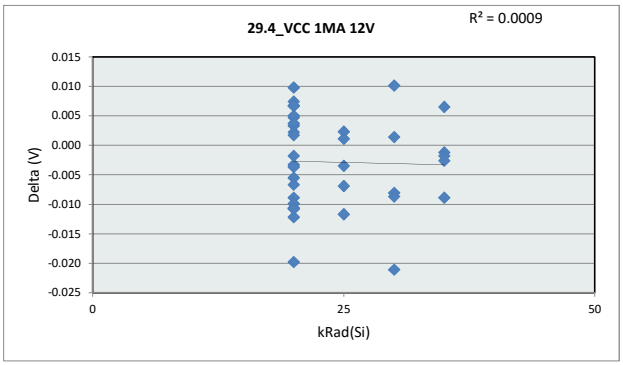


HDR TID Report
TPS7H4010-SEP

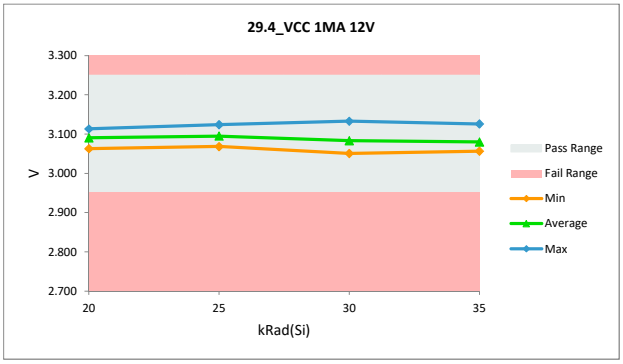
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.4_VCC 1MA 12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	2.95	2.95

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.080	3.085	0.005
20	62	3.107	3.098	-0.009
20	63	3.085	3.092	0.007
20	64	3.119	3.113	-0.005
20	65	3.075	3.072	-0.003
20	67	3.080	3.076	-0.004
20	68	3.122	3.112	-0.010
20	69	3.092	3.097	0.005
20	70	3.079	3.082	0.003
20	71	3.070	3.074	0.004
20	72	3.099	3.109	0.010
20	73	3.094	3.096	0.002
20	74	3.105	3.085	-0.020
20	75	3.095	3.083	-0.012
20	76	3.111	3.104	-0.007
20	77	3.065	3.063	-0.002
20	78	3.104	3.106	0.002
20	79	3.088	3.078	-0.011
20	80	3.080	3.087	0.007
20	81	3.085	3.075	-0.011
20	82	3.096	3.103	0.007
20	83	3.119	3.109	-0.011
25	84	3.131	3.124	-0.007
25	85	3.080	3.068	-0.012
25	86	3.084	3.086	0.002
25	87	3.118	3.119	0.001
25	88	3.080	3.077	-0.003
30	89	3.049	3.050	0.001
30	90	3.109	3.088	-0.021
30	91	3.123	3.133	0.010
30	92	3.069	3.060	-0.008
30	93	3.093	3.085	-0.009
35	94	3.057	3.056	-0.001
35	95	3.066	3.064	-0.002
35	96	3.061	3.058	-0.003
35	97	3.119	3.126	0.007
35	98	3.105	3.096	-0.009
Max		3.131	3.133	0.010
Average		3.092	3.089	-0.003
Min		3.049	3.050	-0.021
Std Dev		0.021	0.021	0.008



	29.4_VCC 1MA 12V			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	2.95	V		
kRad(Si)	20	25	30	35
LL	2.950	2.950	2.950	2.950
Min	3.063	3.068	3.050	3.056
Average	3.091	3.095	3.083	3.080
Max	3.113	3.124	3.133	3.126
UL	3.250	3.250	3.250	3.250

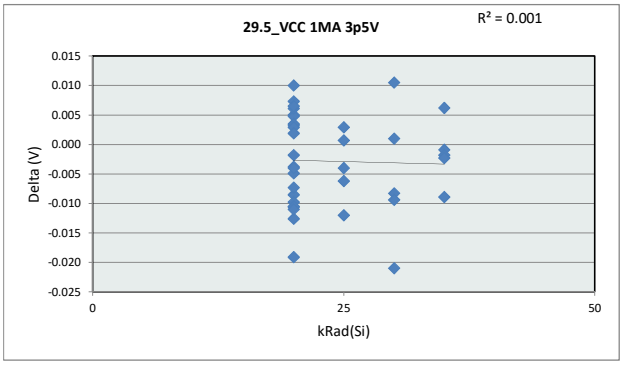


HDR TID Report
TPS7H4010-SEP

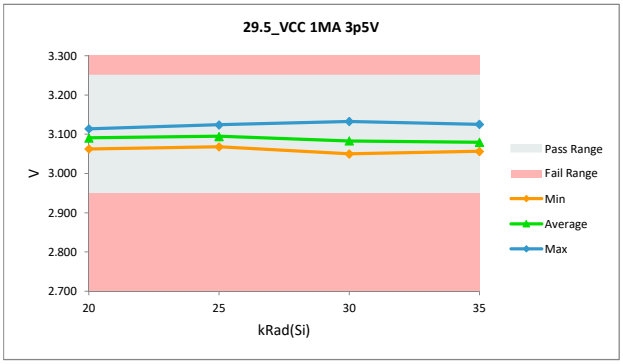
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.5_VCC 1MA 3p5V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	2.95	2.95

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.080	3.085	0.005
20	62	3.107	3.098	-0.008
20	63	3.085	3.092	0.007
20	64	3.119	3.114	-0.005
20	65	3.076	3.072	-0.004
20	67	3.080	3.076	-0.004
20	68	3.122	3.112	-0.010
20	69	3.092	3.097	0.005
20	70	3.078	3.082	0.003
20	71	3.070	3.073	0.003
20	72	3.099	3.109	0.010
20	73	3.094	3.097	0.003
20	74	3.105	3.086	-0.019
20	75	3.095	3.083	-0.013
20	76	3.111	3.103	-0.007
20	77	3.065	3.063	-0.002
20	78	3.104	3.106	0.002
20	79	3.088	3.078	-0.011
20	80	3.080	3.086	0.006
20	81	3.085	3.074	-0.010
20	82	3.096	3.102	0.007
20	83	3.119	3.108	-0.011
25	84	3.130	3.124	-0.006
25	85	3.080	3.068	-0.012
25	86	3.083	3.086	0.003
25	87	3.118	3.118	0.001
25	88	3.080	3.076	-0.004
30	89	3.049	3.050	0.001
30	90	3.109	3.088	-0.021
30	91	3.122	3.133	0.011
30	92	3.069	3.060	-0.008
30	93	3.094	3.084	-0.009
35	94	3.057	3.056	-0.001
35	95	3.066	3.064	-0.002
35	96	3.060	3.058	-0.002
35	97	3.119	3.125	0.006
35	98	3.105	3.096	-0.009
	Max	3.130	3.133	0.011
	Average	3.092	3.089	-0.003
	Min	3.049	3.050	-0.021
	Std Dev	0.021	0.021	0.008



	29.5_VCC 1MA 3p5V			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	2.95	V		
kRad(Si)	20	25	30	35
LL	2.950	2.950	2.950	2.950
Min	3.063	3.068	3.050	3.056
Average	3.091	3.095	3.083	3.080
Max	3.114	3.124	3.133	3.125
UL	3.250	3.250	3.250	3.250

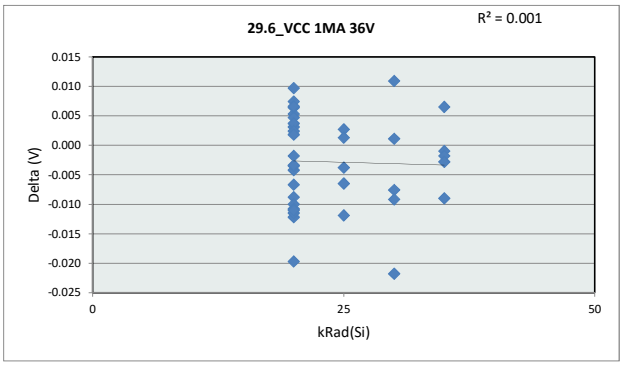


HDR TID Report
TPS7H4010-SEP

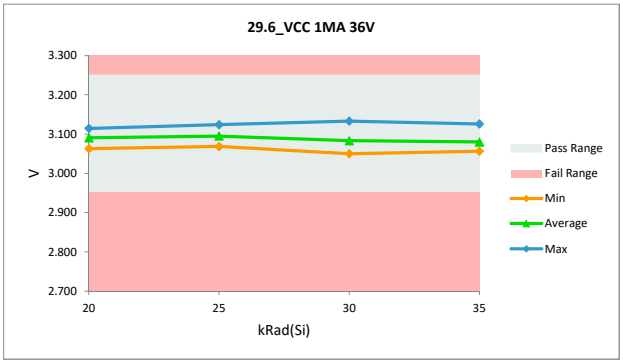
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.6_VCC 1MA 36V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	2.95	2.95

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.079	3.085	0.005
20	62	3.107	3.098	-0.009
20	63	3.085	3.092	0.007
20	64	3.119	3.115	-0.004
20	65	3.076	3.072	-0.003
20	67	3.079	3.076	-0.003
20	68	3.122	3.112	-0.010
20	69	3.092	3.097	0.005
20	70	3.079	3.082	0.003
20	71	3.070	3.074	0.004
20	72	3.099	3.109	0.010
20	73	3.094	3.097	0.002
20	74	3.105	3.086	-0.020
20	75	3.095	3.083	-0.012
20	76	3.111	3.104	-0.007
20	77	3.065	3.063	-0.002
20	78	3.104	3.106	0.002
20	79	3.088	3.078	-0.011
20	80	3.080	3.086	0.006
20	81	3.086	3.074	-0.011
20	82	3.096	3.103	0.007
20	83	3.119	3.108	-0.011
25	84	3.131	3.124	-0.007
25	85	3.080	3.068	-0.012
25	86	3.084	3.087	0.003
25	87	3.118	3.119	0.001
25	88	3.080	3.076	-0.004
30	89	3.049	3.050	0.001
30	90	3.109	3.087	-0.022
30	91	3.122	3.133	0.011
30	92	3.068	3.061	-0.008
30	93	3.093	3.084	-0.009
35	94	3.057	3.056	-0.001
35	95	3.066	3.064	-0.002
35	96	3.061	3.058	-0.003
35	97	3.119	3.126	0.007
35	98	3.105	3.096	-0.009
Max		3.131	3.133	0.011
Average		3.092	3.089	-0.003
Min		3.049	3.050	-0.022
Std Dev		0.021	0.021	0.008



	29.6_VCC 1MA 36V			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	2.95	V		
kRad(Si)	20	25	30	35
LL	2.950	2.950	2.950	2.950
Min	3.063	3.068	3.050	3.056
Average	3.091	3.095	3.083	3.080
Max	3.115	3.124	3.133	3.126
UL	3.250	3.250	3.250	3.250

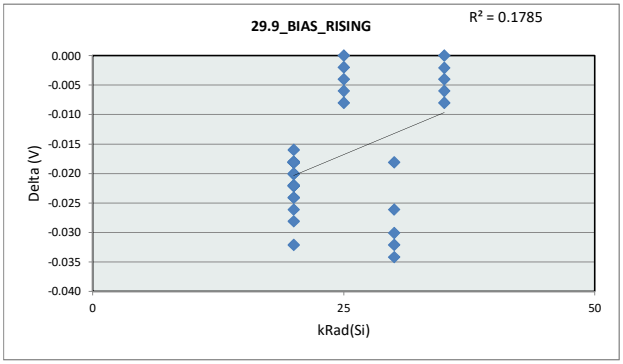


HDR TID Report
TPS7H4010-SEP

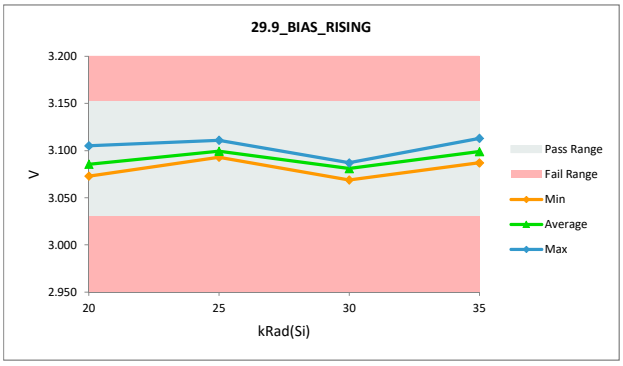
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.9_BIAS_RISING	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.152	3.152
Min Limit	3.03	3.03

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	3.113	3.091	-0.022
20	62	3.105	3.083	-0.022
20	63	3.111	3.089	-0.022
20	64	3.115	3.097	-0.018
20	65	3.105	3.081	-0.024
20	67	3.099	3.073	-0.026
20	68	3.103	3.085	-0.018
20	69	3.095	3.077	-0.018
20	70	3.105	3.089	-0.016
20	71	3.101	3.079	-0.022
20	72	3.105	3.087	-0.018
20	73	3.095	3.077	-0.018
20	74	3.113	3.081	-0.032
20	75	3.105	3.085	-0.020
20	76	3.103	3.083	-0.020
20	77	3.103	3.079	-0.024
20	78	3.107	3.087	-0.020
20	79	3.113	3.085	-0.028
20	80	3.111	3.093	-0.018
20	81	3.119	3.097	-0.022
20	82	3.099	3.081	-0.018
20	83	3.123	3.105	-0.018
25	84	3.093	3.093	0.000
25	85	3.111	3.103	-0.008
25	86	3.097	3.093	-0.004
25	87	3.113	3.111	-0.002
25	88	3.103	3.097	-0.006
30	89	3.099	3.069	-0.030
30	90	3.119	3.087	-0.032
30	91	3.111	3.085	-0.026
30	92	3.119	3.085	-0.034
30	93	3.097	3.079	-0.018
35	94	3.097	3.097	0.000
35	95	3.095	3.087	-0.008
35	96	3.115	3.113	-0.002
35	97	3.113	3.107	-0.006
35	98	3.095	3.091	-0.004
	Max	3.123	3.113	0.000
	Average	3.106	3.089	-0.017
	Min	3.093	3.069	-0.034
	Std Dev	0.008	0.010	0.009



	29.9_BIAS_RISING			
Test Site				
Tester				
Test Number				
Max Limit	3.152	V		
Min Limit	3.03	V		
kRad(Si)	20	25	30	35
LL	3.030	3.030	3.030	3.030
Min	3.073	3.093	3.069	3.087
Average	3.086	3.099	3.081	3.099
Max	3.105	3.111	3.087	3.113
UL	3.152	3.152	3.152	3.152

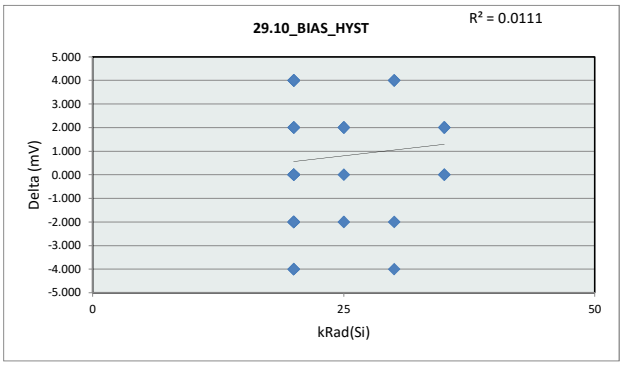


HDR TID Report
TPS7H4010-SEP

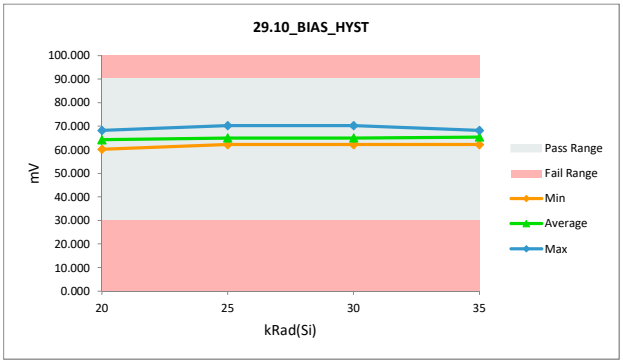
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.10_BIAS_HYST	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	90	90
Min Limit	30	30

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	64.200	62.200	-2.000
20	62	68.200	68.200	0.000
20	63	62.200	64.200	2.000
20	64	66.200	66.200	0.000
20	65	64.200	60.200	-4.000
20	67	62.200	64.200	2.000
20	68	64.200	64.200	0.000
20	69	62.200	66.200	4.000
20	70	64.200	60.200	-4.000
20	71	64.200	62.200	-2.000
20	72	62.200	66.200	4.000
20	73	66.200	66.200	0.000
20	74	62.200	64.200	2.000
20	75	62.200	66.200	4.000
20	76	64.200	66.200	2.000
20	77	66.200	62.200	-4.000
20	78	62.200	66.200	4.000
20	79	62.200	60.200	-2.000
20	80	64.200	62.200	-2.000
20	81	64.200	64.200	0.000
20	82	60.200	64.200	4.000
20	83	64.200	68.200	4.000
25	84	68.200	70.200	2.000
25	85	64.200	62.200	-2.000
25	86	62.200	62.200	0.000
25	87	64.200	66.200	2.000
25	88	62.200	64.200	2.000
30	89	64.200	62.200	-2.000
30	90	60.200	64.200	4.000
30	91	66.200	70.200	4.000
30	92	66.200	62.200	-4.000
30	93	62.200	66.200	4.000
35	94	62.200	64.200	2.000
35	95	62.200	62.200	0.000
35	96	64.200	66.200	2.000
35	97	66.200	68.200	2.000
35	98	66.200	66.200	0.000
Max		68.200	70.200	4.000
Average		63.876	64.632	0.757
Min		60.200	60.200	-4.000
Std Dev		1.973	2.588	2.639



	29.10_BIAS_HYST			
Test Site				
Tester				
Test Number				
Max Limit	90	mV		
Min Limit	30	mV		
kRad(Si)	20	25	30	35
LL	30.000	30.000	30.000	30.000
Min	60.200	62.200	62.200	62.200
Average	64.291	65.000	65.000	65.400
Max	68.200	70.200	70.200	68.200
UL	90.000	90.000	90.000	90.000

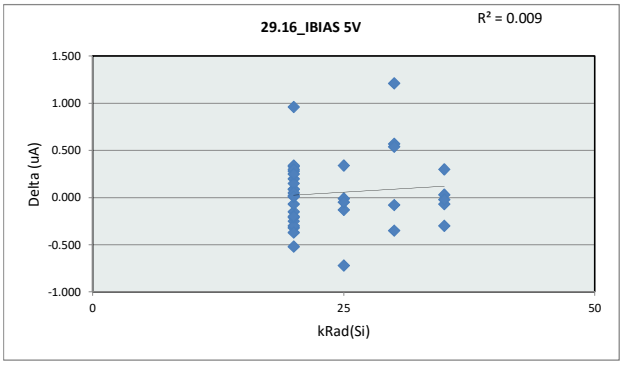


HDR TID Report
TPS7H4010-SEP

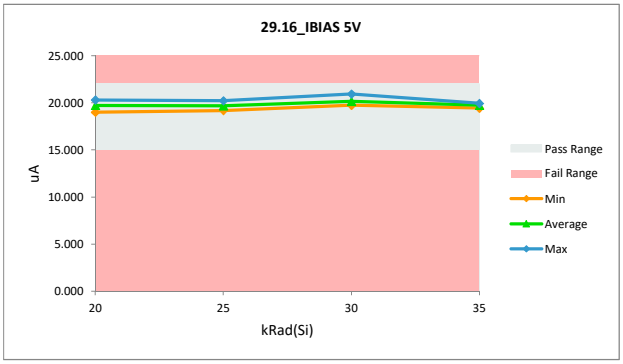
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.16_IBIAS 5V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	22	22
Min Limit	15	15

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	19.650	19.980	0.330
20	62	19.730	19.480	-0.250
20	63	19.450	19.130	-0.320
20	64	20.460	20.310	-0.150
20	65	19.190	19.280	0.090
20	67	19.570	19.590	0.020
20	68	19.690	19.890	0.200
20	69	20.070	19.770	-0.300
20	70	19.680	19.470	-0.210
20	71	19.960	19.590	-0.370
20	72	19.810	20.150	0.340
20	73	19.550	19.640	0.090
20	74	19.630	19.910	0.280
20	75	20.040	19.840	-0.200
20	76	19.820	19.970	0.150
20	77	19.520	19.000	-0.520
20	78	20.370	20.300	-0.070
20	79	19.680	19.980	0.300
20	80	19.790	19.840	0.050
20	81	18.610	19.570	0.960
20	82	19.540	19.790	0.250
20	83	19.620	19.630	0.010
25	84	19.740	19.610	-0.130
25	85	19.910	19.190	-0.720
25	86	19.610	19.600	-0.010
25	87	19.930	19.880	-0.050
25	88	19.880	20.220	0.340
30	89	19.820	19.740	-0.080
30	90	20.190	19.840	-0.350
30	91	19.730	20.940	1.210
30	92	19.720	20.290	0.570
30	93	19.490	20.030	0.540
35	94	19.630	19.560	-0.070
35	95	19.650	19.950	0.300
35	96	19.410	19.440	0.030
35	97	19.960	19.940	-0.020
35	98	20.150	19.850	-0.300
	Max	20.460	20.940	1.210
	Average	19.736	19.789	0.052
	Min	18.610	19.000	-0.720
	Std Dev	0.323	0.372	0.379



	29.16_IBIAS 5V			
Test Site				
Tester				
Test Number				
Max Limit	22	uA		
Min Limit	15	uA		
kRad(Si)	20	25	30	35
LL	15.000	15.000	15.000	15.000
Min	19.000	19.190	19.740	19.440
Average	19.732	19.700	20.168	19.748
Max	20.310	20.220	20.940	19.950
UL	22.000	22.000	22.000	22.000

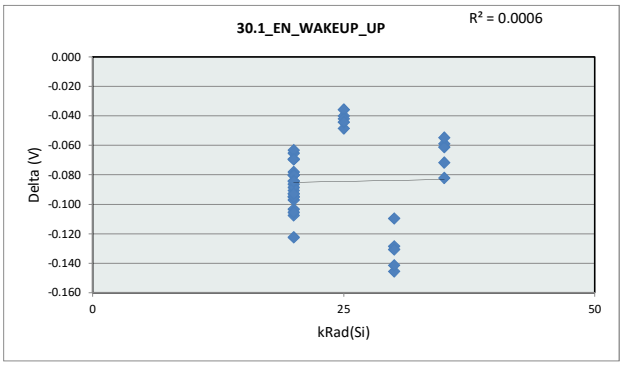


HDR TID Report
TPS7H4010-SEP

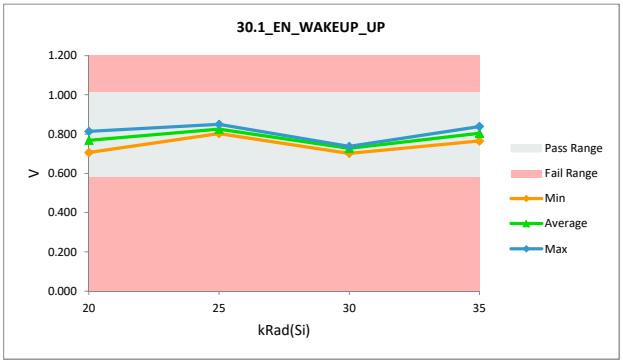
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.1_EN_WAKEUP_UP	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.0099	1.0099
Min Limit	0.58	0.58

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.860	0.794	-0.065
20	62	0.820	0.750	-0.070
20	63	0.832	0.729	-0.103
20	64	0.839	0.746	-0.093
20	65	0.864	0.767	-0.097
20	67	0.874	0.796	-0.078
20	68	0.893	0.813	-0.080
20	69	0.866	0.758	-0.108
20	70	0.866	0.744	-0.122
20	71	0.872	0.792	-0.080
20	72	0.849	0.763	-0.086
20	73	0.849	0.758	-0.091
20	74	0.849	0.769	-0.080
20	75	0.847	0.758	-0.089
20	76	0.855	0.761	-0.095
20	77	0.841	0.756	-0.084
20	78	0.851	0.756	-0.095
20	79	0.811	0.706	-0.106
20	80	0.866	0.773	-0.093
20	81	0.877	0.813	-0.063
20	82	0.879	0.794	-0.084
20	83	0.870	0.801	-0.070
25	84	0.843	0.803	-0.040
25	85	0.885	0.849	-0.036
25	86	0.864	0.822	-0.042
25	87	0.868	0.820	-0.049
25	88	0.872	0.828	-0.044
30	89	0.864	0.735	-0.129
30	90	0.874	0.729	-0.146
30	91	0.843	0.701	-0.141
30	92	0.845	0.735	-0.110
30	93	0.868	0.737	-0.131
35	94	0.864	0.782	-0.082
35	95	0.860	0.801	-0.059
35	96	0.900	0.839	-0.061
35	97	0.887	0.832	-0.055
35	98	0.836	0.765	-0.072
Max		0.900	0.849	-0.036
Average		0.860	0.775	-0.085
Min		0.811	0.701	-0.146
Std Dev		0.019	0.037	0.028



	30.1_EN_WAKEUP_UP			
Test Site				
Tester				
Test Number				
Max Limit	1.0099	V		
Min Limit	0.58	V		
kRad(Si)	20	25	30	35
LL	0.580	0.580	0.580	0.580
Min	0.706	0.803	0.702	0.765
Average	0.768	0.824	0.728	0.804
Max	0.813	0.849	0.737	0.839
UL	1.010	1.010	1.010	1.010

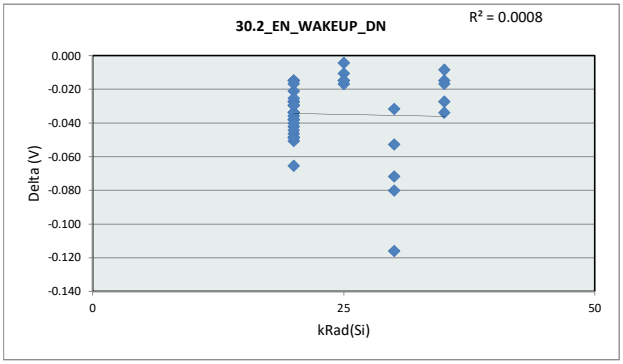


HDR TID Report
TPS7H4010-SEP

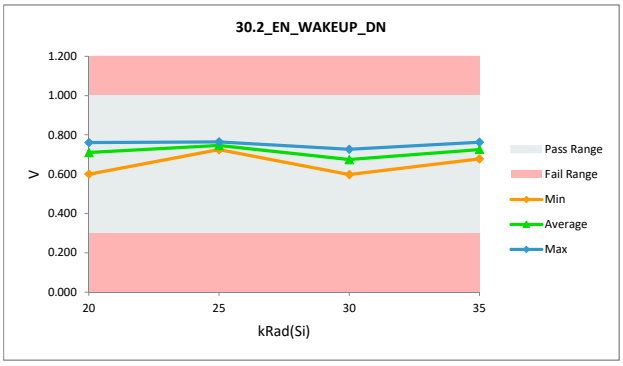
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.2_EN_WAKEUP_DN	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1	1
Min Limit	0.3	0.3

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.746	0.704	-0.042
20	62	0.733	0.718	-0.015
20	63	0.710	0.659	-0.051
20	64	0.794	0.746	-0.049
20	65	0.716	0.678	-0.038
20	67	0.763	0.748	-0.015
20	68	0.756	0.720	-0.036
20	69	0.788	0.761	-0.027
20	70	0.763	0.735	-0.027
20	71	0.746	0.712	-0.034
20	72	0.769	0.748	-0.021
20	73	0.725	0.691	-0.034
20	74	0.666	0.600	-0.065
20	75	0.756	0.727	-0.030
20	76	0.693	0.647	-0.046
20	77	0.723	0.674	-0.049
20	78	0.763	0.737	-0.025
20	79	0.727	0.683	-0.044
20	80	0.773	0.756	-0.017
20	81	0.773	0.735	-0.038
20	82	0.742	0.712	-0.029
20	83	0.775	0.735	-0.040
25	84	0.758	0.748	-0.011
25	85	0.758	0.744	-0.015
25	86	0.782	0.765	-0.017
25	87	0.739	0.725	-0.015
25	88	0.754	0.750	-0.004
30	89	0.714	0.598	-0.116
30	90	0.708	0.676	-0.032
30	91	0.780	0.727	-0.053
30	92	0.748	0.668	-0.080
30	93	0.775	0.704	-0.072
35	94	0.777	0.763	-0.015
35	95	0.716	0.708	-0.008
35	96	0.706	0.678	-0.027
35	97	0.771	0.754	-0.017
35	98	0.758	0.725	-0.034
Max		0.794	0.765	-0.004
Average		0.747	0.712	-0.035
Min		0.666	0.598	-0.116
Std Dev		0.030	0.042	0.022



	30.2_EN_WAKEUP_DN			
Test Site				
Tester				
Test Number				
Max Limit	1	V		
Min Limit	0.3	V		
kRad(Si)	20	25	30	35
LL	0.300	0.300	0.300	0.300
Min	0.600	0.725	0.598	0.678
Average	0.710	0.746	0.675	0.726
Max	0.761	0.765	0.727	0.763
UL	1.000	1.000	1.000	1.000

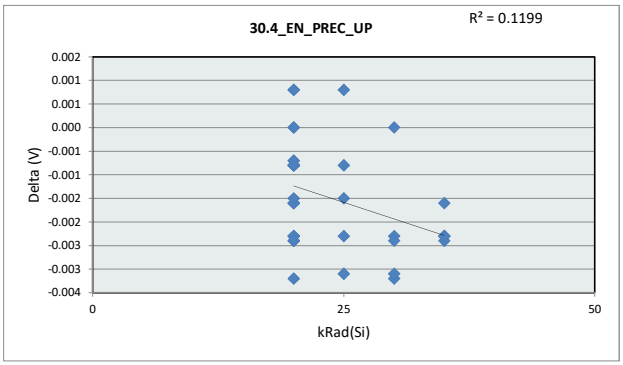


HDR TID Report
TPS7H4010-SEP

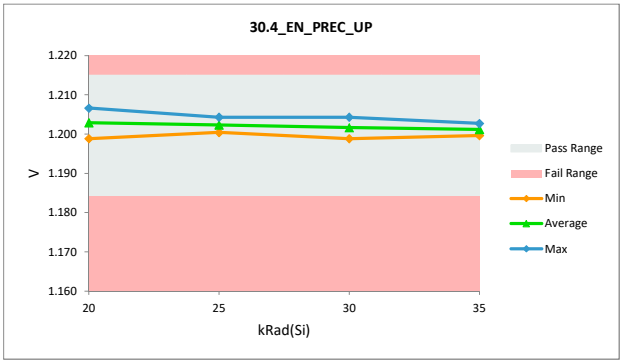
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.4_EN_PREC_UP	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.215	1.215
Min Limit	1.184	1.184

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.203	1.202	-0.001
20	62	1.204	1.202	-0.002
20	63	1.204	1.204	0.001
20	64	1.204	1.204	-0.001
20	65	1.204	1.204	-0.001
20	67	1.204	1.201	-0.002
20	68	1.205	1.203	-0.002
20	69	1.205	1.204	-0.002
20	70	1.204	1.204	0.000
20	71	1.204	1.201	-0.002
20	72	1.205	1.204	-0.002
20	73	1.203	1.203	0.000
20	74	1.201	1.199	-0.002
20	75	1.206	1.203	-0.003
20	76	1.202	1.201	-0.001
20	77	1.205	1.204	-0.001
20	78	1.206	1.204	-0.002
20	79	1.203	1.202	-0.001
20	80	1.204	1.204	-0.001
20	81	1.209	1.207	-0.002
20	82	1.203	1.201	-0.002
20	83	1.204	1.205	0.001
25	84	1.204	1.204	0.001
25	85	1.204	1.202	-0.002
25	86	1.204	1.203	-0.001
25	87	1.204	1.202	-0.002
25	88	1.204	1.200	-0.003
30	89	1.203	1.203	0.000
30	90	1.202	1.199	-0.003
30	91	1.207	1.204	-0.002
30	92	1.203	1.200	-0.003
30	93	1.205	1.203	-0.002
35	94	1.201	1.200	-0.002
35	95	1.204	1.201	-0.002
35	96	1.205	1.203	-0.002
35	97	1.204	1.202	-0.002
35	98	1.203	1.200	-0.002
Max		1.209	1.207	0.001
Average		1.204	1.202	-0.002
Min		1.201	1.199	-0.003
Std Dev		0.002	0.002	0.001



	30.4_EN_PREC_UP			
Test Site				
Tester				
Test Number				
Max Limit	1.215	V		
Min Limit	1.184	V		
kRad(Si)	20	25	30	35
LL	1.184	1.184	1.184	1.184
Min	1.199	1.200	1.199	1.200
Average	1.203	1.202	1.202	1.201
Max	1.207	1.204	1.204	1.203
UL	1.215	1.215	1.215	1.215

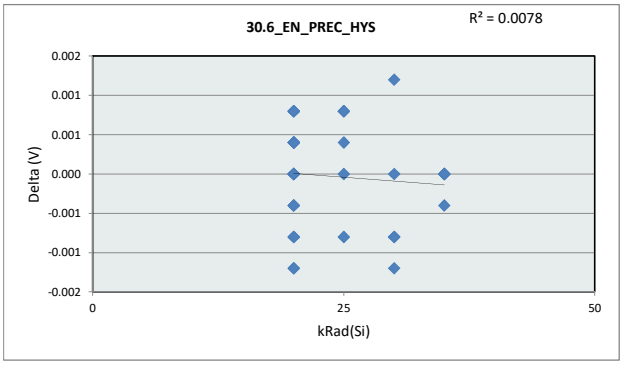


HDR TID Report
TPS7H4010-SEP

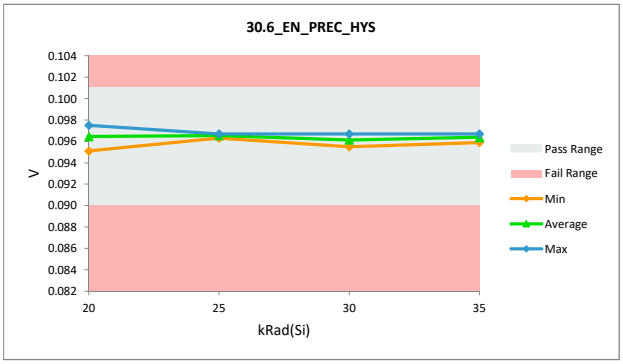
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.6_EN_PREC_HYS	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.101	0.101
Min Limit	0.09	0.09

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.096	0.097	0.000
20	62	0.097	0.097	0.000
20	63	0.096	0.097	0.001
20	64	0.097	0.097	0.000
20	65	0.097	0.097	0.000
20	67	0.096	0.096	0.000
20	68	0.097	0.096	-0.001
20	69	0.096	0.096	0.000
20	70	0.097	0.096	-0.001
20	71	0.096	0.096	0.000
20	72	0.096	0.096	0.000
20	73	0.097	0.097	0.000
20	74	0.096	0.096	0.000
20	75	0.096	0.095	-0.001
20	76	0.097	0.097	0.000
20	77	0.096	0.097	0.000
20	78	0.096	0.097	0.001
20	79	0.096	0.097	0.000
20	80	0.097	0.096	-0.001
20	81	0.097	0.097	0.000
20	82	0.097	0.097	0.000
20	83	0.095	0.096	0.001
25	84	0.096	0.097	0.001
25	85	0.097	0.097	0.000
25	86	0.096	0.096	0.000
25	87	0.096	0.097	0.001
25	88	0.097	0.096	-0.001
30	89	0.095	0.096	0.001
30	90	0.097	0.096	-0.001
30	91	0.097	0.097	0.000
30	92	0.096	0.095	-0.001
30	93	0.097	0.096	-0.001
35	94	0.097	0.097	0.000
35	95	0.096	0.096	0.000
35	96	0.096	0.096	0.000
35	97	0.097	0.097	0.000
35	98	0.096	0.096	0.000
Max		0.097	0.097	0.001
Average		0.096	0.096	0.000
Min		0.095	0.095	-0.001
Std Dev		0.001	0.001	0.001



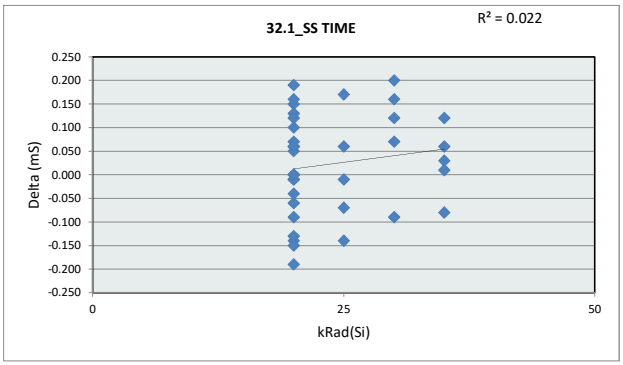
	30.6_EN_PREC_HYS			
Test Site				
Tester				
Test Number				
Max Limit	0.101	V		
Min Limit	0.09	V		
kRad(Si)	20	25	30	35
LL	0.090	0.090	0.090	0.090
Min	0.095	0.096	0.096	0.096
Average	0.096	0.097	0.096	0.096
Max	0.098	0.097	0.097	0.097
UL	0.101	0.101	0.101	0.101



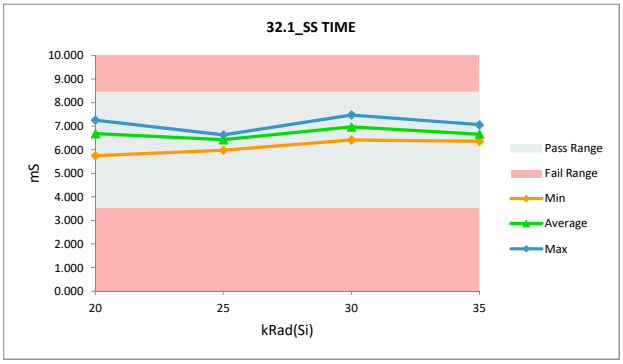
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.1_SS TIME		
Test Site			
Tester			
Test Number			
Unit	mS	mS	
Max Limit	8.45	8.45	
Min Limit	3.5	3.5	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	6.590	6.590	0.000
20	62	6.490	6.540	0.050
20	63	6.990	6.980	-0.010
20	64	6.440	6.540	0.100
20	65	6.660	6.650	-0.010
20	67	6.700	6.700	0.000
20	68	6.710	6.670	-0.040
20	69	7.080	6.940	-0.140
20	70	6.970	7.030	0.060
20	71	5.900	5.750	-0.150
20	72	6.760	6.910	0.150
20	73	6.590	6.400	-0.190
20	74	6.520	6.650	0.130
20	75	6.560	6.560	0.000
20	76	6.970	6.840	-0.130
20	77	7.190	7.260	0.070
20	78	6.210	6.270	0.060
20	79	6.610	6.550	-0.060
20	80	6.470	6.630	0.160
20	81	6.630	6.820	0.190
20	82	7.010	7.130	0.120
20	83	6.730	6.640	-0.090
25	84	6.370	6.540	0.170
25	85	6.120	5.980	-0.140
25	86	6.480	6.410	-0.070
25	87	6.610	6.600	-0.010
25	88	6.570	6.630	0.060
30	89	6.340	6.410	0.070
30	90	6.990	7.150	0.160
30	91	6.720	6.840	0.120
30	92	6.740	6.940	0.200
30	93	7.570	7.480	-0.090
35	94	7.030	7.060	0.030
35	95	6.880	6.800	-0.080
35	96	6.390	6.510	0.120
35	97	6.300	6.360	0.060
35	98	6.570	6.580	0.010
	Max	7.570	7.480	0.200
	Average	6.661	6.685	0.024
	Min	5.900	5.750	-0.190
	Std Dev	0.321	0.335	0.106



	32.1_SS TIME			
Test Site				
Tester				
Test Number				
Max Limit	8.45	mS		
Min Limit	3.5	mS		
kRad(Si)	20	25	30	35
LL	3.500	3.500	3.500	3.500
Min	5.750	5.980	6.410	6.360
Average	6.684	6.432	6.964	6.662
Max	7.260	6.630	7.480	7.060
UL	8.450	8.450	8.450	8.450

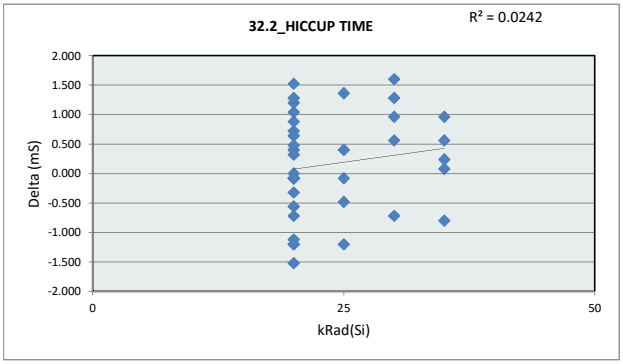


HDR TID Report
TPS7H4010-SEP

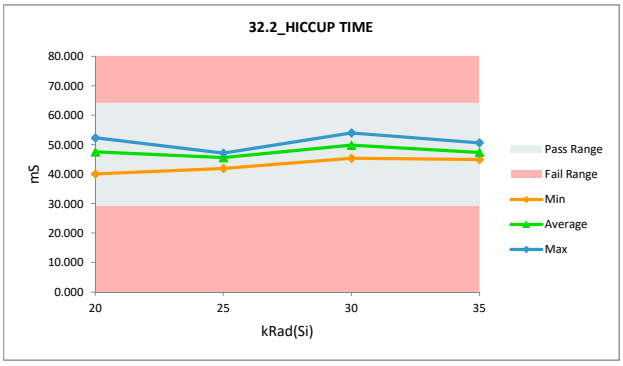
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.2_HICCUP TIME	
Test Site		
Tester		
Test Number		
Unit	mS	mS
Max Limit	64	64
Min Limit	29	29

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	46.880	46.880	0.000
20	62	46.000	46.320	0.320
20	63	50.000	49.920	-0.080
20	64	45.600	46.320	0.720
20	65	47.360	47.280	-0.080
20	67	47.760	47.680	-0.080
20	68	47.760	47.440	-0.320
20	69	50.720	49.520	-1.200
20	70	49.920	50.320	0.400
20	71	41.280	40.080	-1.200
20	72	48.160	49.360	1.200
20	73	46.800	45.280	-1.520
20	74	46.240	47.280	1.040
20	75	46.640	46.560	-0.080
20	76	49.920	48.800	-1.120
20	77	51.680	52.320	0.640
20	78	43.840	44.320	0.480
20	79	47.120	46.560	-0.560
20	80	45.920	47.200	1.280
20	81	47.200	48.720	1.520
20	82	50.240	51.120	0.880
20	83	48.000	47.280	-0.720
25	84	45.120	46.480	1.360
25	85	43.120	41.920	-1.200
25	86	45.920	45.440	-0.480
25	87	46.960	46.880	-0.080
25	88	46.720	47.120	0.400
30	89	44.800	45.360	0.560
30	90	50.000	51.280	1.280
30	91	47.920	48.880	0.960
30	92	48.080	49.680	1.600
30	93	54.720	54.000	-0.720
35	94	50.400	50.640	0.240
35	95	49.200	48.400	-0.800
35	96	45.280	46.240	0.960
35	97	44.400	44.960	0.560
35	98	46.640	46.720	0.080
	Max	54.720	54.000	1.600
	Average	47.414	47.583	0.169
	Min	41.280	40.080	-1.520
	Std Dev	2.575	2.687	0.860



	32.2_HICCUP TIME			
Test Site				
Tester				
Test Number				
Max Limit	64	mS		
Min Limit	29	mS		
kRad(Si)	20	25	30	35
LL	29.000	29.000	29.000	29.000
Min	40.080	41.920	45.360	44.960
Average	47.571	45.568	49.840	47.392
Max	52.320	47.120	54.000	50.640
UL	64.000	64.000	64.000	64.000

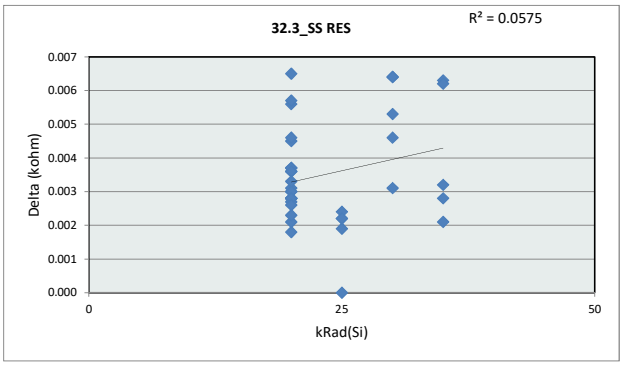


HDR TID Report
TPS7H4010-SEP

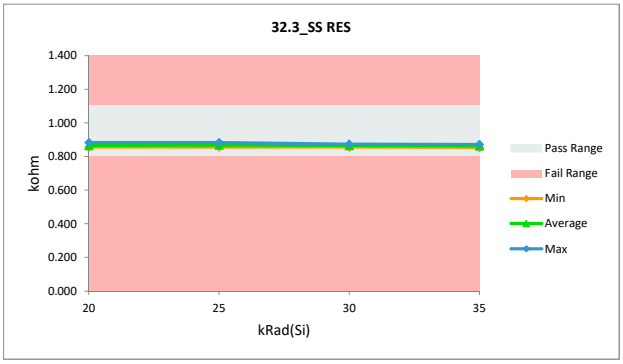
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.3_SS RES	
Test Site		
Tester		
Test Number		
Unit	kohm	kohm
Max Limit	1.1	1.1
Min Limit	0.8	0.8

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.854	0.857	0.003
20	62	0.865	0.868	0.003
20	63	0.863	0.866	0.003
20	64	0.861	0.864	0.003
20	65	0.872	0.876	0.004
20	67	0.855	0.858	0.003
20	68	0.872	0.874	0.002
20	69	0.867	0.872	0.004
20	70	0.872	0.875	0.004
20	71	0.856	0.858	0.002
20	72	0.853	0.856	0.003
20	73	0.868	0.874	0.006
20	74	0.855	0.861	0.006
20	75	0.854	0.858	0.003
20	76	0.863	0.867	0.004
20	77	0.868	0.872	0.004
20	78	0.854	0.857	0.003
20	79	0.877	0.883	0.007
20	80	0.865	0.868	0.003
20	81	0.866	0.868	0.002
20	82	0.856	0.859	0.003
20	83	0.864	0.868	0.005
25	84	0.869	0.872	0.002
25	85	0.855	0.857	0.002
25	86	0.880	0.882	0.002
25	87	0.869	0.871	0.002
25	88	0.858	0.858	0.000
30	89	0.856	0.862	0.006
30	90	0.850	0.856	0.006
30	91	0.871	0.874	0.003
30	92	0.856	0.860	0.005
30	93	0.867	0.872	0.005
35	94	0.867	0.870	0.003
35	95	0.856	0.863	0.006
35	96	0.851	0.854	0.002
35	97	0.868	0.871	0.003
35	98	0.851	0.857	0.006
	Max	0.880	0.883	0.007
	Average	0.862	0.866	0.004
	Min	0.850	0.854	0.000
	Std Dev	0.008	0.008	0.002



	32.3_SS RES			
Test Site				
Tester				
Test Number				
Max Limit	1.1	kohm		
Min Limit	0.8	kohm		
kRad(Si)	20	25	30	35
LL	0.800	0.800	0.800	0.800
Min	0.856	0.857	0.856	0.854
Average	0.866	0.868	0.865	0.863
Max	0.883	0.882	0.874	0.871
UL	1.100	1.100	1.100	1.100

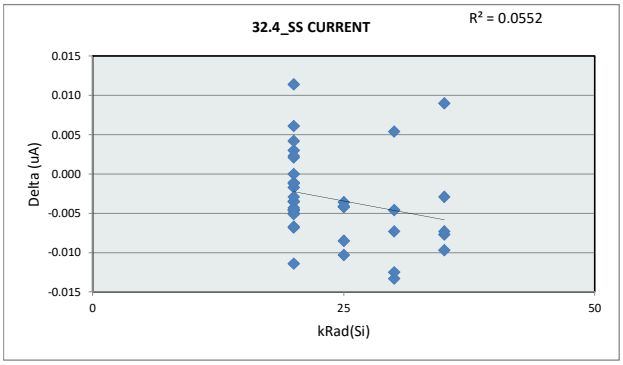


HDR TID Report
TPS7H4010-SEP

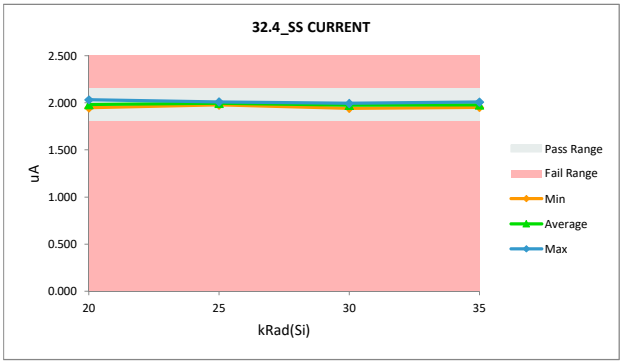
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.4_SS CURRENT	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	2.15	2.15
Min Limit	1.8	1.8

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.950	1.948	-0.002
20	62	1.971	1.967	-0.004
20	63	2.018	2.015	-0.003
20	64	1.969	1.958	-0.011
20	65	2.013	2.009	-0.005
20	67	1.954	1.947	-0.007
20	68	2.009	2.011	0.002
20	69	1.965	1.968	0.003
20	70	1.973	1.976	0.002
20	71	2.011	2.016	0.004
20	72	1.959	1.955	-0.003
20	73	1.957	1.956	-0.001
20	74	1.983	1.978	-0.005
20	75	1.998	1.996	-0.003
20	76	1.964	1.971	0.006
20	77	1.973	1.967	-0.007
20	78	1.998	1.993	-0.005
20	79	2.021	2.033	0.011
20	80	2.000	1.995	-0.005
20	81	1.986	1.982	-0.004
20	82	1.963	1.962	-0.001
20	83	2.016	2.016	0.000
25	84	1.983	1.979	-0.004
25	85	2.018	2.010	-0.009
25	86	2.000	1.997	-0.004
25	87	2.013	2.002	-0.010
25	88	1.997	1.993	-0.004
30	89	1.989	1.995	0.005
30	90	1.988	1.983	-0.005
30	91	1.973	1.959	-0.013
30	92	2.005	1.992	-0.012
30	93	1.950	1.943	-0.007
35	94	1.961	1.953	-0.008
35	95	1.960	1.969	0.009
35	96	1.998	1.991	-0.007
35	97	2.012	2.009	-0.003
35	98	1.977	1.967	-0.010
Max		2.021	2.033	0.011
Average		1.986	1.983	-0.003
Min		1.950	1.943	-0.013
Std Dev		0.022	0.023	0.006



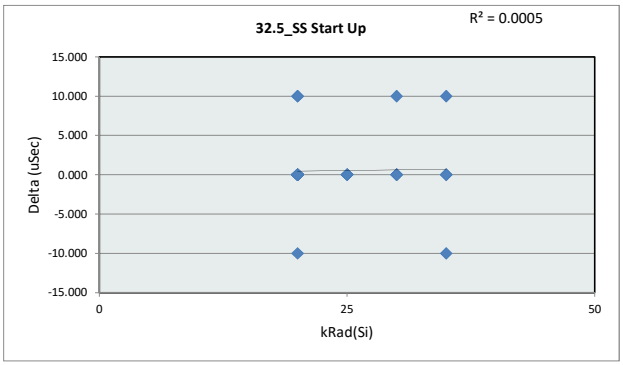
	32.4_SS CURRENT			
Test Site				
Tester				
Test Number				
Max Limit	2.15	uA		
Min Limit	1.8	uA		
kRad(Si)	20	25	30	35
LL	1.800	1.800	1.800	1.800
Min	1.948	1.979	1.943	1.953
Average	1.983	1.996	1.975	1.978
Max	2.033	2.010	1.995	2.009
UL	2.150	2.150	2.150	2.150



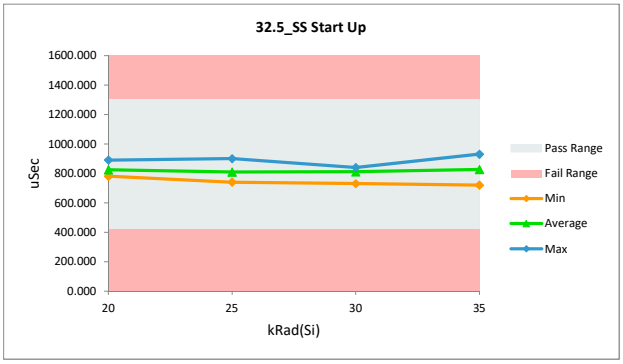
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.5_SS Start Up		
Test Site			
Tester			
Test Number			
Unit	uSec	uSec	
Max Limit	1300	1300	
Min Limit	420	420	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	860.000	860.000	0.000
20	62	780.000	780.000	0.000
20	63	850.000	850.000	0.000
20	64	820.000	810.000	-10.000
20	65	880.000	890.000	10.000
20	67	870.000	870.000	0.000
20	68	820.000	820.000	0.000
20	69	780.000	780.000	0.000
20	70	780.000	780.000	0.000
20	71	840.000	840.000	0.000
20	72	830.000	830.000	0.000
20	73	820.000	830.000	10.000
20	74	870.000	870.000	0.000
20	75	830.000	830.000	0.000
20	76	850.000	850.000	0.000
20	77	810.000	810.000	0.000
20	78	800.000	800.000	0.000
20	79	810.000	810.000	0.000
20	80	790.000	790.000	0.000
20	81	810.000	810.000	0.000
20	82	820.000	820.000	0.000
20	83	790.000	790.000	0.000
25	84	740.000	740.000	0.000
25	85	900.000	900.000	0.000
25	86	760.000	760.000	0.000
25	87	810.000	810.000	0.000
25	88	830.000	830.000	0.000
30	89	840.000	840.000	0.000
30	90	820.000	830.000	10.000
30	91	730.000	730.000	0.000
30	92	820.000	820.000	0.000
30	93	830.000	830.000	0.000
35	94	720.000	720.000	0.000
35	95	860.000	870.000	10.000
35	96	940.000	930.000	-10.000
35	97	810.000	810.000	0.000
35	98	800.000	800.000	0.000
	Max	940.000	930.000	10.000
	Average	819.459	820.000	0.541
	Min	720.000	720.000	-10.000
	Std Dev	44.594	44.659	4.046



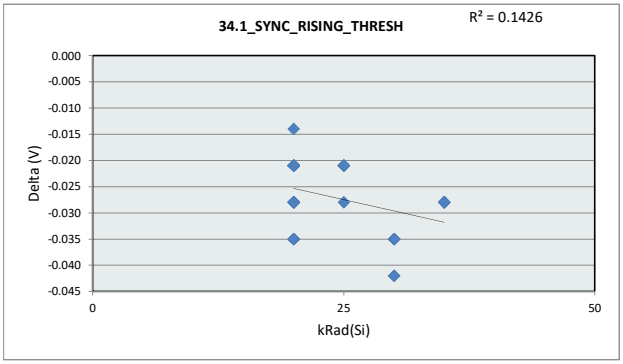
	32.5_SS Start Up			
Test Site				
Tester				
Test Number				
Max Limit	1300	uSec		
Min Limit	420	uSec		
kRad(Si)	20	25	30	35
LL	420.000	420.000	420.000	420.000
Min	780.000	740.000	730.000	720.000
Average	823.636	808.000	810.000	826.000
Max	890.000	900.000	840.000	930.000
UL	1300.000	1300.000	1300.000	1300.000



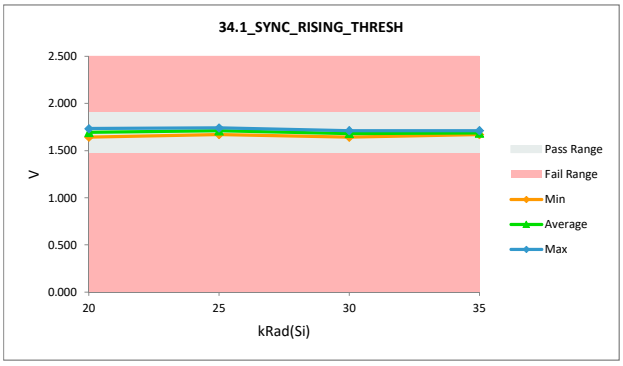
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.1_SYNC_RISING_THRESH		
Test Site			
Tester			
Test Number			
Unit	V	V	
Max Limit	1.9	1.9	
Min Limit	1.47	1.47	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.691	1.670	-0.021
20	62	1.691	1.663	-0.028
20	63	1.705	1.691	-0.014
20	64	1.726	1.698	-0.028
20	65	1.705	1.677	-0.028
20	67	1.712	1.691	-0.021
20	68	1.754	1.726	-0.028
20	69	1.733	1.712	-0.021
20	70	1.705	1.684	-0.021
20	71	1.761	1.733	-0.028
20	72	1.733	1.712	-0.021
20	73	1.747	1.726	-0.021
20	74	1.740	1.705	-0.035
20	75	1.740	1.705	-0.035
20	76	1.698	1.670	-0.028
20	77	1.691	1.663	-0.028
20	78	1.670	1.649	-0.021
20	79	1.677	1.642	-0.035
20	80	1.740	1.712	-0.028
20	81	1.712	1.684	-0.028
20	82	1.740	1.719	-0.021
20	83	1.747	1.726	-0.021
25	84	1.761	1.740	-0.021
25	85	1.733	1.705	-0.028
25	86	1.691	1.670	-0.021
25	87	1.761	1.740	-0.021
25	88	1.719	1.698	-0.021
30	89	1.677	1.642	-0.035
30	90	1.754	1.712	-0.042
30	91	1.740	1.705	-0.035
30	92	1.705	1.670	-0.035
30	93	1.719	1.677	-0.042
35	94	1.712	1.684	-0.028
35	95	1.705	1.677	-0.028
35	96	1.698	1.670	-0.028
35	97	1.740	1.712	-0.028
35	98	1.712	1.684	-0.028
Max		1.761	1.740	-0.014
Average		1.720	1.693	-0.027
Min		1.670	1.642	-0.042
Std Dev		0.026	0.026	0.006



	34.1_SYNC_RISING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	1.9	V		
Min Limit	1.47	V		
kRad(Si)	20	25	30	35
LL	1.470	1.470	1.470	1.470
Min	1.642	1.670	1.642	1.670
Average	1.694	1.711	1.681	1.685
Max	1.733	1.740	1.712	1.712
UL	1.900	1.900	1.900	1.900



HDR TID Report
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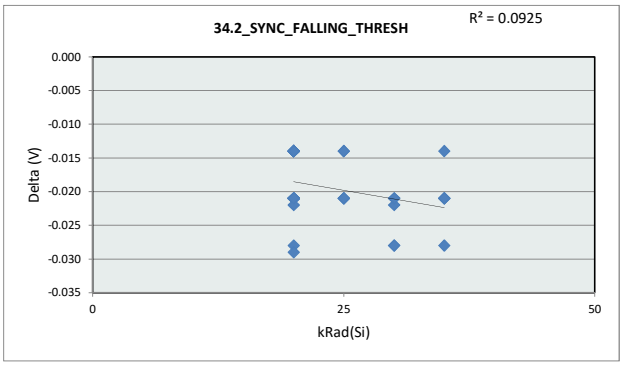
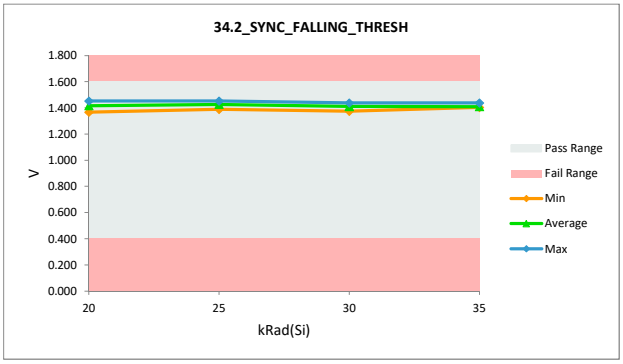
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.2_SYNC_FALLING_THRESH		
Test Site			
Tester			
Test Number			
Unit	V	V	
Max Limit	1.6	1.6	
Min Limit	0.4	0.4	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.417	1.396	-0.021
20	62	1.417	1.396	-0.021
20	63	1.438	1.424	-0.014
20	64	1.431	1.417	-0.014
20	65	1.431	1.410	-0.021
20	67	1.431	1.417	-0.014
20	68	1.466	1.438	-0.028
20	69	1.452	1.438	-0.014
20	70	1.417	1.403	-0.014
20	71	1.466	1.452	-0.014
20	72	1.445	1.431	-0.014
20	73	1.466	1.445	-0.021
20	74	1.452	1.431	-0.021
20	75	1.452	1.431	-0.021
20	76	1.417	1.396	-0.021
20	77	1.410	1.389	-0.021
20	78	1.396	1.374	-0.022
20	79	1.396	1.367	-0.029
20	80	1.445	1.431	-0.014
20	81	1.424	1.403	-0.021
20	82	1.452	1.438	-0.014
20	83	1.459	1.445	-0.014
25	84	1.466	1.445	-0.021
25	85	1.452	1.431	-0.021
25	86	1.410	1.389	-0.021
25	87	1.466	1.452	-0.014
25	88	1.431	1.417	-0.014
30	89	1.396	1.374	-0.022
30	90	1.466	1.438	-0.028
30	91	1.459	1.438	-0.021
30	92	1.424	1.403	-0.021
30	93	1.431	1.403	-0.028
35	94	1.424	1.403	-0.021
35	95	1.424	1.403	-0.021
35	96	1.424	1.403	-0.021
35	97	1.452	1.438	-0.014
35	98	1.431	1.403	-0.028
Max		1.466	1.452	-0.014
Average		1.436	1.417	-0.020
Min		1.396	1.367	-0.029
Std Dev		0.021	0.023	0.005



	34.2_SYNC_FALLING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	1.6	V		
Min Limit	0.4	V		
kRad(Si)	20	25	30	35
LL	0.400	0.400	0.400	0.400
Min	1.367	1.389	1.374	1.403
Average	1.417	1.427	1.411	1.410
Max	1.452	1.452	1.438	1.438
UL	1.600	1.600	1.600	1.600



HDR TID Report
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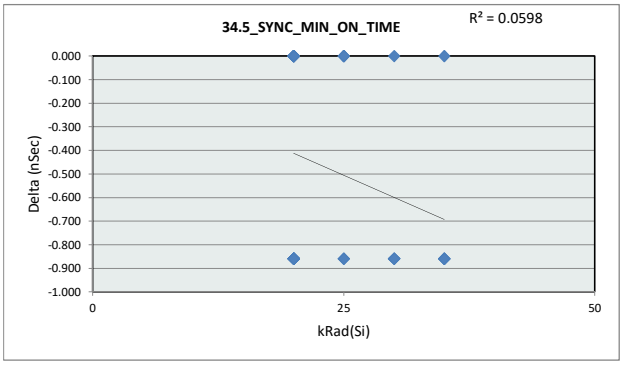
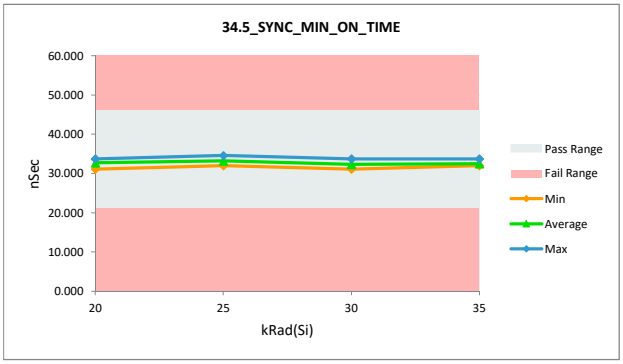
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.5_SYNC_MIN_ON_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	46	46
Min Limit	21	21

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	31.992	31.992	0.000
20	62	31.992	31.133	-0.859
20	63	32.852	32.852	0.000
20	64	32.852	32.852	0.000
20	65	32.852	32.852	0.000
20	67	32.852	31.992	-0.860
20	68	34.570	33.711	-0.859
20	69	33.711	33.711	0.000
20	70	32.852	32.852	0.000
20	71	33.711	33.711	0.000
20	72	33.711	32.852	-0.859
20	73	34.570	33.711	-0.859
20	74	33.711	32.852	-0.859
20	75	33.711	32.852	-0.859
20	76	31.992	31.992	0.000
20	77	31.992	31.992	0.000
20	78	31.133	31.133	0.000
20	79	31.992	31.133	-0.859
20	80	33.711	33.711	0.000
20	81	33.711	32.852	-0.859
20	82	33.711	32.852	-0.859
20	83	34.570	33.711	-0.859
25	84	34.570	33.711	-0.859
25	85	32.852	32.852	0.000
25	86	32.852	31.992	-0.860
25	87	34.570	34.570	0.000
25	88	32.852	32.852	0.000
30	89	31.992	31.133	-0.859
30	90	33.711	32.852	-0.859
30	91	33.711	33.711	0.000
30	92	32.852	31.992	-0.860
30	93	32.852	31.992	-0.860
35	94	33.711	32.852	-0.859
35	95	32.852	31.992	-0.860
35	96	32.852	31.992	-0.860
35	97	33.711	33.711	0.000
35	98	32.852	31.992	-0.860
Max		34.570	34.570	0.000
Average		33.177	32.689	-0.488
Min		31.133	31.133	-0.860
Std Dev		0.868	0.879	0.432



	34.5_SYNC_MIN_ON_TIME			
Test Site				
Tester				
Test Number				
Max Limit	46	nSec		
Min Limit	21	nSec		
kRad(Si)	20	25	30	35
LL	21.000	21.000	21.000	21.000
Min	31.133	31.992	31.133	31.992
Average	32.696	33.195	32.336	32.508
Max	33.711	34.570	33.711	33.711
UL	46.000	46.000	46.000	46.000



HDR TID Report
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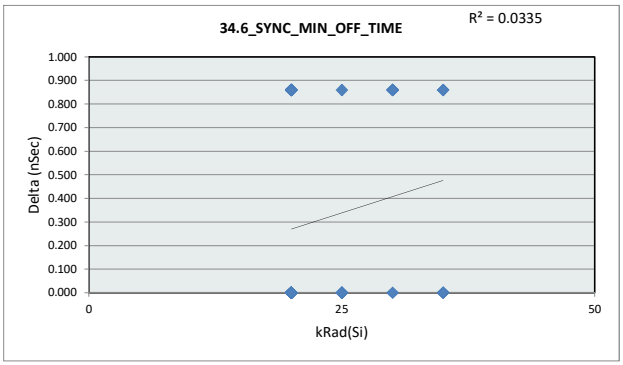
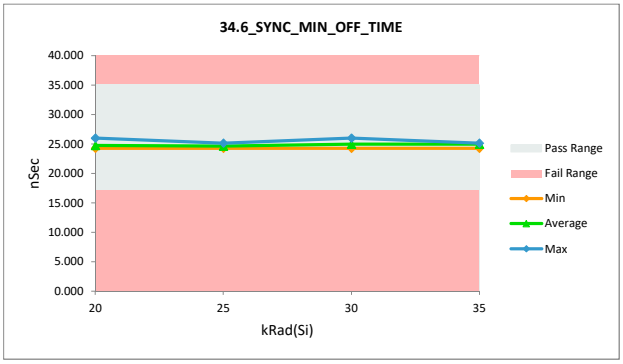
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.6_SYNC_MIN_OFF_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	35	35
Min Limit	17	17

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	24.258	25.117	0.859
20	62	24.258	25.117	0.859
20	63	24.258	24.258	0.000
20	64	24.258	24.258	0.000
20	65	25.117	25.117	0.000
20	67	24.258	25.117	0.859
20	68	24.258	24.258	0.000
20	69	24.258	24.258	0.000
20	70	25.117	25.117	0.000
20	71	23.398	24.258	0.860
20	72	24.258	24.258	0.000
20	73	24.258	24.258	0.000
20	74	24.258	24.258	0.000
20	75	24.258	24.258	0.000
20	76	24.258	25.117	0.859
20	77	25.117	25.117	0.000
20	78	25.117	25.117	0.000
20	79	25.117	25.977	0.860
20	80	24.258	25.117	0.859
20	81	25.117	25.117	0.000
20	82	24.258	24.258	0.000
20	83	24.258	24.258	0.000
25	84	24.258	24.258	0.000
25	85	24.258	24.258	0.000
25	86	25.117	25.117	0.000
25	87	24.258	24.258	0.000
25	88	24.258	25.117	0.859
30	89	25.117	25.977	0.860
30	90	23.398	24.258	0.860
30	91	24.258	24.258	0.000
30	92	24.258	25.117	0.859
30	93	24.258	25.117	0.859
35	94	25.117	25.117	0.000
35	95	24.258	25.117	0.859
35	96	25.117	25.117	0.000
35	97	24.258	24.258	0.000
35	98	24.258	25.117	0.859
Max		25.117	25.977	0.860
Average		24.444	24.769	0.325
Min		23.398	24.258	0.000
Std Dev		0.459	0.515	0.422



	34.6_SYNC_MIN_OFF_TIME			
Test Site				
Tester				
Test Number				
Max Limit	35	nSec		
Min Limit	17	nSec		
kRad(Si)	20	25	30	35
LL	17.000	17.000	17.000	17.000
Min	24.258	24.258	24.258	24.258
Average	24.727	24.602	24.945	24.945
Max	25.977	25.117	25.977	25.117
UL	35.000	35.000	35.000	35.000

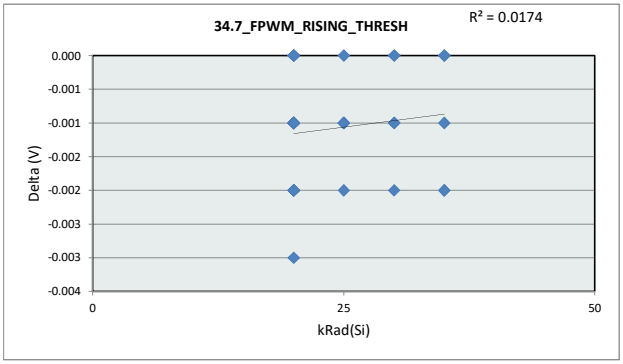


HDR TID Report
TPS7H4010-SEP

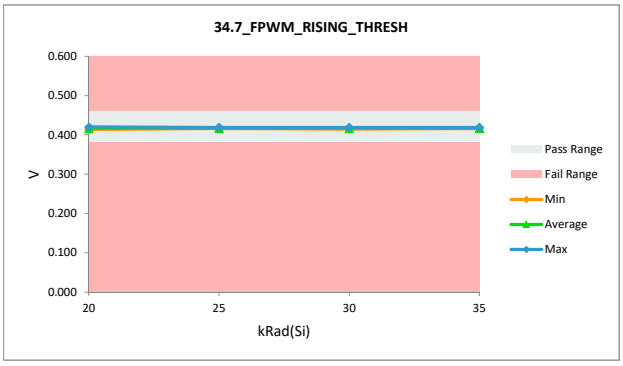
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.7_FPWM_RISING_THRESH	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.46	0.46
Min Limit	0.38	0.38

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.416	0.414	-0.002
20	62	0.419	0.417	-0.002
20	63	0.421	0.419	-0.002
20	64	0.419	0.417	-0.002
20	65	0.419	0.419	0.000
20	67	0.419	0.417	-0.002
20	68	0.417	0.416	-0.001
20	69	0.416	0.415	-0.001
20	70	0.419	0.419	0.000
20	71	0.419	0.419	0.000
20	72	0.420	0.419	-0.001
20	73	0.417	0.416	-0.001
20	74	0.420	0.419	-0.001
20	75	0.420	0.417	-0.003
20	76	0.417	0.416	-0.001
20	77	0.416	0.415	-0.001
20	78	0.415	0.415	0.000
20	79	0.416	0.415	-0.001
20	80	0.419	0.419	0.000
20	81	0.421	0.420	-0.001
20	82	0.419	0.417	-0.002
20	83	0.417	0.415	-0.002
25	84	0.417	0.417	0.000
25	85	0.417	0.416	-0.001
25	86	0.417	0.416	-0.001
25	87	0.419	0.417	-0.002
25	88	0.420	0.419	-0.001
30	89	0.420	0.419	-0.001
30	90	0.416	0.415	-0.001
30	91	0.416	0.416	0.000
30	92	0.419	0.417	-0.002
30	93	0.417	0.417	0.000
35	94	0.419	0.417	-0.002
35	95	0.419	0.417	-0.002
35	96	0.417	0.416	-0.001
35	97	0.419	0.419	0.000
35	98	0.416	0.416	0.000
Max		0.421	0.420	0.000
Average		0.418	0.417	-0.001
Min		0.415	0.414	-0.003
Std Dev		0.002	0.002	0.001



	34.7_FPWM_RISING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	0.46	V		
Min Limit	0.38	V		
kRad(Si)	20	25	30	35
LL	0.380	0.380	0.380	0.380
Min	0.414	0.416	0.415	0.416
Average	0.417	0.417	0.417	0.417
Max	0.420	0.419	0.419	0.419
UL	0.460	0.460	0.460	0.460



HDR TID Report
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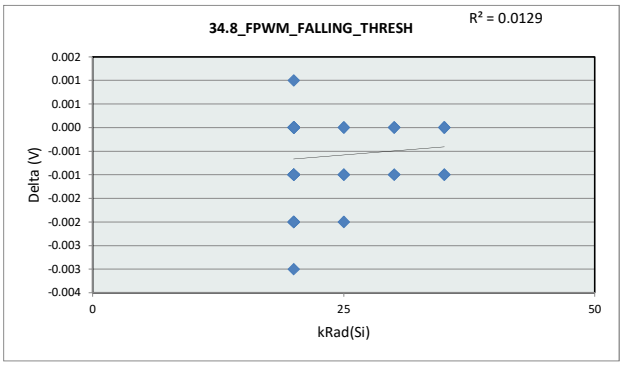
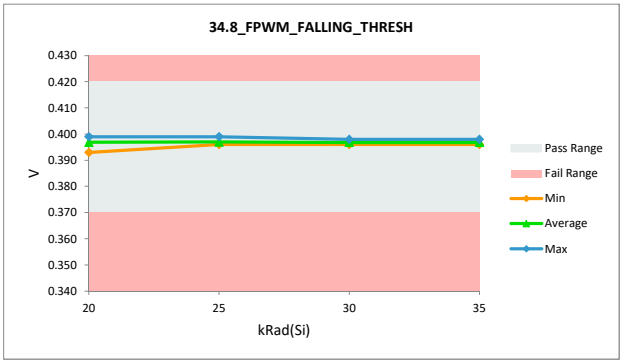
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.8_FPWM_FALLING_THRESH		
Test Site			
Tester			
Test Number			
Unit	V	V	
Max Limit	0.42	0.42	
Min Limit	0.37	0.37	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.396	0.393	-0.003
20	62	0.398	0.397	-0.001
20	63	0.399	0.398	-0.001
20	64	0.398	0.398	0.000
20	65	0.398	0.398	0.000
20	67	0.398	0.397	-0.001
20	68	0.397	0.396	-0.001
20	69	0.396	0.396	0.000
20	70	0.398	0.399	0.001
20	71	0.398	0.398	0.000
20	72	0.399	0.399	0.000
20	73	0.397	0.397	0.000
20	74	0.399	0.398	-0.001
20	75	0.399	0.397	-0.002
20	76	0.397	0.396	-0.001
20	77	0.395	0.395	0.000
20	78	0.395	0.395	0.000
20	79	0.395	0.395	0.000
20	80	0.398	0.398	0.000
20	81	0.401	0.399	-0.002
20	82	0.397	0.397	0.000
20	83	0.397	0.395	-0.002
25	84	0.397	0.397	0.000
25	85	0.397	0.396	-0.001
25	86	0.396	0.396	0.000
25	87	0.398	0.397	-0.001
25	88	0.401	0.399	-0.002
30	89	0.398	0.398	0.000
30	90	0.396	0.396	0.000
30	91	0.397	0.396	-0.001
30	92	0.398	0.397	-0.001
30	93	0.397	0.397	0.000
35	94	0.398	0.397	-0.001
35	95	0.397	0.397	0.000
35	96	0.397	0.396	-0.001
35	97	0.398	0.398	0.000
35	98	0.396	0.396	0.000
	Max	0.401	0.399	0.001
	Average	0.397	0.397	-0.001
	Min	0.395	0.393	-0.003
	Std Dev	0.001	0.001	0.001



	34.8_FPWM_FALLING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	0.42	V		
Min Limit	0.37	V		
kRad(Si)	20	25	30	35
LL	0.370	0.370	0.370	0.370
Min	0.393	0.396	0.396	0.396
Average	0.397	0.397	0.397	0.397
Max	0.399	0.399	0.398	0.398
UL	0.420	0.420	0.420	0.420

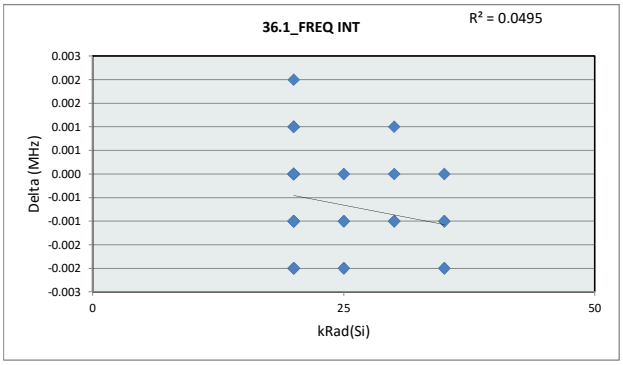


HDR TID Report
TPS7H4010-SEP

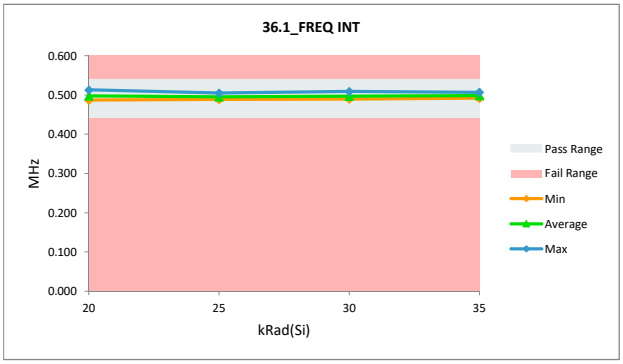
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.1_FREQ INT	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	0.54	0.54
Min Limit	0.44	0.44

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.502	0.502	0.000
20	62	0.500	0.498	-0.002
20	63	0.494	0.495	0.001
20	64	0.506	0.506	0.000
20	65	0.510	0.510	0.000
20	67	0.499	0.501	0.002
20	68	0.496	0.496	0.000
20	69	0.486	0.487	0.001
20	70	0.495	0.494	-0.001
20	71	0.495	0.494	-0.001
20	72	0.492	0.492	0.000
20	73	0.492	0.491	-0.001
20	74	0.498	0.496	-0.002
20	75	0.498	0.497	-0.001
20	76	0.494	0.492	-0.002
20	77	0.493	0.492	-0.001
20	78	0.511	0.511	0.000
20	79	0.513	0.513	0.000
20	80	0.495	0.496	0.001
20	81	0.491	0.489	-0.002
20	82	0.501	0.501	0.000
20	83	0.499	0.498	-0.001
25	84	0.493	0.492	-0.001
25	85	0.496	0.496	0.000
25	86	0.506	0.505	-0.001
25	87	0.491	0.489	-0.002
25	88	0.495	0.493	-0.002
30	89	0.499	0.500	0.001
30	90	0.490	0.490	0.000
30	91	0.492	0.491	-0.001
30	92	0.510	0.509	-0.001
30	93	0.497	0.496	-0.001
35	94	0.496	0.494	-0.002
35	95	0.498	0.498	0.000
35	96	0.508	0.507	-0.001
35	97	0.494	0.492	-0.002
35	98	0.503	0.502	-0.001
Max		0.513	0.513	0.002
Average		0.498	0.497	-0.001
Min		0.486	0.487	-0.002
Std Dev		0.007	0.007	0.001



	36.1_FREQ INT			
Test Site				
Tester				
Test Number				
Max Limit	0.54	MHz		
Min Limit	0.44	MHz		
kRad(Si)	20	25	30	35
LL	0.440	0.440	0.440	0.440
Min	0.487	0.489	0.490	0.492
Average	0.498	0.495	0.497	0.499
Max	0.513	0.505	0.509	0.507
UL	0.540	0.540	0.540	0.540



HDR TID Report
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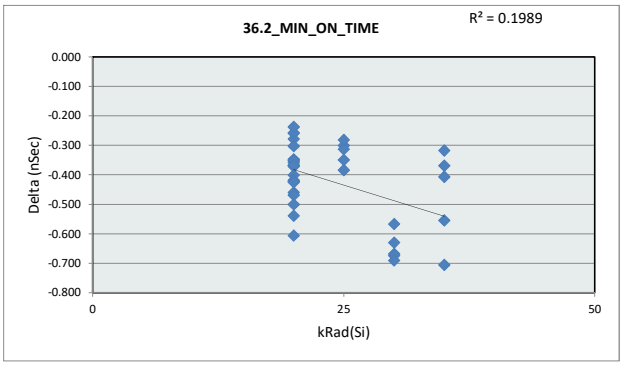
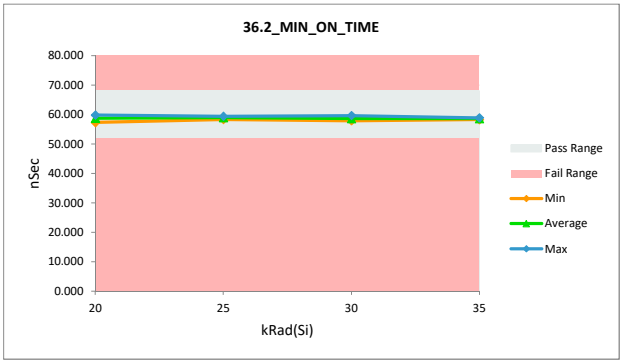
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.2_MIN_ON_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	68	68
Min Limit	52	52

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	59.135	58.734	-0.401
20	62	59.027	58.768	-0.259
20	63	59.353	59.005	-0.348
20	64	59.225	58.803	-0.422
20	65	59.237	58.958	-0.279
20	67	58.750	58.492	-0.258
20	68	60.098	59.492	-0.606
20	69	59.041	58.540	-0.501
20	70	59.438	59.135	-0.303
20	71	58.789	58.437	-0.352
20	72	59.125	58.706	-0.419
20	73	59.051	58.679	-0.372
20	74	58.608	58.148	-0.460
20	75	59.019	58.661	-0.358
20	76	58.284	57.861	-0.423
20	77	58.524	58.156	-0.368
20	78	59.255	58.716	-0.539
20	79	57.589	57.238	-0.351
20	80	59.458	59.033	-0.425
20	81	59.994	59.756	-0.238
20	82	58.197	57.728	-0.469
20	83	60.112	59.744	-0.368
25	84	59.698	59.314	-0.384
25	85	58.558	58.257	-0.301
25	86	59.701	59.388	-0.313
25	87	59.361	59.079	-0.282
25	88	58.995	58.645	-0.350
30	89	58.907	58.340	-0.567
30	90	59.059	58.391	-0.668
30	91	59.213	58.583	-0.630
30	92	58.535	57.861	-0.674
30	93	60.314	59.623	-0.691
35	94	59.195	58.640	-0.555
35	95	59.150	58.832	-0.318
35	96	59.068	58.699	-0.369
35	97	58.943	58.237	-0.706
35	98	58.741	58.334	-0.407
	Max	60.314	59.756	-0.238
	Average	59.101	58.676	-0.425
	Min	57.589	57.238	-0.706
	Std Dev	0.549	0.557	0.133



	36.2_MIN_ON_TIME			
Test Site				
Tester				
Test Number				
Max Limit	68	nSec		
Min Limit	52	nSec		
kRad(Si)	20	25	30	35
LL	52.000	52.000	52.000	52.000
Min	57.238	58.257	57.861	58.237
Average	58.672	58.937	58.560	58.548
Max	59.756	59.388	59.623	58.832
UL	68.000	68.000	68.000	68.000



HDR TID Report
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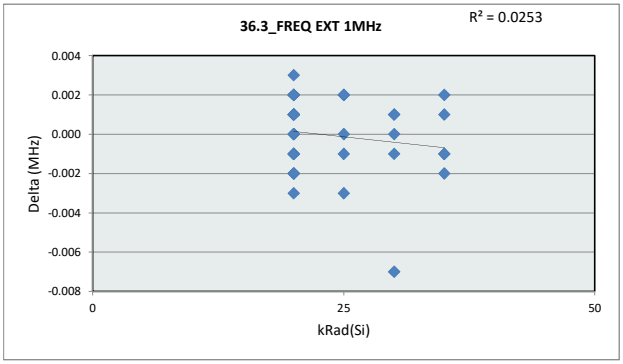
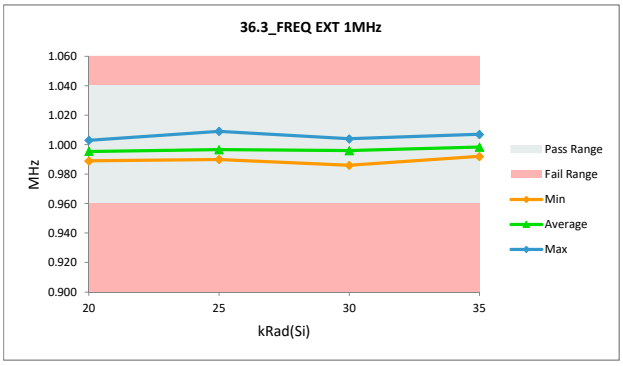
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.3_FREQ EXT 1MHz	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	1.04	1.04
Min Limit	0.96	0.96

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.999	1.001	0.002
20	62	0.995	0.992	-0.003
20	63	0.996	0.996	0.000
20	64	0.994	0.995	0.001
20	65	0.995	0.996	0.001
20	67	0.993	0.996	0.003
20	68	0.993	0.991	-0.002
20	69	0.998	0.999	0.001
20	70	0.991	0.992	0.001
20	71	0.992	0.992	0.000
20	72	0.993	0.992	-0.001
20	73	0.995	0.995	0.000
20	74	0.996	0.995	-0.001
20	75	0.996	0.994	-0.002
20	76	0.993	0.991	-0.002
20	77	0.994	0.995	0.001
20	78	1.000	0.999	-0.001
20	79	1.001	1.003	0.002
20	80	0.996	0.998	0.002
20	81	0.990	0.989	-0.001
20	82	1.000	1.002	0.002
20	83	0.996	0.997	0.001
25	84	0.991	0.990	-0.001
25	85	0.993	0.995	0.002
25	86	1.007	1.009	0.002
25	87	1.000	0.997	-0.003
25	88	0.992	0.992	0.000
30	89	1.004	1.004	0.000
30	90	0.993	0.994	0.001
30	91	0.993	0.986	-0.007
30	92	0.999	0.998	-0.001
30	93	0.997	0.998	0.001
35	94	1.002	1.001	-0.001
35	95	0.998	0.997	-0.001
35	96	0.990	0.992	0.002
35	97	0.997	0.995	-0.002
35	98	1.006	1.007	0.001
	Max	1.007	1.009	0.003
	Average	0.996	0.996	0.000
	Min	0.990	0.986	-0.007
	Std Dev	0.004	0.005	0.002



	36.3_FREQ EXT 1MHz			
Test Site				
Tester				
Test Number				
Max Limit	1.04	MHz		
Min Limit	0.96	MHz		
kRad(Si)	20	25	30	35
LL	0.960	0.960	0.960	0.960
Min	0.989	0.990	0.986	0.992
Average	0.995	0.997	0.996	0.998
Max	1.003	1.009	1.004	1.007
UL	1.040	1.040	1.040	1.040

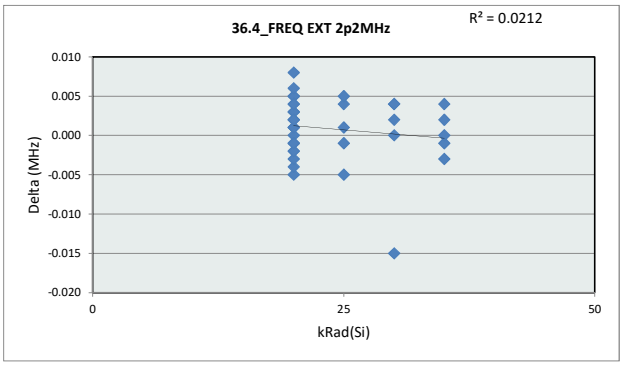


HDR TID Report
TPS7H4010-SEP

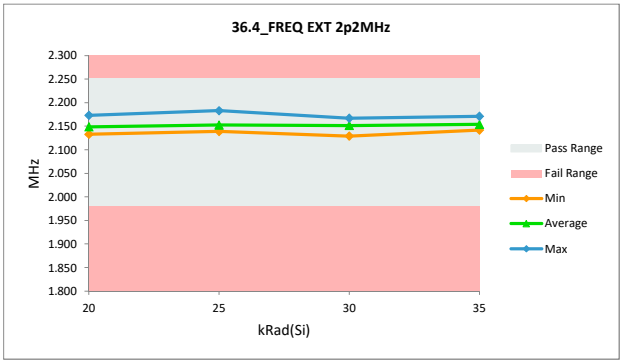
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.4_FREQ EXT 2p2MHz	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	2.25	2.25
Min Limit	1.98	1.98

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	2.153	2.158	0.005
20	62	2.149	2.144	-0.005
20	63	2.150	2.151	0.001
20	64	2.142	2.145	0.003
20	65	2.152	2.154	0.002
20	67	2.138	2.146	0.008
20	68	2.146	2.142	-0.004
20	69	2.154	2.159	0.005
20	70	2.141	2.142	0.001
20	71	2.141	2.141	0.000
20	72	2.144	2.146	0.002
20	73	2.151	2.152	0.001
20	74	2.148	2.146	-0.002
20	75	2.148	2.145	-0.003
20	76	2.141	2.140	-0.001
20	77	2.141	2.144	0.003
20	78	2.157	2.155	-0.002
20	79	2.169	2.173	0.004
20	80	2.148	2.154	0.006
20	81	2.134	2.133	-0.001
20	82	2.152	2.156	0.004
20	83	2.144	2.146	0.002
25	84	2.140	2.139	-0.001
25	85	2.145	2.149	0.004
25	86	2.178	2.183	0.005
25	87	2.157	2.152	-0.005
25	88	2.138	2.139	0.001
30	89	2.165	2.167	0.002
30	90	2.145	2.149	0.004
30	91	2.144	2.129	-0.015
30	92	2.154	2.154	0.000
30	93	2.154	2.158	0.004
35	94	2.157	2.156	-0.001
35	95	2.150	2.150	0.000
35	96	2.138	2.142	0.004
35	97	2.153	2.150	-0.003
35	98	2.169	2.171	0.002
Max		2.178	2.183	0.008
Average		2.149	2.150	0.001
Min		2.134	2.129	-0.015
Std Dev		0.010	0.011	0.004



	36.4_FREQ EXT 2p2MHz			
Test Site				
Tester				
Test Number				
Max Limit	2.25	MHz		
Min Limit	1.98	MHz		
kRad(Si)	20	25	30	35
LL	1.980	1.980	1.980	1.980
Min	2.133	2.139	2.129	2.142
Average	2.149	2.152	2.151	2.154
Max	2.173	2.183	2.167	2.171
UL	2.250	2.250	2.250	2.250

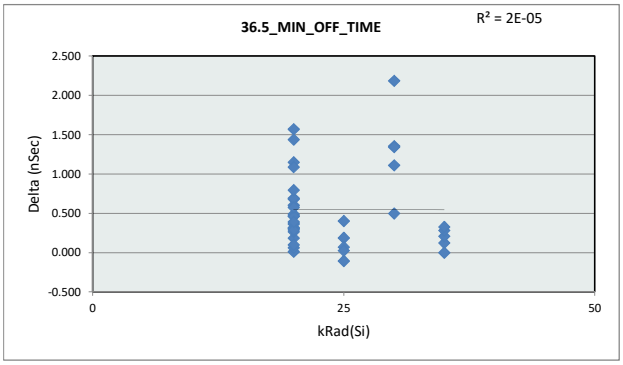


HDR TID Report
TPS7H4010-SEP

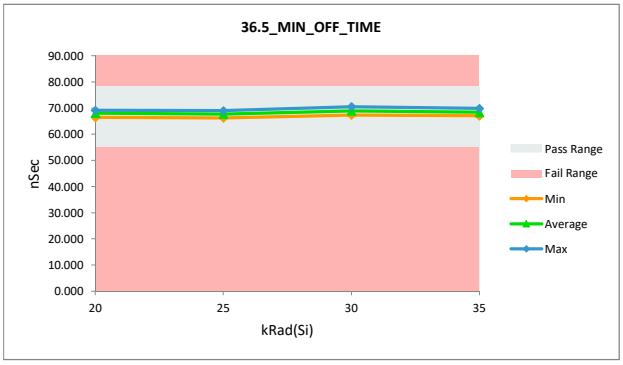
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.5_MIN_OFF_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	78	78
Min Limit	55	55

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	67.600	67.611	0.011
20	62	66.960	67.425	0.465
20	63	66.666	66.729	0.063
20	64	68.366	68.732	0.366
20	65	67.203	67.693	0.490
20	67	65.784	66.464	0.680
20	68	67.462	68.063	0.601
20	69	68.666	68.982	0.316
20	70	67.601	69.170	1.569
20	71	68.770	68.955	0.185
20	72	68.088	68.397	0.309
20	73	67.407	67.673	0.266
20	74	66.603	68.041	1.438
20	75	67.985	68.675	0.690
20	76	66.345	67.495	1.150
20	77	67.432	67.896	0.464
20	78	68.350	68.640	0.290
20	79	66.488	67.283	0.795
20	80	68.635	69.024	0.389
20	81	67.984	69.072	1.088
20	82	67.279	67.377	0.098
20	83	67.745	68.320	0.575
25	84	68.056	67.949	-0.107
25	85	65.995	66.182	0.187
25	86	67.932	68.333	0.401
25	87	66.843	66.913	0.070
25	88	68.999	69.025	0.026
30	89	68.023	68.520	0.497
30	90	66.408	68.593	2.185
30	91	65.968	67.323	1.355
30	92	69.184	70.525	1.341
30	93	68.538	69.649	1.111
35	94	69.783	69.907	0.124
35	95	66.841	67.051	0.210
35	96	68.979	69.262	0.283
35	97	68.028	68.027	-0.001
35	98	67.273	67.598	0.325
	Max	69.783	70.525	2.185
	Average	67.629	68.178	0.549
	Min	65.784	66.182	-0.107
	Std Dev	0.980	0.970	0.523



	36.5_MIN_OFF_TIME			
Test Site				
Tester				
Test Number				
Max Limit	78	nSec		
Min Limit	55	nSec		
kRad(Si)	20	25	30	35
LL	55.000	55.000	55.000	55.000
Min	66.464	66.182	67.323	67.051
Average	68.078	67.680	68.922	68.369
Max	69.170	69.025	70.525	69.907
UL	78.000	78.000	78.000	78.000

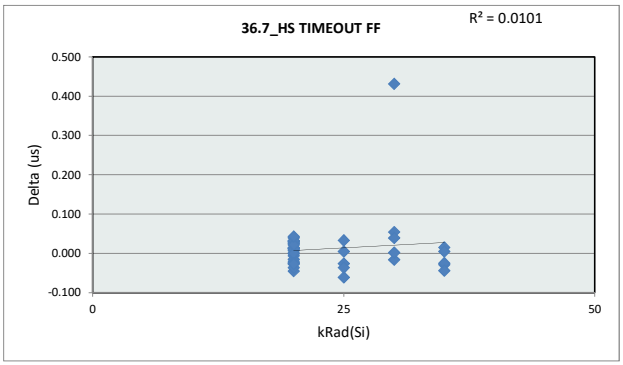


HDR TID Report
TPS7H4010-SEP

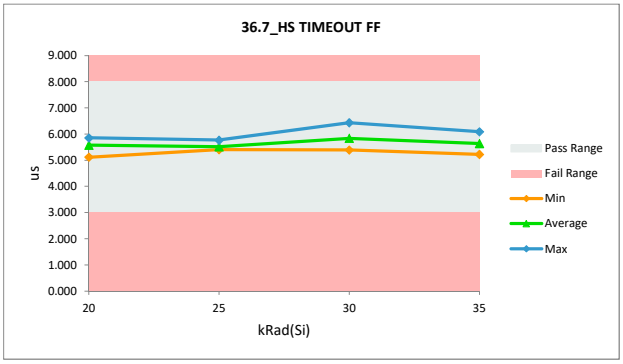
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.7_HS TIMEOUT FF	
Test Site		
Tester		
Test Number		
Unit	us	us
Max Limit	8	8
Min Limit	3	3

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	5.738	5.778	0.040
20	62	5.799	5.830	0.031
20	63	5.797	5.809	0.012
20	64	5.570	5.584	0.014
20	65	5.463	5.418	-0.045
20	67	5.366	5.392	0.026
20	68	5.478	5.485	0.007
20	69	5.396	5.427	0.031
20	70	5.825	5.852	0.027
20	71	5.756	5.750	-0.006
20	72	5.839	5.824	-0.015
20	73	5.423	5.387	-0.036
20	74	5.810	5.810	0.000
20	75	5.552	5.566	0.014
20	76	5.390	5.422	0.032
20	77	5.429	5.407	-0.022
20	78	5.595	5.606	0.011
20	79	5.561	5.561	0.000
20	80	5.742	5.717	-0.025
20	81	5.398	5.371	-0.027
20	82	5.095	5.117	0.022
20	83	5.435	5.478	0.043
25	84	5.490	5.429	-0.061
25	85	5.438	5.412	-0.026
25	86	5.527	5.560	0.033
25	87	5.803	5.767	-0.036
25	88	5.397	5.402	0.005
30	89	5.768	5.752	-0.016
30	90	5.339	5.393	0.054
30	91	5.912	5.914	0.002
30	92	5.643	5.682	0.039
30	93	6.002	6.433	0.431
35	94	5.475	5.490	0.015
35	95	5.611	5.582	-0.029
35	96	5.851	5.826	-0.025
35	97	6.080	6.085	0.005
35	98	5.268	5.224	-0.044
	Max	6.080	6.433	0.431
	Average	5.596	5.609	0.013
	Min	5.095	5.117	-0.061
	Std Dev	0.221	0.252	0.076



	36.7_HS TIMEOUT FF			
Test Site				
Tester				
Test Number				
Max Limit	8	us		
Min Limit	3	us		
kRad(Si)	20	25	30	35
LL	3.000	3.000	3.000	3.000
Min	5.117	5.402	5.393	5.224
Average	5.572	5.514	5.835	5.641
Max	5.852	5.767	6.433	6.085
UL	8.000	8.000	8.000	8.000

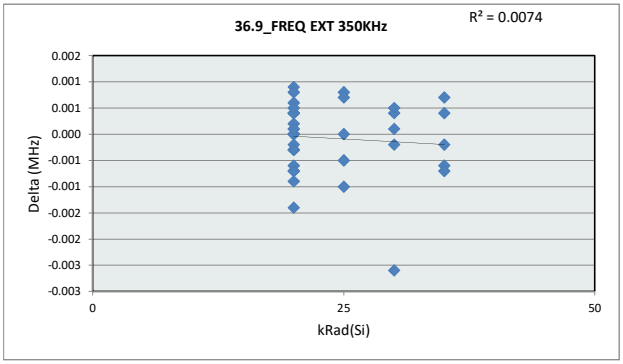


HDR TID Report
TPS7H4010-SEP

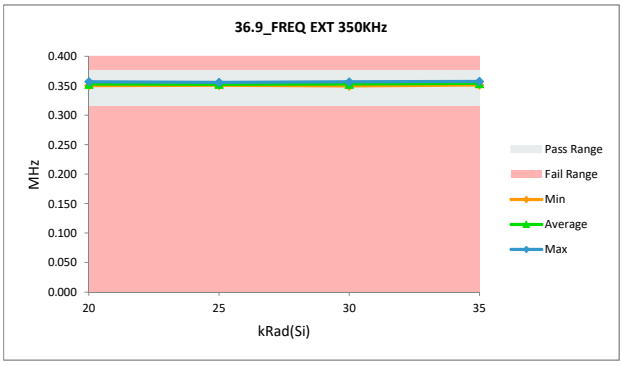
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.9_FREQ EXT 350KHz	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	0.376	0.376
Min Limit	0.315	0.315

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.354	0.355	0.001
20	62	0.352	0.351	-0.001
20	63	0.353	0.353	0.000
20	64	0.353	0.353	0.000
20	65	0.352	0.352	0.000
20	67	0.353	0.354	0.001
20	68	0.351	0.350	-0.001
20	69	0.353	0.354	0.000
20	70	0.351	0.351	0.000
20	71	0.352	0.352	0.000
20	72	0.351	0.350	0.000
20	73	0.352	0.352	0.000
20	74	0.353	0.353	0.000
20	75	0.354	0.353	-0.001
20	76	0.352	0.351	-0.001
20	77	0.354	0.354	0.000
20	78	0.355	0.354	-0.001
20	79	0.353	0.354	0.000
20	80	0.353	0.354	0.001
20	81	0.351	0.350	0.000
20	82	0.356	0.357	0.000
20	83	0.355	0.355	0.000
25	84	0.351	0.351	-0.001
25	85	0.351	0.352	0.001
25	86	0.355	0.356	0.001
25	87	0.355	0.354	-0.001
25	88	0.351	0.351	0.000
30	89	0.356	0.357	0.000
30	90	0.351	0.351	0.000
30	91	0.352	0.350	-0.003
30	92	0.354	0.354	0.000
30	93	0.352	0.352	0.000
35	94	0.355	0.355	-0.001
35	95	0.354	0.354	0.000
35	96	0.351	0.351	0.001
35	97	0.353	0.352	-0.001
35	98	0.357	0.357	0.000
Max		0.357	0.357	0.001
Average		0.353	0.353	0.000
Min		0.351	0.350	-0.003
Std Dev		0.002	0.002	0.001



	36.9_FREQ EXT 350KHz			
Test Site				
Tester				
Test Number				
Max Limit	0.376	MHz		
Min Limit	0.315	MHz		
kRad(Si)	20	25	30	35
LL	0.315	0.315	0.315	0.315
Min	0.350	0.351	0.350	0.351
Average	0.353	0.353	0.353	0.354
Max	0.357	0.356	0.357	0.357
UL	0.376	0.376	0.376	0.376

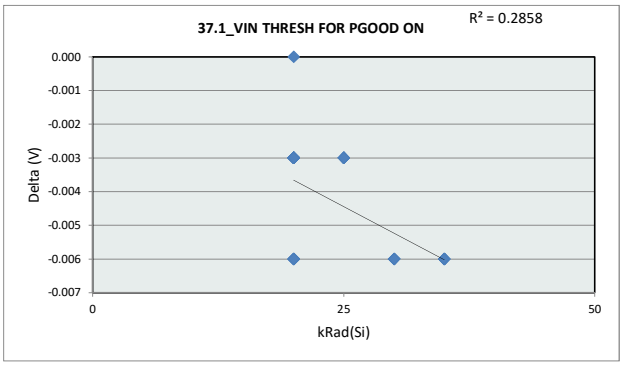


HDR TID Report
TPS7H4010-SEP

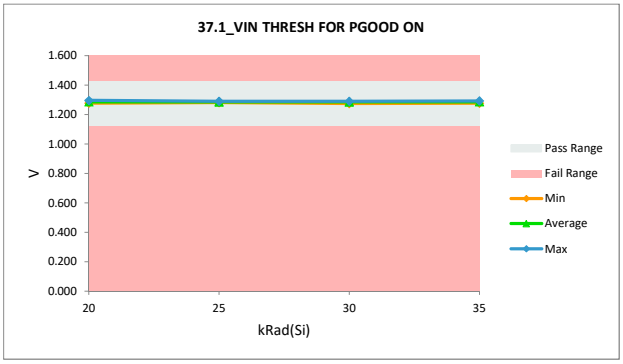
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.1_VIN THRESH FOR PGOOD O	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.42	1.42
Min Limit	1.12	1.12

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.289	1.289	0.000
20	62	1.280	1.277	-0.003
20	63	1.283	1.280	-0.003
20	64	1.289	1.286	-0.003
20	65	1.286	1.283	-0.003
20	67	1.286	1.280	-0.006
20	68	1.295	1.292	-0.003
20	69	1.301	1.295	-0.006
20	70	1.286	1.283	-0.003
20	71	1.289	1.283	-0.006
20	72	1.289	1.286	-0.003
20	73	1.286	1.283	-0.003
20	74	1.283	1.277	-0.006
20	75	1.292	1.286	-0.006
20	76	1.292	1.289	-0.003
20	77	1.283	1.280	-0.003
20	78	1.286	1.283	-0.003
20	79	1.283	1.280	-0.003
20	80	1.301	1.295	-0.006
20	81	1.295	1.289	-0.006
20	82	1.286	1.283	-0.003
20	83	1.298	1.295	-0.003
25	84	1.292	1.289	-0.003
25	85	1.286	1.283	-0.003
25	86	1.283	1.280	-0.003
25	87	1.283	1.280	-0.003
25	88	1.292	1.289	-0.003
30	89	1.280	1.274	-0.006
30	90	1.292	1.286	-0.006
30	91	1.295	1.289	-0.006
30	92	1.289	1.283	-0.006
30	93	1.295	1.289	-0.006
35	94	1.298	1.292	-0.006
35	95	1.283	1.277	-0.006
35	96	1.295	1.289	-0.006
35	97	1.295	1.289	-0.006
35	98	1.286	1.280	-0.006
	Max	1.301	1.295	0.000
	Average	1.289	1.285	-0.004
	Min	1.280	1.274	-0.006
	Std Dev	0.006	0.005	0.002



	37.1_VIN THRESH FOR PGOOD			
Test Site				
Tester				
Test Number				
Max Limit	1.42	V		
Min Limit	1.12	V		
kRad(Si)	20	25	30	35
LL	1.120	1.120	1.120	1.120
Min	1.277	1.280	1.274	1.277
Average	1.285	1.284	1.284	1.285
Max	1.295	1.289	1.289	1.292
UL	1.420	1.420	1.420	1.420

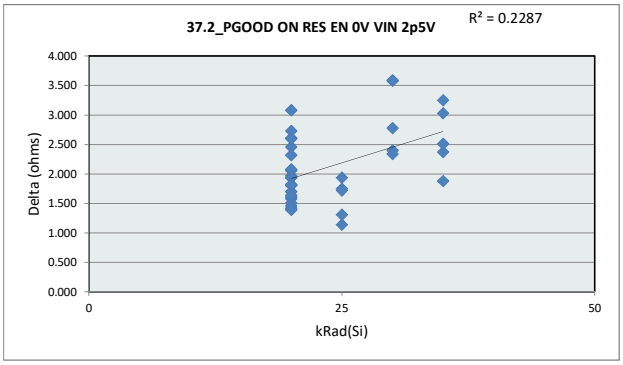


HDR TID Report
TPS7H4010-SEP

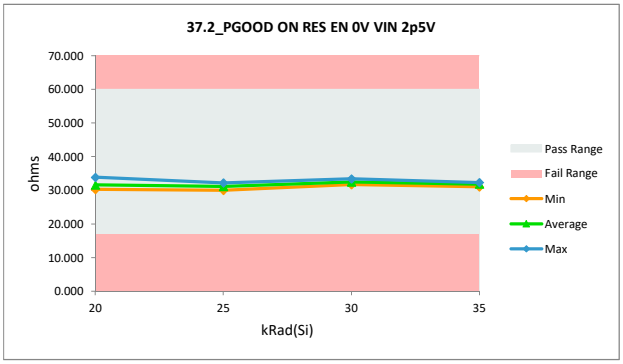
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.2_PGOOD ON RES EN 0V VIN	
Test Site		
Tester		
Test Number		
Unit	ohms	ohms
Max Limit	60	60
Min Limit	17	17

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	29.280	31.250	1.970
20	62	29.980	31.920	1.940
20	63	30.660	33.120	2.460
20	64	29.470	31.170	1.700
20	65	30.270	32.590	2.320
20	67	29.560	31.620	2.060
20	68	30.010	31.520	1.510
20	69	29.270	31.350	2.080
20	70	29.310	31.130	1.820
20	71	29.110	30.690	1.580
20	72	29.410	31.350	1.940
20	73	30.070	32.670	2.600
20	74	29.820	32.550	2.730
20	75	29.010	30.820	1.810
20	76	30.550	33.160	2.610
20	77	29.720	31.330	1.610
20	78	28.790	30.250	1.460
20	79	30.790	33.870	3.080
20	80	29.240	30.660	1.420
20	81	29.380	30.770	1.390
20	82	28.920	30.560	1.640
20	83	29.170	30.980	1.810
25	84	29.110	30.860	1.750
25	85	29.490	30.800	1.310
25	86	30.510	32.230	1.720
25	87	30.010	31.950	1.940
25	88	28.840	29.980	1.140
30	89	29.340	32.930	3.590
30	90	29.840	33.420	3.580
30	91	29.360	31.760	2.400
30	92	29.830	32.610	2.780
30	93	29.340	31.680	2.340
35	94	29.180	31.550	2.370
35	95	28.990	32.240	3.250
35	96	29.140	31.020	1.880
35	97	29.800	32.310	2.510
35	98	29.050	32.080	3.030
	Max	30.790	33.870	3.590
	Average	29.557	31.696	2.139
	Min	28.790	29.980	1.140
	Std Dev	0.529	0.938	0.629



	37.2_PGOOD ON RES EN 0V VI			
Test Site				
Tester				
Test Number				
Max Limit	60	ohms		
Min Limit	17	ohms		
kRad(Si)	20	25	30	35
LL	17.000	17.000	17.000	17.000
Min	30.250	29.980	31.680	31.020
Average	31.606	31.164	32.480	31.840
Max	33.870	32.230	33.420	32.310
UL	60.000	60.000	60.000	60.000

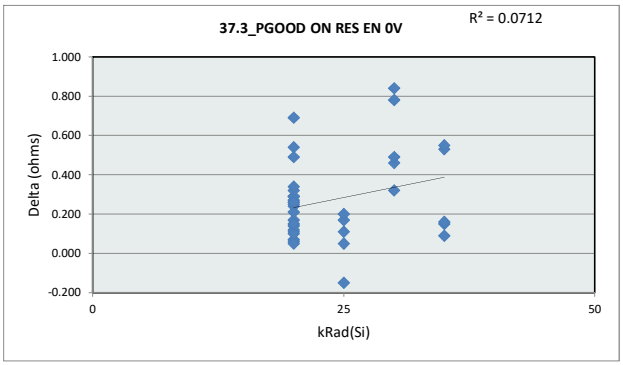


HDR TID Report
TPS7H4010-SEP

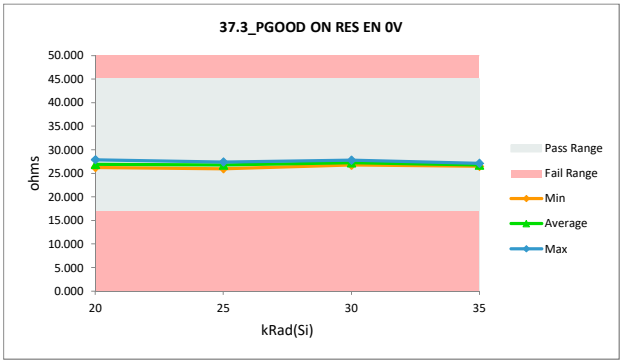
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.3_PGOOD ON RES EN 0V	
Test Site		
Tester		
Test Number		
Unit	ohms	ohms
Max Limit	45	45
Min Limit	17	17

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	26.270	26.440	0.170
20	62	27.420	27.660	0.240
20	63	27.460	27.750	0.290
20	64	26.370	26.440	0.070
20	65	26.970	27.260	0.290
20	67	26.610	26.750	0.140
20	68	26.880	26.990	0.110
20	69	26.190	26.510	0.320
20	70	26.420	26.680	0.260
20	71	26.370	26.430	0.060
20	72	26.120	26.240	0.120
20	73	26.770	27.310	0.540
20	74	26.730	27.220	0.490
20	75	26.340	26.590	0.250
20	76	27.390	27.730	0.340
20	77	27.090	27.360	0.270
20	78	26.120	26.220	0.100
20	79	27.200	27.890	0.690
20	80	26.440	26.590	0.150
20	81	26.430	26.480	0.050
20	82	26.420	26.630	0.210
20	83	26.350	26.610	0.260
25	84	26.340	26.450	0.110
25	85	26.770	26.820	0.050
25	86	27.240	27.410	0.170
25	87	27.020	27.220	0.200
25	88	26.130	25.980	-0.150
30	89	26.940	27.780	0.840
30	90	26.790	27.570	0.780
30	91	26.420	26.740	0.320
30	92	26.580	27.040	0.460
30	93	26.620	27.110	0.490
35	94	26.340	26.490	0.150
35	95	26.590	27.120	0.530
35	96	26.520	26.610	0.090
35	97	26.690	26.850	0.160
35	98	26.150	26.700	0.550
	Max	27.460	27.890	0.840
	Average	26.635	26.910	0.275
	Min	26.120	25.980	-0.150
	Std Dev	0.384	0.499	0.218



	37.3_PGOOD ON RES EN 0V			
Test Site				
Tester				
Test Number				
Max Limit	45	ohms		
Min Limit	17	ohms		
kRad(Si)	20	25	30	35
LL	17.000	17.000	17.000	17.000
Min	26.220	25.980	26.740	26.490
Average	26.899	26.776	27.248	26.754
Max	27.890	27.410	27.780	27.120
UL	45.000	45.000	45.000	45.000

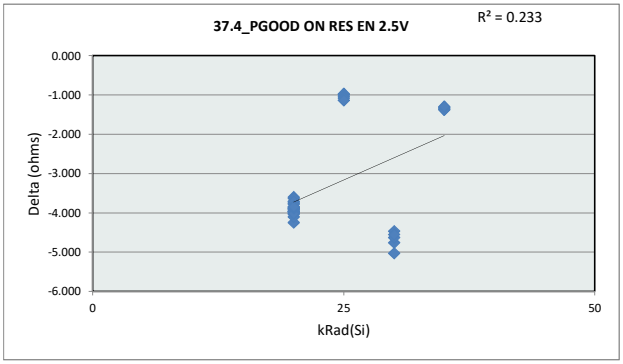


HDR TID Report
TPS7H4010-SEP

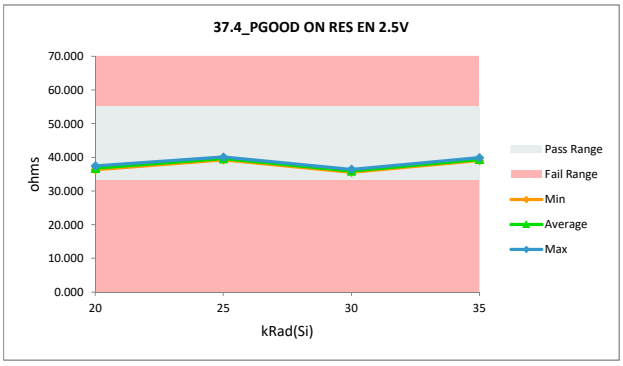
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.4_PGOOD ON RES EN 2.5V	
Test Site		
Tester		
Test Number		
Unit	ohms	ohms
Max Limit	55	55
Min Limit	33	33

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	40.560	36.680	-3.880
20	62	40.670	36.710	-3.960
20	63	41.050	36.800	-4.250
20	64	40.240	36.340	-3.900
20	65	40.850	36.900	-3.950
20	67	40.710	36.730	-3.980
20	68	40.470	36.500	-3.970
20	69	40.620	36.590	-4.030
20	70	40.570	36.810	-3.760
20	71	40.730	36.950	-3.780
20	72	40.360	36.450	-3.910
20	73	40.600	36.710	-3.890
20	74	40.420	36.820	-3.600
20	75	40.390	36.670	-3.720
20	76	40.720	36.750	-3.970
20	77	41.000	36.900	-4.100
20	78	40.170	36.540	-3.630
20	79	41.150	37.440	-3.710
20	80	40.800	36.780	-4.020
20	81	40.720	36.840	-3.880
20	82	40.570	36.720	-3.850
20	83	40.460	36.610	-3.850
25	84	40.260	39.270	-0.990
25	85	40.810	39.840	-0.970
25	86	41.090	40.060	-1.030
25	87	40.560	39.480	-1.080
25	88	40.640	39.500	-1.140
30	89	41.200	36.440	-4.760
30	90	40.220	35.750	-4.470
30	91	40.610	35.580	-5.030
30	92	40.510	35.880	-4.630
30	93	40.630	36.080	-4.550
35	94	41.040	39.720	-1.320
35	95	41.250	39.870	-1.380
35	96	40.470	39.120	-1.350
35	97	40.530	39.150	-1.380
35	98	40.330	39.030	-1.300
Max		41.250	40.060	-0.970
Average		40.648	37.379	-3.269
Min		40.170	35.580	-5.030
Std Dev		0.282	1.365	1.318



	37.4_PGOOD ON RES EN 2.5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ohms		
Min Limit	33	ohms		
kRad(Si)	20	25	30	35
LL	33.000	33.000	33.000	33.000
Min	36.340	39.270	35.580	39.030
Average	36.738	39.630	35.946	39.378
Max	37.440	40.060	36.440	39.870
UL	55.000	55.000	55.000	55.000

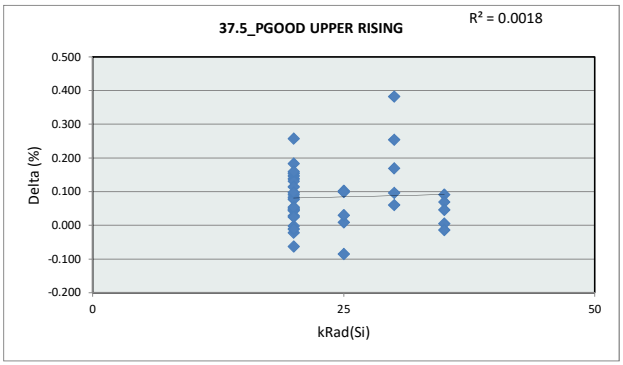


HDR TID Report
TPS7H4010-SEP

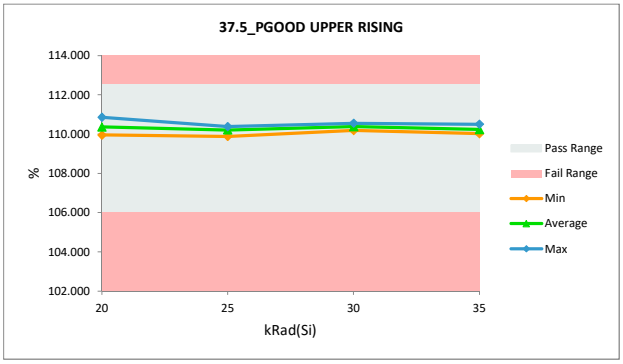
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.5_PGOOD UPPER RISING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	112.5	112.5
Min Limit	106	106

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	110.151	110.179	0.028
20	62	110.375	110.513	0.138
20	63	110.410	110.557	0.147
20	64	110.701	110.855	0.154
20	65	110.370	110.368	-0.002
20	67	110.233	110.324	0.091
20	68	110.387	110.431	0.044
20	69	110.135	110.113	-0.022
20	70	110.509	110.592	0.083
20	71	110.223	110.270	0.047
20	72	110.336	110.387	0.051
20	73	110.330	110.407	0.077
20	74	110.407	110.461	0.054
20	75	110.435	110.618	0.183
20	76	110.170	110.427	0.257
20	77	110.048	110.179	0.131
20	78	110.016	109.953	-0.063
20	79	110.368	110.482	0.114
20	80	110.049	110.074	0.025
20	81	110.342	110.439	0.097
20	82	110.091	110.250	0.159
20	83	110.147	110.136	-0.011
25	84	110.228	110.330	0.102
25	85	110.234	110.243	0.009
25	86	110.179	110.209	0.030
25	87	109.966	109.881	-0.085
25	88	110.284	110.383	0.099
30	89	110.100	110.269	0.169
30	90	110.170	110.552	0.382
30	91	110.350	110.446	0.096
30	92	110.216	110.470	0.254
30	93	110.124	110.184	0.060
35	94	110.222	110.313	0.091
35	95	110.015	110.020	0.005
35	96	110.266	110.252	-0.014
35	97	110.433	110.502	0.069
35	98	110.012	110.058	0.046
Max		110.701	110.855	0.382
Average		110.244	110.328	0.084
Min		109.966	109.881	-0.085
Std Dev		0.161	0.203	0.092



	37.5_PGOOD UPPER RISING			
Test Site				
Tester				
Test Number				
Max Limit	112.5	%		
Min Limit	106	%		
kRad(Si)	20	25	30	35
LL	106.000	106.000	106.000	106.000
Min	109.953	109.881	110.184	110.020
Average	110.364	110.209	110.384	110.229
Max	110.855	110.383	110.552	110.502
UL	112.500	112.500	112.500	112.500

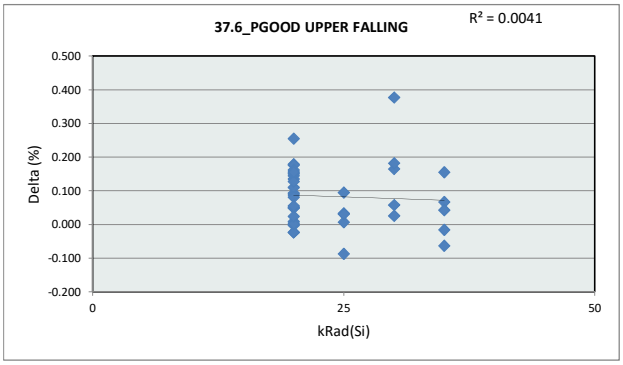


HDR TID Report
TPS7H4010-SEP

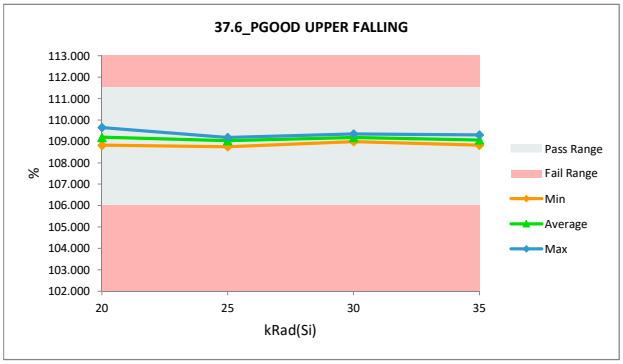
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.6_PGOOD UPPER FALLING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	111.5	111.5
Min Limit	106	106

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	108.955	109.048	0.093
20	62	109.178	109.313	0.135
20	63	109.214	109.359	0.145
20	64	109.502	109.653	0.151
20	65	109.107	109.105	-0.002
20	67	109.104	109.192	0.088
20	68	109.191	109.301	0.110
20	69	109.006	108.983	-0.023
20	70	109.312	109.393	0.081
20	71	109.094	109.071	-0.023
20	72	109.205	109.254	0.049
20	73	109.198	109.207	0.009
20	74	109.208	109.258	0.050
20	75	109.241	109.420	0.179
20	76	108.974	109.229	0.255
20	77	108.852	108.980	0.128
20	78	108.820	108.822	0.002
20	79	109.105	109.282	0.177
20	80	108.919	108.943	0.024
20	81	109.148	109.310	0.162
20	82	108.894	109.050	0.156
20	83	108.951	109.006	0.055
25	84	109.099	109.132	0.033
25	85	109.105	109.112	0.007
25	86	108.914	109.009	0.095
25	87	108.837	108.750	-0.087
25	88	109.154	109.185	0.031
30	89	108.905	109.070	0.165
30	90	108.972	109.349	0.377
30	91	109.220	109.246	0.026
30	92	109.085	109.267	0.182
30	93	108.929	108.987	0.058
35	94	109.023	109.178	0.155
35	95	108.885	108.822	-0.063
35	96	109.138	109.122	-0.016
35	97	109.235	109.302	0.067
35	98	108.882	108.925	0.043
	Max	109.502	109.653	0.377
	Average	109.069	109.152	0.083
	Min	108.820	108.750	-0.087
	Std Dev	0.155	0.188	0.092



	37.6_PGOOD UPPER FALLING			
Test Site				
Tester				
Test Number				
Max Limit	111.5	%		
Min Limit	106	%		
kRad(Si)	20	25	30	35
LL	106.000	106.000	106.000	106.000
Min	108.822	108.750	108.987	108.822
Average	109.190	109.038	109.184	109.070
Max	109.653	109.185	109.349	109.302
UL	111.500	111.500	111.500	111.500

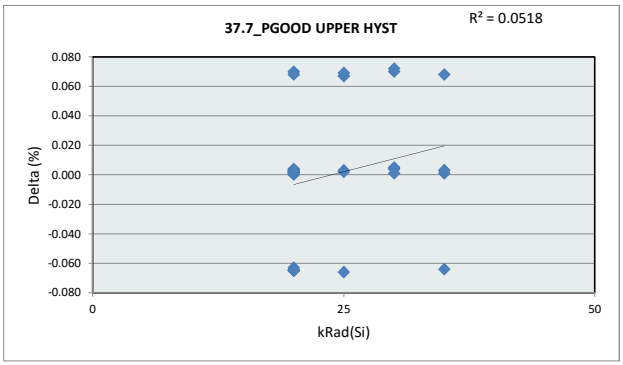


HDR TID Report
TPS7H4010-SEP

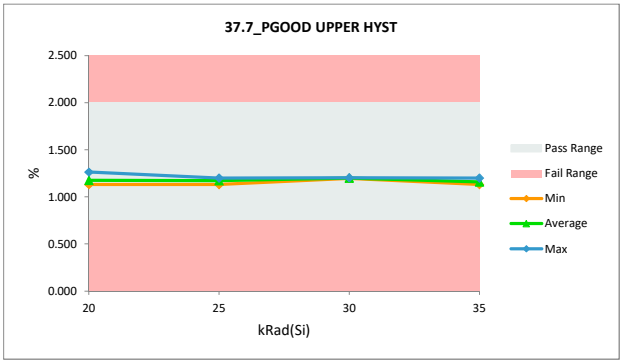
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.7_PGOOD UPPER HYST	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	2	2
Min Limit	0.75	0.75

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.196	1.131	-0.065
20	62	1.197	1.200	0.003
20	63	1.197	1.198	0.001
20	64	1.199	1.201	0.002
20	65	1.263	1.263	0.000
20	67	1.129	1.131	0.002
20	68	1.196	1.131	-0.065
20	69	1.129	1.130	0.001
20	70	1.198	1.199	0.001
20	71	1.129	1.199	0.070
20	72	1.131	1.133	0.002
20	73	1.131	1.199	0.068
20	74	1.199	1.203	0.004
20	75	1.195	1.198	0.003
20	76	1.196	1.198	0.002
20	77	1.196	1.199	0.003
20	78	1.196	1.131	-0.065
20	79	1.263	1.200	-0.063
20	80	1.130	1.131	0.001
20	81	1.194	1.130	-0.064
20	82	1.197	1.200	0.003
20	83	1.196	1.131	-0.065
25	84	1.130	1.197	0.067
25	85	1.129	1.132	0.003
25	86	1.265	1.199	-0.066
25	87	1.129	1.131	0.002
25	88	1.129	1.198	0.069
30	89	1.195	1.199	0.004
30	90	1.198	1.203	0.005
30	91	1.130	1.200	0.070
30	92	1.131	1.203	0.072
30	93	1.196	1.197	0.001
35	94	1.199	1.135	-0.064
35	95	1.129	1.197	0.068
35	96	1.129	1.130	0.001
35	97	1.197	1.200	0.003
35	98	1.130	1.133	0.003
Max		1.265	1.263	0.072
Average		1.175	1.175	0.000
Min		1.129	1.130	-0.066
Std Dev		0.042	0.036	0.043



	37.7_PGOOD UPPER HYST			
Test Site				
Tester				
Test Number				
Max Limit	2	%		
Min Limit	0.75	%		
kRad(Si)	20	25	30	35
LL	0.750	0.750	0.750	0.750
Min	1.130	1.131	1.197	1.130
Average	1.174	1.171	1.200	1.159
Max	1.263	1.199	1.203	1.200
UL	2.000	2.000	2.000	2.000

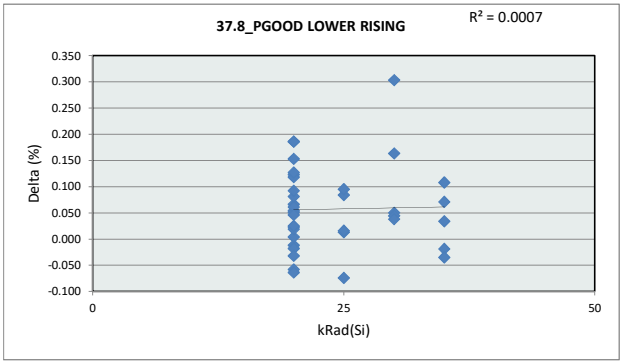


HDR TID Report
TPS7H4010-SEP

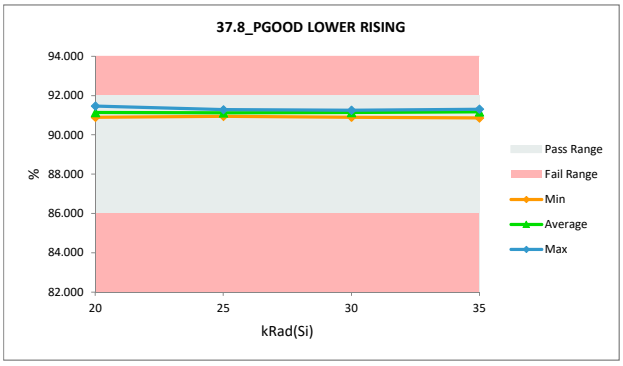
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.8_PGOOD LOWER RISING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	92	92
Min Limit	86	86

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	91.084	91.150	0.066
20	62	90.893	90.916	0.023
20	63	91.133	91.121	-0.012
20	64	91.318	91.300	-0.018
20	65	91.365	91.419	0.054
20	67	90.842	90.893	0.051
20	68	91.391	91.472	0.081
20	69	90.871	90.963	0.092
20	70	91.082	91.205	0.123
20	71	91.088	91.092	0.004
20	72	91.115	91.134	0.019
20	73	91.032	91.150	0.118
20	74	90.895	91.081	0.186
20	75	91.188	91.249	0.061
20	76	90.966	90.991	0.025
20	77	91.108	91.261	0.153
20	78	90.882	90.928	0.046
20	79	91.286	91.413	0.127
20	80	90.976	90.918	-0.058
20	81	91.299	91.235	-0.064
20	82	90.933	91.119	0.186
20	83	91.014	90.982	-0.032
25	84	91.092	91.176	0.084
25	85	91.042	91.137	0.095
25	86	91.272	91.285	0.013
25	87	91.041	91.057	0.016
25	88	91.017	90.943	-0.074
30	89	91.108	91.158	0.050
30	90	90.932	91.235	0.303
30	91	91.205	91.249	0.044
30	92	90.993	91.156	0.163
30	93	90.862	90.900	0.038
35	94	91.174	91.282	0.108
35	95	90.881	90.862	-0.019
35	96	91.213	91.178	-0.035
35	97	91.273	91.307	0.034
35	98	91.133	91.204	0.071
	Max	91.391	91.472	0.303
	Average	91.081	91.138	0.057
	Min	90.842	90.862	-0.074
	Std Dev	0.153	0.158	0.079



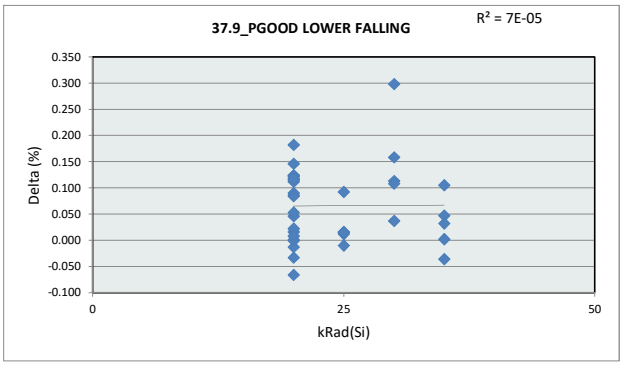
	37.8_PGOOD LOWER RISING			
Test Site				
Tester				
Test Number				
Max Limit	92	%		
Min Limit	86	%		
kRad(Si)	20	25	30	35
LL	86.000	86.000	86.000	86.000
Min	90.893	90.943	90.900	90.862
Average	91.136	91.120	91.140	91.167
Max	91.472	91.285	91.249	91.307
UL	92.000	92.000	92.000	92.000



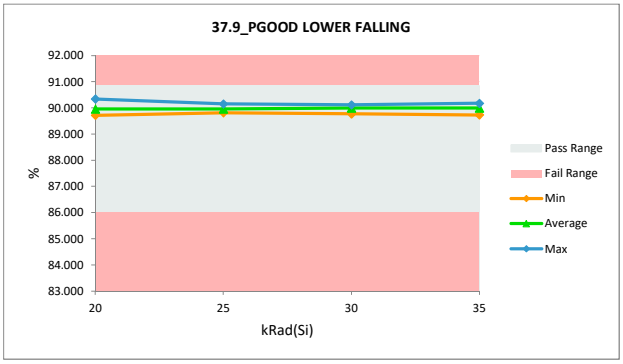
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.9_PGOOD LOWER FALLING		
Test Site			
Tester			
Test Number			
Unit	%	%	
Max Limit	90.84	90.84	
Min Limit	86	86	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	89.954	89.953	-0.001
20	62	89.630	89.716	0.086
20	63	89.936	89.923	-0.013
20	64	90.119	90.165	0.046
20	65	90.169	90.222	0.053
20	67	89.647	89.762	0.115
20	68	90.195	90.341	0.146
20	69	89.676	89.766	0.090
20	70	89.884	90.006	0.122
20	71	89.892	89.893	0.001
20	72	89.918	89.934	0.016
20	73	89.834	89.951	0.117
20	74	89.697	89.879	0.182
20	75	89.994	90.118	0.124
20	76	89.837	89.859	0.022
20	77	89.978	90.062	0.084
20	78	89.686	89.798	0.112
20	79	90.023	90.146	0.123
20	80	89.780	89.788	0.008
20	81	90.105	90.039	-0.066
20	82	89.802	89.920	0.118
20	83	89.751	89.718	-0.033
25	84	89.963	89.979	0.016
25	85	89.913	90.005	0.092
25	86	90.140	90.152	0.012
25	87	89.845	89.860	0.015
25	88	89.821	89.811	-0.010
30	89	89.913	90.026	0.113
30	90	89.734	90.032	0.298
30	91	90.008	90.116	0.108
30	92	89.862	90.020	0.158
30	93	89.733	89.770	0.037
35	94	89.975	90.080	0.105
35	95	89.685	89.732	0.047
35	96	90.018	89.982	-0.036
35	97	90.142	90.174	0.032
35	98	90.003	90.005	0.002
	Max	90.195	90.341	0.298
	Average	89.899	89.965	0.066
	Min	89.630	89.716	-0.066
	Std Dev	0.157	0.155	0.073



	37.9_PGOOD LOWER FALLING			
Test Site				
Tester				
Test Number				
Max Limit	90.84	%		
Min Limit	86	%		
kRad(Si)	20	25	30	35
LL	86.000	86.000	86.000	86.000
Min	89.716	89.811	89.770	89.732
Average	89.953	89.961	89.993	89.995
Max	90.341	90.152	90.116	90.174
UL	90.840	90.840	90.840	90.840

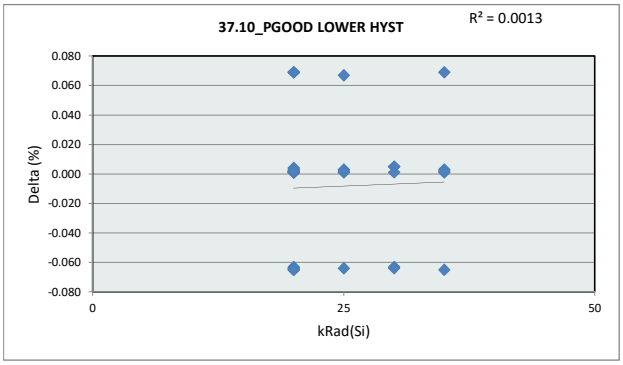


HDR TID Report
TPS7H4010-SEP

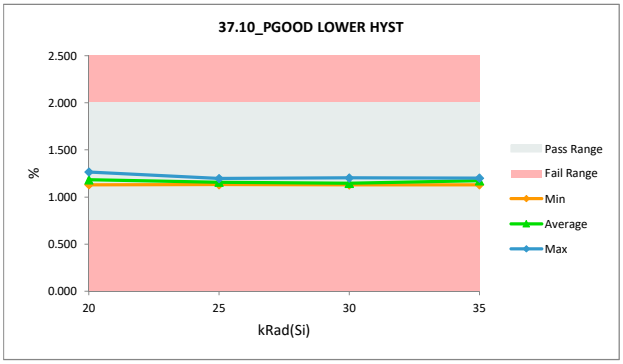
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.10_PGOOD LOWER HYST	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	2	2
Min Limit	0.75	0.75

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	1.129	1.198	0.069
20	62	1.263	1.200	-0.063
20	63	1.197	1.198	0.001
20	64	1.199	1.135	-0.064
20	65	1.196	1.197	0.001
20	67	1.195	1.131	-0.064
20	68	1.196	1.131	-0.065
20	69	1.196	1.197	0.001
20	70	1.198	1.199	0.001
20	71	1.196	1.199	0.003
20	72	1.197	1.199	0.002
20	73	1.198	1.199	0.001
20	74	1.199	1.203	0.004
20	75	1.195	1.131	-0.064
20	76	1.130	1.132	0.002
20	77	1.130	1.199	0.069
20	78	1.196	1.131	-0.065
20	79	1.263	1.267	0.004
20	80	1.196	1.131	-0.065
20	81	1.194	1.196	0.002
20	82	1.131	1.200	0.069
20	83	1.262	1.264	0.002
25	84	1.130	1.197	0.067
25	85	1.129	1.132	0.003
25	86	1.132	1.133	0.001
25	87	1.195	1.197	0.002
25	88	1.196	1.132	-0.064
30	89	1.195	1.132	-0.063
30	90	1.198	1.203	0.005
30	91	1.197	1.133	-0.064
30	92	1.131	1.136	0.005
30	93	1.129	1.130	0.001
35	94	1.199	1.202	0.003
35	95	1.196	1.131	-0.065
35	96	1.195	1.196	0.001
35	97	1.131	1.133	0.002
35	98	1.130	1.199	0.069
Max		1.263	1.267	0.069
Average		1.182	1.174	-0.009
Min		1.129	1.130	-0.065
Std Dev		0.039	0.040	0.043



	37.10_PGOOD LOWER HYST			
Test Site				
Tester				
Test Number				
Max Limit	2	%		
Min Limit	0.75	%		
kRad(Si)	20	25	30	35
LL	0.750	0.750	0.750	0.750
Min	1.131	1.132	1.130	1.131
Average	1.184	1.158	1.147	1.172
Max	1.267	1.197	1.203	1.202
UL	2.000	2.000	2.000	2.000

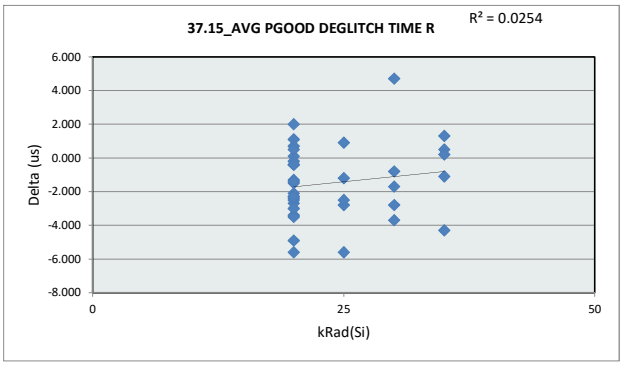


HDR TID Report
TPS7H4010-SEP

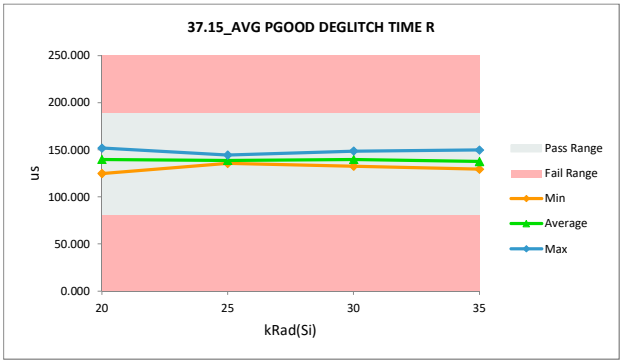
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.15_AVG PGOOD DEGLITCH TI	
Test Site		
Tester		
Test Number		
Unit	us	us
Max Limit	188	188
Min Limit	80	80

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	137.200	134.500	-2.700
20	62	148.400	148.500	0.100
20	63	141.400	141.000	-0.400
20	64	145.400	146.500	1.100
20	65	142.400	140.300	-2.100
20	67	141.100	140.900	-0.200
20	68	137.000	134.700	-2.300
20	69	138.100	134.700	-3.400
20	70	138.700	140.700	2.000
20	71	127.300	124.800	-2.500
20	72	154.200	151.800	-2.400
20	73	139.900	139.500	-0.400
20	74	142.900	141.600	-1.300
20	75	144.300	142.000	-2.300
20	76	144.300	142.800	-1.500
20	77	143.400	139.900	-3.500
20	78	142.800	139.800	-3.000
20	79	143.000	137.400	-5.600
20	80	136.100	134.700	-1.400
20	81	147.200	142.300	-4.900
20	82	141.600	142.300	0.700
20	83	130.600	131.100	0.500
25	84	138.500	135.700	-2.800
25	85	145.700	144.500	-1.200
25	86	143.600	141.100	-2.500
25	87	134.500	135.400	0.900
25	88	142.700	137.100	-5.600
30	89	138.900	138.100	-0.800
30	90	136.900	134.100	-2.800
30	91	143.900	148.600	4.700
30	92	134.200	132.500	-1.700
30	93	148.600	144.900	-3.700
35	94	134.900	136.200	1.300
35	95	133.900	134.400	0.500
35	96	149.500	149.700	0.200
35	97	130.400	129.300	-1.100
35	98	142.400	138.100	-4.300
	Max	154.200	151.800	4.700
	Average	140.700	139.230	-1.470
	Min	127.300	124.800	-5.600
	Std Dev	5.719	5.800	2.181



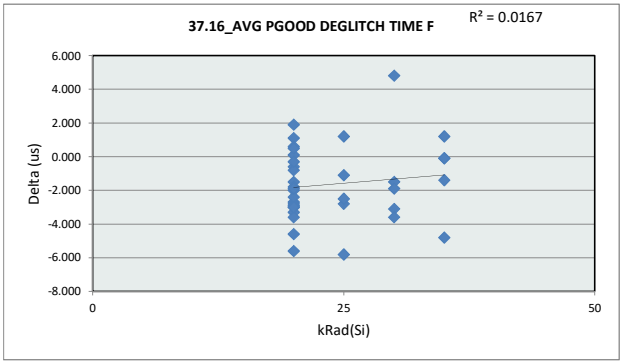
	37.15_AVG PGOOD DEGLITCH			
Test Site				
Tester				
Test Number				
Max Limit	188	us		
Min Limit	80	us		
kRad(Si)	20	25	30	35
LL	80.000	80.000	80.000	80.000
Min	124.800	135.400	132.500	129.300
Average	139.627	138.760	139.640	137.540
Max	151.800	144.500	148.600	149.700
UL	188.000	188.000	188.000	188.000



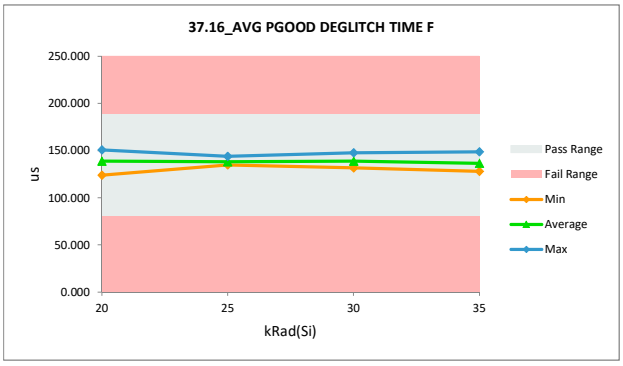
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.16_AVG PGOOD DEGLITCH TI		
Test Site			
Tester			
Test Number			
Unit	us	us	
Max Limit	188	188	
Min Limit	80	80	
kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	136.500	133.800	-2.700
20	62	147.500	147.600	0.100
20	63	140.600	140.000	-0.600
20	64	144.600	145.700	1.100
20	65	141.500	139.500	-2.000
20	67	140.700	139.900	-0.800
20	68	136.100	133.300	-2.800
20	69	137.300	134.000	-3.300
20	70	137.900	139.800	1.900
20	71	126.900	124.000	-2.900
20	72	153.800	150.800	-3.000
20	73	139.200	138.900	-0.300
20	74	142.500	141.000	-1.500
20	75	143.600	141.200	-2.400
20	76	143.500	141.700	-1.800
20	77	142.700	139.100	-3.600
20	78	142.000	139.000	-3.000
20	79	142.200	136.600	-5.600
20	80	135.800	133.900	-1.900
20	81	146.000	141.400	-4.600
20	82	140.900	141.500	0.600
20	83	129.800	130.300	0.500
25	84	137.700	134.900	-2.800
25	85	144.900	143.800	-1.100
25	86	142.900	140.400	-2.500
25	87	134.000	135.200	1.200
25	88	142.000	136.200	-5.800
30	89	138.000	136.500	-1.500
30	90	136.400	133.300	-3.100
30	91	143.000	147.800	4.800
30	92	133.600	131.700	-1.900
30	93	148.200	144.600	-3.600
35	94	134.300	135.500	1.200
35	95	133.100	133.000	-0.100
35	96	148.900	148.800	-0.100
35	97	129.500	128.100	-1.400
35	98	141.900	137.100	-4.800
	Max	153.800	150.800	4.800
	Average	140.000	138.376	-1.624
	Min	126.900	124.000	-5.800
	Std Dev	5.709	5.829	2.198



	37.16_AVG PGOOD DEGLITCH T			
Test Site				
Tester				
Test Number				
Max Limit	188	us		
Min Limit	80	us		
kRad(Si)	20	25	30	35
LL	80.000	80.000	80.000	80.000
Min	124.000	134.900	131.700	128.100
Average	138.773	138.100	138.780	136.500
Max	150.800	143.800	147.800	148.800
UL	188.000	188.000	188.000	188.000



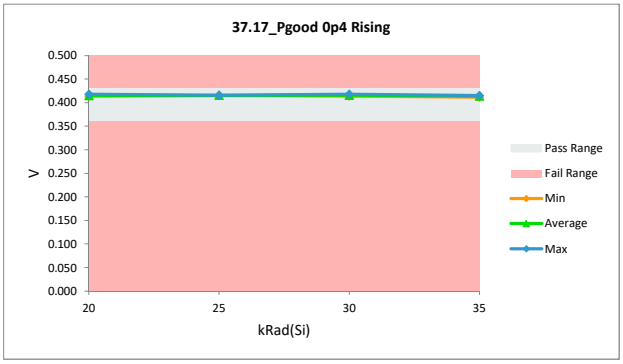
HDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.17_Pgood 0p4 Rising	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.43	0.43
Min Limit	0.36	0.36

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.416	0.414	-0.002
20	62	0.416	0.416	0.000
20	63	0.416	0.415	-0.001
20	64	0.414	0.414	0.000
20	65	0.414	0.415	0.001
20	67	0.416	0.416	0.000
20	68	0.415	0.414	-0.001
20	69	0.414	0.414	0.000
20	70	0.416	0.416	0.000
20	71	0.415	0.414	-0.001
20	72	0.416	0.416	0.000
20	73	0.416	0.416	0.000
20	74	0.416	0.414	-0.002
20	75	0.415	0.415	0.000
20	76	0.416	0.416	0.000
20	77	0.417	0.416	-0.001
20	78	0.414	0.414	0.000
20	79	0.416	0.415	-0.001
20	80	0.414	0.414	0.000
20	81	0.418	0.418	0.000
20	82	0.415	0.414	-0.001
20	83	0.418	0.418	0.000
25	84	0.416	0.415	-0.001
25	85	0.417	0.416	-0.001
25	86	0.417	0.416	-0.001
25	87	0.416	0.415	-0.001
25	88	0.416	0.415	-0.001
30	89	0.418	0.418	0.000
30	90	0.417	0.416	-0.001
30	91	0.414	0.414	0.000
30	92	0.416	0.415	-0.001
30	93	0.414	0.415	0.001
35	94	0.415	0.415	0.000
35	95	0.416	0.415	-0.001
35	96	0.412	0.412	0.000
35	97	0.416	0.414	-0.002
35	98	0.414	0.413	-0.001
Max		0.418	0.418	0.001
Average		0.416	0.415	-0.001
Min		0.412	0.412	-0.002
Std Dev		0.001	0.001	0.001

	37.17_Pgood 0p4 Rising			
Test Site				
Tester				
Test Number				
Max Limit	0.43	V		
Min Limit	0.36	V		
kRad(Si)	20	25	30	35
LL	0.360	0.360	0.360	0.360
Min	0.414	0.415	0.414	0.412
Average	0.415	0.415	0.416	0.414
Max	0.418	0.416	0.418	0.415
UL	0.430	0.430	0.430	0.430

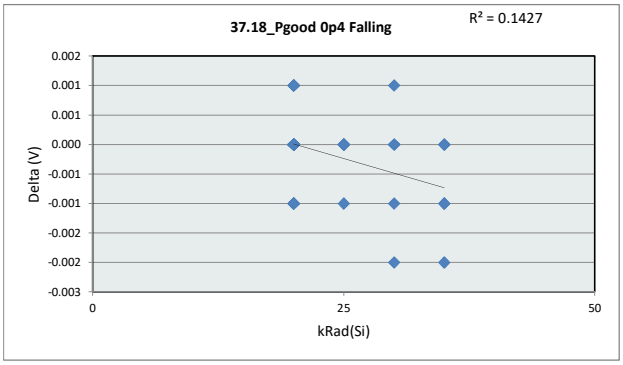


HDR TID Report
TPS7H4010-SEP

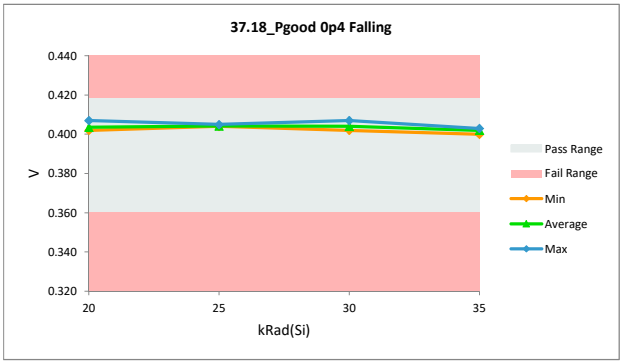
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.18_Pgood 0p4 Falling	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.418	0.418
Min Limit	0.36	0.36

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	0.404	0.403	-0.001
20	62	0.404	0.404	0.000
20	63	0.404	0.404	0.000
20	64	0.402	0.402	0.000
20	65	0.402	0.403	0.001
20	67	0.404	0.404	0.000
20	68	0.403	0.403	0.000
20	69	0.402	0.403	0.001
20	70	0.404	0.404	0.000
20	71	0.403	0.402	-0.001
20	72	0.404	0.404	0.000
20	73	0.404	0.404	0.000
20	74	0.404	0.403	-0.001
20	75	0.403	0.403	0.000
20	76	0.404	0.404	0.000
20	77	0.405	0.404	-0.001
20	78	0.402	0.402	0.000
20	79	0.402	0.403	0.001
20	80	0.402	0.402	0.000
20	81	0.406	0.406	0.000
20	82	0.403	0.403	0.000
20	83	0.406	0.407	0.001
25	84	0.404	0.404	0.000
25	85	0.405	0.404	-0.001
25	86	0.405	0.405	0.000
25	87	0.404	0.404	0.000
25	88	0.404	0.404	0.000
30	89	0.406	0.407	0.001
30	90	0.406	0.404	-0.002
30	91	0.402	0.402	0.000
30	92	0.404	0.403	-0.001
30	93	0.404	0.404	0.000
35	94	0.404	0.403	-0.001
35	95	0.403	0.403	0.000
35	96	0.401	0.400	-0.001
35	97	0.404	0.402	-0.002
35	98	0.402	0.402	0.000
Max		0.406	0.407	0.001
Average		0.404	0.403	0.000
Min		0.401	0.400	-0.002
Std Dev		0.001	0.001	0.001



	37.18_Pgood 0p4 Falling			
Test Site				
Tester				
Test Number				
Max Limit	0.418	V		
Min Limit	0.36	V		
kRad(Si)	20	25	30	35
LL	0.360	0.360	0.360	0.360
Min	0.402	0.404	0.402	0.400
Average	0.404	0.404	0.404	0.402
Max	0.407	0.405	0.407	0.403
UL	0.418	0.418	0.418	0.418

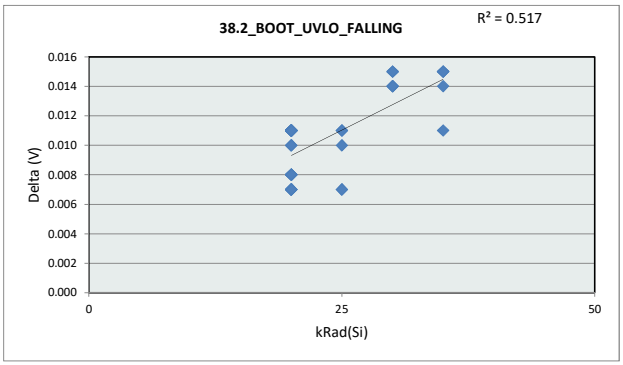


HDR TID Report
TPS7H4010-SEP

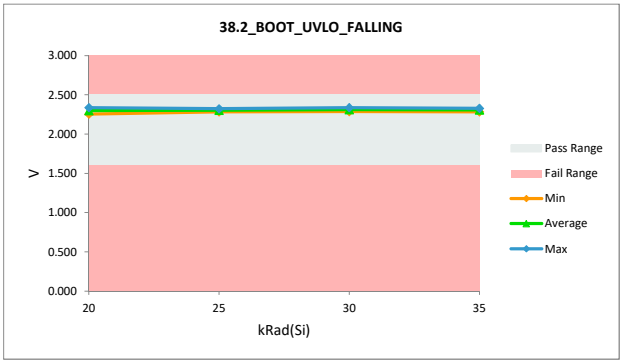
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	38.2_BOOT_UVLO_FALLING	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.5	2.5
Min Limit	1.6	1.6

kRad(Si)	Serial #	Pre_HDR	Post_HDR	Delta
20	61	2.308	2.315	0.007
20	62	2.276	2.286	0.010
20	63	2.261	2.272	0.011
20	64	2.326	2.337	0.011
20	65	2.261	2.272	0.011
20	67	2.286	2.297	0.011
20	68	2.286	2.294	0.008
20	69	2.286	2.294	0.008
20	70	2.283	2.294	0.011
20	71	2.301	2.312	0.011
20	72	2.304	2.312	0.008
20	73	2.283	2.294	0.011
20	74	2.301	2.312	0.011
20	75	2.297	2.308	0.011
20	76	2.286	2.297	0.011
20	77	2.272	2.283	0.011
20	78	2.319	2.326	0.007
20	79	2.247	2.254	0.007
20	80	2.286	2.294	0.008
20	81	2.279	2.286	0.007
20	82	2.294	2.304	0.010
20	83	2.301	2.308	0.007
25	84	2.301	2.308	0.007
25	85	2.297	2.308	0.011
25	86	2.283	2.294	0.011
25	87	2.276	2.283	0.007
25	88	2.312	2.322	0.010
30	89	2.279	2.294	0.015
30	90	2.312	2.326	0.014
30	91	2.272	2.286	0.014
30	92	2.322	2.337	0.015
30	93	2.290	2.304	0.014
35	94	2.286	2.301	0.015
35	95	2.272	2.283	0.011
35	96	2.304	2.319	0.015
35	97	2.297	2.312	0.015
35	98	2.312	2.326	0.014
Max		2.326	2.337	0.015
Average		2.291	2.301	0.011
Min		2.247	2.254	0.007
Std Dev		0.018	0.018	0.003



	38.2_BOOT_UVLO_FALLING			
Test Site				
Tester				
Test Number				
Max Limit	2.5	V		
Min Limit	1.6	V		
kRad(Si)	20	25	30	35
LL	1.600	1.600	1.600	1.600
Min	2.254	2.283	2.286	2.283
Average	2.298	2.303	2.309	2.308
Max	2.337	2.322	2.337	2.326
UL	2.500	2.500	2.500	2.500



B Appendix B: LDR TID Report

This appendix contains the LDR TID report data.

LDR TID Report
TPS7H4010-SEP

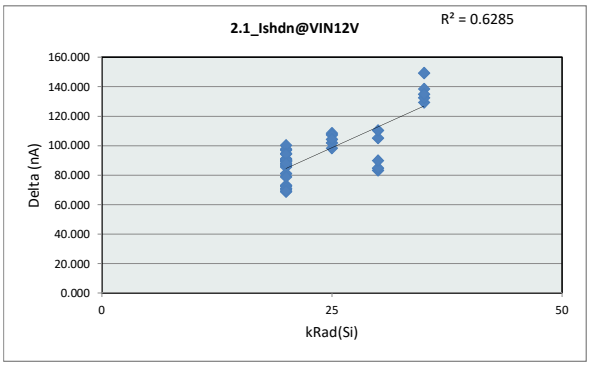
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

LDR TID Report
TPS7H4010-SEP

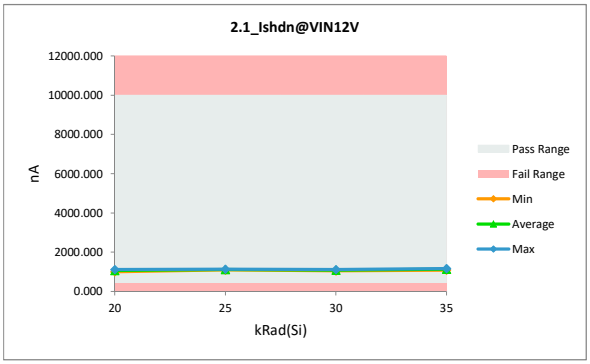
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.1_Ishdn@VIN12V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	10000	10000
Min Limit	400	400

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1027.910	1126.230	98.320
25	2	1003.270	1111.820	108.550
25	3	985.800	1093.120	107.320
25	4	1034.930	1136.770	101.840
25	5	1006.480	1110.900	104.420
20	6	1003.050	1071.810	68.760
20	7	949.290	1040.500	91.210
20	8	1019.860	1090.540	70.680
20	9	973.650	1064.070	90.420
20	10	987.750	1077.320	89.570
20	11	1000.850	1095.510	94.660
20	12	910.040	997.000	86.960
20	13	994.390	1084.280	89.890
20	14	946.900	1044.050	97.150
20	15	1025.650	1098.790	73.140
20	16	976.580	1062.180	85.600
20	17	1003.620	1092.930	89.310
20	18	1021.430	1094.030	72.600
20	19	1005.090	1076.060	70.970
20	20	1020.640	1089.880	69.240
20	21	986.370	1067.470	81.100
20	22	994.580	1092.270	97.690
20	23	932.610	1032.880	100.270
20	24	970.160	1060.450	90.290
20	25	989.670	1084.150	94.480
20	26	958.290	1046.260	87.970
20	27	1043.710	1122.710	79.000
35	28	1009.470	1138.850	129.380
35	29	980.200	1112.730	132.530
35	30	942.210	1091.550	149.340
35	31	986.810	1125.290	138.480
35	32	1032.480	1167.490	135.010
30	33	1013.060	1096.330	83.270
30	34	1009.750	1094.570	84.820
30	35	938.430	1043.580	105.150
30	36	1005.940	1116.320	110.380
30	37	1007.770	1097.650	89.880
	Max	1043.710	1167.490	149.340
	Average	991.856	1087.793	95.936
	Min	910.040	997.000	68.760
	Std Dev	31.314	33.557	20.020



	2.1_Ishdn@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	10000	nA		
Min Limit	400	nA		
kRad(Si)	20	25	30	35
LL	400.000	400.000	400.000	400.000
Min	997.000	1093.120	1043.580	1091.550
Average	1072.052	1115.768	1089.690	1127.182
Max	1122.710	1136.770	1116.320	1167.490
UL	10000.000	10000.000	10000.000	10000.000

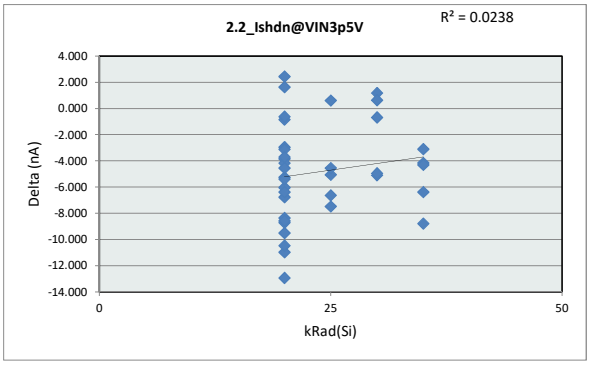


LDR TID Report
TPS7H4010-SEP

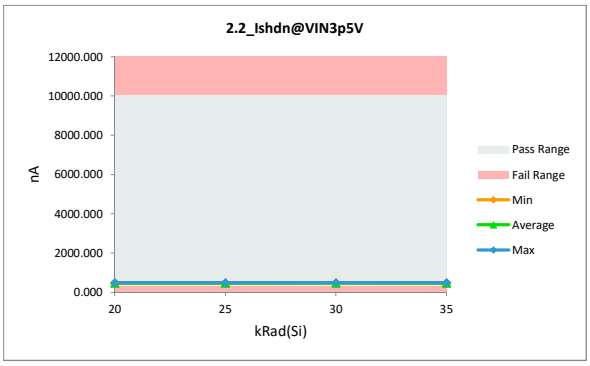
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.2_Ishdn@VIN3p5V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	10000	10000
Min Limit	295	295

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	471.270	464.630	-6.640
25	2	478.610	473.540	-5.070
25	3	483.520	484.120	0.600
25	4	473.380	465.890	-7.490
25	5	474.920	470.360	-4.560
20	6	480.900	467.970	-12.930
20	7	470.270	466.430	-3.840
20	8	474.920	468.880	-6.040
20	9	480.620	479.770	-0.850
20	10	484.050	475.680	-8.370
20	11	486.850	482.670	-4.180
20	12	457.300	456.670	-0.630
20	13	484.680	477.910	-6.770
20	14	484.180	481.220	-2.960
20	15	478.800	469.290	-9.510
20	16	487.100	476.120	-10.980
20	17	489.780	484.520	-5.260
20	18	476.060	465.580	-10.480
20	19	473.100	468.540	-4.560
20	20	480.590	477.470	-3.120
20	21	474.520	465.800	-8.720
20	22	480.970	482.600	1.630
20	23	488.180	482.790	-5.390
20	24	478.950	481.380	2.430
20	25	488.430	482.040	-6.390
20	26	484.680	480.970	-3.710
20	27	478.320	469.730	-8.590
35	28	471.530	462.740	-8.790
35	29	486.730	482.570	-4.160
35	30	485.590	481.280	-4.310
35	31	483.640	480.530	-3.110
35	32	477.410	471.020	-6.390
30	33	480.090	474.990	-5.100
30	34	478.800	473.850	-4.950
30	35	475.740	475.050	-0.690
30	36	483.640	484.810	1.170
30	37	473.070	473.700	0.630
	Max	489.780	484.810	2.430
	Average	479.492	474.679	-4.813
	Min	457.300	456.670	-12.930
	Std Dev	6.551	7.321	3.686



	2.2_Ishdn@VIN3p5V			
Test Site				
Tester				
Test Number				
Max Limit	10000	nA		
Min Limit	295	nA		
kRad(Si)	20	25	30	35
LL	295.000	295.000	295.000	295.000
Min	456.670	464.630	473.700	462.740
Average	474.729	471.708	476.480	475.628
Max	484.520	484.120	484.810	482.570
UL	10000.000	10000.000	10000.000	10000.000

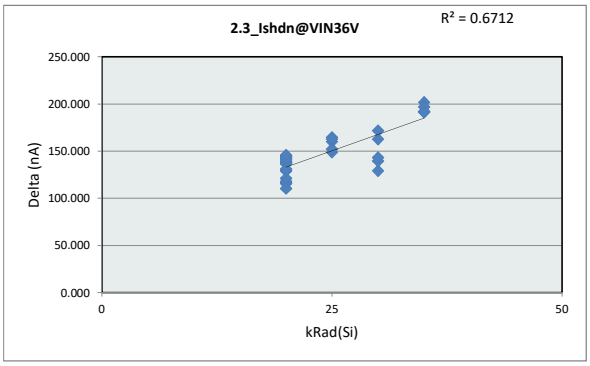


LDR TID Report
TPS7H4010-SEP

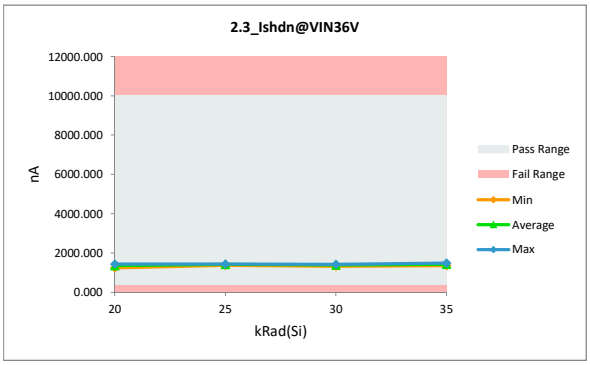
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.3_Ishdn@VIN36V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	10000	10000
Min Limit	345	345

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1282.220	1431.050	148.830
25	2	1250.780	1415.310	164.530
25	3	1215.340	1375.470	160.130
25	4	1278.190	1430.360	152.170
25	5	1248.860	1411.530	162.670
20	6	1247.380	1363.220	115.840
20	7	1162.120	1299.990	137.870
20	8	1263.710	1379.340	115.630
20	9	1211.840	1353.340	141.500
20	10	1219.590	1358.220	138.630
20	11	1247.500	1386.070	138.570
20	12	1114.970	1243.810	128.840
20	13	1228.020	1371.120	143.100
20	14	1166.020	1311.230	145.210
20	15	1274.980	1392.240	117.260
20	16	1208.190	1345.000	136.810
20	17	1247.350	1386.260	138.910
20	18	1270.350	1380.850	110.500
20	19	1247.970	1365.770	117.800
20	20	1264.720	1385.850	121.130
20	21	1204.450	1341.190	136.740
20	22	1236.680	1377.420	140.740
20	23	1145.910	1290.390	144.480
20	24	1188.180	1331.910	143.730
20	25	1222.950	1365.360	142.410
20	26	1174.330	1320.140	145.810
20	27	1303.490	1434.480	130.990
35	28	1254.430	1446.440	192.010
35	29	1214.830	1406.590	191.760
35	30	1156.320	1358.000	201.680
35	31	1225.090	1421.920	196.830
35	32	1292.350	1483.480	191.130
30	33	1261.000	1390.200	129.200
30	34	1251.120	1390.640	139.520
30	35	1151.320	1314.000	162.680
30	36	1247.720	1419.280	171.560
30	37	1256.540	1399.790	143.250
Max		1303.490	1483.480	201.680
Average		1228.022	1375.061	147.039
Min		1114.970	1243.810	110.500
Std Dev		44.979	47.904	23.774



	2.3_Ishdn@VIN36V			
Test Site				
Tester				
Test Number				
Max Limit	10000	nA		
Min Limit	345	nA		
kRad(Si)	20	25	30	35
LL	345.000	345.000	345.000	345.000
Min	1243.810	1375.470	1314.000	1358.000
Average	1353.782	1412.744	1382.782	1423.286
Max	1434.480	1431.050	1419.280	1483.480
UL	10000.000	10000.000	10000.000	10000.000

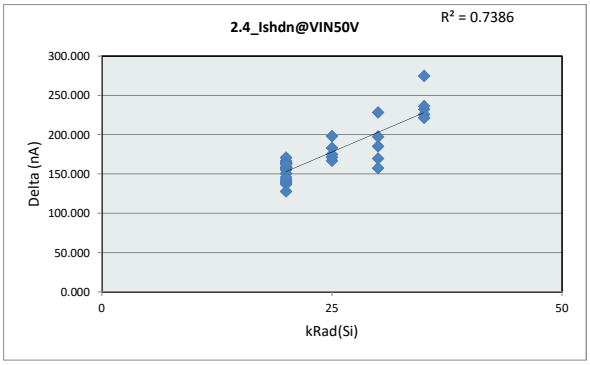


LDR TID Report
TPS7H4010-SEP

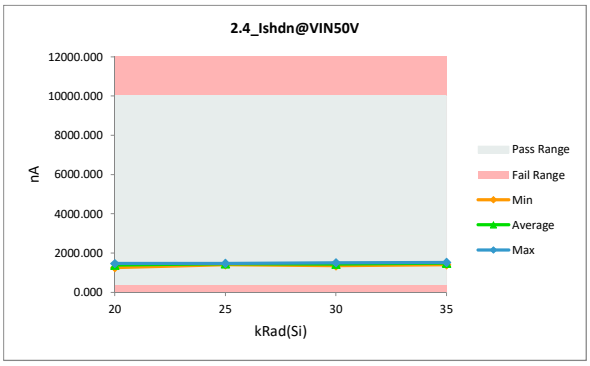
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	2.4_Ishdn@VIN50V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	10000	10000
Min Limit	345	345

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1296.190	1467.600	171.410
25	2	1271.040	1469.170	198.130
25	3	1230.020	1404.960	174.940
25	4	1292.520	1459.460	166.940
25	5	1265.260	1448.400	183.140
20	6	1269.920	1428.180	158.260
20	7	1176.520	1332.070	155.550
20	8	1282.190	1420.590	138.400
20	9	1223.830	1388.350	164.520
20	10	1235.820	1394.070	158.250
20	11	1257.660	1424.320	166.660
20	12	1124.080	1261.070	136.990
20	13	1241.380	1404.520	163.140
20	14	1184.460	1349.040	164.580
20	15	1293.610	1434.310	140.700
20	16	1221.860	1379.660	157.800
20	17	1258.100	1421.330	163.230
20	18	1279.530	1407.470	127.940
20	19	1261.170	1401.130	139.960
20	20	1277.830	1420.820	142.990
20	21	1218.250	1368.880	150.630
20	22	1248.780	1410.950	162.170
20	23	1164.150	1334.950	170.800
20	24	1205.640	1363.970	158.330
20	25	1236.870	1400.590	163.720
20	26	1190.280	1352.800	162.520
20	27	1320.790	1466.540	145.750
35	28	1267.860	1499.870	232.010
35	29	1234.410	1508.890	274.480
35	30	1166.450	1402.750	236.300
35	31	1240.680	1466.450	225.770
35	32	1300.420	1521.890	221.470
30	33	1273.600	1430.920	157.320
30	34	1277.030	1505.280	228.250
30	35	1161.830	1347.140	185.310
30	36	1264.110	1461.460	197.350
30	37	1271.160	1440.700	169.540
	Max	1320.790	1521.890	274.480
	Average	1242.846	1416.231	173.385
	Min	1124.080	1261.070	127.940
	Std Dev	45.532	55.581	32.673



	2.4_Ishdn@VIN50V			
Test Site				
Tester				
Test Number				
Max Limit	10000	nA		
Min Limit	345	nA		
kRad(Si)	20	25	30	35
LL	345.000	345.000	345.000	345.000
Min	1261.070	1404.960	1347.140	1402.750
Average	1389.346	1449.918	1437.100	1479.970
Max	1466.540	1469.170	1505.280	1521.890
UL	10000.000	10000.000	10000.000	10000.000

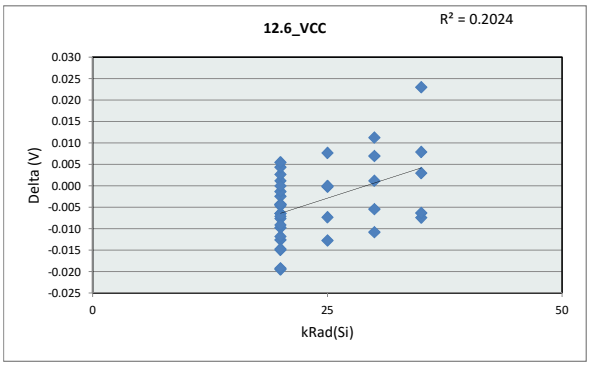


LDR TID Report
TPS7H4010-SEP

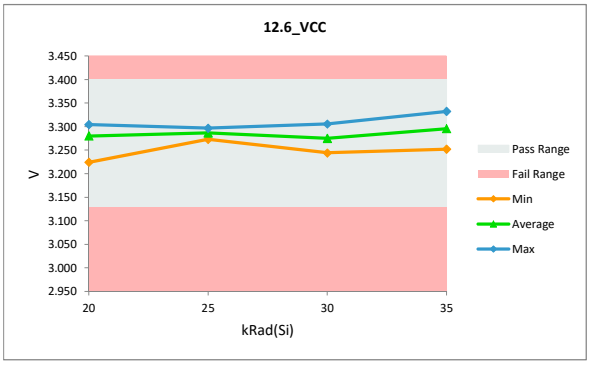
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	12.6_VCC	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.4	3.4
Min Limit	3.13	3.13

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.274	3.282	0.008
25	2	3.286	3.273	-0.013
25	3	3.304	3.297	-0.007
25	4	3.295	3.295	0.000
25	5	3.287	3.287	0.000
20	6	3.274	3.270	-0.004
20	7	3.308	3.301	-0.006
20	8	3.295	3.296	0.001
20	9	3.303	3.288	-0.015
20	10	3.280	3.278	-0.002
20	11	3.237	3.224	-0.013
20	12	3.257	3.256	-0.001
20	13	3.286	3.274	-0.012
20	14	3.288	3.282	-0.006
20	15	3.272	3.262	-0.010
20	16	3.293	3.296	0.003
20	17	3.295	3.276	-0.020
20	18	3.298	3.298	0.000
20	19	3.297	3.290	-0.008
20	20	3.307	3.292	-0.015
20	21	3.309	3.304	-0.005
20	22	3.280	3.284	0.004
20	23	3.278	3.274	-0.004
20	24	3.285	3.278	-0.007
20	25	3.276	3.282	0.005
20	26	3.284	3.275	-0.009
20	27	3.303	3.283	-0.019
35	28	3.309	3.332	0.023
35	29	3.296	3.304	0.008
35	30	3.280	3.272	-0.007
35	31	3.259	3.252	-0.006
35	32	3.315	3.318	0.003
30	33	3.299	3.306	0.007
30	34	3.272	3.283	0.011
30	35	3.255	3.244	-0.011
30	36	3.257	3.258	0.001
30	37	3.288	3.283	-0.005
	Max	3.315	3.332	0.023
	Average	3.286	3.282	-0.004
	Min	3.237	3.224	-0.020
	Std Dev	0.018	0.020	0.009



	12.6_VCC			
Test Site				
Tester				
Test Number				
Max Limit	3.4	V		
Min Limit	3.13	V		
kRad(Si)	20	25	30	35
LL	3.130	3.130	3.130	3.130
Min	3.224	3.273	3.244	3.252
Average	3.280	3.287	3.275	3.296
Max	3.304	3.297	3.306	3.332
UL	3.400	3.400	3.400	3.400

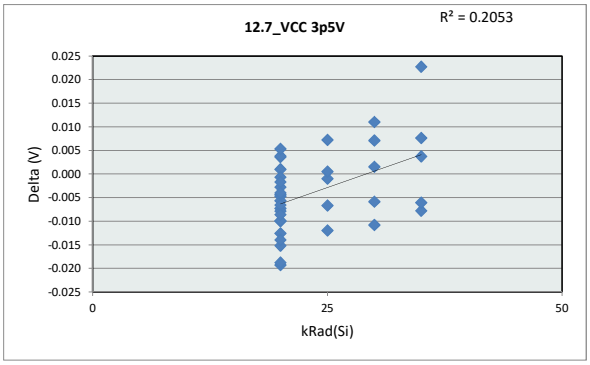


LDR TID Report
TPS7H4010-SEP

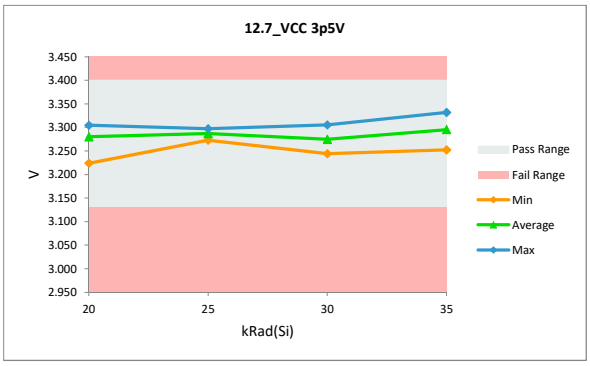
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	12.7_VCC 3p5V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.4	3.4
Min Limit	3.13	3.13

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.274	3.282	0.007
25	2	3.285	3.273	-0.012
25	3	3.304	3.297	-0.007
25	4	3.296	3.295	-0.001
25	5	3.287	3.288	0.000
20	6	3.275	3.270	-0.005
20	7	3.308	3.301	-0.007
20	8	3.295	3.296	0.001
20	9	3.303	3.288	-0.015
20	10	3.280	3.277	-0.003
20	11	3.237	3.224	-0.013
20	12	3.256	3.255	-0.001
20	13	3.286	3.276	-0.010
20	14	3.288	3.282	-0.006
20	15	3.272	3.262	-0.010
20	16	3.293	3.296	0.004
20	17	3.295	3.276	-0.019
20	18	3.300	3.298	-0.002
20	19	3.297	3.289	-0.008
20	20	3.306	3.292	-0.014
20	21	3.309	3.305	-0.004
20	22	3.280	3.283	0.004
20	23	3.278	3.274	-0.004
20	24	3.284	3.278	-0.007
20	25	3.276	3.282	0.005
20	26	3.283	3.274	-0.009
20	27	3.302	3.283	-0.019
35	28	3.309	3.332	0.023
35	29	3.296	3.303	0.008
35	30	3.280	3.272	-0.008
35	31	3.258	3.252	-0.006
35	32	3.314	3.318	0.004
30	33	3.298	3.305	0.007
30	34	3.272	3.283	0.011
30	35	3.255	3.244	-0.011
30	36	3.257	3.258	0.001
30	37	3.289	3.283	-0.006
Max		3.314	3.332	0.023
Average		3.286	3.282	-0.004
Min		3.237	3.224	-0.019
Std Dev		0.018	0.020	0.009



	12.7_VCC 3p5V			
Test Site				
Tester				
Test Number				
Max Limit	3.4	V		
Min Limit	3.13	V		
kRad(Si)	20	25	30	35
LL	3.130	3.130	3.130	3.130
Min	3.224	3.273	3.244	3.252
Average	3.280	3.287	3.275	3.295
Max	3.305	3.297	3.305	3.332
UL	3.400	3.400	3.400	3.400

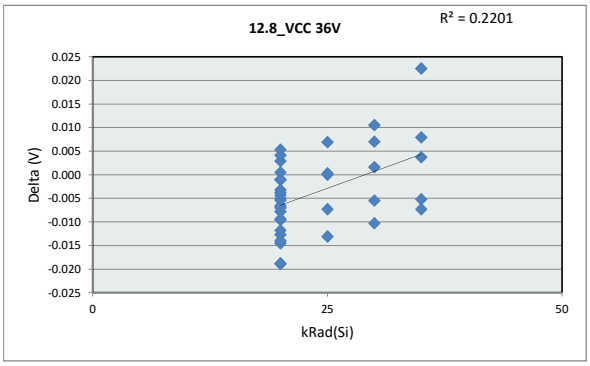


LDR TID Report
TPS7H4010-SEP

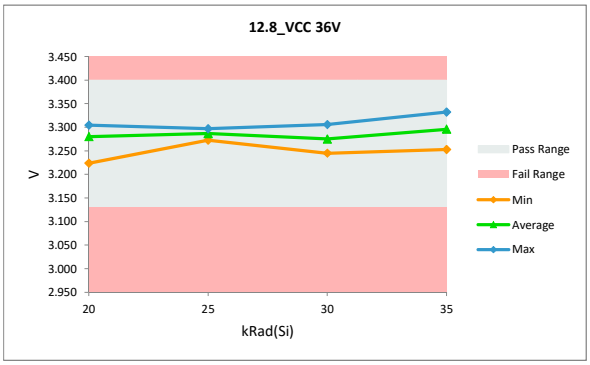
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	12.8_VCC 36V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.4	3.4
Min Limit	3.13	3.13

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.275	3.282	0.007
25	2	3.286	3.273	-0.013
25	3	3.304	3.297	-0.007
25	4	3.295	3.295	0.000
25	5	3.287	3.288	0.000
20	6	3.275	3.270	-0.005
20	7	3.308	3.301	-0.007
20	8	3.295	3.295	0.000
20	9	3.303	3.288	-0.015
20	10	3.281	3.277	-0.003
20	11	3.237	3.224	-0.013
20	12	3.256	3.255	-0.001
20	13	3.286	3.274	-0.012
20	14	3.288	3.283	-0.005
20	15	3.272	3.262	-0.010
20	16	3.293	3.296	0.003
20	17	3.295	3.276	-0.019
20	18	3.300	3.299	-0.001
20	19	3.298	3.290	-0.008
20	20	3.307	3.293	-0.014
20	21	3.309	3.305	-0.004
20	22	3.280	3.284	0.004
20	23	3.278	3.274	-0.004
20	24	3.285	3.279	-0.007
20	25	3.276	3.281	0.005
20	26	3.283	3.274	-0.009
20	27	3.302	3.284	-0.019
35	28	3.310	3.332	0.022
35	29	3.296	3.303	0.008
35	30	3.280	3.273	-0.007
35	31	3.258	3.253	-0.005
35	32	3.314	3.318	0.004
30	33	3.299	3.306	0.007
30	34	3.272	3.283	0.011
30	35	3.255	3.245	-0.010
30	36	3.257	3.259	0.002
30	37	3.289	3.283	-0.006
	Max	3.314	3.332	0.022
	Average	3.286	3.282	-0.004
	Min	3.237	3.224	-0.019
	Std Dev	0.018	0.020	0.009



	12.8_VCC 36V			
Test Site				
Tester				
Test Number				
Max Limit	3.4	V		
Min Limit	3.13	V		
kRad(Si)	20	25	30	35
LL	3.130	3.130	3.130	3.130
Min	3.224	3.273	3.245	3.253
Average	3.280	3.287	3.275	3.296
Max	3.305	3.297	3.306	3.332
UL	3.400	3.400	3.400	3.400

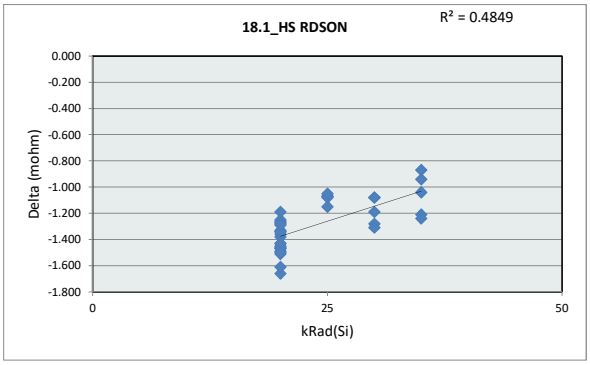


LDR TID Report
TPS7H4010-SEP

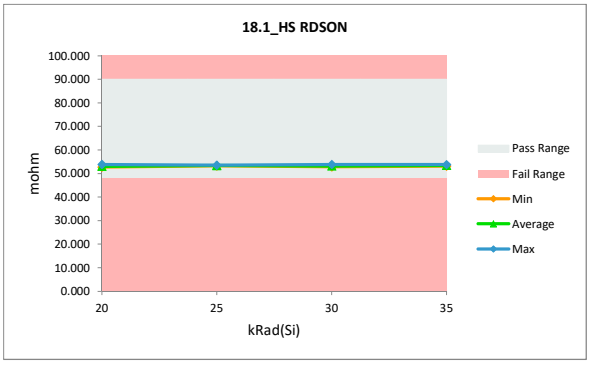
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	18.1_HS RDSON	
Test Site		
Tester		
Test Number		
Unit	mohm	mohm
Max Limit	90	90
Min Limit	48	48

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	54.530	53.460	-1.070
25	2	54.330	53.260	-1.070
25	3	54.400	53.250	-1.150
25	4	54.620	53.540	-1.080
25	5	54.260	53.210	-1.050
20	6	54.480	52.990	-1.490
20	7	55.320	53.660	-1.660
20	8	54.290	52.910	-1.380
20	9	54.130	52.680	-1.450
20	10	54.200	52.770	-1.430
20	11	54.320	52.710	-1.610
20	12	55.200	53.730	-1.470
20	13	54.240	52.780	-1.460
20	14	54.530	53.060	-1.470
20	15	54.280	52.950	-1.330
20	16	54.230	52.800	-1.430
20	17	54.190	52.680	-1.510
20	18	54.670	53.330	-1.340
20	19	54.230	52.970	-1.260
20	20	54.240	52.960	-1.280
20	21	55.350	53.850	-1.500
20	22	54.430	53.070	-1.360
20	23	54.850	53.510	-1.340
20	24	54.010	52.760	-1.250
20	25	54.130	52.860	-1.270
20	26	54.470	53.180	-1.290
20	27	54.340	53.150	-1.190
35	28	54.230	53.190	-1.040
35	29	54.590	53.380	-1.210
35	30	54.840	53.600	-1.240
35	31	54.050	53.110	-0.940
35	32	54.650	53.780	-0.870
30	33	54.140	53.060	-1.080
30	34	54.280	53.000	-1.280
30	35	55.180	53.870	-1.310
30	36	54.020	52.830	-1.190
30	37	54.130	53.050	-1.080
	Max	55.350	53.870	-0.870
	Average	54.443	53.161	-1.282
	Min	54.010	52.680	-1.660
	Std Dev	0.357	0.346	0.186



	18.1_HS RDSON			
Test Site				
Tester				
Test Number				
Max Limit	90	mohm		
Min Limit	48	mohm		
kRad(Si)	20	25	30	35
LL	48.000	48.000	48.000	48.000
Min	52.680	53.210	52.830	53.110
Average	53.062	53.344	53.162	53.412
Max	53.850	53.540	53.870	53.780
UL	90.000	90.000	90.000	90.000

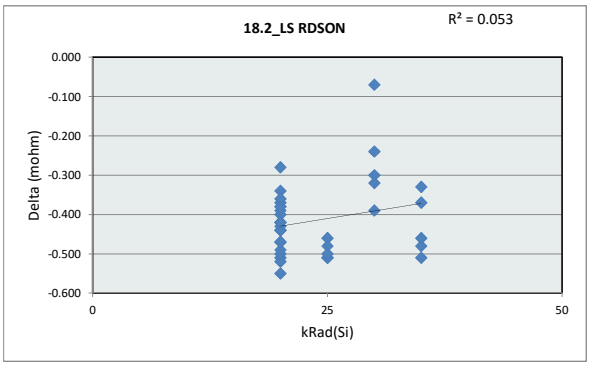


LDR TID Report
TPS7H4010-SEP

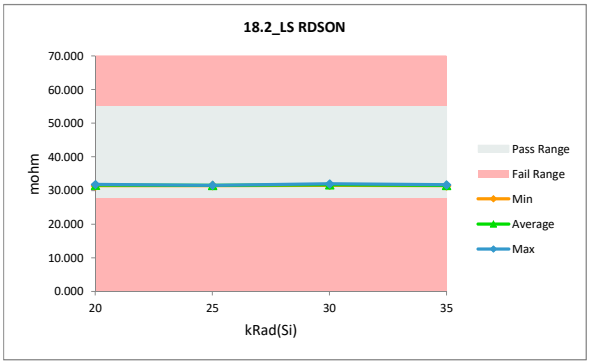
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	18.2_LS RDSON	
Test Site		
Tester		
Test Number		
Unit	mohm	mohm
Max Limit	55	55
Min Limit	27.8	27.8

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	32.050	31.540	-0.510
25	2	31.980	31.520	-0.460
25	3	32.010	31.500	-0.510
25	4	32.040	31.560	-0.480
25	5	31.960	31.460	-0.500
20	6	32.030	31.520	-0.510
20	7	32.280	31.730	-0.550
20	8	31.900	31.480	-0.420
20	9	31.830	31.400	-0.430
20	10	31.990	31.550	-0.440
20	11	32.040	31.520	-0.520
20	12	32.300	31.800	-0.500
20	13	31.870	31.450	-0.420
20	14	32.060	31.570	-0.490
20	15	32.000	31.580	-0.420
20	16	31.940	31.500	-0.440
20	17	31.870	31.400	-0.470
20	18	32.030	31.630	-0.400
20	19	31.920	31.540	-0.380
20	20	31.910	31.520	-0.390
20	21	32.300	31.830	-0.470
20	22	32.030	31.610	-0.420
20	23	32.160	31.790	-0.370
20	24	31.800	31.460	-0.340
20	25	31.890	31.530	-0.360
20	26	32.050	31.670	-0.380
20	27	31.970	31.690	-0.280
35	28	31.870	31.390	-0.480
35	29	31.980	31.470	-0.510
35	30	32.140	31.680	-0.460
35	31	31.910	31.540	-0.370
35	32	31.990	31.660	-0.330
30	33	31.870	31.800	-0.070
30	34	31.960	31.570	-0.390
30	35	32.310	31.990	-0.320
30	36	31.930	31.630	-0.300
30	37	31.900	31.660	-0.240
	Max	32.310	31.990	-0.070
	Average	32.002	31.588	-0.414
	Min	31.800	31.390	-0.550
	Std Dev	0.131	0.134	0.094



	18.2_LS RDSON			
Test Site				
Tester				
Test Number				
Max Limit	55	mohm		
Min Limit	27.8	mohm		
kRad(Si)	20	25	30	35
LL	27.800	27.800	27.800	27.800
Min	31.400	31.460	31.570	31.390
Average	31.580	31.516	31.730	31.548
Max	31.830	31.560	31.990	31.680
UL	55.000	55.000	55.000	55.000

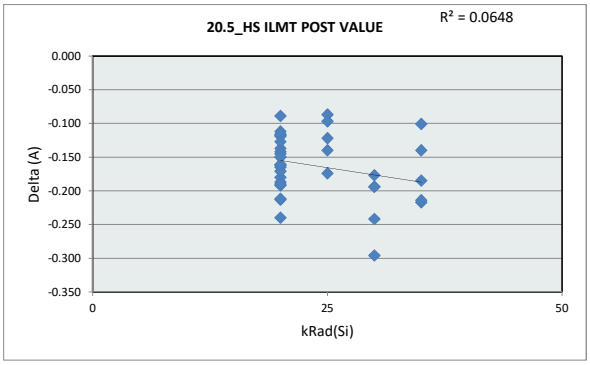


LDR TID Report
TPS7H4010-SEP

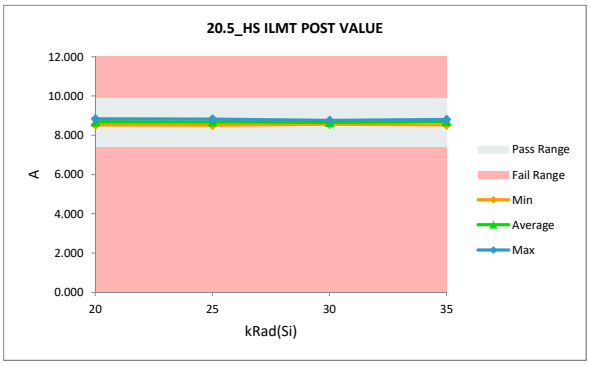
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	20.5_HS ILMT POST VALUE	
Test Site		
Tester		
Test Number		
Unit	A	A
Max Limit	9.85	9.85
Min Limit	7.4	7.4

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	8.739	8.652	-0.087
25	2	8.645	8.505	-0.140
25	3	8.784	8.662	-0.122
25	4	8.922	8.825	-0.097
25	5	8.931	8.757	-0.174
20	6	8.801	8.682	-0.119
20	7	8.860	8.680	-0.180
20	8	8.957	8.839	-0.118
20	9	8.959	8.822	-0.137
20	10	8.843	8.731	-0.112
20	11	8.918	8.776	-0.142
20	12	8.751	8.564	-0.187
20	13	8.783	8.591	-0.192
20	14	8.756	8.566	-0.190
20	15	8.740	8.624	-0.116
20	16	8.751	8.586	-0.165
20	17	8.776	8.626	-0.150
20	18	8.895	8.750	-0.145
20	19	8.818	8.691	-0.127
20	20	8.766	8.604	-0.162
20	21	8.969	8.729	-0.240
20	22	8.962	8.791	-0.171
20	23	8.741	8.528	-0.213
20	24	8.898	8.737	-0.161
20	25	8.840	8.751	-0.089
20	26	8.970	8.820	-0.150
20	27	8.763	8.551	-0.212
35	28	8.937	8.797	-0.140
35	29	8.995	8.810	-0.185
35	30	8.777	8.560	-0.217
35	31	8.737	8.523	-0.214
35	32	8.914	8.813	-0.101
30	33	8.938	8.761	-0.177
30	34	8.925	8.683	-0.242
30	35	8.855	8.559	-0.296
30	36	8.778	8.584	-0.194
30	37	8.923	8.729	-0.194
	Max	8.995	8.839	-0.087
	Average	8.846	8.683	-0.164
	Min	8.645	8.505	-0.296
	Std Dev	0.091	0.103	0.047



	20.5_HS ILMT POST VALUE			
Test Site				
Tester				
Test Number				
Max Limit	9.85	A		
Min Limit	7.4	A		
kRad(Si)	20	25	30	35
LL	7.400	7.400	7.400	7.400
Min	8.528	8.505	8.559	8.523
Average	8.684	8.680	8.663	8.701
Max	8.839	8.825	8.761	8.813
UL	9.850	9.850	9.850	9.850

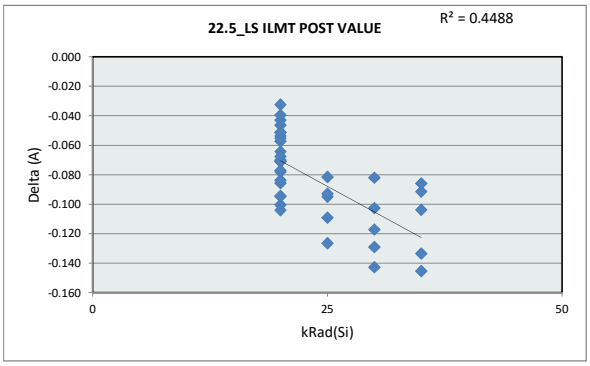


LDR TID Report
TPS7H4010-SEP

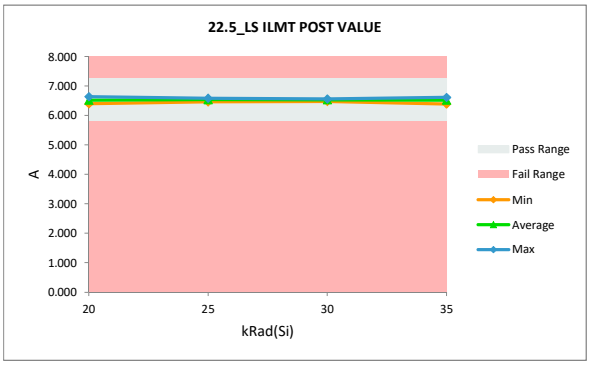
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	22.5_LS ILMT POST VALUE	
Test Site		
Tester		
Test Number		
Unit	A	A
Max Limit	7.25	7.25
Min Limit	5.8	5.8

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	6.639	6.544	-0.095
25	2	6.695	6.586	-0.109
25	3	6.552	6.460	-0.093
25	4	6.685	6.559	-0.126
25	5	6.616	6.534	-0.082
20	6	6.662	6.609	-0.054
20	7	6.502	6.431	-0.071
20	8	6.628	6.571	-0.057
20	9	6.560	6.509	-0.051
20	10	6.648	6.605	-0.043
20	11	6.674	6.596	-0.078
20	12	6.491	6.396	-0.095
20	13	6.626	6.526	-0.100
20	14	6.510	6.470	-0.040
20	15	6.572	6.525	-0.046
20	16	6.667	6.582	-0.086
20	17	6.703	6.639	-0.064
20	18	6.542	6.448	-0.094
20	19	6.559	6.504	-0.055
20	20	6.593	6.522	-0.071
20	21	6.644	6.574	-0.070
20	22	6.545	6.461	-0.084
20	23	6.579	6.502	-0.077
20	24	6.614	6.582	-0.032
20	25	6.520	6.469	-0.051
20	26	6.487	6.419	-0.068
20	27	6.557	6.453	-0.104
35	28	6.676	6.585	-0.091
35	29	6.525	6.392	-0.133
35	30	6.637	6.492	-0.145
35	31	6.698	6.612	-0.086
35	32	6.608	6.504	-0.104
30	33	6.643	6.526	-0.117
30	34	6.643	6.561	-0.082
30	35	6.694	6.551	-0.143
30	36	6.656	6.553	-0.103
30	37	6.602	6.473	-0.129
	Max	6.703	6.639	-0.032
	Average	6.607	6.522	-0.085
	Min	6.487	6.392	-0.145
	Std Dev	0.064	0.064	0.029



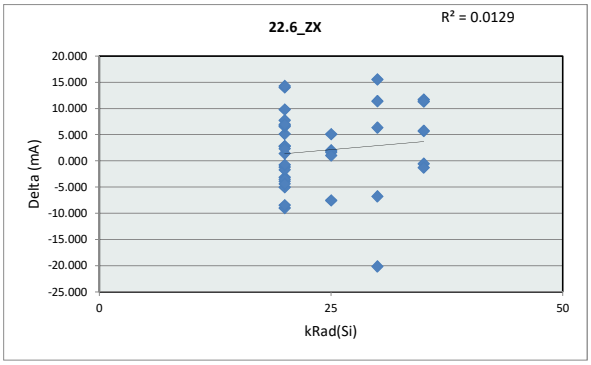
	22.5_LS ILMT POST VALUE			
Test Site				
Tester				
Test Number				
Max Limit	7.25	A		
Min Limit	5.8	A		
kRad(Si)	20	25	30	35
LL	5.800	5.800	5.800	5.800
Min	6.396	6.460	6.473	6.392
Average	6.518	6.536	6.533	6.517
Max	6.639	6.586	6.561	6.612
UL	7.250	7.250	7.250	7.250



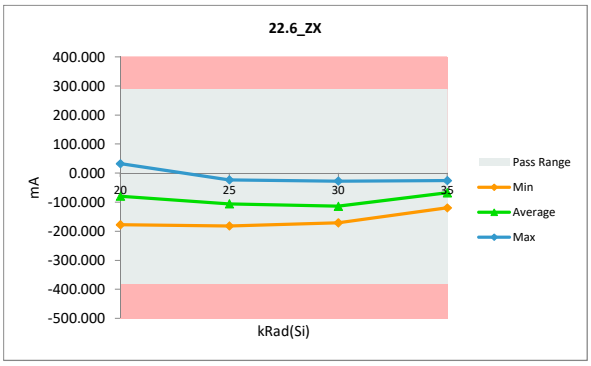
LDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

		22.6_ZX	
Test Site			
Tester			
Test Number			
Unit		mA	mA
Max Limit		288	288
Min Limit		-380	-380
kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	-116.730	-114.730	2.000
25	2	-124.610	-122.940	1.670
25	3	-15.400	-22.940	-7.540
25	4	-186.900	-181.810	5.090
25	5	-86.620	-85.610	1.010
20	6	-110.620	-109.220	1.400
20	7	27.490	32.630	5.140
20	8	-82.640	-91.640	-9.000
20	9	-184.440	-177.870	6.570
20	10	-74.190	-67.430	6.760
20	11	-108.300	-113.340	-5.040
20	12	-39.740	-40.940	-1.200
20	13	-113.910	-99.930	13.980
20	14	-27.790	-31.720	-3.930
20	15	-42.670	-45.810	-3.140
20	16	-92.950	-94.670	-1.720
20	17	-82.690	-86.260	-3.570
20	18	-122.860	-120.110	2.750
20	19	-96.520	-88.780	7.740
20	20	-104.850	-102.040	2.810
20	21	-80.890	-66.620	14.270
20	22	-133.670	-126.720	6.950
20	23	-74.800	-83.270	-8.470
20	24	-69.670	-67.360	2.310
20	25	-69.930	-74.310	-4.380
20	26	-30.790	-31.570	-0.780
20	27	-63.960	-54.190	9.770
35	28	-93.680	-82.000	11.680
35	29	-49.440	-38.120	11.320
35	30	-31.560	-25.830	5.730
35	31	-69.900	-70.440	-0.540
35	32	-118.310	-119.610	-1.300
30	33	-150.970	-171.130	-20.160
30	34	-169.580	-163.230	6.350
30	35	-105.920	-94.540	11.380
30	36	-129.200	-113.670	15.530
30	37	-20.530	-27.290	-6.760
	Max	27.490	32.630	15.530
	Average	-87.831	-85.812	2.018
	Min	-186.900	-181.810	-20.160
	Std Dev	47.514	46.877	7.608



	22.6_ZX			
Test Site				
Tester				
Test Number				
Max Limit	288	mA		
Min Limit	-380	mA		
kRad(Si)	20	25	30	35
LL	-380.000	-380.000	-380.000	-380.000
Min	-177.870	-181.810	-171.130	-119.610
Average	-79.144	-105.606	-113.972	-67.200
Max	32.630	-22.940	-27.290	-25.830
UL	288.000	288.000	288.000	288.000

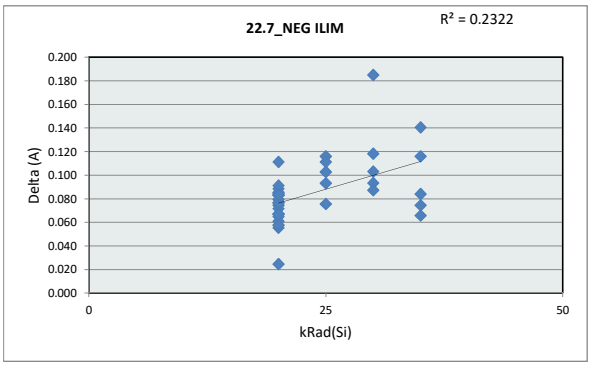


LDR TID Report
TPS7H4010-SEP

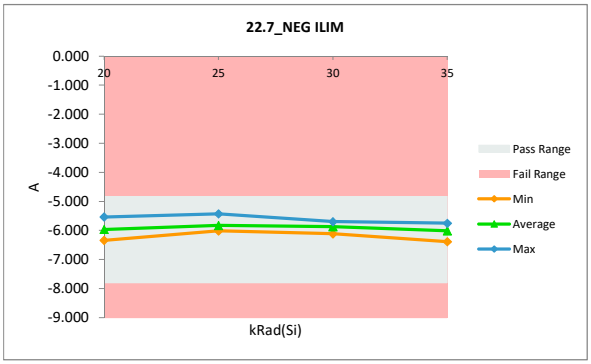
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	22.7_NEG ILIM	
Test Site		
Tester		
Test Number		
Unit	A	A
Max Limit	-4.8	-4.8
Min Limit	-7.8	-7.8

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	-6.060	-5.984	0.076
25	2	-6.061	-5.945	0.116
25	3	-5.532	-5.430	0.103
25	4	-5.868	-5.775	0.093
25	5	-6.125	-6.014	0.111
20	6	-6.144	-6.077	0.067
20	7	-6.048	-5.963	0.085
20	8	-6.097	-6.009	0.088
20	9	-6.035	-5.980	0.055
20	10	-5.972	-5.915	0.057
20	11	-6.029	-5.944	0.085
20	12	-6.028	-5.964	0.065
20	13	-5.884	-5.772	0.111
20	14	-6.080	-6.019	0.061
20	15	-5.973	-5.902	0.072
20	16	-5.970	-5.896	0.074
20	17	-6.417	-6.340	0.077
20	18	-6.068	-5.985	0.083
20	19	-6.277	-6.210	0.067
20	20	-5.905	-5.825	0.079
20	21	-6.285	-6.218	0.067
20	22	-5.901	-5.843	0.058
20	23	-6.386	-6.302	0.084
20	24	-6.144	-6.119	0.025
20	25	-5.858	-5.767	0.091
20	26	-5.611	-5.534	0.076
20	27	-5.731	-5.648	0.083
35	28	-6.050	-5.976	0.075
35	29	-6.115	-5.999	0.116
35	30	-5.892	-5.752	0.141
35	31	-6.451	-6.385	0.066
35	32	-6.027	-5.943	0.084
30	33	-5.883	-5.698	0.185
30	34	-5.930	-5.837	0.093
30	35	-6.231	-6.113	0.118
30	36	-5.840	-5.736	0.103
30	37	-6.067	-5.980	0.087
	Max	-5.532	-5.430	0.185
	Average	-6.026	-5.940	0.086
	Min	-6.451	-6.385	0.025
	Std Dev	0.197	0.205	0.028



	22.7_NEG ILIM			
Test Site				
Tester				
Test Number				
Max Limit	-4.8	A		
Min Limit	-7.8	A		
kRad(Si)	20	25	30	35
LL	-7.800	-7.800	-7.800	-7.800
Min	-6.340	-6.014	-6.113	-6.385
Average	-5.965	-5.830	-5.873	-6.011
Max	-5.534	-5.430	-5.698	-5.752
UL	-4.800	-4.800	-4.800	-4.800

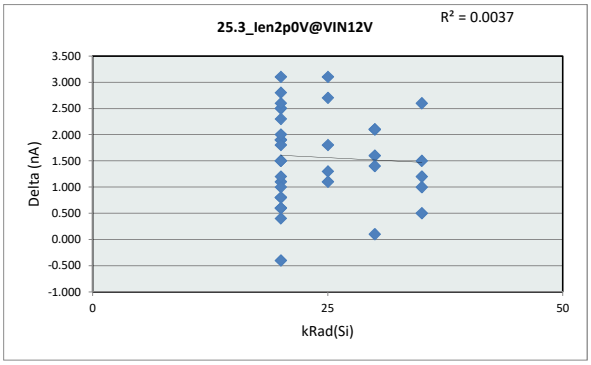


LDR TID Report
TPS7H4010-SEP

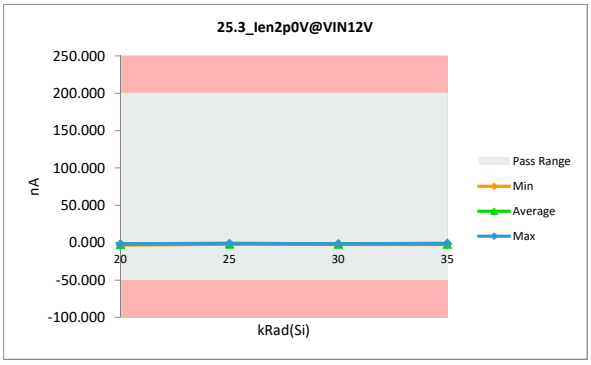
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.3_Ien2p0V@VIN12V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	200	200
Min Limit	-50	-50

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	-4.400	-1.700	2.700
25	2	-2.800	-1.500	1.300
25	3	-3.900	-0.800	3.100
25	4	-3.300	-2.200	1.100
25	5	-3.900	-2.100	1.800
20	6	-4.100	-2.200	1.900
20	7	-4.200	-2.700	1.500
20	8	-3.700	-1.800	1.900
20	9	-3.000	-1.900	1.100
20	10	-3.400	-1.600	1.800
20	11	-4.700	-1.600	3.100
20	12	-3.200	-2.800	0.400
20	13	-3.900	-1.900	2.000
20	14	-4.100	-1.600	2.500
20	15	-3.300	-2.500	0.800
20	16	-3.700	-2.200	1.500
20	17	-4.500	-3.000	1.500
20	18	-3.200	-2.600	0.600
20	19	-4.400	-1.600	2.800
20	20	-2.800	-1.600	1.200
20	21	-3.800	-2.800	1.000
20	22	-5.000	-2.500	2.500
20	23	-3.600	-2.800	0.800
20	24	-3.000	-2.400	0.600
20	25	-4.000	-1.700	2.300
20	26	-4.200	-1.600	2.600
20	27	-2.800	-3.200	-0.400
35	28	-2.700	-2.200	0.500
35	29	-3.600	-2.100	1.500
35	30	-3.300	-2.300	1.000
35	31	-3.700	-2.500	1.200
35	32	-3.300	-0.700	2.600
30	33	-3.700	-2.300	1.400
30	34	-3.600	-1.500	2.100
30	35	-3.200	-1.600	1.600
30	36	-3.900	-1.800	2.100
30	37	-1.900	-1.800	0.100
	Max	-1.900	-0.700	3.100
	Average	-3.616	-2.046	1.570
	Min	-5.000	-3.200	-0.400
	Std Dev	0.630	0.565	0.850



	25.3_Ien2p0V@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	200	nA		
Min Limit	-50	nA		
kRad(Si)	20	25	30	35
LL	-50.000	-50.000	-50.000	-50.000
Min	-3.200	-2.200	-2.300	-2.500
Average	-2.209	-1.660	-1.800	-1.960
Max	-1.600	-0.800	-1.500	-0.700
UL	200.000	200.000	200.000	200.000

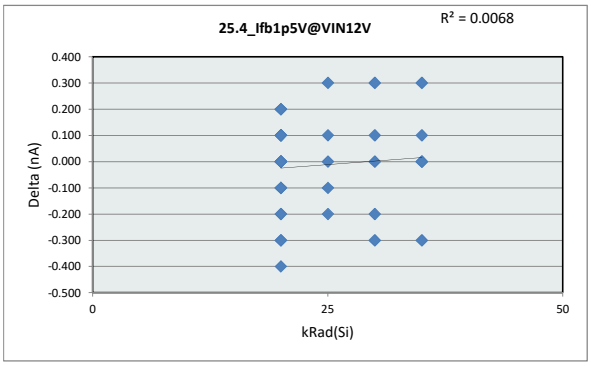


LDR TID Report
TPS7H4010-SEP

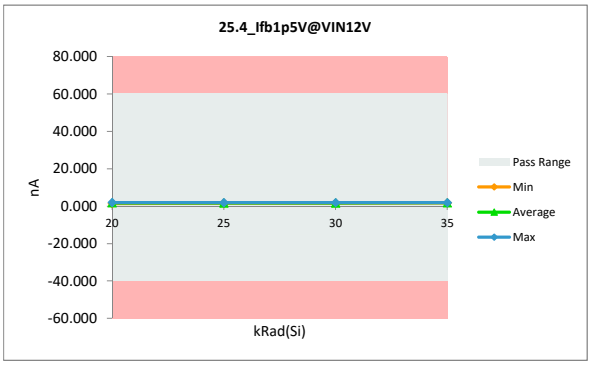
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.4_Ifb1p5V@VIN12V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	60	60
Min Limit	-40	-40

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.600	1.600	0.000
25	2	1.600	1.700	0.100
25	3	2.000	1.900	-0.100
25	4	1.800	1.600	-0.200
25	5	1.600	1.900	0.300
20	6	1.800	1.700	-0.100
20	7	2.000	1.700	-0.300
20	8	1.900	2.000	0.100
20	9	1.800	1.700	-0.100
20	10	1.700	1.900	0.200
20	11	1.800	1.800	0.000
20	12	1.600	1.600	0.000
20	13	2.000	2.000	0.000
20	14	1.700	1.800	0.100
20	15	1.700	1.900	0.200
20	16	2.100	2.000	-0.100
20	17	1.600	1.600	0.000
20	18	1.600	1.600	0.000
20	19	1.800	1.900	0.100
20	20	1.700	1.800	0.100
20	21	1.800	1.900	0.100
20	22	2.100	1.800	-0.300
20	23	1.700	1.900	0.200
20	24	2.000	1.800	-0.200
20	25	1.800	1.800	0.000
20	26	1.700	1.500	-0.200
20	27	2.000	1.600	-0.400
35	28	1.800	1.900	0.100
35	29	2.100	1.800	-0.300
35	30	1.600	1.900	0.300
35	31	1.900	1.900	0.000
35	32	1.800	1.800	0.000
30	33	1.700	1.700	0.000
30	34	1.500	1.600	0.100
30	35	1.600	1.900	0.300
30	36	2.000	1.700	-0.300
30	37	1.900	1.700	-0.200
	Max	2.100	2.000	0.300
	Average	1.795	1.781	-0.014
	Min	1.500	1.500	-0.400
	Std Dev	0.168	0.135	0.181



	25.4_Ifb1p5V@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	60	nA		
Min Limit	-40	nA		
kRad(Si)	20	25	30	35
LL	-40.000	-40.000	-40.000	-40.000
Min	1.500	1.600	1.600	1.800
Average	1.786	1.740	1.720	1.860
Max	2.000	1.900	1.900	1.900
UL	60.000	60.000	60.000	60.000

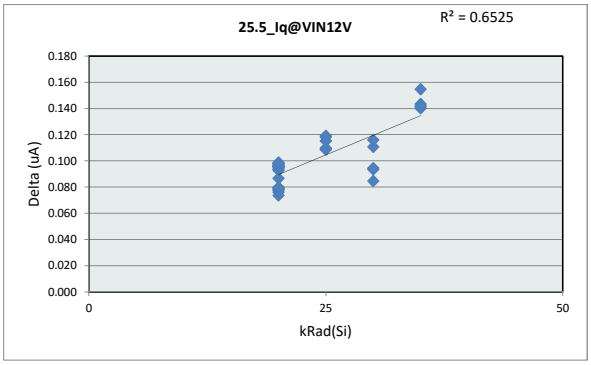


LDR TID Report
TPS7H4010-SEP

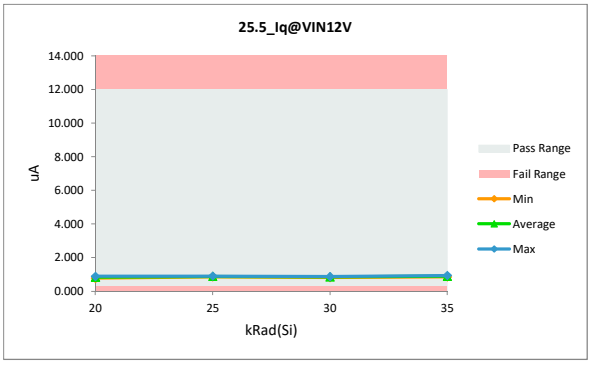
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.5_Iq@VIN12V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	12	12
Min Limit	0.33	0.33

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.793	0.902	0.110
25	2	0.766	0.885	0.119
25	3	0.735	0.853	0.118
25	4	0.794	0.903	0.109
25	5	0.765	0.881	0.115
20	6	0.763	0.840	0.078
20	7	0.716	0.810	0.094
20	8	0.782	0.855	0.074
20	9	0.733	0.828	0.095
20	10	0.749	0.845	0.096
20	11	0.757	0.853	0.096
20	12	0.688	0.775	0.087
20	13	0.747	0.840	0.094
20	14	0.705	0.802	0.096
20	15	0.785	0.863	0.078
20	16	0.731	0.824	0.093
20	17	0.754	0.849	0.095
20	18	0.787	0.863	0.076
20	19	0.768	0.847	0.079
20	20	0.777	0.856	0.079
20	21	0.748	0.844	0.096
20	22	0.756	0.853	0.097
20	23	0.693	0.791	0.098
20	24	0.726	0.821	0.095
20	25	0.744	0.842	0.098
20	26	0.711	0.810	0.099
20	27	0.809	0.889	0.080
35	28	0.775	0.917	0.142
35	29	0.736	0.876	0.140
35	30	0.697	0.852	0.155
35	31	0.743	0.886	0.143
35	32	0.797	0.939	0.142
30	33	0.776	0.860	0.085
30	34	0.769	0.863	0.094
30	35	0.703	0.814	0.111
30	36	0.761	0.877	0.116
30	37	0.772	0.867	0.095
	Max	0.809	0.939	0.155
	Average	0.752	0.853	0.102
	Min	0.688	0.775	0.074
	Std Dev	0.031	0.035	0.021



	25.5_Iq@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	12	uA		
Min Limit	0.33	uA		
kRad(Si)	20	25	30	35
LL	0.330	0.330	0.330	0.330
Min	0.775	0.853	0.814	0.852
Average	0.836	0.885	0.856	0.894
Max	0.889	0.903	0.877	0.939
UL	12.000	12.000	12.000	12.000

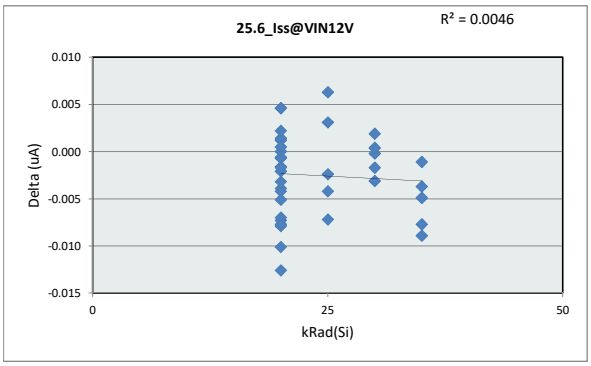


LDR TID Report
TPS7H4010-SEP

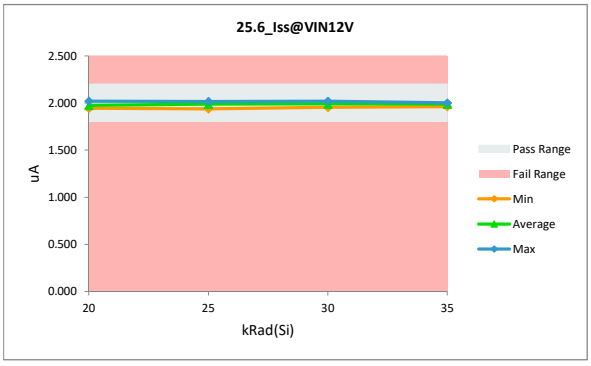
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	25.6_Iss@VIN12V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	2.2	2.2
Min Limit	1.8	1.8

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.946	1.938	-0.007
25	2	2.016	2.014	-0.002
25	3	2.013	2.017	0.003
25	4	1.986	1.982	-0.004
25	5	1.987	1.994	0.006
20	6	1.948	1.944	-0.004
20	7	1.957	1.950	-0.007
20	8	1.967	1.960	-0.007
20	9	1.962	1.960	-0.002
20	10	1.999	1.998	-0.001
20	11	1.970	1.969	-0.001
20	12	1.954	1.954	0.000
20	13	1.952	1.947	-0.005
20	14	2.000	2.001	0.001
20	15	1.977	1.973	-0.004
20	16	1.955	1.947	-0.008
20	17	2.018	2.020	0.001
20	18	2.016	2.021	0.005
20	19	1.992	1.994	0.002
20	20	1.966	1.964	-0.002
20	21	1.953	1.957	0.005
20	22	2.014	2.006	-0.008
20	23	1.967	1.968	0.001
20	24	2.020	2.010	-0.010
20	25	1.950	1.948	-0.002
20	26	2.015	2.002	-0.013
20	27	1.950	1.947	-0.003
35	28	1.970	1.962	-0.009
35	29	1.993	1.986	-0.008
35	30	1.991	1.987	-0.004
35	31	2.007	2.002	-0.005
35	32	2.004	2.003	-0.001
30	33	2.016	2.018	0.002
30	34	2.022	2.021	-0.002
30	35	1.957	1.954	-0.003
30	36	2.002	2.002	0.000
30	37	1.959	1.959	0.000
	Max	2.022	2.021	0.006
	Average	1.983	1.981	-0.003
	Min	1.946	1.938	-0.013
	Std Dev	0.026	0.027	0.004



	25.6_Iss@VIN12V			
Test Site				
Tester				
Test Number				
Max Limit	2.2	uA		
Min Limit	1.8	uA		
kRad(Si)	20	25	30	35
LL	1.800	1.800	1.800	1.800
Min	1.944	1.938	1.954	1.962
Average	1.975	1.989	1.991	1.988
Max	2.021	2.017	2.021	2.003
UL	2.200	2.200	2.200	2.200

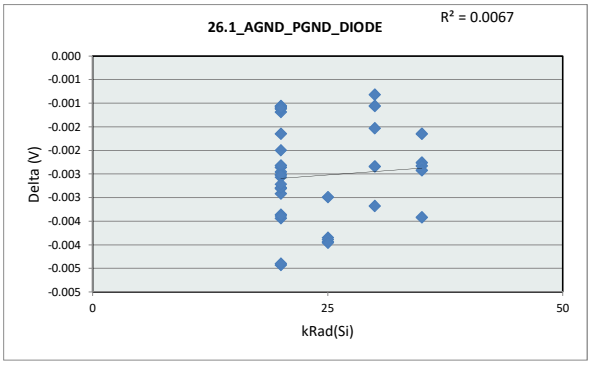


LDR TID Report
TPS7H4010-SEP

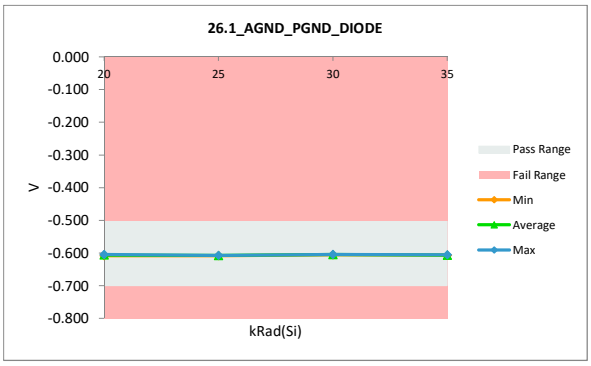
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.1_AGND_PGND_DIODE	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	-0.5	-0.5
Min Limit	-0.7	-0.7

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	-0.604	-0.608	-0.004
25	2	-0.604	-0.608	-0.004
25	3	-0.605	-0.608	-0.003
25	4	-0.604	-0.608	-0.004
25	5	-0.603	-0.607	-0.004
20	6	-0.602	-0.606	-0.004
20	7	-0.604	-0.607	-0.003
20	8	-0.603	-0.606	-0.003
20	9	-0.604	-0.607	-0.003
20	10	-0.603	-0.606	-0.003
20	11	-0.604	-0.608	-0.004
20	12	-0.603	-0.605	-0.002
20	13	-0.603	-0.606	-0.003
20	14	-0.604	-0.607	-0.002
20	15	-0.603	-0.606	-0.003
20	16	-0.603	-0.606	-0.002
20	17	-0.604	-0.607	-0.003
20	18	-0.604	-0.607	-0.003
20	19	-0.604	-0.606	-0.003
20	20	-0.602	-0.605	-0.003
20	21	-0.604	-0.606	-0.002
20	22	-0.605	-0.606	-0.001
20	23	-0.604	-0.605	-0.001
20	24	-0.604	-0.605	-0.001
20	25	-0.604	-0.605	-0.001
20	26	-0.604	-0.605	-0.001
20	27	-0.604	-0.605	-0.002
35	28	-0.603	-0.606	-0.003
35	29	-0.605	-0.607	-0.002
35	30	-0.605	-0.607	-0.002
35	31	-0.603	-0.605	-0.002
35	32	-0.604	-0.606	-0.002
30	33	-0.603	-0.605	-0.002
30	34	-0.603	-0.606	-0.003
30	35	-0.604	-0.605	-0.001
30	36	-0.603	-0.604	-0.001
30	37	-0.603	-0.604	-0.002
	Max	-0.602	-0.604	-0.001
	Average	-0.604	-0.606	-0.003
	Min	-0.605	-0.608	-0.004
	Std Dev	0.001	0.001	0.001



	26.1_AGND_PGND_DIODE			
Test Site				
Tester				
Test Number				
Max Limit	-0.5	V		
Min Limit	-0.7	V		
kRad(Si)	20	25	30	35
LL	-0.700	-0.700	-0.700	-0.700
Min	-0.608	-0.608	-0.606	-0.607
Average	-0.606	-0.608	-0.605	-0.606
Max	-0.605	-0.607	-0.604	-0.605
UL	-0.500	-0.500	-0.500	-0.500

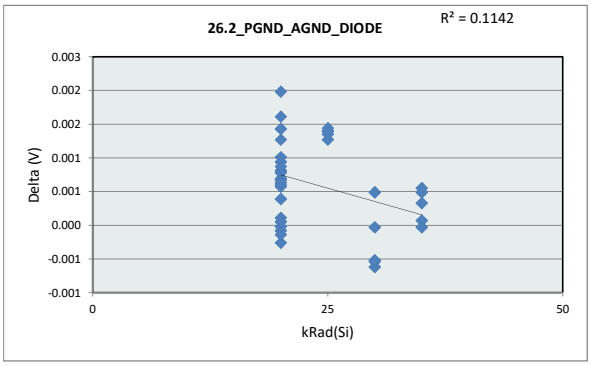


LDR TID Report
TPS7H4010-SEP

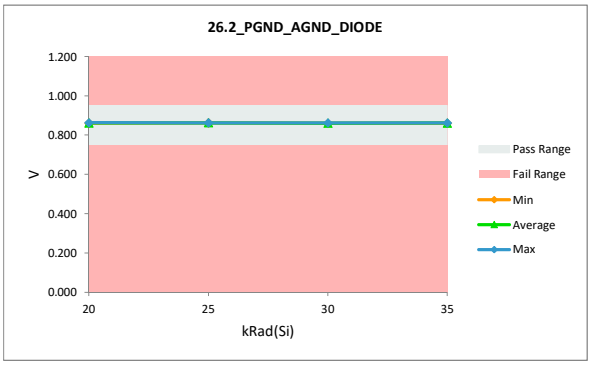
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.2_PGND_AGND_DIODE	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.95	0.95
Min Limit	0.75	0.75

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.861	0.863	0.001
25	2	0.861	0.863	0.001
25	3	0.861	0.862	0.001
25	4	0.861	0.862	0.001
25	5	0.861	0.862	0.001
20	6	0.861	0.862	0.002
20	7	0.860	0.862	0.001
20	8	0.861	0.862	0.001
20	9	0.861	0.862	0.001
20	10	0.861	0.862	0.001
20	11	0.861	0.863	0.002
20	12	0.861	0.862	0.001
20	13	0.861	0.862	0.001
20	14	0.861	0.862	0.001
20	15	0.861	0.862	0.001
20	16	0.861	0.862	0.001
20	17	0.861	0.862	0.001
20	18	0.861	0.862	0.001
20	19	0.861	0.862	0.001
20	20	0.861	0.862	0.001
20	21	0.861	0.861	0.000
20	22	0.861	0.861	0.000
20	23	0.861	0.861	0.000
20	24	0.861	0.861	0.000
20	25	0.861	0.861	0.000
20	26	0.861	0.861	0.000
20	27	0.861	0.861	0.000
35	28	0.861	0.861	0.000
35	29	0.861	0.861	0.001
35	30	0.861	0.861	0.000
35	31	0.861	0.861	0.000
35	32	0.861	0.861	0.000
30	33	0.861	0.861	0.000
30	34	0.861	0.861	0.000
30	35	0.860	0.860	-0.001
30	36	0.861	0.860	-0.001
30	37	0.861	0.860	-0.001
	Max	0.861	0.863	0.002
	Average	0.861	0.861	0.001
	Min	0.860	0.860	-0.001
	Std Dev	0.000	0.001	0.001



	26.2_PGND_AGND_DIODE			
Test Site				
Tester				
Test Number				
Max Limit	0.95	V		
Min Limit	0.75	V		
kRad(Si)	20	25	30	35
LL	0.750	0.750	0.750	0.750
Min	0.861	0.862	0.860	0.861
Average	0.862	0.862	0.860	0.861
Max	0.863	0.863	0.861	0.861
UL	0.950	0.950	0.950	0.950

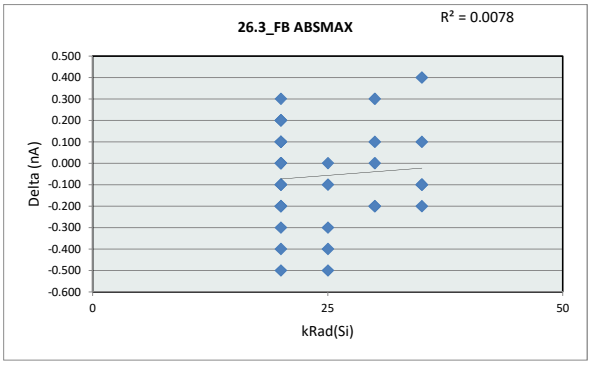


LDR TID Report
TPS7H4010-SEP

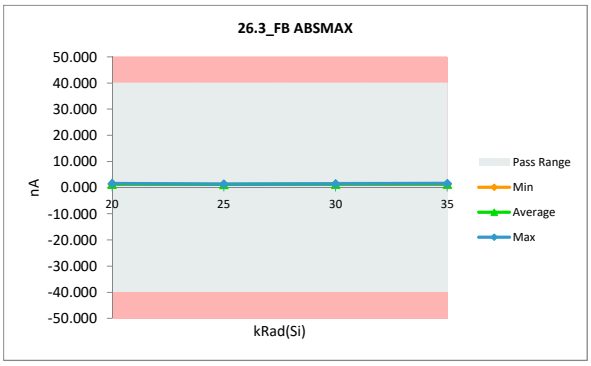
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.3_FB ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	40	40
Min Limit	-40	-40

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.400	1.400	0.000
25	2	1.600	1.200	-0.400
25	3	1.300	1.200	-0.100
25	4	1.600	1.300	-0.300
25	5	1.700	1.200	-0.500
20	6	1.600	1.200	-0.400
20	7	1.300	1.600	0.300
20	8	1.300	1.300	0.000
20	9	1.600	1.300	-0.300
20	10	1.400	1.300	-0.100
20	11	1.200	1.300	0.100
20	12	1.700	1.500	-0.200
20	13	1.200	1.400	0.200
20	14	1.400	1.300	-0.100
20	15	1.400	1.600	0.200
20	16	1.300	1.400	0.100
20	17	1.200	1.400	0.200
20	18	1.400	1.200	-0.200
20	19	1.500	1.400	-0.100
20	20	1.400	1.500	0.100
20	21	1.400	1.400	0.000
20	22	1.600	1.600	0.000
20	23	1.400	1.200	-0.200
20	24	1.700	1.200	-0.500
20	25	1.600	1.600	0.000
20	26	1.200	1.300	0.100
20	27	1.500	1.300	-0.200
35	28	1.500	1.300	-0.200
35	29	1.200	1.600	0.400
35	30	1.300	1.400	0.100
35	31	1.400	1.300	-0.100
35	32	1.400	1.300	-0.100
30	33	1.600	1.400	-0.200
30	34	1.600	1.400	-0.200
30	35	1.400	1.500	0.100
30	36	1.200	1.500	0.300
30	37	1.200	1.200	0.000
	Max	1.700	1.600	0.400
	Average	1.424	1.365	-0.059
	Min	1.200	1.200	-0.500
	Std Dev	0.161	0.132	0.219



	26.3_FB ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	40	nA		
Min Limit	-40	nA		
kRad(Si)	20	25	30	35
LL	-40.000	-40.000	-40.000	-40.000
Min	1.200	1.200	1.200	1.300
Average	1.377	1.260	1.400	1.380
Max	1.600	1.400	1.500	1.600
UL	40.000	40.000	40.000	40.000

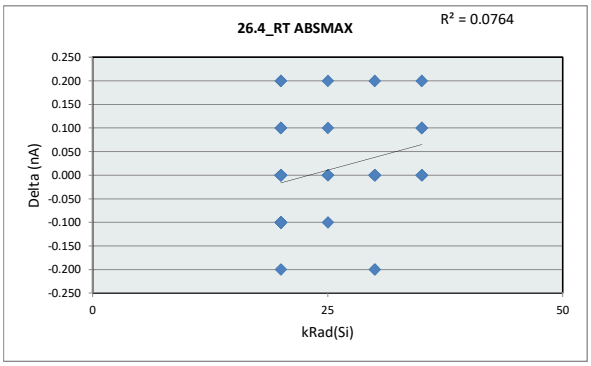


LDR TID Report
TPS7H4010-SEP

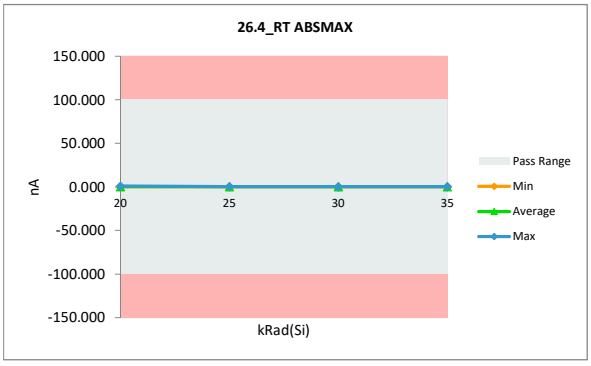
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.4_RT ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	100	100
Min Limit	-100	-100

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.100	0.300	0.200
25	2	0.200	0.100	-0.100
25	3	0.100	0.100	0.000
25	4	0.200	0.200	0.000
25	5	0.100	0.200	0.100
20	6	0.100	0.200	0.100
20	7	0.300	0.200	-0.100
20	8	0.200	0.100	-0.100
20	9	0.200	0.200	0.000
20	10	0.100	0.100	0.000
20	11	0.300	0.200	-0.100
20	12	0.600	0.800	0.200
20	13	0.100	0.200	0.100
20	14	0.200	0.100	-0.100
20	15	0.100	0.100	0.000
20	16	0.100	0.100	0.000
20	17	0.200	0.100	-0.100
20	18	0.300	0.300	0.000
20	19	0.300	0.200	-0.100
20	20	0.200	0.100	-0.100
20	21	0.200	0.400	0.200
20	22	0.100	0.200	0.100
20	23	0.200	0.200	0.000
20	24	0.300	0.200	-0.100
20	25	0.100	0.000	-0.100
20	26	0.200	0.000	-0.200
20	27	0.200	0.200	0.000
35	28	0.100	0.100	0.000
35	29	0.100	0.200	0.100
35	30	0.100	0.100	0.000
35	31	0.000	0.200	0.200
35	32	0.200	0.300	0.100
30	33	0.000	0.200	0.200
30	34	0.400	0.200	-0.200
30	35	0.200	0.200	0.000
30	36	0.100	0.100	0.000
30	37	0.200	0.200	0.000
	Max	0.600	0.800	0.200
	Average	0.181	0.186	0.005
	Min	0.000	0.000	-0.200
	Std Dev	0.113	0.132	0.110



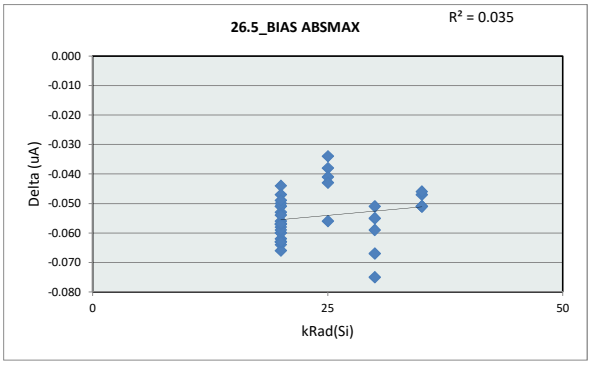
	26.4_RT ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	100	nA		
Min Limit	-100	nA		
kRad(Si)	20	25	30	35
LL	-100.000	-100.000	-100.000	-100.000
Min	0.100	0.100	0.100	0.100
Average	0.191	0.180	0.180	0.180
Max	0.800	0.300	0.200	0.300
UL	100.000	100.000	100.000	100.000



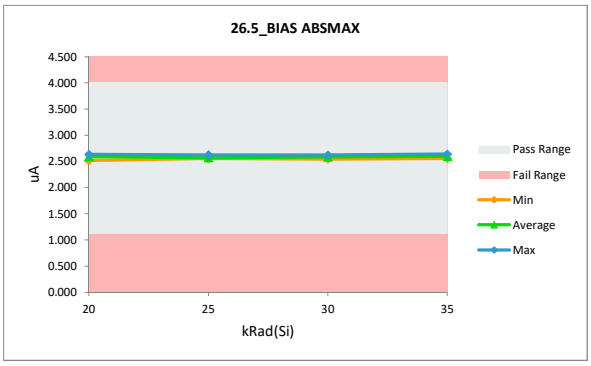
LDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.5_BIAS ABSMAX		
Test Site			
Tester			
Test Number			
Unit	uA	uA	
Max Limit	4	4	
Min Limit	1.1	1.1	
kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	2.589	2.555	-0.034
25	2	2.608	2.570	-0.038
25	3	2.665	2.624	-0.041
25	4	2.596	2.553	-0.043
25	5	2.610	2.554	-0.056
20	6	2.627	2.576	-0.051
20	7	2.624	2.564	-0.060
20	8	2.621	2.559	-0.062
20	9	2.645	2.592	-0.053
20	10	2.675	2.611	-0.064
20	11	2.681	2.618	-0.063
20	12	2.579	2.519	-0.060
20	13	2.669	2.613	-0.056
20	14	2.678	2.621	-0.057
20	15	2.628	2.577	-0.051
20	16	2.676	2.618	-0.058
20	17	2.687	2.624	-0.063
20	18	2.598	2.548	-0.050
20	19	2.612	2.555	-0.057
20	20	2.635	2.569	-0.066
20	21	2.626	2.563	-0.063
20	22	2.668	2.624	-0.044
20	23	2.684	2.625	-0.059
20	24	2.663	2.606	-0.057
20	25	2.676	2.622	-0.054
20	26	2.680	2.633	-0.047
20	27	2.601	2.552	-0.049
35	28	2.623	2.572	-0.051
35	29	2.692	2.641	-0.051
35	30	2.664	2.613	-0.051
35	31	2.659	2.612	-0.047
35	32	2.601	2.555	-0.046
30	33	2.618	2.543	-0.075
30	34	2.638	2.571	-0.067
30	35	2.675	2.616	-0.059
30	36	2.674	2.623	-0.051
30	37	2.627	2.572	-0.055
	Max	2.692	2.641	-0.034
	Average	2.642	2.588	-0.054
	Min	2.579	2.519	-0.075
	Std Dev	0.033	0.032	0.009



	26.5_BIAS ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	4	uA		
Min Limit	1.1	uA		
kRad(Si)	20	25	30	35
LL	1.100	1.100	1.100	1.100
Min	2.519	2.553	2.543	2.555
Average	2.590	2.571	2.585	2.599
Max	2.633	2.624	2.623	2.641
UL	4.000	4.000	4.000	4.000

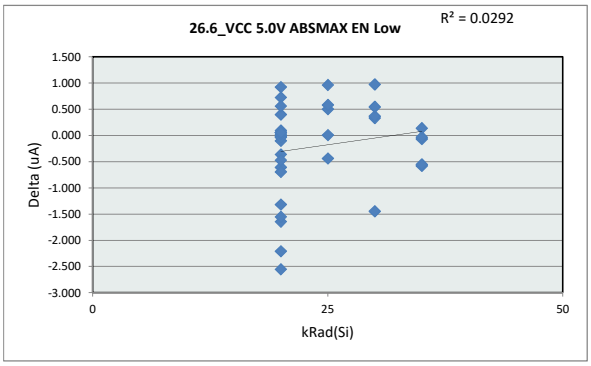


LDR TID Report
TPS7H4010-SEP

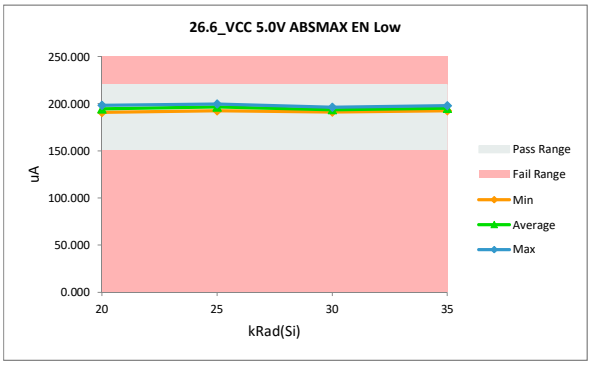
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.6_VCC 5.0V ABSMAX EN Low	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	220	220
Min Limit	150	150

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	195.166	194.726	-0.440
25	2	196.447	196.451	0.004
25	3	198.643	199.606	0.963
25	4	198.579	199.077	0.498
25	5	191.813	192.392	0.579
20	6	192.659	192.553	-0.106
20	7	191.377	191.429	0.052
20	8	195.922	195.913	-0.009
20	9	191.316	191.410	0.094
20	10	195.096	195.148	0.052
20	11	198.665	198.300	-0.365
20	12	191.236	190.627	-0.609
20	13	196.363	193.808	-2.555
20	14	196.931	196.915	-0.016
20	15	190.859	190.819	-0.040
20	16	195.579	195.977	0.398
20	17	197.348	198.070	0.722
20	18	196.671	197.593	0.922
20	19	192.429	192.449	0.020
20	20	196.111	194.792	-1.319
20	21	192.651	191.004	-1.647
20	22	195.964	195.491	-0.473
20	23	192.611	193.170	0.559
20	24	198.252	196.043	-2.209
20	25	193.935	193.988	0.053
20	26	196.885	195.331	-1.554
20	27	194.994	194.297	-0.697
35	28	192.515	192.446	-0.069
35	29	194.897	194.316	-0.581
35	30	193.627	193.592	-0.035
35	31	198.441	197.885	-0.556
35	32	196.715	196.851	0.136
30	33	195.836	196.169	0.333
30	34	192.994	193.967	0.973
30	35	192.486	191.036	-1.450
30	36	194.725	195.090	0.365
30	37	191.192	191.737	0.545
	Max	198.665	199.606	0.973
	Average	194.809	194.607	-0.202
	Min	190.859	190.627	-2.555
	Std Dev	2.431	2.481	0.847



	26.6_VCC 5.0V ABSMAX EN Low			
Test Site				
Tester				
Test Number				
Max Limit	220	uA		
Min Limit	150	uA		
kRad(Si)	20	25	30	35
LL	150.000	150.000	150.000	150.000
Min	190.627	192.392	191.036	192.446
Average	194.324	196.450	193.600	195.018
Max	198.300	199.606	196.169	197.885
UL	220.000	220.000	220.000	220.000

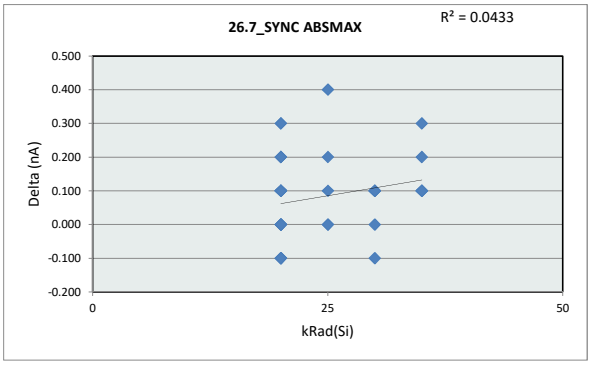


LDR TID Report
TPS7H4010-SEP

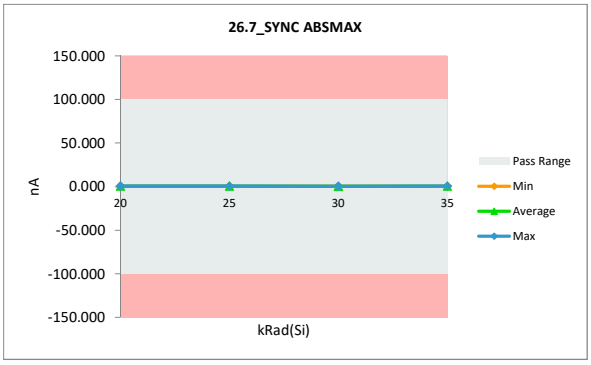
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.7_SYNC ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	100	100
Min Limit	-100	-100

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.300	0.700	0.400
25	2	0.300	0.500	0.200
25	3	0.500	0.500	0.000
25	4	0.600	0.600	0.000
25	5	0.400	0.500	0.100
20	6	0.400	0.700	0.300
20	7	0.500	0.800	0.300
20	8	0.500	0.600	0.100
20	9	0.500	0.500	0.000
20	10	0.500	0.600	0.100
20	11	0.500	0.500	0.000
20	12	0.900	0.900	0.000
20	13	0.400	0.400	0.000
20	14	0.400	0.500	0.100
20	15	0.500	0.500	0.000
20	16	0.500	0.400	-0.100
20	17	0.300	0.500	0.200
20	18	0.600	0.500	-0.100
20	19	0.500	0.400	-0.100
20	20	0.400	0.300	-0.100
20	21	0.500	0.600	0.100
20	22	0.500	0.500	0.000
20	23	0.400	0.600	0.200
20	24	0.400	0.600	0.200
20	25	0.400	0.500	0.100
20	26	0.500	0.400	-0.100
20	27	0.700	0.800	0.100
35	28	0.200	0.500	0.300
35	29	0.500	0.600	0.100
35	30	0.400	0.600	0.200
35	31	0.500	0.600	0.100
35	32	0.600	0.700	0.100
30	33	0.500	0.500	0.000
30	34	0.500	0.400	-0.100
30	35	0.400	0.500	0.100
30	36	0.500	0.600	0.100
30	37	0.300	0.400	0.100
	Max	0.900	0.900	0.400
	Average	0.468	0.549	0.081
	Min	0.200	0.300	-0.100
	Std Dev	0.123	0.126	0.127



	26.7_SYNC ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	100	nA		
Min Limit	-100	nA		
kRad(Si)	20	25	30	35
LL	-100.000	-100.000	-100.000	-100.000
Min	0.300	0.500	0.400	0.500
Average	0.550	0.560	0.480	0.600
Max	0.900	0.700	0.600	0.700
UL	100.000	100.000	100.000	100.000

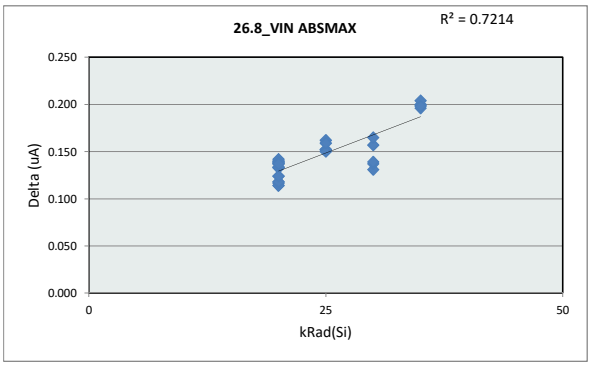


LDR TID Report
TPS7H4010-SEP

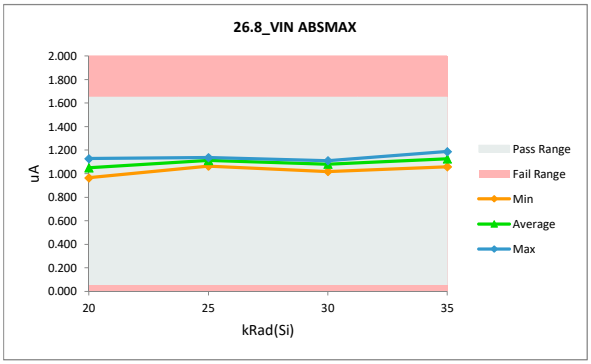
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.8_VIN ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	1.65	1.65
Min Limit	0.05	0.05

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.985	1.137	0.152
25	2	0.953	1.115	0.162
25	3	0.913	1.065	0.152
25	4	0.982	1.132	0.150
25	5	0.953	1.112	0.159
20	6	0.948	1.062	0.114
20	7	0.874	1.007	0.133
20	8	0.967	1.083	0.116
20	9	0.908	1.048	0.140
20	10	0.922	1.060	0.138
20	11	0.934	1.072	0.138
20	12	0.841	0.965	0.124
20	13	0.920	1.060	0.140
20	14	0.868	1.007	0.139
20	15	0.973	1.091	0.118
20	16	0.903	1.036	0.133
20	17	0.934	1.071	0.137
20	18	0.969	1.083	0.114
20	19	0.954	1.071	0.117
20	20	0.961	1.079	0.118
20	21	0.917	1.050	0.133
20	22	0.933	1.075	0.142
20	23	0.853	0.992	0.139
20	24	0.892	1.026	0.134
20	25	0.917	1.054	0.137
20	26	0.875	1.012	0.137
20	27	1.004	1.128	0.124
35	28	0.958	1.158	0.200
35	29	0.909	1.108	0.199
35	30	0.855	1.059	0.204
35	31	0.921	1.117	0.196
35	32	0.990	1.188	0.198
30	33	0.957	1.088	0.131
30	34	0.953	1.090	0.137
30	35	0.862	1.019	0.157
30	36	0.946	1.111	0.165
30	37	0.961	1.100	0.139
	Max	1.004	1.188	0.204
	Average	0.929	1.074	0.145
	Min	0.841	0.965	0.114
	Std Dev	0.042	0.047	0.025



	26.8_VIN ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	1.65	uA		
Min Limit	0.05	uA		
kRad(Si)	20	25	30	35
LL	0.050	0.050	0.050	0.050
Min	0.965	1.065	1.019	1.059
Average	1.051	1.112	1.082	1.126
Max	1.128	1.137	1.111	1.188
UL	1.650	1.650	1.650	1.650

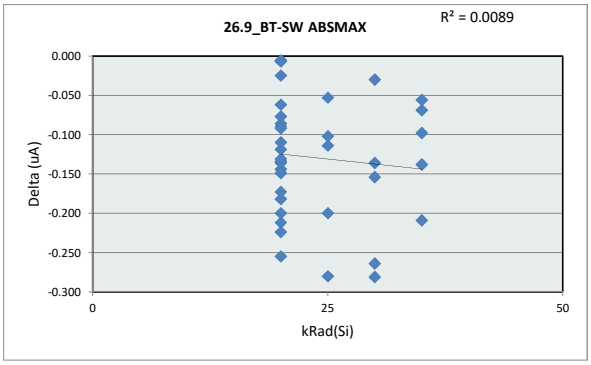


LDR TID Report
TPS7H4010-SEP

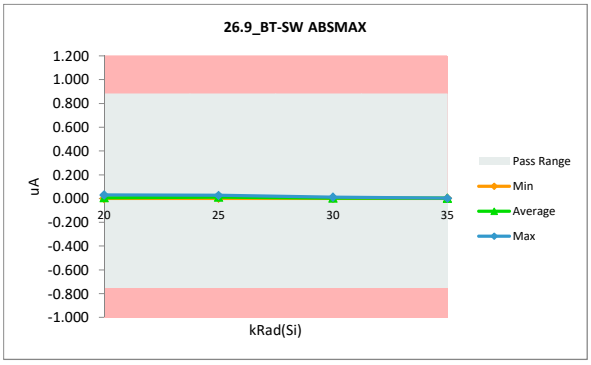
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.9_BT-SW ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	0.88	0.88
Min Limit	-0.75	-0.75

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.107	0.005	-0.102
25	2	0.299	0.019	-0.280
25	3	0.119	0.005	-0.114
25	4	0.055	0.002	-0.053
25	5	0.227	0.027	-0.200
20	6	0.217	0.005	-0.212
20	7	0.009	0.002	-0.007
20	8	0.272	0.017	-0.255
20	9	0.027	0.002	-0.025
20	10	0.121	0.002	-0.119
20	11	0.153	0.009	-0.144
20	12	0.007	0.001	-0.006
20	13	0.136	0.002	-0.134
20	14	0.139	0.003	-0.136
20	15	0.140	0.009	-0.131
20	16	0.091	0.001	-0.090
20	17	0.119	0.009	-0.110
20	18	0.199	0.017	-0.182
20	19	0.200	0.027	-0.173
20	20	0.214	0.014	-0.200
20	21	0.008	0.002	-0.006
20	22	0.088	0.002	-0.086
20	23	0.094	0.002	-0.092
20	24	0.153	0.004	-0.149
20	25	0.079	0.002	-0.077
20	26	0.063	0.001	-0.062
20	27	0.254	0.030	-0.224
35	28	0.100	0.002	-0.098
35	29	0.212	0.003	-0.209
35	30	0.058	0.002	-0.056
35	31	0.141	0.003	-0.138
35	32	0.071	0.002	-0.069
30	33	0.293	0.012	-0.281
30	34	0.138	0.002	-0.136
30	35	0.032	0.002	-0.030
30	36	0.156	0.002	-0.154
30	37	0.266	0.002	-0.264
	Max	0.299	0.030	-0.006
	Average	0.137	0.007	-0.130
	Min	0.007	0.001	-0.281
	Std Dev	0.082	0.008	0.077



	26.9_BT-SW ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	0.88	uA		
Min Limit	-0.75	uA		
kRad(Si)	20	25	30	35
LL	-0.750	-0.750	-0.750	-0.750
Min	0.001	0.002	0.002	0.002
Average	0.007	0.012	0.004	0.002
Max	0.030	0.027	0.012	0.003
UL	0.880	0.880	0.880	0.880

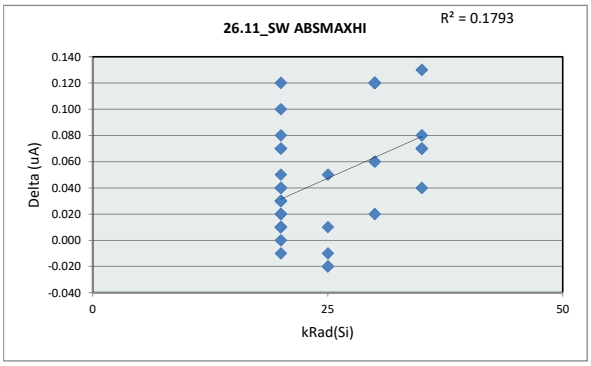


LDR TID Report
TPS7H4010-SEP

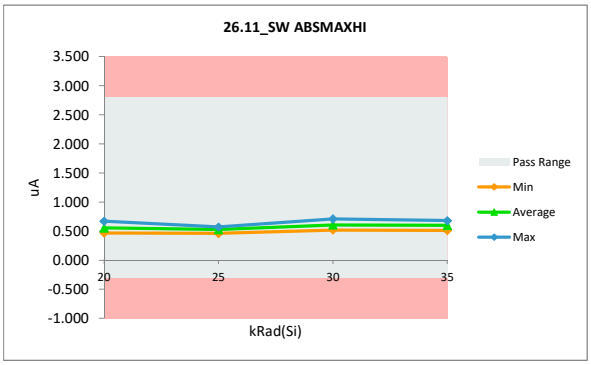
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.11_SW ABSMAXHI	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	2.8	2.8
Min Limit	-0.3	-0.3

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.530	0.540	0.010
25	2	0.480	0.460	-0.020
25	3	0.510	0.500	-0.010
25	4	0.590	0.570	-0.020
25	5	0.520	0.570	0.050
20	6	0.440	0.470	0.030
20	7	0.490	0.500	0.010
20	8	0.510	0.530	0.020
20	9	0.540	0.550	0.010
20	10	0.540	0.610	0.070
20	11	0.470	0.470	0.000
20	12	0.540	0.530	-0.010
20	13	0.520	0.620	0.100
20	14	0.470	0.510	0.040
20	15	0.540	0.590	0.050
20	16	0.540	0.610	0.070
20	17	0.500	0.530	0.030
20	18	0.600	0.610	0.010
20	19	0.500	0.540	0.040
20	20	0.570	0.590	0.020
20	21	0.480	0.490	0.010
20	22	0.540	0.550	0.010
20	23	0.490	0.510	0.020
20	24	0.590	0.670	0.080
20	25	0.510	0.630	0.120
20	26	0.510	0.540	0.030
20	27	0.530	0.570	0.040
35	28	0.530	0.600	0.070
35	29	0.470	0.510	0.040
35	30	0.460	0.540	0.080
35	31	0.550	0.680	0.130
35	32	0.610	0.680	0.070
30	33	0.540	0.560	0.020
30	34	0.460	0.520	0.060
30	35	0.480	0.600	0.120
30	36	0.590	0.710	0.120
30	37	0.520	0.640	0.120
	Max	0.610	0.710	0.130
	Average	0.521	0.565	0.044
	Min	0.440	0.460	-0.020
	Std Dev	0.042	0.063	0.043



	26.11_SW ABSMAXHI			
Test Site				
Tester				
Test Number				
Max Limit	2.8	uA		
Min Limit	-0.3	uA		
kRad(Si)	20	25	30	35
LL	-0.300	-0.300	-0.300	-0.300
Min	0.470	0.460	0.520	0.510
Average	0.555	0.528	0.606	0.602
Max	0.670	0.570	0.710	0.680
UL	2.800	2.800	2.800	2.800

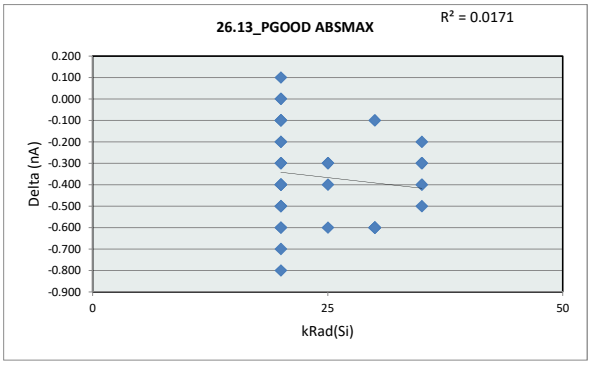


LDR TID Report
TPS7H4010-SEP

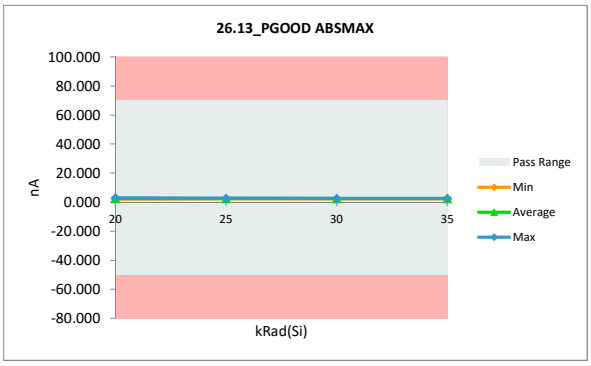
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.13_PGOOD ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	70	70
Min Limit	-50	-50

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.000	2.700	-0.300
25	2	3.000	2.700	-0.300
25	3	3.000	2.400	-0.600
25	4	2.900	2.600	-0.300
25	5	2.800	2.400	-0.400
20	6	2.800	2.500	-0.300
20	7	2.700	2.600	-0.100
20	8	2.700	2.500	-0.200
20	9	2.700	2.600	-0.100
20	10	2.800	2.800	0.000
20	11	2.800	2.400	-0.400
20	12	2.700	2.600	-0.100
20	13	2.900	2.400	-0.500
20	14	2.900	2.900	0.000
20	15	2.800	2.400	-0.400
20	16	3.100	2.600	-0.500
20	17	2.800	2.600	-0.200
20	18	2.700	2.400	-0.300
20	19	3.100	2.400	-0.700
20	20	3.200	2.400	-0.800
20	21	2.800	2.500	-0.300
20	22	3.100	2.500	-0.600
20	23	2.700	2.800	0.100
20	24	2.800	2.400	-0.400
20	25	2.700	2.200	-0.500
20	26	2.700	2.300	-0.400
20	27	2.900	2.300	-0.600
35	28	2.700	2.500	-0.200
35	29	3.100	2.600	-0.500
35	30	2.900	2.600	-0.300
35	31	2.800	2.500	-0.300
35	32	2.800	2.400	-0.400
30	33	2.700	2.600	-0.100
30	34	2.900	2.300	-0.600
30	35	3.000	2.400	-0.600
30	36	3.000	2.400	-0.600
30	37	3.200	2.600	-0.600
	Max	3.200	2.900	0.100
	Average	2.870	2.508	-0.362
	Min	2.700	2.200	-0.800
	Std Dev	0.154	0.153	0.214



	26.13_PGOOD ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	70	nA		
Min Limit	-50	nA		
kRad(Si)	20	25	30	35
LL	-50.000	-50.000	-50.000	-50.000
Min	2.200	2.400	2.300	2.400
Average	2.505	2.560	2.460	2.520
Max	2.900	2.700	2.600	2.600
UL	70.000	70.000	70.000	70.000

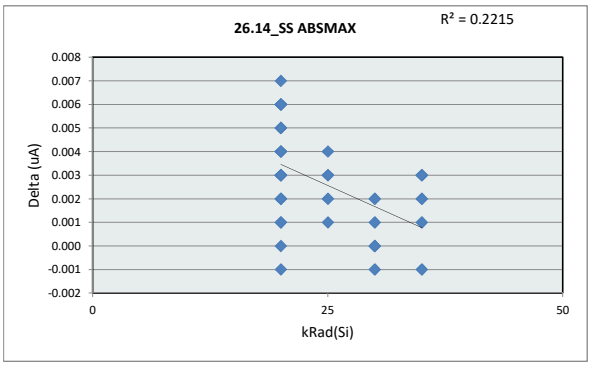


LDR TID Report
TPS7H4010-SEP

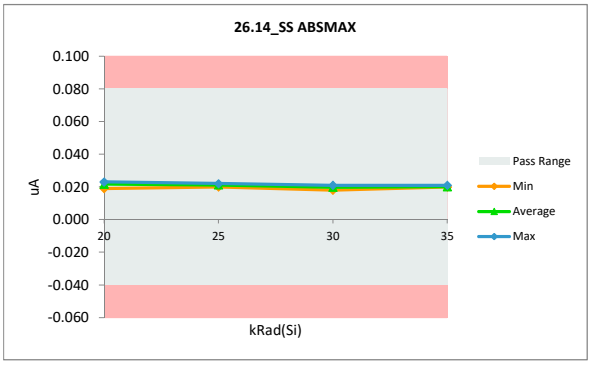
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.14_SS ABSMAX	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	0.08	0.08
Min Limit	-0.04	-0.04

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.019	0.022	0.003
25	2	0.017	0.020	0.003
25	3	0.018	0.022	0.004
25	4	0.021	0.022	0.001
25	5	0.018	0.020	0.002
20	6	0.016	0.022	0.006
20	7	0.018	0.019	0.001
20	8	0.018	0.020	0.002
20	9	0.020	0.019	-0.001
20	10	0.018	0.022	0.004
20	11	0.019	0.022	0.003
20	12	0.019	0.021	0.002
20	13	0.017	0.023	0.006
20	14	0.018	0.021	0.003
20	15	0.016	0.023	0.007
20	16	0.017	0.023	0.006
20	17	0.021	0.022	0.001
20	18	0.020	0.023	0.003
20	19	0.017	0.021	0.004
20	20	0.017	0.022	0.005
20	21	0.017	0.021	0.004
20	22	0.021	0.021	0.000
20	23	0.019	0.022	0.003
20	24	0.018	0.021	0.003
20	25	0.017	0.023	0.006
20	26	0.018	0.023	0.005
20	27	0.018	0.023	0.005
35	28	0.017	0.020	0.003
35	29	0.017	0.020	0.003
35	30	0.018	0.020	0.002
35	31	0.021	0.020	-0.001
35	32	0.020	0.021	0.001
30	33	0.021	0.020	-0.001
30	34	0.018	0.018	0.000
30	35	0.020	0.020	0.000
30	36	0.020	0.021	0.001
30	37	0.018	0.020	0.002
	Max	0.021	0.023	0.007
	Average	0.018	0.021	0.003
	Min	0.016	0.018	-0.001
	Std Dev	0.001	0.001	0.002



	26.14_SS ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	0.08	uA		
Min Limit	-0.04	uA		
kRad(Si)	20	25	30	35
LL	-0.040	-0.040	-0.040	-0.040
Min	0.019	0.020	0.018	0.020
Average	0.022	0.021	0.020	0.020
Max	0.023	0.022	0.021	0.021
UL	0.080	0.080	0.080	0.080

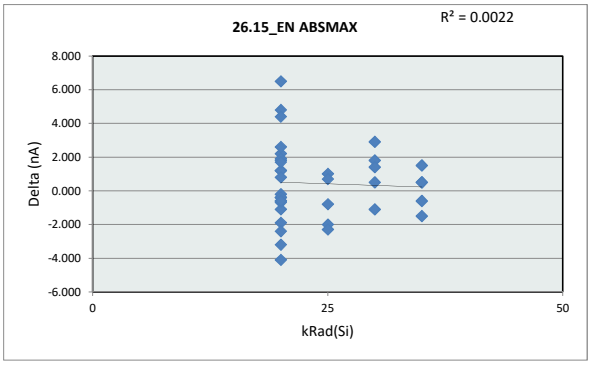


LDR TID Report
TPS7H4010-SEP

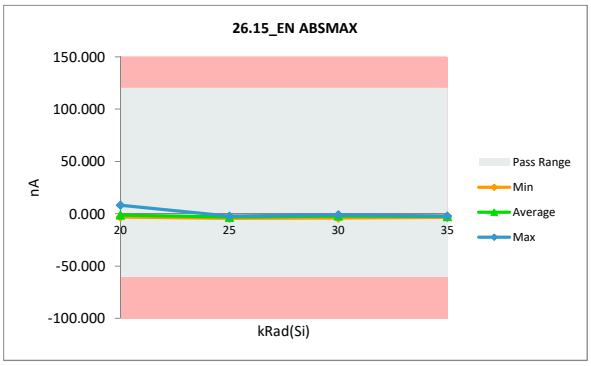
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	26.15_EN ABSMAX	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	120	120
Min Limit	-60	-60

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	-1.800	-3.800	-2.000
25	2	-3.900	-2.900	1.000
25	3	-3.800	-3.100	0.700
25	4	-1.900	-4.200	-2.300
25	5	-1.400	-2.200	-0.800
20	6	-2.400	-1.200	1.200
20	7	-3.500	1.300	4.800
20	8	-1.200	-1.600	-0.400
20	9	-0.500	-2.400	-1.900
20	10	-0.100	-0.800	-0.700
20	11	-2.300	-1.100	1.200
20	12	1.800	8.300	6.500
20	13	0.900	-2.300	-3.200
20	14	-3.000	-2.200	0.800
20	15	0.000	-0.200	-0.200
20	16	-0.500	-2.900	-2.400
20	17	-1.400	-2.500	-1.100
20	18	-4.700	-2.900	1.800
20	19	1.200	-2.900	-4.100
20	20	-1.400	-1.800	-0.400
20	21	-0.700	-1.300	-0.600
20	22	-3.300	-1.100	2.200
20	23	-3.900	-2.000	1.900
20	24	-5.800	-1.400	4.400
20	25	-2.000	-0.300	1.700
20	26	-2.900	-0.300	2.600
20	27	-2.400	-3.000	-0.600
35	28	-3.600	-2.100	1.500
35	29	-1.900	-2.500	-0.600
35	30	-3.000	-2.500	0.500
35	31	-0.900	-2.400	-1.500
35	32	-4.000	-3.500	0.500
30	33	-3.500	-1.700	1.800
30	34	-4.500	-4.000	0.500
30	35	-3.800	-0.900	2.900
30	36	-3.200	-1.800	1.400
30	37	-0.700	-1.800	-1.100
	Max	1.800	8.300	6.500
	Average	-2.162	-1.730	0.432
	Min	-5.800	-4.200	-4.100
	Std Dev	1.746	2.044	2.196



	26.15_EN ABSMAX			
Test Site				
Tester				
Test Number				
Max Limit	120	nA		
Min Limit	-60	nA		
kRad(Si)	20	25	30	35
LL	-60.000	-60.000	-60.000	-60.000
Min	-3.000	-4.200	-4.000	-3.500
Average	-1.118	-3.240	-2.040	-2.600
Max	8.300	-2.200	-0.900	-2.100
UL	120.000	120.000	120.000	120.000

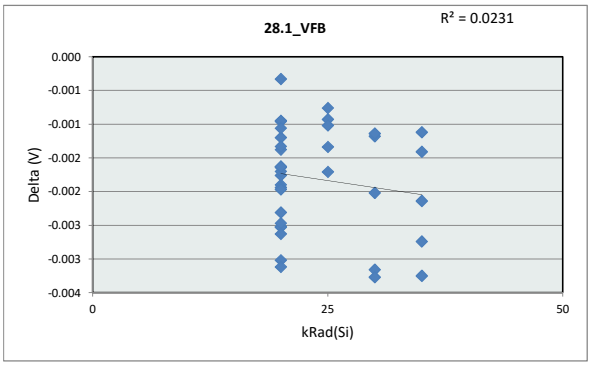


LDR TID Report
TPS7H4010-SEP

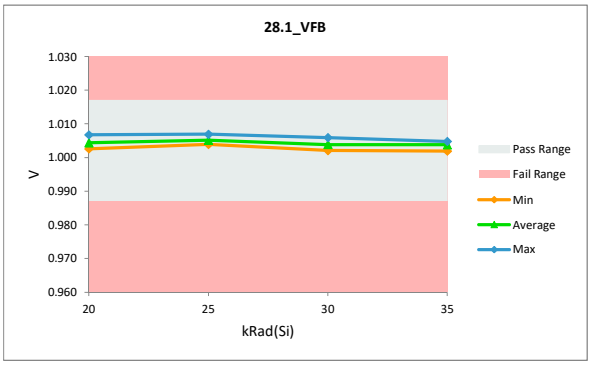
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	28.1_VFB	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.017	1.017
Min Limit	0.987	0.987

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.008	1.007	-0.001
25	2	1.007	1.006	-0.001
25	3	1.006	1.004	-0.002
25	4	1.005	1.004	-0.001
25	5	1.006	1.005	-0.001
20	6	1.007	1.005	-0.002
20	7	1.006	1.004	-0.002
20	8	1.005	1.004	-0.001
20	9	1.006	1.005	-0.001
20	10	1.006	1.005	-0.001
20	11	1.006	1.004	-0.001
20	12	1.006	1.004	-0.002
20	13	1.007	1.004	-0.003
20	14	1.005	1.003	-0.003
20	15	1.007	1.007	0.000
20	16	1.004	1.003	-0.002
20	17	1.007	1.006	-0.002
20	18	1.006	1.003	-0.002
20	19	1.006	1.003	-0.003
20	20	1.006	1.004	-0.002
20	21	1.007	1.004	-0.003
20	22	1.006	1.004	-0.002
20	23	1.006	1.005	-0.001
20	24	1.007	1.005	-0.002
20	25	1.007	1.005	-0.003
20	26	1.006	1.004	-0.002
20	27	1.007	1.006	-0.001
35	28	1.006	1.005	-0.001
35	29	1.006	1.004	-0.001
35	30	1.005	1.002	-0.003
35	31	1.006	1.003	-0.003
35	32	1.007	1.004	-0.002
30	33	1.008	1.004	-0.003
30	34	1.005	1.002	-0.003
30	35	1.005	1.003	-0.002
30	36	1.005	1.003	-0.001
30	37	1.007	1.006	-0.001
	Max	1.008	1.007	0.000
	Average	1.006	1.004	-0.002
	Min	1.004	1.002	-0.003
	Std Dev	0.001	0.001	0.001



	28.1_VFB			
Test Site				
Tester				
Test Number				
Max Limit	1.017	V		
Min Limit	0.987	V		
kRad(Si)	20	25	30	35
LL	0.987	0.987	0.987	0.987
Min	1.003	1.004	1.002	1.002
Average	1.004	1.005	1.004	1.004
Max	1.007	1.007	1.006	1.005
UL	1.017	1.017	1.017	1.017

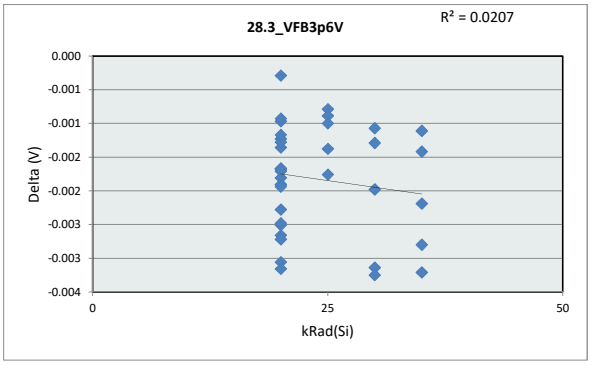


LDR TID Report
TPS7H4010-SEP

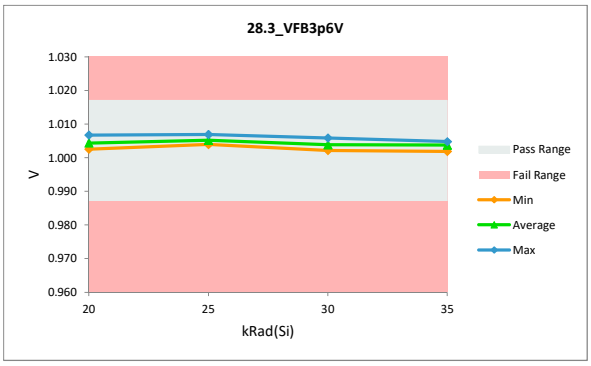
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	28.3_VFB3p6V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.017	1.017
Min Limit	0.987	0.987

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.008	1.007	-0.001
25	2	1.007	1.006	-0.001
25	3	1.006	1.004	-0.002
25	4	1.005	1.004	-0.001
25	5	1.006	1.005	-0.001
20	6	1.007	1.005	-0.002
20	7	1.006	1.004	-0.002
20	8	1.005	1.004	-0.001
20	9	1.006	1.005	-0.001
20	10	1.006	1.005	-0.001
20	11	1.006	1.004	-0.001
20	12	1.006	1.004	-0.002
20	13	1.007	1.004	-0.003
20	14	1.005	1.003	-0.003
20	15	1.007	1.007	0.000
20	16	1.004	1.003	-0.002
20	17	1.007	1.006	-0.002
20	18	1.006	1.003	-0.002
20	19	1.006	1.003	-0.003
20	20	1.006	1.004	-0.002
20	21	1.007	1.004	-0.003
20	22	1.006	1.004	-0.002
20	23	1.006	1.005	-0.001
20	24	1.007	1.005	-0.002
20	25	1.007	1.005	-0.003
20	26	1.006	1.004	-0.002
20	27	1.008	1.006	-0.001
35	28	1.006	1.005	-0.001
35	29	1.006	1.004	-0.001
35	30	1.005	1.002	-0.003
35	31	1.006	1.003	-0.003
35	32	1.007	1.004	-0.002
30	33	1.008	1.004	-0.003
30	34	1.005	1.002	-0.003
30	35	1.005	1.004	-0.002
30	36	1.005	1.003	-0.001
30	37	1.007	1.006	-0.001
	Max	1.008	1.007	0.000
	Average	1.006	1.004	-0.002
	Min	1.004	1.002	-0.003
	Std Dev	0.001	0.001	0.001



	28.3_VFB3p6V			
Test Site				
Tester				
Test Number				
Max Limit	1.017	V		
Min Limit	0.987	V		
kRad(Si)	20	25	30	35
LL	0.987	0.987	0.987	0.987
Min	1.003	1.004	1.002	1.002
Average	1.004	1.005	1.004	1.004
Max	1.007	1.007	1.006	1.005
UL	1.017	1.017	1.017	1.017

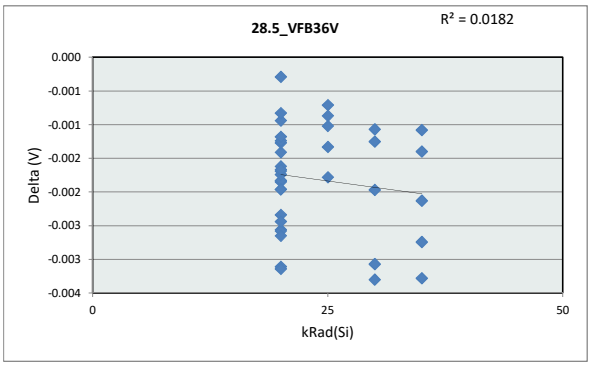


LDR TID Report
TPS7H4010-SEP

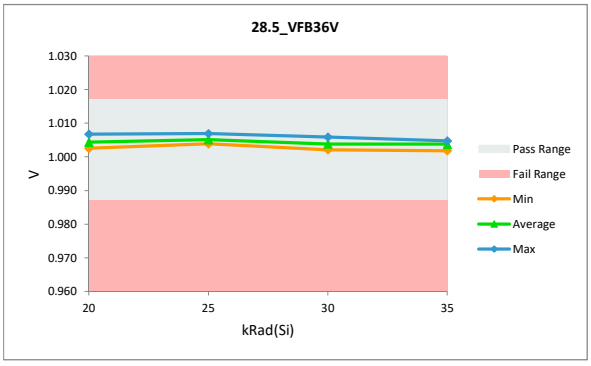
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	28.5_VFB36V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.017	1.017
Min Limit	0.987	0.987

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.008	1.007	-0.001
25	2	1.007	1.006	-0.001
25	3	1.006	1.004	-0.002
25	4	1.005	1.004	-0.001
25	5	1.006	1.005	-0.001
20	6	1.007	1.005	-0.002
20	7	1.006	1.004	-0.002
20	8	1.005	1.004	-0.001
20	9	1.006	1.005	-0.001
20	10	1.006	1.005	-0.001
20	11	1.006	1.004	-0.001
20	12	1.006	1.004	-0.002
20	13	1.007	1.004	-0.003
20	14	1.005	1.003	-0.003
20	15	1.007	1.007	0.000
20	16	1.004	1.003	-0.002
20	17	1.007	1.006	-0.002
20	18	1.006	1.003	-0.002
20	19	1.006	1.003	-0.003
20	20	1.006	1.004	-0.002
20	21	1.007	1.004	-0.003
20	22	1.006	1.004	-0.002
20	23	1.006	1.005	-0.001
20	24	1.007	1.005	-0.002
20	25	1.007	1.005	-0.003
20	26	1.006	1.004	-0.002
20	27	1.008	1.006	-0.001
35	28	1.006	1.005	-0.001
35	29	1.006	1.004	-0.001
35	30	1.005	1.002	-0.003
35	31	1.006	1.003	-0.003
35	32	1.007	1.004	-0.002
30	33	1.008	1.004	-0.003
30	34	1.005	1.002	-0.003
30	35	1.005	1.003	-0.002
30	36	1.005	1.003	-0.001
30	37	1.007	1.006	-0.001
	Max	1.008	1.007	0.000
	Average	1.006	1.004	-0.002
	Min	1.004	1.002	-0.003
	Std Dev	0.001	0.001	0.001



	28.5_VFB36V			
Test Site				
Tester				
Test Number				
Max Limit	1.017	V		
Min Limit	0.987	V		
kRad(Si)	20	25	30	35
LL	0.987	0.987	0.987	0.987
Min	1.003	1.004	1.002	1.002
Average	1.004	1.005	1.004	1.004
Max	1.007	1.007	1.006	1.005
UL	1.017	1.017	1.017	1.017

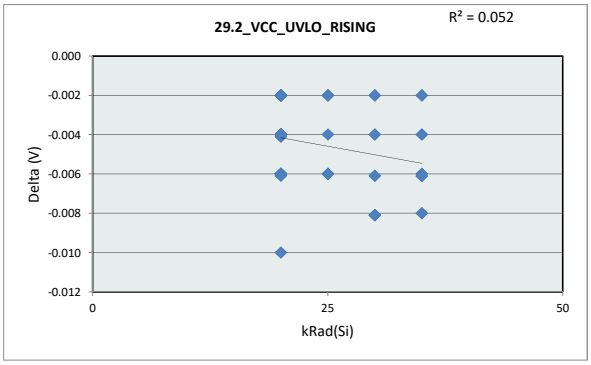


LDR TID Report
TPS7H4010-SEP

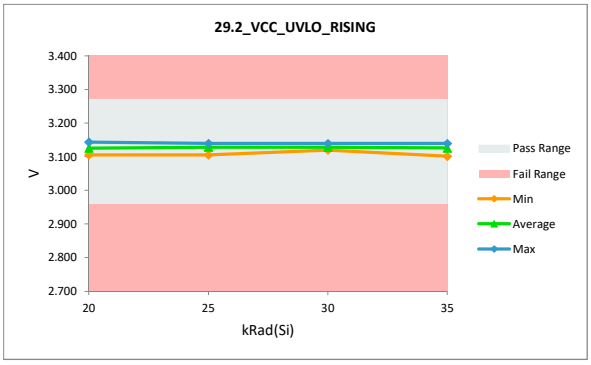
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.2_VCC_UVLO_RISING	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.27	3.27
Min Limit	2.96	2.96

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.139	3.137	-0.002
25	2	3.123	3.121	-0.002
25	3	3.111	3.105	-0.006
25	4	3.145	3.139	-0.006
25	5	3.141	3.137	-0.004
20	6	3.135	3.131	-0.004
20	7	3.119	3.113	-0.006
20	8	3.135	3.133	-0.002
20	9	3.143	3.139	-0.004
20	10	3.125	3.121	-0.004
20	11	3.131	3.129	-0.002
20	12	3.119	3.117	-0.002
20	13	3.141	3.131	-0.010
20	14	3.123	3.121	-0.002
20	15	3.129	3.127	-0.002
20	16	3.147	3.143	-0.004
20	17	3.137	3.135	-0.002
20	18	3.133	3.129	-0.004
20	19	3.139	3.133	-0.006
20	20	3.139	3.135	-0.004
20	21	3.111	3.105	-0.006
20	22	3.115	3.109	-0.006
20	23	3.109	3.107	-0.002
20	24	3.121	3.117	-0.004
20	25	3.137	3.131	-0.006
20	26	3.127	3.121	-0.006
20	27	3.135	3.131	-0.004
35	28	3.133	3.131	-0.002
35	29	3.139	3.133	-0.006
35	30	3.109	3.101	-0.008
35	31	3.129	3.123	-0.006
35	32	3.143	3.139	-0.004
30	33	3.131	3.123	-0.008
30	34	3.127	3.119	-0.008
30	35	3.127	3.121	-0.006
30	36	3.141	3.139	-0.002
30	37	3.141	3.137	-0.004
	Max	3.147	3.143	-0.002
	Average	3.131	3.126	-0.005
	Min	3.109	3.101	-0.010
	Std Dev	0.011	0.011	0.002



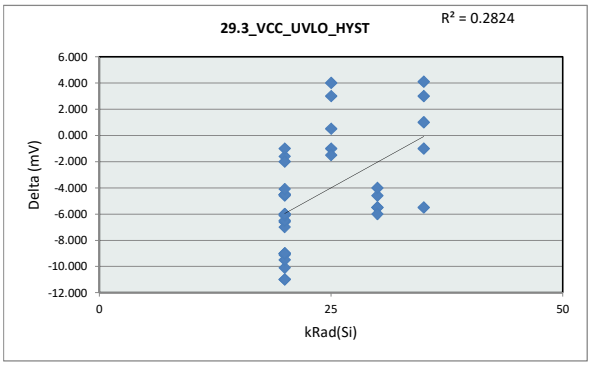
	29.2_VCC_UVLO_RISING			
Test Site				
Tester				
Test Number				
Max Limit	3.27	V		
Min Limit	2.96	V		
kRad(Si)	20	25	30	35
LL	2.960	2.960	2.960	2.960
Min	3.105	3.105	3.119	3.101
Average	3.126	3.128	3.128	3.126
Max	3.143	3.139	3.139	3.139
UL	3.270	3.270	3.270	3.270



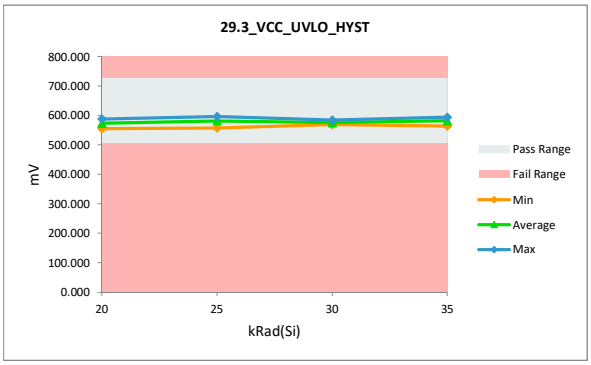
LDR TID Report
TPS7H4010-SEP

Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

		29.3_VCC_UVLO_HYST	
Test Site			
Tester			
Test Number			
Unit		mV	mV
Max Limit		725	725
Min Limit		505	505
kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	586.600	587.100	0.500
25	2	570.600	573.600	3.000
25	3	558.600	557.600	-1.000
25	4	592.700	596.700	4.000
25	5	593.700	592.200	-1.500
20	6	587.700	586.100	-1.600
20	7	569.100	558.100	-11.000
20	8	590.200	585.600	-4.600
20	9	593.200	586.600	-6.600
20	10	575.100	566.100	-9.000
20	11	578.600	576.600	-2.000
20	12	569.100	564.600	-4.500
20	13	593.700	583.600	-10.100
20	14	570.600	566.100	-4.500
20	15	576.600	572.100	-4.500
20	16	592.200	588.100	-4.100
20	17	582.100	575.100	-7.000
20	18	580.600	574.100	-6.500
20	19	591.700	585.600	-6.100
20	20	591.700	582.600	-9.100
20	21	566.100	565.100	-1.000
20	22	570.100	559.100	-11.000
20	23	564.100	554.600	-9.500
20	24	573.600	564.600	-9.000
20	25	584.600	578.600	-6.000
20	26	572.100	566.100	-6.000
20	27	582.600	573.600	-9.000
35	28	575.600	578.600	3.000
35	29	586.600	590.700	4.100
35	30	569.100	563.600	-5.500
35	31	586.700	585.700	-1.000
35	32	593.200	594.200	1.000
30	33	581.100	575.600	-5.500
30	34	574.600	569.100	-5.500
30	35	574.600	568.600	-6.000
30	36	588.700	584.100	-4.600
30	37	586.100	582.100	-4.000
	Max	593.700	596.700	4.100
	Average	580.376	576.005	-4.370
	Min	558.600	554.600	-11.000
	Std Dev	9.858	11.281	4.163



	29.3_VCC_UVLO_HYST			
Test Site				
Tester				
Test Number				
Max Limit	725	mV		
Min Limit	505	mV		
kRad(Si)	20	25	30	35
LL	505.000	505.000	505.000	505.000
Min	554.600	557.600	568.600	563.600
Average	573.305	581.440	575.900	582.560
Max	588.100	596.700	584.100	594.200
UL	725.000	725.000	725.000	725.000

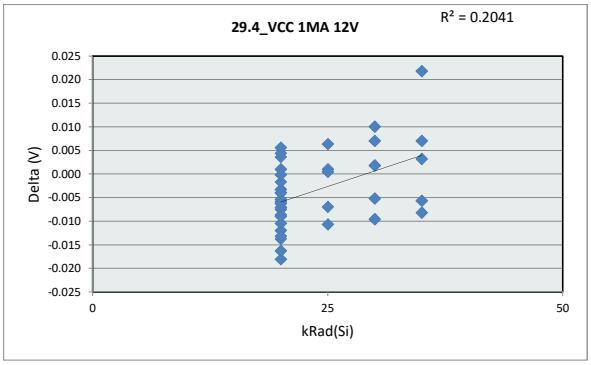


LDR TID Report
TPS7H4010-SEP

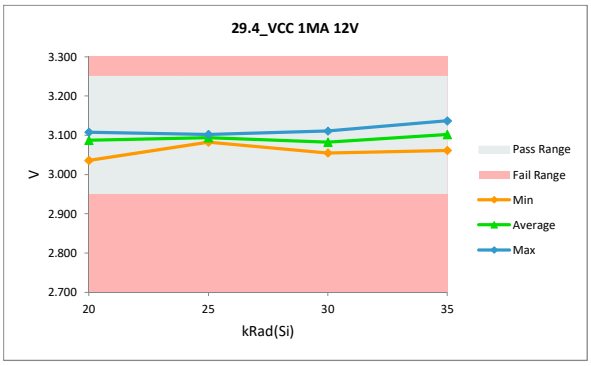
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.4_VCC 1MA 12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	2.95	2.95

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.081	3.088	0.006
25	2	3.093	3.083	-0.011
25	3	3.109	3.102	-0.007
25	4	3.101	3.102	0.001
25	5	3.093	3.093	0.000
20	6	3.081	3.077	-0.004
20	7	3.114	3.106	-0.008
20	8	3.100	3.101	0.001
20	9	3.109	3.095	-0.014
20	10	3.088	3.084	-0.003
20	11	3.048	3.036	-0.012
20	12	3.066	3.064	-0.002
20	13	3.093	3.083	-0.010
20	14	3.096	3.091	-0.005
20	15	3.080	3.071	-0.009
20	16	3.099	3.102	0.004
20	17	3.102	3.083	-0.018
20	18	3.105	3.104	0.000
20	19	3.103	3.096	-0.007
20	20	3.111	3.098	-0.013
20	21	3.114	3.108	-0.006
20	22	3.085	3.090	0.004
20	23	3.086	3.082	-0.004
20	24	3.092	3.085	-0.006
20	25	3.084	3.089	0.006
20	26	3.092	3.082	-0.009
20	27	3.107	3.091	-0.016
35	28	3.115	3.137	0.022
35	29	3.101	3.108	0.007
35	30	3.088	3.080	-0.008
35	31	3.067	3.061	-0.006
35	32	3.119	3.122	0.003
30	33	3.104	3.111	0.007
30	34	3.080	3.090	0.010
30	35	3.064	3.055	-0.010
30	36	3.065	3.066	0.002
30	37	3.094	3.089	-0.005
	Max	3.119	3.137	0.022
	Average	3.093	3.089	-0.003
	Min	3.048	3.036	-0.018
	Std Dev	0.016	0.019	0.008



	29.4_VCC 1MA 12V			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	2.95	V		
kRad(Si)	20	25	30	35
LL	2.950	2.950	2.950	2.950
Min	3.036	3.083	3.055	3.061
Average	3.087	3.093	3.082	3.102
Max	3.108	3.102	3.111	3.137
UL	3.250	3.250	3.250	3.250

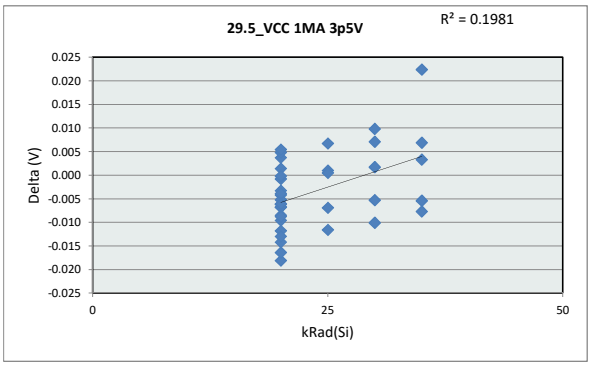


LDR TID Report
TPS7H4010-SEP

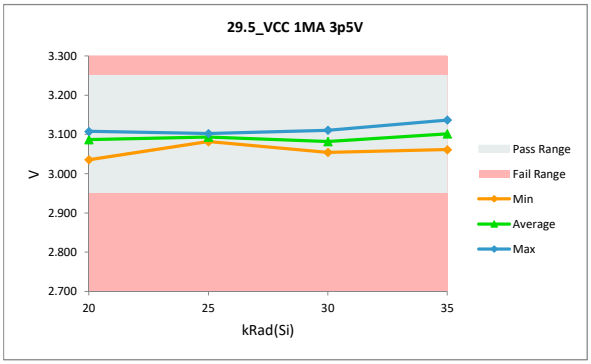
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.5_VCC 1MA 3p5V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	2.95	2.95

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.081	3.088	0.007
25	2	3.093	3.082	-0.012
25	3	3.109	3.102	-0.007
25	4	3.101	3.102	0.001
25	5	3.093	3.093	0.000
20	6	3.081	3.076	-0.004
20	7	3.114	3.107	-0.007
20	8	3.100	3.101	0.001
20	9	3.110	3.095	-0.014
20	10	3.088	3.084	-0.003
20	11	3.048	3.036	-0.012
20	12	3.065	3.064	-0.001
20	13	3.092	3.083	-0.010
20	14	3.096	3.090	-0.005
20	15	3.080	3.071	-0.008
20	16	3.099	3.102	0.004
20	17	3.101	3.083	-0.018
20	18	3.105	3.104	0.000
20	19	3.103	3.096	-0.007
20	20	3.111	3.098	-0.013
20	21	3.114	3.108	-0.006
20	22	3.085	3.090	0.005
20	23	3.086	3.082	-0.004
20	24	3.092	3.086	-0.006
20	25	3.083	3.089	0.005
20	26	3.091	3.082	-0.009
20	27	3.107	3.091	-0.016
35	28	3.115	3.137	0.022
35	29	3.101	3.108	0.007
35	30	3.088	3.080	-0.008
35	31	3.067	3.061	-0.005
35	32	3.119	3.122	0.003
30	33	3.104	3.111	0.007
30	34	3.080	3.090	0.010
30	35	3.064	3.054	-0.010
30	36	3.065	3.066	0.002
30	37	3.094	3.089	-0.005
	Max	3.119	3.137	0.022
	Average	3.092	3.089	-0.003
	Min	3.048	3.036	-0.018
	Std Dev	0.016	0.019	0.008



	29.5_VCC 1MA 3p5V			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	2.95	V		
kRad(Si)	20	25	30	35
LL	2.950	2.950	2.950	2.950
Min	3.036	3.082	3.054	3.061
Average	3.087	3.093	3.082	3.102
Max	3.108	3.102	3.111	3.137
UL	3.250	3.250	3.250	3.250

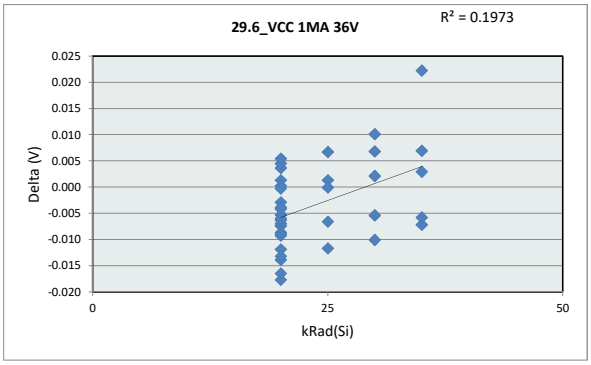


LDR TID Report
TPS7H4010-SEP

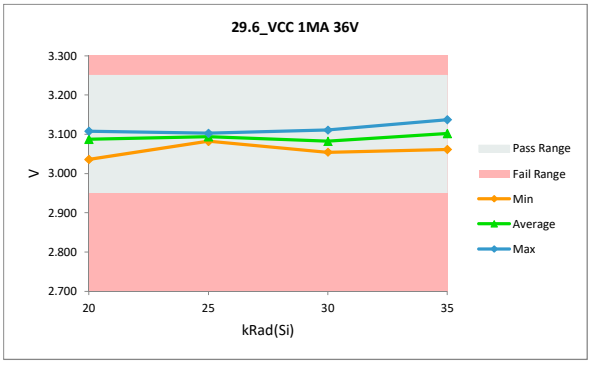
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.6_VCC 1MA 36V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	2.95	2.95

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.081	3.088	0.007
25	2	3.094	3.082	-0.012
25	3	3.108	3.102	-0.007
25	4	3.101	3.102	0.001
25	5	3.094	3.093	0.000
20	6	3.081	3.077	-0.004
20	7	3.114	3.106	-0.007
20	8	3.100	3.101	0.001
20	9	3.109	3.095	-0.014
20	10	3.087	3.085	-0.003
20	11	3.048	3.036	-0.012
20	12	3.065	3.065	0.000
20	13	3.092	3.083	-0.009
20	14	3.096	3.090	-0.005
20	15	3.080	3.071	-0.009
20	16	3.099	3.102	0.004
20	17	3.101	3.083	-0.018
20	18	3.105	3.104	0.000
20	19	3.103	3.096	-0.007
20	20	3.111	3.097	-0.013
20	21	3.114	3.108	-0.006
20	22	3.085	3.090	0.004
20	23	3.086	3.082	-0.004
20	24	3.092	3.086	-0.006
20	25	3.084	3.089	0.005
20	26	3.091	3.082	-0.009
20	27	3.108	3.091	-0.016
35	28	3.115	3.137	0.022
35	29	3.102	3.109	0.007
35	30	3.088	3.080	-0.007
35	31	3.067	3.061	-0.006
35	32	3.119	3.122	0.003
30	33	3.104	3.111	0.007
30	34	3.080	3.090	0.010
30	35	3.064	3.054	-0.010
30	36	3.064	3.066	0.002
30	37	3.094	3.089	-0.005
	Max	3.119	3.137	0.022
	Average	3.093	3.089	-0.003
	Min	3.048	3.036	-0.018
	Std Dev	0.016	0.019	0.008



	29.6_VCC 1MA 36V			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	2.95	V		
kRad(Si)	20	25	30	35
LL	2.950	2.950	2.950	2.950
Min	3.036	3.082	3.054	3.061
Average	3.087	3.094	3.082	3.102
Max	3.108	3.103	3.111	3.137
UL	3.250	3.250	3.250	3.250

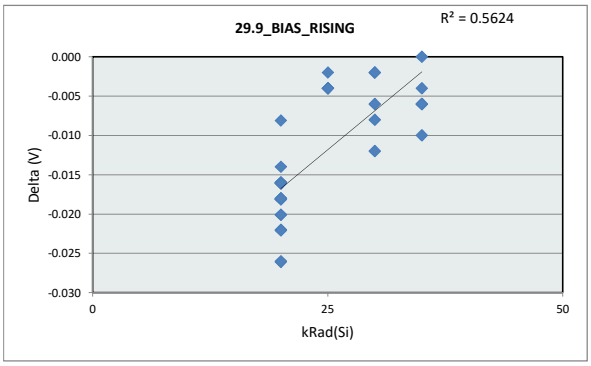


LDR TID Report
TPS7H4010-SEP

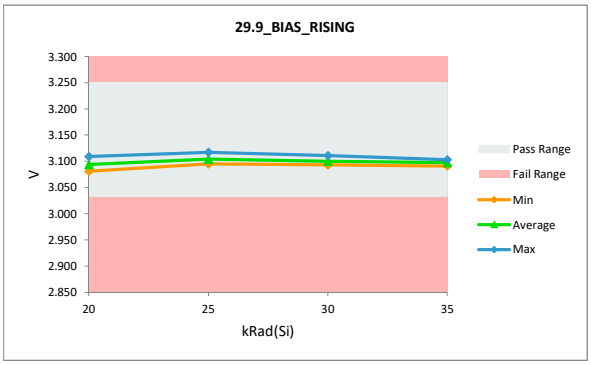
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.9_BIAS_RISING	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.25	3.25
Min Limit	3.03	3.03

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	3.105	3.103	-0.002
25	2	3.109	3.105	-0.004
25	3	3.099	3.095	-0.004
25	4	3.105	3.101	-0.004
25	5	3.121	3.117	-0.004
20	6	3.117	3.099	-0.018
20	7	3.113	3.091	-0.022
20	8	3.105	3.091	-0.014
20	9	3.119	3.101	-0.018
20	10	3.105	3.087	-0.018
20	11	3.105	3.089	-0.016
20	12	3.119	3.093	-0.026
20	13	3.103	3.087	-0.016
20	14	3.099	3.081	-0.018
20	15	3.121	3.105	-0.016
20	16	3.097	3.081	-0.016
20	17	3.119	3.101	-0.018
20	18	3.121	3.099	-0.022
20	19	3.103	3.087	-0.016
20	20	3.121	3.103	-0.018
20	21	3.113	3.087	-0.026
20	22	3.101	3.085	-0.016
20	23	3.115	3.095	-0.020
20	24	3.107	3.089	-0.018
20	25	3.115	3.099	-0.016
20	26	3.119	3.099	-0.020
20	27	3.117	3.109	-0.008
35	28	3.097	3.097	0.000
35	29	3.101	3.095	-0.006
35	30	3.113	3.103	-0.010
35	31	3.097	3.091	-0.006
35	32	3.105	3.101	-0.004
30	33	3.109	3.101	-0.008
30	34	3.099	3.093	-0.006
30	35	3.107	3.095	-0.012
30	36	3.101	3.099	-0.002
30	37	3.113	3.111	-0.002
	Max	3.121	3.117	0.000
	Average	3.109	3.096	-0.013
	Min	3.097	3.081	-0.026
	Std Dev	0.008	0.008	0.007



	29.9_BIAS_RISING			
Test Site				
Tester				
Test Number				
Max Limit	3.25	V		
Min Limit	3.03	V		
kRad(Si)	20	25	30	35
LL	3.030	3.030	3.030	3.030
Min	3.081	3.095	3.093	3.091
Average	3.094	3.104	3.100	3.097
Max	3.109	3.117	3.111	3.103
UL	3.250	3.250	3.250	3.250

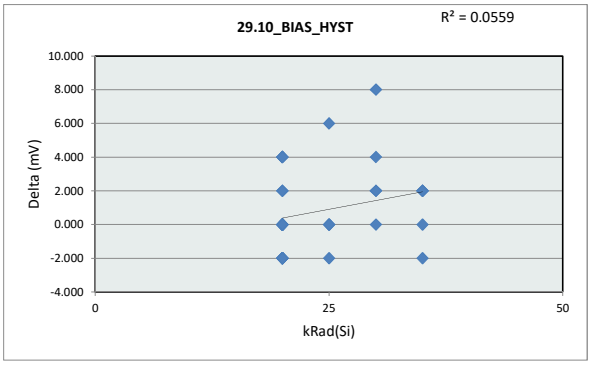


LDR TID Report
TPS7H4010-SEP

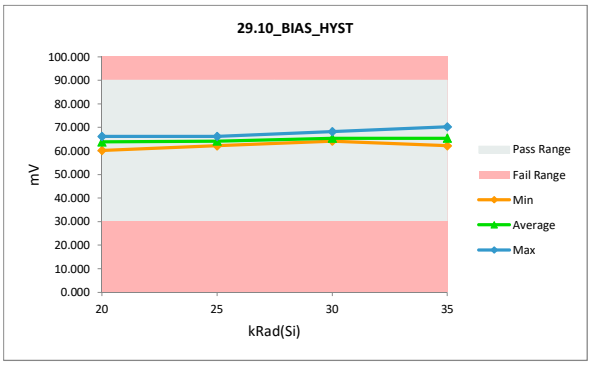
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.10_BIAS_HYST	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	90	90
Min Limit	30	30

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	62.200	62.200	0.000
25	2	64.200	64.200	0.000
25	3	66.200	66.200	0.000
25	4	60.200	66.200	6.000
25	5	64.200	62.200	-2.000
20	6	66.200	64.200	-2.000
20	7	66.200	66.200	0.000
20	8	62.200	66.200	4.000
20	9	62.200	62.200	0.000
20	10	62.200	64.200	2.000
20	11	64.200	64.200	0.000
20	12	64.200	62.200	-2.000
20	13	62.200	66.200	4.000
20	14	62.200	66.200	4.000
20	15	66.200	66.200	0.000
20	16	66.200	66.200	0.000
20	17	62.200	62.200	0.000
20	18	62.200	64.200	2.000
20	19	66.200	64.200	-2.000
20	20	62.200	62.200	0.000
20	21	68.200	66.200	-2.000
20	22	60.200	64.200	4.000
20	23	64.200	62.200	-2.000
20	24	60.200	60.200	0.000
20	25	62.200	60.200	-2.000
20	26	62.200	60.200	-2.000
20	27	64.200	64.200	0.000
35	28	68.200	70.200	2.000
35	29	64.200	64.200	0.000
35	30	64.200	62.200	-2.000
35	31	62.200	64.200	2.000
35	32	64.200	66.200	2.000
30	33	60.200	68.200	8.000
30	34	62.200	66.200	4.000
30	35	64.200	64.200	0.000
30	36	62.200	64.200	2.000
30	37	62.200	64.200	2.000
	Max	68.200	70.200	8.000
	Average	63.497	64.308	0.811
	Min	60.200	60.200	-2.000
	Std Dev	2.120	2.208	2.470



	29.10_BIAS_HYST			
Test Site				
Tester				
Test Number				
Max Limit	90	mV		
Min Limit	30	mV		
kRad(Si)	20	25	30	35
LL	30.000	30.000	30.000	30.000
Min	60.200	62.200	64.200	62.200
Average	63.836	64.200	65.400	65.400
Max	66.200	66.200	68.200	70.200
UL	90.000	90.000	90.000	90.000

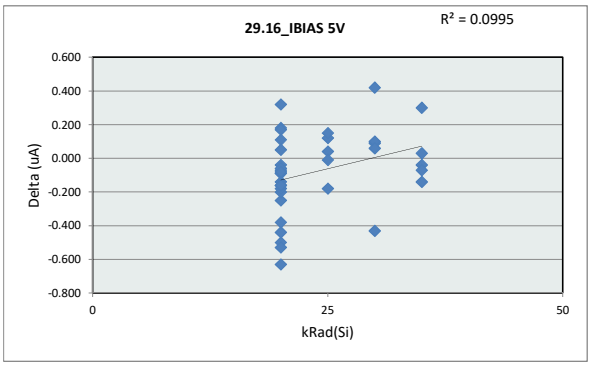


LDR TID Report
TPS7H4010-SEP

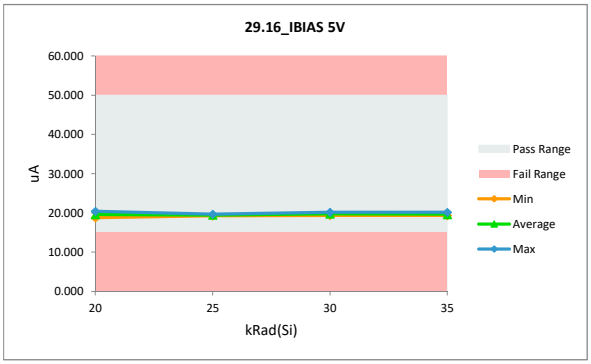
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	29.16_IBIAS 5V	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	50	50
Min Limit	15	15

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	19.240	19.280	0.040
25	2	19.490	19.310	-0.180
25	3	19.540	19.660	0.120
25	4	19.310	19.460	0.150
25	5	19.620	19.610	-0.010
20	6	19.820	19.570	-0.250
20	7	19.340	19.140	-0.200
20	8	19.930	19.430	-0.500
20	9	20.150	19.620	-0.530
20	10	19.940	19.850	-0.090
20	11	19.970	19.590	-0.380
20	12	19.450	18.820	-0.630
20	13	19.930	19.860	-0.070
20	14	19.900	19.720	-0.180
20	15	19.390	19.250	-0.140
20	16	20.230	20.410	0.180
20	17	19.990	20.100	0.110
20	18	19.890	19.730	-0.160
20	19	19.840	19.680	-0.160
20	20	19.270	19.230	-0.040
20	21	19.270	19.590	0.320
20	22	19.820	19.990	0.170
20	23	19.400	19.340	-0.060
20	24	19.560	19.470	-0.090
20	25	20.080	20.000	-0.080
20	26	19.810	19.860	0.050
20	27	19.490	19.050	-0.440
35	28	19.390	19.350	-0.040
35	29	19.860	20.160	0.300
35	30	19.750	19.680	-0.070
35	31	19.510	19.540	0.030
35	32	19.670	19.530	-0.140
30	33	19.650	19.740	0.090
30	34	19.270	19.690	0.420
30	35	19.930	20.030	0.100
30	36	20.600	20.170	-0.430
30	37	19.320	19.380	0.060
Max		20.600	20.410	0.420
Average		19.692	19.619	-0.074
Min		19.240	18.820	-0.630
Std Dev		0.320	0.338	0.239



	29.16_IBIAS 5V			
Test Site				
Tester				
Test Number				
Max Limit	50	uA		
Min Limit	15	uA		
kRad(Si)	20	25	30	35
LL	15.000	15.000	15.000	15.000
Min	18.820	19.280	19.380	19.350
Average	19.605	19.464	19.802	19.652
Max	20.410	19.660	20.170	20.160
UL	50.000	50.000	50.000	50.000

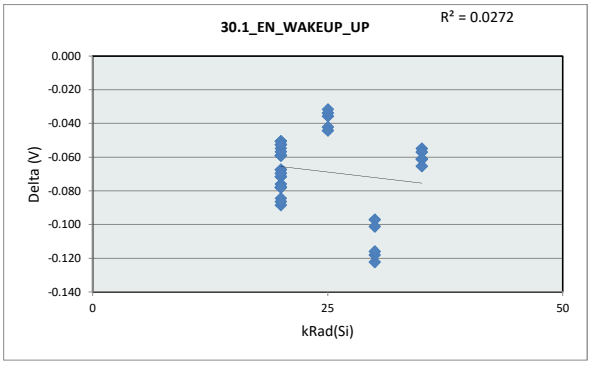


LDR TID Report
TPS7H4010-SEP

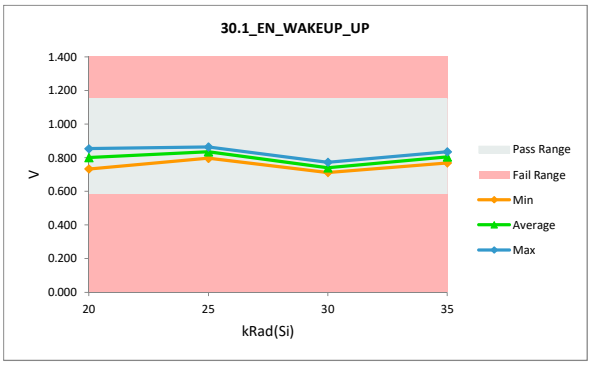
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.1_EN_WAKEUP_UP	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.15	1.15
Min Limit	0.58	0.58

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.862	0.826	-0.036
25	2	0.839	0.796	-0.042
25	3	0.891	0.858	-0.034
25	4	0.896	0.864	-0.032
25	5	0.872	0.828	-0.044
20	6	0.853	0.765	-0.089
20	7	0.872	0.801	-0.072
20	8	0.870	0.786	-0.084
20	9	0.862	0.794	-0.067
20	10	0.887	0.832	-0.055
20	11	0.887	0.836	-0.051
20	12	0.811	0.733	-0.078
20	13	0.872	0.796	-0.076
20	14	0.870	0.784	-0.086
20	15	0.881	0.811	-0.070
20	16	0.849	0.771	-0.078
20	17	0.845	0.786	-0.059
20	18	0.902	0.834	-0.067
20	19	0.874	0.803	-0.072
20	20	0.862	0.803	-0.059
20	21	0.862	0.784	-0.078
20	22	0.862	0.792	-0.070
20	23	0.870	0.811	-0.059
20	24	0.864	0.807	-0.057
20	25	0.860	0.807	-0.053
20	26	0.864	0.813	-0.051
20	27	0.906	0.853	-0.053
35	28	0.896	0.834	-0.061
35	29	0.874	0.820	-0.055
35	30	0.826	0.769	-0.057
35	31	0.855	0.794	-0.061
35	32	0.870	0.805	-0.065
30	33	0.870	0.773	-0.097
30	34	0.877	0.754	-0.122
30	35	0.830	0.712	-0.118
30	36	0.834	0.718	-0.116
30	37	0.841	0.739	-0.101
Max		0.906	0.864	-0.032
Average		0.865	0.797	-0.068
Min		0.811	0.712	-0.122
Std Dev		0.021	0.036	0.022



	30.1_EN_WAKEUP_UP			
Test Site				
Tester				
Test Number				
Max Limit	1.15	V		
Min Limit	0.58	V		
kRad(Si)	20	25	30	35
LL	0.580	0.580	0.580	0.580
Min	0.733	0.796	0.712	0.769
Average	0.800	0.834	0.740	0.804
Max	0.853	0.864	0.773	0.834
UL	1.150	1.150	1.150	1.150

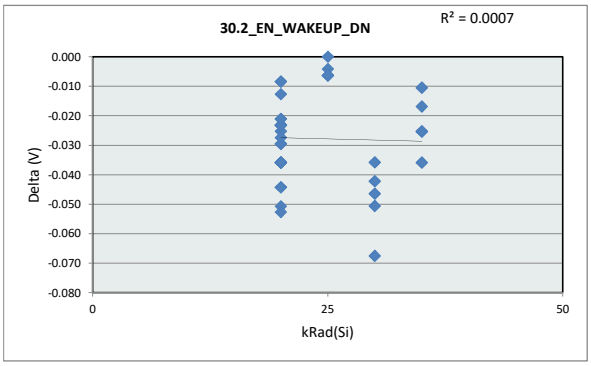


LDR TID Report
TPS7H4010-SEP

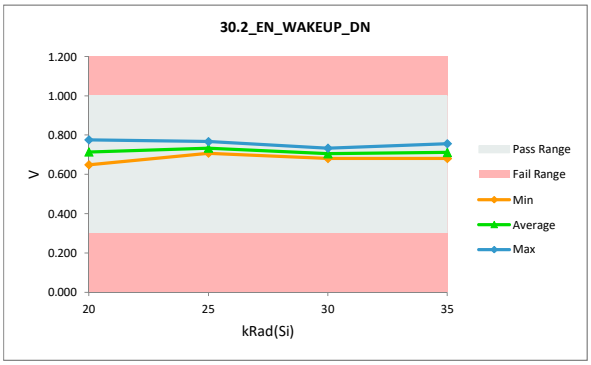
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.2_EN_WAKEUP_DN	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1	1
Min Limit	0.3	0.3

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.733	0.727	-0.006
25	2	0.767	0.767	0.000
25	3	0.727	0.723	-0.004
25	4	0.714	0.708	-0.006
25	5	0.750	0.744	-0.006
20	6	0.799	0.775	-0.023
20	7	0.712	0.687	-0.025
20	8	0.737	0.701	-0.036
20	9	0.720	0.676	-0.044
20	10	0.733	0.697	-0.036
20	11	0.767	0.737	-0.030
20	12	0.680	0.657	-0.023
20	13	0.752	0.729	-0.023
20	14	0.735	0.685	-0.051
20	15	0.784	0.748	-0.036
20	16	0.735	0.691	-0.044
20	17	0.782	0.769	-0.013
20	18	0.699	0.678	-0.021
20	19	0.763	0.739	-0.023
20	20	0.799	0.769	-0.030
20	21	0.754	0.718	-0.036
20	22	0.742	0.714	-0.027
20	23	0.701	0.649	-0.053
20	24	0.723	0.714	-0.008
20	25	0.758	0.723	-0.036
20	26	0.758	0.750	-0.008
20	27	0.718	0.697	-0.021
35	28	0.737	0.720	-0.017
35	29	0.767	0.756	-0.011
35	30	0.731	0.706	-0.025
35	31	0.716	0.680	-0.036
35	32	0.718	0.693	-0.025
30	33	0.746	0.704	-0.042
30	34	0.784	0.733	-0.051
30	35	0.727	0.680	-0.046
30	36	0.744	0.708	-0.036
30	37	0.771	0.704	-0.067
Max		0.799	0.775	0.000
Average		0.743	0.715	-0.028
Min		0.680	0.649	-0.067
Std Dev		0.028	0.032	0.016



	30.2_EN_WAKEUP_DN			
Test Site				
Tester				
Test Number				
Max Limit	1	V		
Min Limit	0.3	V		
kRad(Si)	20	25	30	35
LL	0.300	0.300	0.300	0.300
Min	0.649	0.708	0.680	0.680
Average	0.714	0.734	0.706	0.711
Max	0.775	0.767	0.733	0.756
UL	1.000	1.000	1.000	1.000

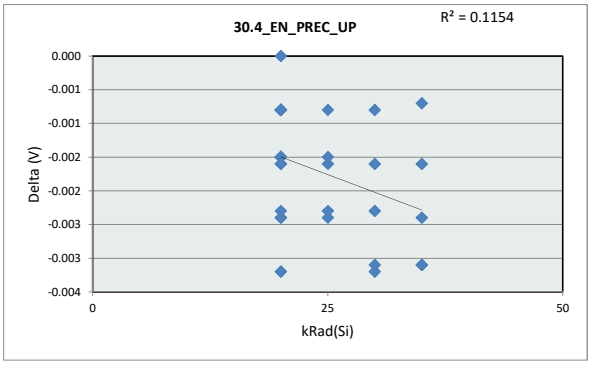


LDR TID Report
TPS7H4010-SEP

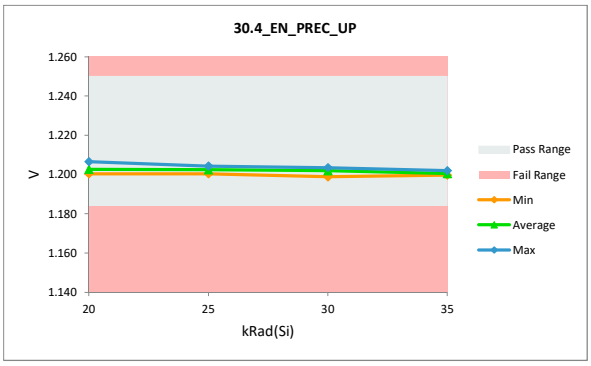
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.4_EN_PREC_UP	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.25	1.25
Min Limit	1.184	1.184

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.204	1.203	-0.002
25	2	1.205	1.204	-0.001
25	3	1.205	1.203	-0.002
25	4	1.203	1.200	-0.002
25	5	1.204	1.202	-0.002
20	6	1.203	1.201	-0.002
20	7	1.204	1.203	-0.001
20	8	1.206	1.204	-0.002
20	9	1.201	1.200	-0.001
20	10	1.204	1.202	-0.002
20	11	1.204	1.203	-0.001
20	12	1.204	1.204	-0.001
20	13	1.206	1.203	-0.003
20	14	1.203	1.201	-0.002
20	15	1.205	1.204	-0.002
20	16	1.203	1.201	-0.002
20	17	1.206	1.203	-0.003
20	18	1.207	1.207	-0.001
20	19	1.205	1.203	-0.002
20	20	1.204	1.202	-0.002
20	21	1.204	1.202	-0.002
20	22	1.204	1.202	-0.002
20	23	1.204	1.204	0.000
20	24	1.204	1.203	-0.001
20	25	1.204	1.202	-0.002
20	26	1.206	1.204	-0.002
20	27	1.204	1.204	-0.001
35	28	1.203	1.202	-0.001
35	29	1.202	1.200	-0.002
35	30	1.204	1.201	-0.003
35	31	1.202	1.200	-0.002
35	32	1.203	1.200	-0.003
30	33	1.207	1.204	-0.003
30	34	1.202	1.199	-0.003
30	35	1.204	1.204	-0.001
30	36	1.204	1.201	-0.002
30	37	1.204	1.203	-0.002
Max		1.207	1.207	0.000
Average		1.204	1.202	-0.002
Min		1.201	1.199	-0.003
Std Dev		0.001	0.002	0.001



	30.4_EN_PREC_UP			
Test Site				
Tester				
Test Number				
Max Limit	1.25	V		
Min Limit	1.184	V		
kRad(Si)	20	25	30	35
LL	1.184	1.184	1.184	1.184
Min	1.200	1.200	1.199	1.200
Average	1.203	1.202	1.202	1.201
Max	1.207	1.204	1.204	1.202
UL	1.250	1.250	1.250	1.250

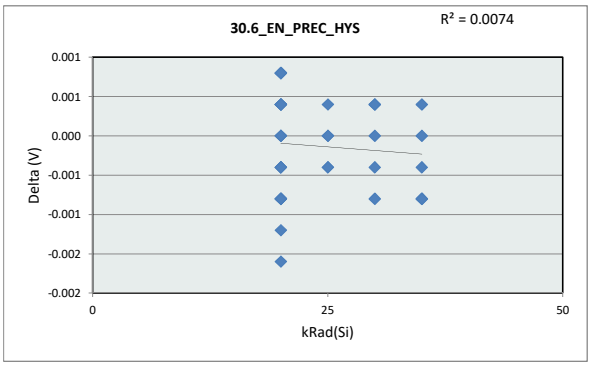


LDR TID Report
TPS7H4010-SEP

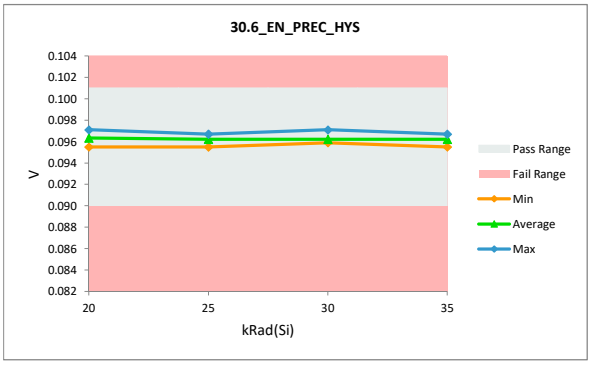
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	30.6_EN_PREC_HYS	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.101	0.101
Min Limit	0.09	0.09

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.097	0.096	0.000
25	2	0.096	0.097	0.000
25	3	0.096	0.096	0.000
25	4	0.096	0.096	0.000
25	5	0.096	0.095	0.000
20	6	0.096	0.097	0.001
20	7	0.096	0.096	0.000
20	8	0.097	0.096	-0.001
20	9	0.096	0.096	0.000
20	10	0.095	0.095	0.000
20	11	0.097	0.096	-0.001
20	12	0.097	0.096	-0.001
20	13	0.097	0.096	-0.001
20	14	0.096	0.096	0.000
20	15	0.097	0.097	0.000
20	16	0.096	0.096	0.000
20	17	0.097	0.096	-0.001
20	18	0.096	0.097	0.000
20	19	0.096	0.096	0.000
20	20	0.097	0.095	-0.002
20	21	0.096	0.097	0.001
20	22	0.096	0.097	0.001
20	23	0.097	0.097	0.000
20	24	0.096	0.096	0.000
20	25	0.096	0.097	0.001
20	26	0.096	0.095	0.000
20	27	0.097	0.097	0.000
35	28	0.096	0.097	0.000
35	29	0.097	0.096	0.000
35	30	0.097	0.096	-0.001
35	31	0.097	0.097	0.000
35	32	0.096	0.095	-0.001
30	33	0.097	0.096	-0.001
30	34	0.097	0.097	0.000
30	35	0.095	0.096	0.000
30	36	0.096	0.096	0.000
30	37	0.097	0.096	0.000
Max		0.097	0.097	0.001
Average		0.096	0.096	0.000
Min		0.095	0.095	-0.002
Std Dev		0.000	0.000	0.001



	30.6_EN_PREC_HYS			
Test Site				
Tester				
Test Number				
Max Limit	0.101	V		
Min Limit	0.09	V		
kRad(Si)	20	25	30	35
LL	0.090	0.090	0.090	0.090
Min	0.096	0.096	0.096	0.096
Average	0.096	0.096	0.096	0.096
Max	0.097	0.097	0.097	0.097
UL	0.101	0.101	0.101	0.101

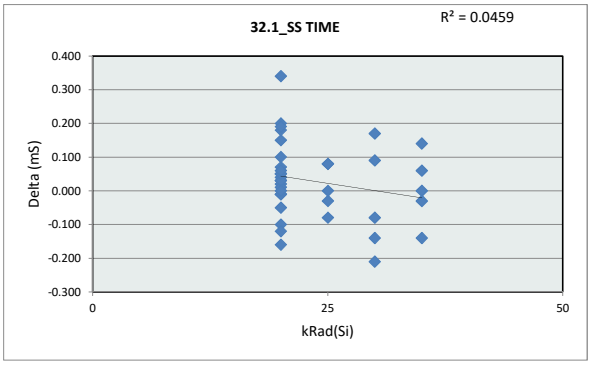


LDR TID Report
TPS7H4010-SEP

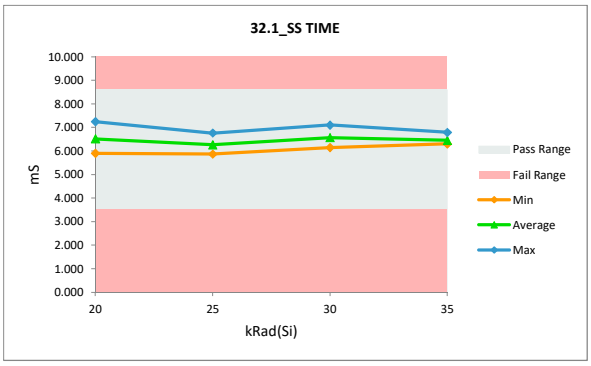
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.1_SS TIME	
Test Site		
Tester		
Test Number		
Unit	mS	mS
Max Limit	8.6	8.6
Min Limit	3.5	3.5

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	6.350	6.430	0.080
25	2	5.950	6.030	0.080
25	3	6.230	6.200	-0.030
25	4	5.950	5.870	-0.080
25	5	6.760	6.760	0.000
20	6	7.260	7.100	-0.160
20	7	6.290	6.280	-0.010
20	8	6.470	6.500	0.030
20	9	7.250	7.240	-0.010
20	10	6.330	6.230	-0.100
20	11	5.930	5.970	0.040
20	12	6.370	6.390	0.020
20	13	6.250	6.450	0.200
20	14	5.850	5.900	0.050
20	15	7.030	7.100	0.070
20	16	6.630	6.580	-0.050
20	17	6.370	6.380	0.010
20	18	6.340	6.220	-0.120
20	19	6.540	6.690	0.150
20	20	6.360	6.540	0.180
20	21	6.510	6.540	0.030
20	22	6.630	6.730	0.100
20	23	6.350	6.400	0.050
20	24	5.900	6.240	0.340
20	25	6.690	6.690	0.000
20	26	6.630	6.820	0.190
20	27	6.280	6.340	0.060
35	28	6.440	6.300	-0.140
35	29	6.650	6.790	0.140
35	30	6.470	6.470	0.000
35	31	6.240	6.300	0.060
35	32	6.410	6.380	-0.030
30	33	6.510	6.300	-0.210
30	34	7.010	7.100	0.090
30	35	6.320	6.490	0.170
30	36	6.220	6.140	-0.080
30	37	6.940	6.800	-0.140
	Max	7.260	7.240	0.340
	Average	6.452	6.478	0.026
	Min	5.850	5.870	-0.210
	Std Dev	0.344	0.335	0.114



	32.1_SS TIME			
Test Site				
Tester				
Test Number				
Max Limit	8.6	mS		
Min Limit	3.5	mS		
kRad(Si)	20	25	30	35
LL	3.500	3.500	3.500	3.500
Min	5.900	5.870	6.140	6.300
Average	6.515	6.258	6.566	6.448
Max	7.240	6.760	7.100	6.790
UL	8.600	8.600	8.600	8.600

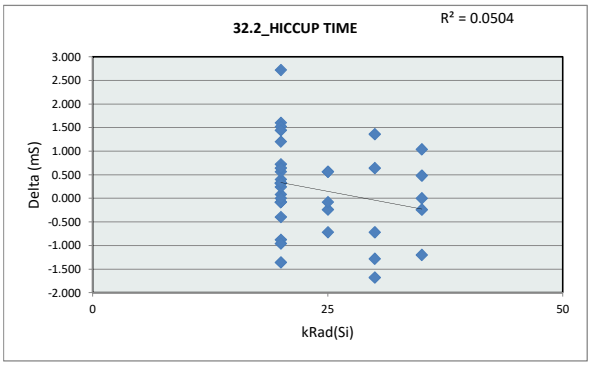


LDR TID Report
TPS7H4010-SEP

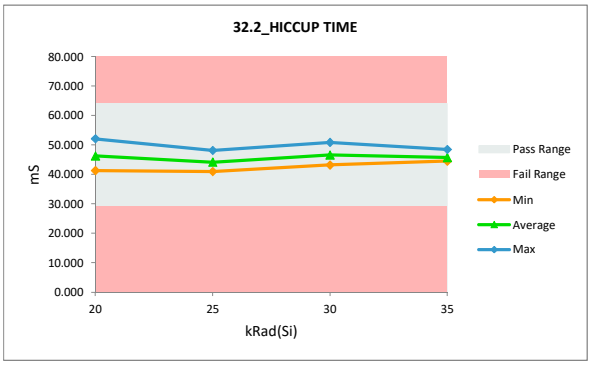
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.2_HICCUP TIME	
Test Site		
Tester		
Test Number		
Unit	mS	mS
Max Limit	64	64
Min Limit	29	29

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	44.960	45.520	0.560
25	2	41.760	42.320	0.560
25	3	44.000	43.760	-0.240
25	4	41.680	40.960	-0.720
25	5	48.240	48.160	-0.080
20	6	52.320	50.960	-1.360
20	7	44.400	44.320	-0.080
20	8	45.840	46.160	0.320
20	9	52.160	52.080	-0.080
20	10	44.800	43.920	-0.880
20	11	41.520	41.840	0.320
20	12	45.040	45.120	0.080
20	13	44.160	45.760	1.600
20	14	40.880	41.280	0.400
20	15	50.400	50.960	0.560
20	16	47.120	46.720	-0.400
20	17	45.200	45.120	-0.080
20	18	44.720	43.760	-0.960
20	19	46.480	47.680	1.200
20	20	44.880	46.400	1.520
20	21	46.160	46.400	0.240
20	22	47.280	48.000	0.720
20	23	44.960	45.280	0.320
20	24	41.360	44.080	2.720
20	25	47.600	47.600	0.000
20	26	47.200	48.640	1.440
20	27	44.240	44.880	0.640
35	28	45.680	44.480	-1.200
35	29	47.440	48.480	1.040
35	30	45.920	45.920	0.000
35	31	44.000	44.480	0.480
35	32	45.440	45.200	-0.240
30	33	46.160	44.480	-1.680
30	34	50.240	50.880	0.640
30	35	44.640	46.000	1.360
30	36	43.920	43.200	-0.720
30	37	49.680	48.400	-1.280
	Max	52.320	52.080	2.720
	Average	45.743	45.924	0.182
	Min	40.880	40.960	-1.680
	Std Dev	2.773	2.698	0.933



	32.2_HICCUP TIME			
Test Site				
Tester				
Test Number				
Max Limit	64	mS		
Min Limit	29	mS		
kRad(Si)	20	25	30	35
LL	29.000	29.000	29.000	29.000
Min	41.280	40.960	43.200	44.480
Average	46.225	44.144	46.592	45.712
Max	52.080	48.160	50.880	48.480
UL	64.000	64.000	64.000	64.000

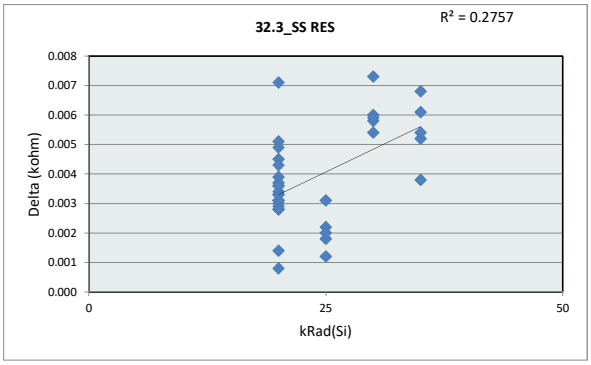


LDR TID Report
TPS7H4010-SEP

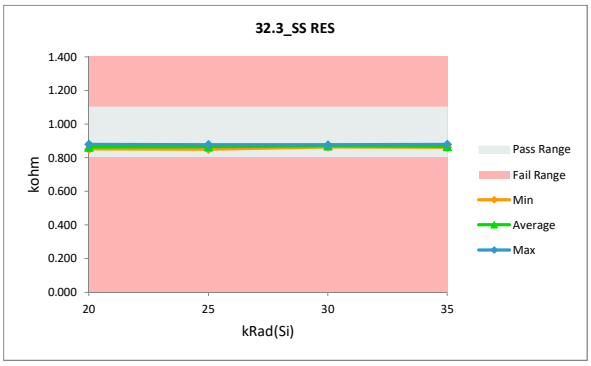
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.3_SS RES	
Test Site		
Tester		
Test Number		
Unit	kohm	kohm
Max Limit	1.1	1.1
Min Limit	0.8	0.8

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.858	0.861	0.003
25	2	0.875	0.877	0.002
25	3	0.850	0.851	0.001
25	4	0.863	0.865	0.002
25	5	0.868	0.870	0.002
20	6	0.865	0.869	0.004
20	7	0.862	0.865	0.004
20	8	0.871	0.874	0.004
20	9	0.854	0.857	0.003
20	10	0.860	0.863	0.004
20	11	0.857	0.860	0.003
20	12	0.874	0.879	0.005
20	13	0.855	0.855	0.001
20	14	0.857	0.861	0.003
20	15	0.869	0.872	0.003
20	16	0.850	0.851	0.001
20	17	0.850	0.852	0.003
20	18	0.865	0.868	0.003
20	19	0.871	0.874	0.003
20	20	0.869	0.872	0.003
20	21	0.866	0.873	0.007
20	22	0.849	0.853	0.004
20	23	0.859	0.863	0.004
20	24	0.856	0.861	0.005
20	25	0.852	0.855	0.003
20	26	0.854	0.857	0.003
20	27	0.864	0.868	0.004
35	28	0.874	0.880	0.005
35	29	0.857	0.862	0.005
35	30	0.861	0.865	0.004
35	31	0.856	0.862	0.007
35	32	0.862	0.868	0.006
30	33	0.869	0.875	0.006
30	34	0.871	0.876	0.006
30	35	0.862	0.869	0.007
30	36	0.859	0.864	0.005
30	37	0.864	0.870	0.006
	Max	0.875	0.880	0.007
	Average	0.861	0.865	0.004
	Min	0.849	0.851	0.001
	Std Dev	0.007	0.008	0.002



	32.3_SS RES			
Test Site				
Tester				
Test Number				
Max Limit	1.1	kohm		
Min Limit	0.8	kohm		
kRad(Si)	20	25	30	35
LL	0.800	0.800	0.800	0.800
Min	0.851	0.851	0.864	0.862
Average	0.864	0.865	0.871	0.867
Max	0.879	0.877	0.876	0.880
UL	1.100	1.100	1.100	1.100

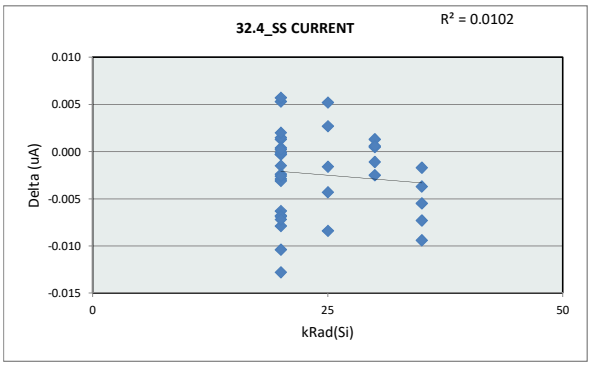


LDR TID Report
TPS7H4010-SEP

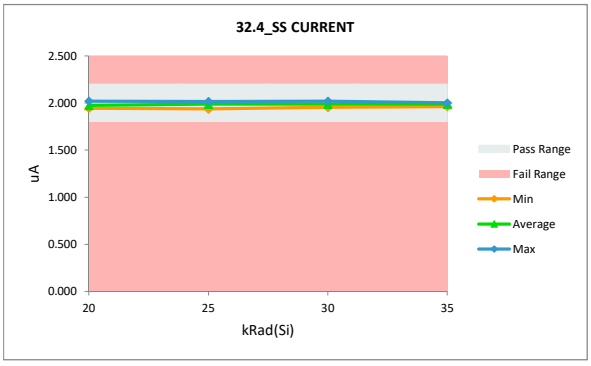
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.4_SS CURRENT	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	2.2	2.2
Min Limit	1.8	1.8

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.946	1.938	-0.008
25	2	2.016	2.014	-0.002
25	3	2.014	2.016	0.003
25	4	1.985	1.981	-0.004
25	5	1.987	1.993	0.005
20	6	1.948	1.945	-0.003
20	7	1.957	1.950	-0.006
20	8	1.967	1.960	-0.007
20	9	1.962	1.960	-0.002
20	10	1.998	1.998	0.000
20	11	1.969	1.969	0.000
20	12	1.953	1.953	0.000
20	13	1.953	1.946	-0.007
20	14	2.000	2.001	0.001
20	15	1.976	1.973	-0.003
20	16	1.954	1.946	-0.008
20	17	2.018	2.019	0.001
20	18	2.016	2.021	0.005
20	19	1.992	1.994	0.002
20	20	1.967	1.965	-0.002
20	21	1.952	1.958	0.006
20	22	2.013	2.006	-0.007
20	23	1.968	1.968	0.000
20	24	2.020	2.009	-0.010
20	25	1.949	1.949	0.000
20	26	2.015	2.002	-0.013
20	27	1.949	1.947	-0.003
35	28	1.970	1.961	-0.009
35	29	1.993	1.986	-0.007
35	30	1.990	1.987	-0.004
35	31	2.007	2.002	-0.005
35	32	2.004	2.003	-0.002
30	33	2.017	2.018	0.001
30	34	2.021	2.020	-0.001
30	35	1.956	1.954	-0.003
30	36	2.001	2.002	0.001
30	37	1.958	1.958	0.001
	Max	2.021	2.021	0.006
	Average	1.983	1.980	-0.002
	Min	1.946	1.938	-0.013
	Std Dev	0.026	0.027	0.004



	32.4_SS CURRENT			
Test Site				
Tester				
Test Number				
Max Limit	2.2	uA		
Min Limit	1.8	uA		
kRad(Si)	20	25	30	35
LL	1.800	1.800	1.800	1.800
Min	1.945	1.938	1.954	1.961
Average	1.975	1.988	1.990	1.988
Max	2.021	2.016	2.020	2.003
UL	2.200	2.200	2.200	2.200

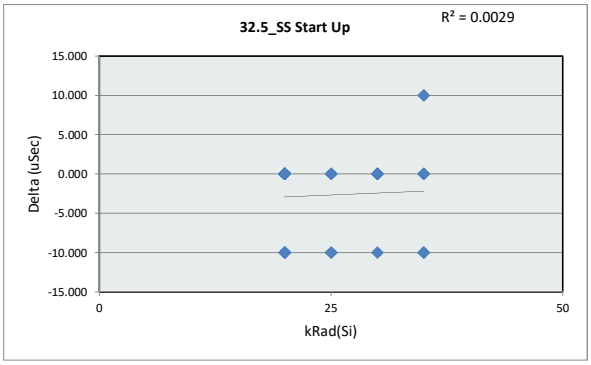


LDR TID Report
TPS7H4010-SEP

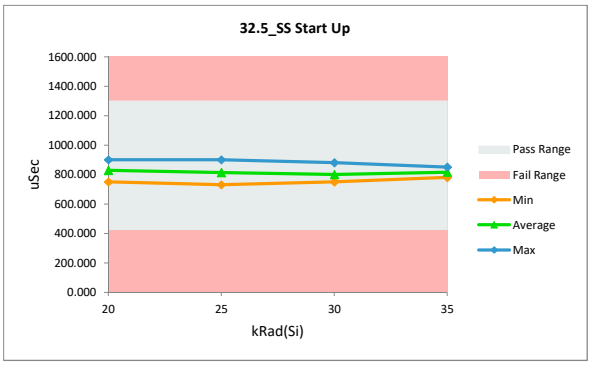
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	32.5_SS Start Up	
Test Site		
Tester		
Test Number		
Unit	uSec	uSec
Max Limit	1300	1300
Min Limit	420	420

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	830.000	830.000	0.000
25	2	740.000	730.000	-10.000
25	3	900.000	900.000	0.000
25	4	830.000	830.000	0.000
25	5	790.000	780.000	-10.000
20	6	780.000	770.000	-10.000
20	7	870.000	870.000	0.000
20	8	800.000	800.000	0.000
20	9	880.000	880.000	0.000
20	10	870.000	860.000	-10.000
20	11	790.000	790.000	0.000
20	12	900.000	900.000	0.000
20	13	810.000	810.000	0.000
20	14	840.000	830.000	-10.000
20	15	800.000	800.000	0.000
20	16	830.000	820.000	-10.000
20	17	750.000	750.000	0.000
20	18	890.000	890.000	0.000
20	19	780.000	780.000	0.000
20	20	820.000	820.000	0.000
20	21	840.000	840.000	0.000
20	22	790.000	780.000	-10.000
20	23	810.000	810.000	0.000
20	24	840.000	840.000	0.000
20	25	870.000	870.000	0.000
20	26	830.000	820.000	-10.000
20	27	870.000	870.000	0.000
35	28	810.000	800.000	-10.000
35	29	820.000	820.000	0.000
35	30	790.000	780.000	-10.000
35	31	820.000	830.000	10.000
35	32	850.000	850.000	0.000
30	33	750.000	750.000	0.000
30	34	790.000	780.000	-10.000
30	35	880.000	880.000	0.000
30	36	810.000	810.000	0.000
30	37	780.000	780.000	0.000
	Max	900.000	900.000	10.000
	Average	822.973	820.270	-2.703
	Min	740.000	730.000	-10.000
	Std Dev	42.089	43.620	5.082



	32.5_SS Start Up			
Test Site				
Tester				
Test Number				
Max Limit	1300	uSec		
Min Limit	420	uSec		
kRad(Si)	20	25	30	35
LL	420.000	420.000	420.000	420.000
Min	750.000	730.000	750.000	780.000
Average	827.273	814.000	800.000	816.000
Max	900.000	900.000	880.000	850.000
UL	1300.000	1300.000	1300.000	1300.000

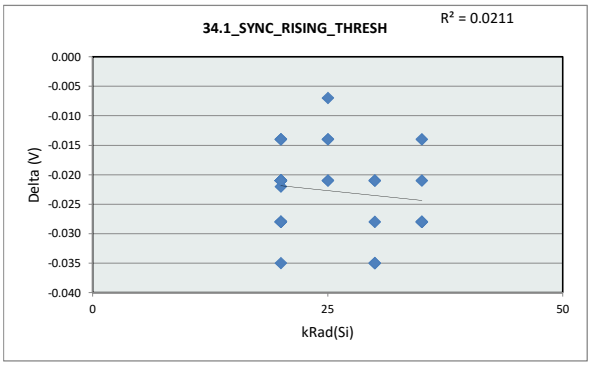


LDR TID Report
TPS7H4010-SEP

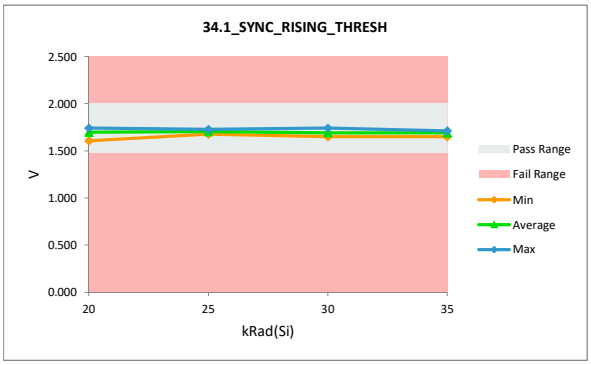
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.1_SYNC_RISING_THRESH	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2	2
Min Limit	1.47	1.47

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.726	1.712	-0.014
25	2	1.691	1.677	-0.014
25	3	1.726	1.705	-0.021
25	4	1.705	1.698	-0.007
25	5	1.747	1.726	-0.021
20	6	1.712	1.691	-0.021
20	7	1.719	1.691	-0.028
20	8	1.712	1.698	-0.014
20	9	1.740	1.719	-0.021
20	10	1.705	1.684	-0.021
20	11	1.719	1.698	-0.021
20	12	1.628	1.606	-0.022
20	13	1.761	1.740	-0.021
20	14	1.712	1.691	-0.021
20	15	1.747	1.719	-0.028
20	16	1.719	1.705	-0.014
20	17	1.712	1.684	-0.028
20	18	1.712	1.691	-0.021
20	19	1.733	1.712	-0.021
20	20	1.726	1.698	-0.028
20	21	1.740	1.712	-0.028
20	22	1.733	1.712	-0.021
20	23	1.712	1.691	-0.021
20	24	1.705	1.684	-0.021
20	25	1.726	1.712	-0.014
20	26	1.719	1.691	-0.028
20	27	1.733	1.698	-0.035
35	28	1.726	1.712	-0.014
35	29	1.733	1.705	-0.028
35	30	1.698	1.670	-0.028
35	31	1.677	1.649	-0.028
35	32	1.733	1.712	-0.021
30	33	1.761	1.740	-0.021
30	34	1.726	1.705	-0.021
30	35	1.684	1.649	-0.035
30	36	1.705	1.677	-0.028
30	37	1.719	1.684	-0.035
	Max	1.761	1.740	-0.007
	Average	1.718	1.696	-0.023
	Min	1.628	1.606	-0.035
	Std Dev	0.024	0.025	0.006



	34.1_SYNC_RISING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	2	V		
Min Limit	1.47	V		
kRad(Si)	20	25	30	35
LL	1.470	1.470	1.470	1.470
Min	1.606	1.677	1.649	1.649
Average	1.697	1.704	1.691	1.690
Max	1.740	1.726	1.740	1.712
UL	2.000	2.000	2.000	2.000

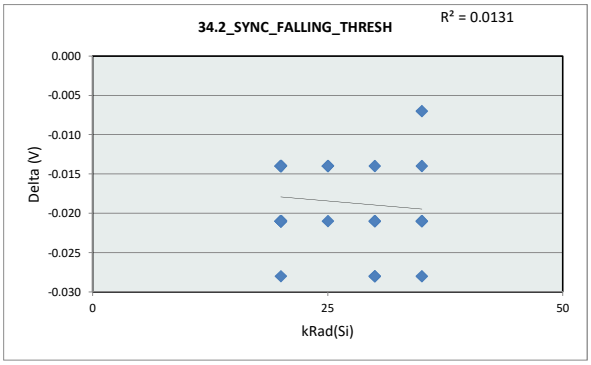


LDR TID Report
TPS7H4010-SEP

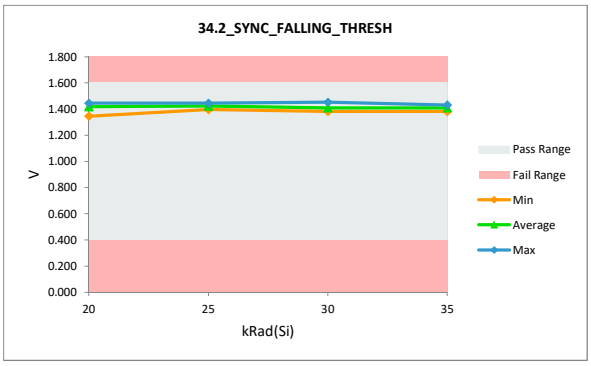
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.2_SYNC_FALLING_THRESH	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.6	1.6
Min Limit	0.4	0.4

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.452	1.438	-0.014
25	2	1.410	1.396	-0.014
25	3	1.438	1.417	-0.021
25	4	1.431	1.417	-0.014
25	5	1.459	1.445	-0.014
20	6	1.431	1.410	-0.021
20	7	1.431	1.410	-0.021
20	8	1.431	1.417	-0.014
20	9	1.459	1.445	-0.014
20	10	1.431	1.410	-0.021
20	11	1.431	1.417	-0.014
20	12	1.367	1.346	-0.021
20	13	1.466	1.445	-0.021
20	14	1.431	1.410	-0.021
20	15	1.452	1.438	-0.014
20	16	1.438	1.424	-0.014
20	17	1.424	1.403	-0.021
20	18	1.431	1.417	-0.014
20	19	1.445	1.424	-0.021
20	20	1.438	1.424	-0.014
20	21	1.452	1.431	-0.021
20	22	1.445	1.431	-0.014
20	23	1.431	1.410	-0.021
20	24	1.431	1.410	-0.021
20	25	1.445	1.431	-0.014
20	26	1.431	1.417	-0.014
20	27	1.445	1.417	-0.028
35	28	1.431	1.424	-0.007
35	29	1.445	1.417	-0.028
35	30	1.417	1.396	-0.021
35	31	1.403	1.382	-0.021
35	32	1.445	1.431	-0.014
30	33	1.473	1.452	-0.021
30	34	1.431	1.417	-0.014
30	35	1.403	1.382	-0.021
30	36	1.424	1.396	-0.028
30	37	1.431	1.403	-0.028
Max		1.473	1.452	-0.007
Average		1.435	1.416	-0.018
Min		1.367	1.346	-0.028
Std Dev		0.019	0.020	0.005



	34.2_SYNC_FALLING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	1.6	V		
Min Limit	0.4	V		
kRad(Si)	20	25	30	35
LL	0.400	0.400	0.400	0.400
Min	1.346	1.396	1.382	1.382
Average	1.418	1.423	1.410	1.410
Max	1.445	1.445	1.452	1.431
UL	1.600	1.600	1.600	1.600

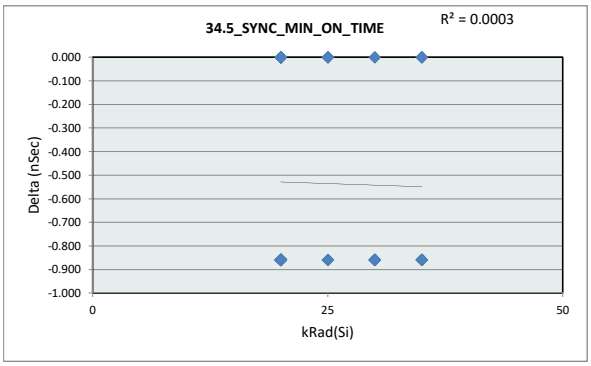


LDR TID Report
TPS7H4010-SEP

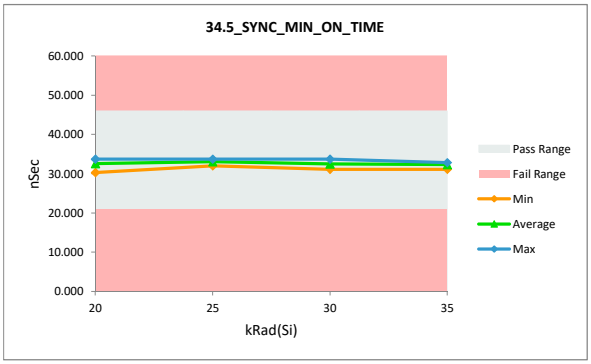
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.5_SYNC_MIN_ON_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	46	46
Min Limit	21	21

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	33.711	33.711	0.000
25	2	32.852	31.992	-0.860
25	3	32.852	32.852	0.000
25	4	32.852	32.852	0.000
25	5	34.570	33.711	-0.859
20	6	32.852	31.992	-0.860
20	7	32.852	31.992	-0.860
20	8	32.852	32.852	0.000
20	9	33.711	33.711	0.000
20	10	32.852	31.992	-0.860
20	11	32.852	32.852	0.000
20	12	30.273	30.273	0.000
20	13	34.570	33.711	-0.859
20	14	32.852	31.992	-0.860
20	15	34.570	33.711	-0.859
20	16	32.852	32.852	0.000
20	17	32.852	31.992	-0.860
20	18	32.852	32.852	0.000
20	19	33.711	33.711	0.000
20	20	33.711	32.852	-0.859
20	21	33.711	32.852	-0.859
20	22	33.711	32.852	-0.859
20	23	32.852	31.992	-0.860
20	24	32.852	31.992	-0.860
20	25	32.852	32.852	0.000
20	26	32.852	31.992	-0.860
20	27	33.711	32.852	-0.859
35	28	33.711	32.852	-0.859
35	29	32.852	32.852	0.000
35	30	31.992	31.992	0.000
35	31	31.992	31.133	-0.859
35	32	33.711	32.852	-0.859
30	33	34.570	33.711	-0.859
30	34	33.711	32.852	-0.859
30	35	31.992	31.133	-0.859
30	36	32.852	31.992	-0.860
30	37	32.852	32.852	0.000
	Max	34.570	33.711	0.000
	Average	33.130	32.596	-0.534
	Min	30.273	30.273	-0.860
	Std Dev	0.836	0.807	0.423



	34.5_SYNC_MIN_ON_TIME			
Test Site				
Tester				
Test Number				
Max Limit	46	nSec		
Min Limit	21	nSec		
kRad(Si)	20	25	30	35
LL	21.000	21.000	21.000	21.000
Min	30.273	31.992	31.133	31.133
Average	32.578	33.024	32.508	32.336
Max	33.711	33.711	33.711	32.852
UL	46.000	46.000	46.000	46.000

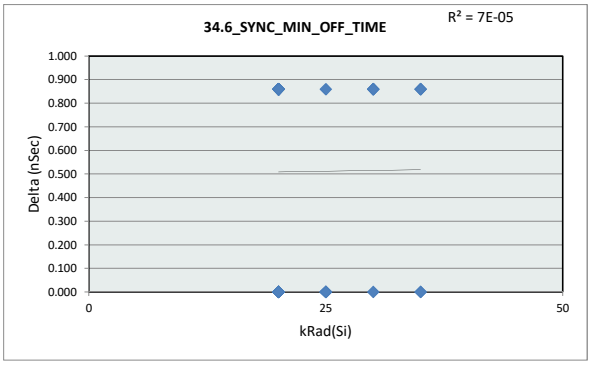


LDR TID Report
TPS7H4010-SEP

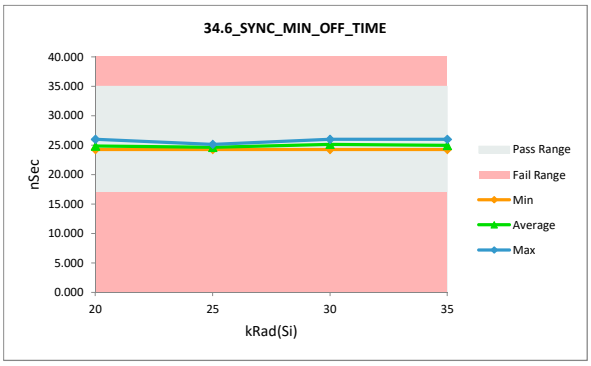
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.6_SYNC_MIN_OFF_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	35	35
Min Limit	17	17

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	24.258	24.258	0.000
25	2	25.117	25.117	0.000
25	3	24.258	24.258	0.000
25	4	24.258	25.117	0.859
25	5	24.258	24.258	0.000
20	6	24.258	25.117	0.859
20	7	24.258	24.258	0.000
20	8	24.258	25.117	0.859
20	9	24.258	24.258	0.000
20	10	24.258	25.117	0.859
20	11	24.258	25.117	0.859
20	12	25.977	25.977	0.000
20	13	23.398	24.258	0.860
20	14	24.258	25.117	0.859
20	15	24.258	24.258	0.000
20	16	24.258	24.258	0.000
20	17	24.258	25.117	0.859
20	18	24.258	25.117	0.859
20	19	24.258	25.117	0.859
20	20	24.258	25.117	0.859
20	21	24.258	24.258	0.000
20	22	24.258	24.258	0.000
20	23	24.258	25.117	0.859
20	24	24.258	25.117	0.859
20	25	24.258	24.258	0.000
20	26	24.258	25.117	0.859
20	27	24.258	25.117	0.859
35	28	24.258	24.258	0.000
35	29	24.258	24.258	0.000
35	30	24.258	25.117	0.859
35	31	25.117	25.977	0.860
35	32	24.258	25.117	0.859
30	33	24.258	24.258	0.000
30	34	24.258	25.117	0.859
30	35	25.117	25.977	0.860
30	36	24.258	25.117	0.859
30	37	24.258	25.117	0.859
	Max	25.977	25.977	0.860
	Average	24.351	24.862	0.511
	Min	23.398	24.258	0.000
	Std Dev	0.394	0.531	0.428



	34.6_SYNC_MIN_OFF_TIME			
Test Site				
Tester				
Test Number				
Max Limit	35	nSec		
Min Limit	17	nSec		
kRad(Si)	20	25	30	35
LL	17.000	17.000	17.000	17.000
Min	24.258	24.258	24.258	24.258
Average	24.844	24.602	25.117	24.945
Max	25.977	25.117	25.977	25.977
UL	35.000	35.000	35.000	35.000

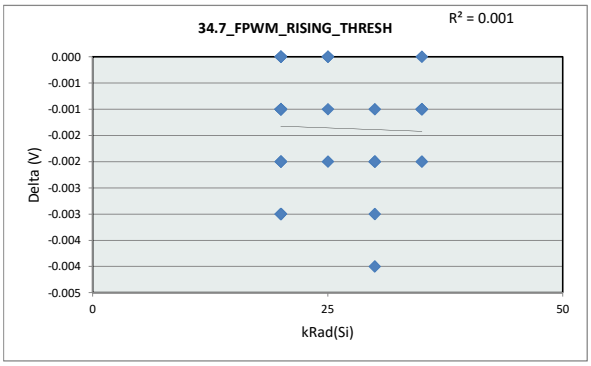


LDR TID Report
TPS7H4010-SEP

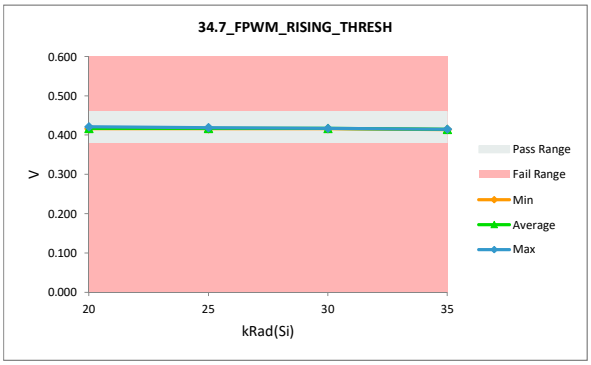
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.7_FPWM_RISING_THRESH	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.46	0.46
Min Limit	0.38	0.38

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.416	0.416	0.000
25	2	0.419	0.419	0.000
25	3	0.419	0.417	-0.002
25	4	0.420	0.419	-0.001
25	5	0.416	0.416	0.000
20	6	0.417	0.416	-0.001
20	7	0.421	0.420	-0.001
20	8	0.419	0.417	-0.002
20	9	0.420	0.417	-0.003
20	10	0.417	0.417	0.000
20	11	0.416	0.416	0.000
20	12	0.420	0.417	-0.003
20	13	0.420	0.419	-0.001
20	14	0.417	0.416	-0.001
20	15	0.420	0.419	-0.001
20	16	0.417	0.416	-0.001
20	17	0.419	0.417	-0.002
20	18	0.422	0.421	-0.001
20	19	0.419	0.416	-0.003
20	20	0.417	0.416	-0.001
20	21	0.419	0.416	-0.003
20	22	0.419	0.419	0.000
20	23	0.420	0.420	0.000
20	24	0.417	0.417	0.000
20	25	0.419	0.416	-0.003
20	26	0.417	0.416	-0.001
20	27	0.419	0.417	-0.002
35	28	0.415	0.415	0.000
35	29	0.415	0.414	-0.001
35	30	0.415	0.414	-0.001
35	31	0.416	0.415	-0.001
35	32	0.417	0.415	-0.002
30	33	0.421	0.417	-0.004
30	34	0.419	0.417	-0.002
30	35	0.419	0.417	-0.002
30	36	0.420	0.417	-0.003
30	37	0.417	0.416	-0.001
	Max	0.422	0.421	0.000
	Average	0.418	0.417	-0.001
	Min	0.415	0.414	-0.004
	Std Dev	0.002	0.002	0.001



	34.7_FPWM_RISING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	0.46	V		
Min Limit	0.38	V		
kRad(Si)	20	25	30	35
LL	0.380	0.380	0.380	0.380
Min	0.416	0.416	0.416	0.414
Average	0.417	0.417	0.417	0.415
Max	0.421	0.419	0.417	0.415
UL	0.460	0.460	0.460	0.460

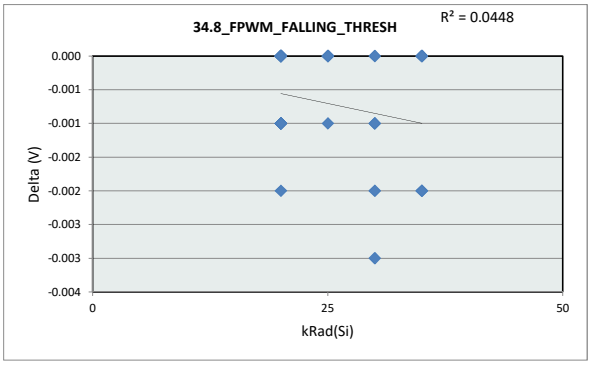


LDR TID Report
TPS7H4010-SEP

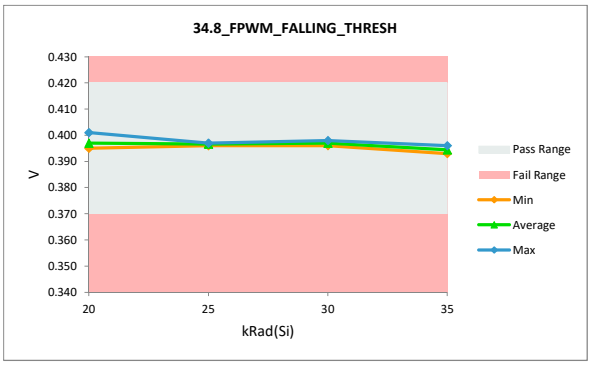
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	34.8_FPWM_FALLING_THRESH	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.42	0.42
Min Limit	0.37	0.37

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.396	0.396	0.000
25	2	0.397	0.397	0.000
25	3	0.397	0.397	0.000
25	4	0.398	0.397	-0.001
25	5	0.396	0.396	0.000
20	6	0.397	0.396	-0.001
20	7	0.398	0.398	0.000
20	8	0.398	0.397	-0.001
20	9	0.398	0.397	-0.001
20	10	0.397	0.397	0.000
20	11	0.396	0.396	0.000
20	12	0.396	0.396	0.000
20	13	0.399	0.398	-0.001
20	14	0.397	0.396	-0.001
20	15	0.398	0.398	0.000
20	16	0.397	0.396	-0.001
20	17	0.398	0.397	-0.001
20	18	0.401	0.401	0.000
20	19	0.397	0.396	-0.001
20	20	0.397	0.396	-0.001
20	21	0.396	0.395	-0.001
20	22	0.398	0.398	0.000
20	23	0.399	0.398	-0.001
20	24	0.397	0.397	0.000
20	25	0.398	0.396	-0.002
20	26	0.397	0.397	0.000
20	27	0.397	0.397	0.000
35	28	0.395	0.395	0.000
35	29	0.395	0.393	-0.002
35	30	0.395	0.393	-0.002
35	31	0.395	0.395	0.000
35	32	0.396	0.396	0.000
30	33	0.401	0.398	-0.003
30	34	0.398	0.397	-0.001
30	35	0.397	0.397	0.000
30	36	0.399	0.397	-0.002
30	37	0.397	0.396	-0.001
	Max	0.401	0.401	0.000
	Average	0.397	0.397	-0.001
	Min	0.395	0.393	-0.003
	Std Dev	0.001	0.001	0.001



	34.8_FPWM_FALLING_THRESH			
Test Site				
Tester				
Test Number				
Max Limit	0.42	V		
Min Limit	0.37	V		
kRad(Si)	20	25	30	35
LL	0.370	0.370	0.370	0.370
Min	0.395	0.396	0.396	0.393
Average	0.397	0.397	0.397	0.394
Max	0.401	0.397	0.398	0.396
UL	0.420	0.420	0.420	0.420

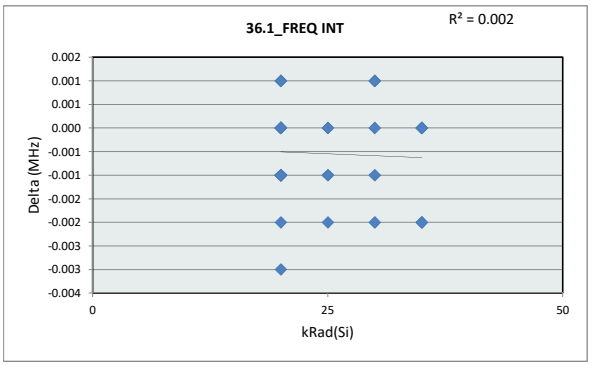


LDR TID Report
TPS7H4010-SEP

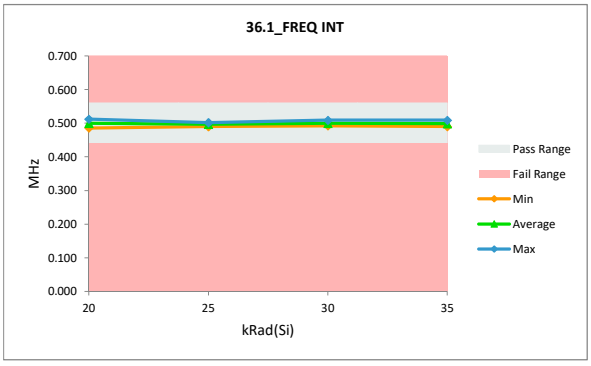
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.1_FREQ INT	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	0.56	0.56
Min Limit	0.44	0.44

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.491	0.491	0.000
25	2	0.504	0.502	-0.002
25	3	0.498	0.498	0.000
25	4	0.503	0.502	-0.001
25	5	0.491	0.490	-0.001
20	6	0.502	0.501	-0.001
20	7	0.489	0.488	-0.001
20	8	0.504	0.505	0.001
20	9	0.506	0.507	0.001
20	10	0.502	0.502	0.000
20	11	0.504	0.501	-0.003
20	12	0.496	0.496	0.000
20	13	0.498	0.498	0.000
20	14	0.507	0.506	-0.001
20	15	0.504	0.503	-0.001
20	16	0.501	0.500	-0.001
20	17	0.506	0.505	-0.001
20	18	0.497	0.495	-0.002
20	19	0.493	0.493	0.000
20	20	0.511	0.512	0.001
20	21	0.510	0.510	0.000
20	22	0.492	0.492	0.000
20	23	0.503	0.502	-0.001
20	24	0.499	0.498	-0.001
20	25	0.486	0.486	0.000
20	26	0.499	0.498	-0.001
20	27	0.503	0.503	0.000
35	28	0.509	0.509	0.000
35	29	0.507	0.505	-0.002
35	30	0.493	0.491	-0.002
35	31	0.498	0.498	0.000
35	32	0.490	0.490	0.000
30	33	0.508	0.509	0.001
30	34	0.493	0.492	-0.001
30	35	0.504	0.502	-0.002
30	36	0.501	0.502	0.001
30	37	0.492	0.492	0.000
	Max	0.511	0.512	0.001
	Average	0.500	0.499	-0.001
	Min	0.486	0.486	-0.003
	Std Dev	0.007	0.007	0.001



	36.1_FREQ INT			
Test Site				
Tester				
Test Number				
Max Limit	0.56	MHz		
Min Limit	0.44	MHz		
kRad(Si)	20	25	30	35
LL	0.440	0.440	0.440	0.440
Min	0.486	0.490	0.492	0.490
Average	0.500	0.497	0.499	0.499
Max	0.512	0.502	0.509	0.509
UL	0.560	0.560	0.560	0.560

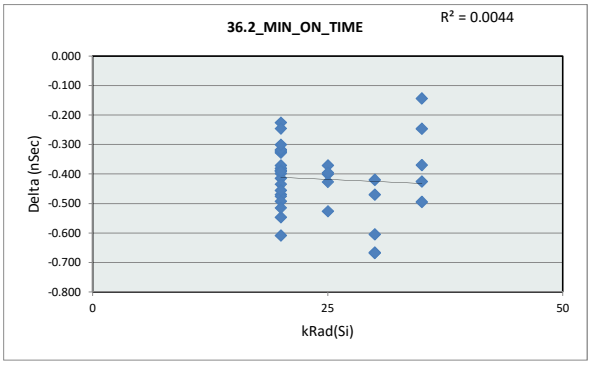


LDR TID Report
TPS7H4010-SEP

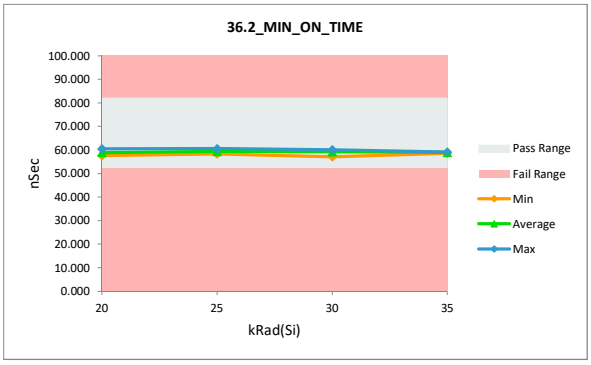
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.2_MIN_ON_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	82	82
Min Limit	52	52

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	59.208	58.781	-0.427
25	2	60.908	60.537	-0.371
25	3	58.743	58.342	-0.401
25	4	60.320	59.793	-0.527
25	5	60.108	59.712	-0.396
20	6	60.042	59.661	-0.381
20	7	58.177	57.630	-0.547
20	8	59.537	59.067	-0.470
20	9	58.871	58.482	-0.389
20	10	59.465	59.094	-0.371
20	11	59.504	59.176	-0.328
20	12	58.458	58.138	-0.320
20	13	60.482	60.083	-0.399
20	14	59.063	58.675	-0.388
20	15	60.964	60.488	-0.476
20	16	60.138	59.723	-0.415
20	17	59.053	58.618	-0.435
20	18	59.031	58.422	-0.609
20	19	60.481	60.157	-0.324
20	20	59.591	59.365	-0.226
20	21	58.145	57.899	-0.246
20	22	59.112	58.619	-0.493
20	23	59.095	58.580	-0.515
20	24	58.614	58.296	-0.318
20	25	59.119	58.663	-0.456
20	26	58.820	58.519	-0.301
20	27	58.950	58.558	-0.392
35	28	59.534	59.039	-0.495
35	29	59.307	58.881	-0.426
35	30	58.842	58.595	-0.247
35	31	59.000	58.856	-0.144
35	32	59.544	59.174	-0.370
30	33	60.233	59.813	-0.420
30	34	59.826	59.221	-0.605
30	35	57.771	57.104	-0.667
30	36	60.710	60.042	-0.668
30	37	60.277	59.807	-0.470
	Max	60.964	60.537	-0.144
	Average	59.434	59.016	-0.417
	Min	57.771	57.104	-0.668
	Std Dev	0.789	0.784	0.117



	36.2_MIN_ON_TIME			
Test Site				
Tester				
Test Number				
Max Limit	82	nSec		
Min Limit	52	nSec		
kRad(Si)	20	25	30	35
LL	52.000	52.000	52.000	52.000
Min	57.630	58.342	57.104	58.595
Average	58.905	59.433	59.197	58.909
Max	60.488	60.537	60.042	59.174
UL	82.000	82.000	82.000	82.000

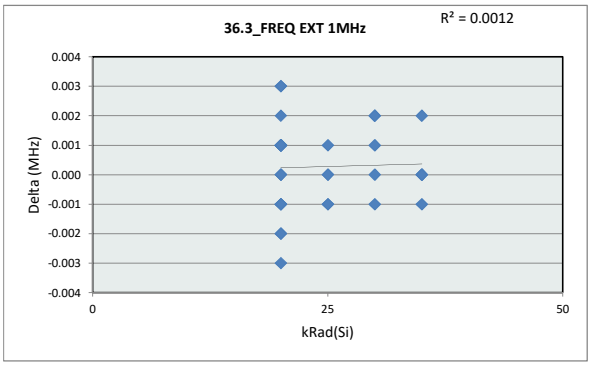


LDR TID Report
TPS7H4010-SEP

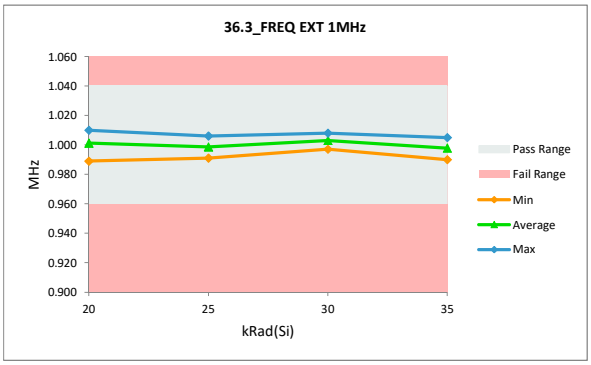
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.3_FREQ EXT 1MHz	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	1.04	1.04
Min Limit	0.96	0.96

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.993	0.994	0.001
25	2	1.007	1.006	-0.001
25	3	1.003	1.003	0.000
25	4	0.991	0.991	0.000
25	5	1.000	0.999	-0.001
20	6	0.989	0.990	0.001
20	7	1.002	1.003	0.001
20	8	1.006	1.009	0.003
20	9	1.005	1.006	0.001
20	10	1.004	1.004	0.000
20	11	0.992	0.989	-0.003
20	12	1.009	1.010	0.001
20	13	1.007	1.007	0.000
20	14	1.010	1.008	-0.002
20	15	1.006	1.007	0.001
20	16	0.993	0.991	-0.002
20	17	0.997	0.997	0.000
20	18	0.997	0.996	-0.001
20	19	1.001	1.004	0.003
20	20	1.003	1.004	0.001
20	21	1.001	1.002	0.001
20	22	0.995	0.997	0.002
20	23	0.994	0.993	-0.001
20	24	1.003	1.002	-0.001
20	25	1.005	1.006	0.001
20	26	0.995	0.994	-0.001
20	27	1.006	1.007	0.001
35	28	1.005	1.005	0.000
35	29	1.005	1.005	0.000
35	30	0.992	0.991	-0.001
35	31	0.996	0.998	0.002
35	32	0.990	0.990	0.000
30	33	1.006	1.008	0.002
30	34	0.997	0.997	0.000
30	35	1.004	1.003	-0.001
30	36	0.997	0.999	0.002
30	37	1.007	1.008	0.001
Max		1.010	1.010	0.003
Average		1.000	1.001	0.000
Min		0.989	0.989	-0.003
Std Dev		0.006	0.006	0.001



	36.3_FREQ EXT 1MHz			
Test Site				
Tester				
Test Number				
Max Limit	1.04	MHz		
Min Limit	0.96	MHz		
kRad(Si)	20	25	30	35
LL	0.960	0.960	0.960	0.960
Min	0.989	0.991	0.997	0.990
Average	1.001	0.999	1.003	0.998
Max	1.010	1.006	1.008	1.005
UL	1.040	1.040	1.040	1.040

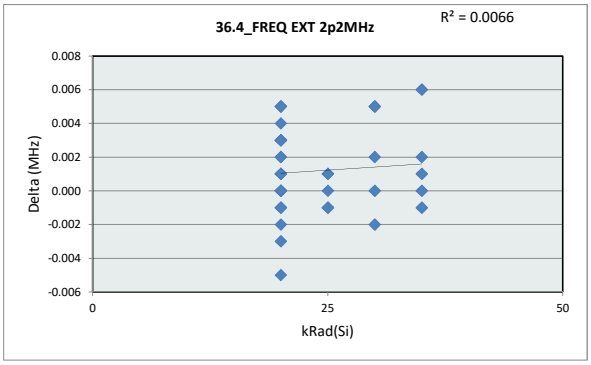


LDR TID Report
TPS7H4010-SEP

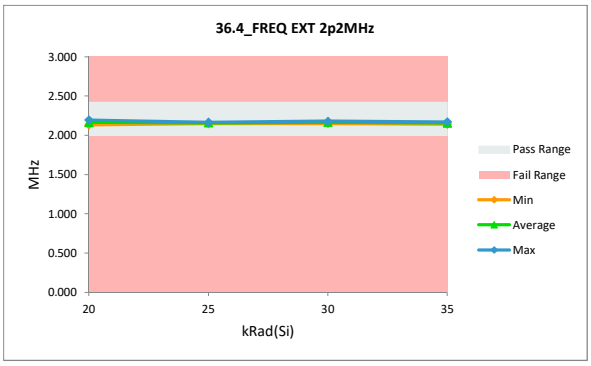
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.4_FREQ EXT 2p2MHz	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	2.42	2.42
Min Limit	1.98	1.98

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	2.152	2.153	0.001
25	2	2.167	2.166	-0.001
25	3	2.164	2.165	0.001
25	4	2.149	2.149	0.000
25	5	2.158	2.157	-0.001
20	6	2.135	2.136	0.001
20	7	2.168	2.170	0.002
20	8	2.168	2.173	0.005
20	9	2.177	2.180	0.003
20	10	2.163	2.166	0.003
20	11	2.137	2.132	-0.005
20	12	2.191	2.194	0.003
20	13	2.166	2.165	-0.001
20	14	2.182	2.181	-0.001
20	15	2.173	2.174	0.001
20	16	2.139	2.136	-0.003
20	17	2.151	2.149	-0.002
20	18	2.152	2.152	0.000
20	19	2.165	2.170	0.005
20	20	2.167	2.171	0.004
20	21	2.168	2.170	0.002
20	22	2.147	2.152	0.005
20	23	2.146	2.146	0.000
20	24	2.165	2.165	0.000
20	25	2.174	2.177	0.003
20	26	2.142	2.142	0.000
20	27	2.176	2.177	0.001
35	28	2.168	2.170	0.002
35	29	2.166	2.167	0.001
35	30	2.143	2.142	-0.001
35	31	2.150	2.156	0.006
35	32	2.139	2.139	0.000
30	33	2.174	2.179	0.005
30	34	2.150	2.150	0.000
30	35	2.170	2.168	-0.002
30	36	2.150	2.155	0.005
30	37	2.174	2.176	0.002
Max		2.191	2.194	0.006
Average		2.160	2.161	0.001
Min		2.135	2.132	-0.005
Std Dev		0.014	0.015	0.003



	36.4_FREQ EXT 2p2MHz			
Test Site				
Tester				
Test Number				
Max Limit	2.42	MHz		
Min Limit	1.98	MHz		
kRad(Si)	20	25	30	35
LL	1.980	1.980	1.980	1.980
Min	2.132	2.149	2.150	2.139
Average	2.163	2.158	2.166	2.155
Max	2.194	2.166	2.179	2.170
UL	2.420	2.420	2.420	2.420

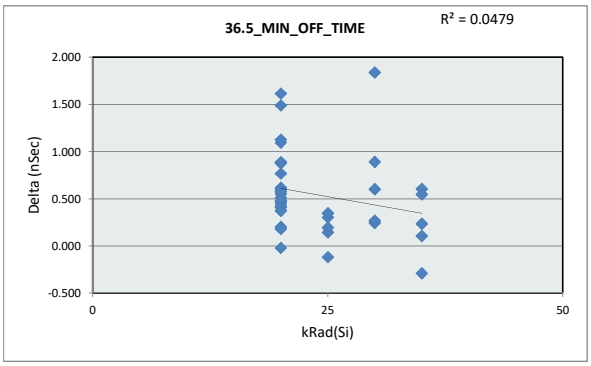


LDR TID Report
TPS7H4010-SEP

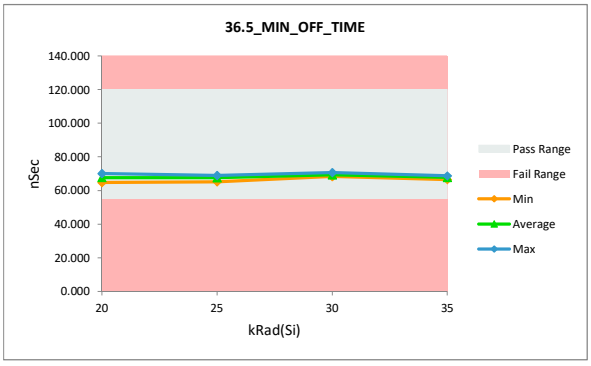
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.5_MIN_OFF_TIME	
Test Site		
Tester		
Test Number		
Unit	nSec	nSec
Max Limit	120	120
Min Limit	55	55

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	67.711	67.592	-0.119
25	2	68.712	69.015	0.303
25	3	64.874	65.222	0.348
25	4	66.962	67.105	0.143
25	5	68.690	68.884	0.194
20	6	68.578	68.949	0.371
20	7	64.306	64.729	0.423
20	8	69.105	69.083	-0.022
20	9	67.417	67.869	0.452
20	10	66.155	66.703	0.548
20	11	69.324	69.733	0.409
20	12	64.109	64.985	0.876
20	13	68.273	68.753	0.480
20	14	66.103	66.869	0.766
20	15	68.988	70.082	1.094
20	16	67.440	68.038	0.598
20	17	67.916	68.533	0.617
20	18	66.978	67.181	0.203
20	19	68.533	68.908	0.375
20	20	66.445	68.060	1.615
20	21	64.899	65.370	0.471
20	22	67.774	67.954	0.180
20	23	66.651	68.140	1.489
20	24	66.164	67.052	0.888
20	25	67.962	68.472	0.510
20	26	66.044	66.618	0.574
20	27	66.462	67.589	1.127
35	28	68.634	68.344	-0.290
35	29	68.479	68.714	0.235
35	30	65.858	66.461	0.603
35	31	68.231	68.777	0.546
35	32	66.780	66.886	0.106
30	33	68.217	68.460	0.243
30	34	69.292	69.559	0.267
30	35	67.459	68.349	0.890
30	36	70.087	70.689	0.602
30	37	67.709	69.548	1.839
	Max	70.087	70.689	1.839
	Average	67.387	67.926	0.539
	Min	64.109	64.729	-0.290
	Std Dev	1.461	1.416	0.454



	36.5_MIN_OFF_TIME			
Test Site				
Tester				
Test Number				
Max Limit	120	nSec		
Min Limit	55	nSec		
kRad(Si)	20	25	30	35
LL	55.000	55.000	55.000	55.000
Min	64.729	65.222	68.349	66.461
Average	67.712	67.564	69.321	67.836
Max	70.082	69.015	70.689	68.777
UL	120.000	120.000	120.000	120.000

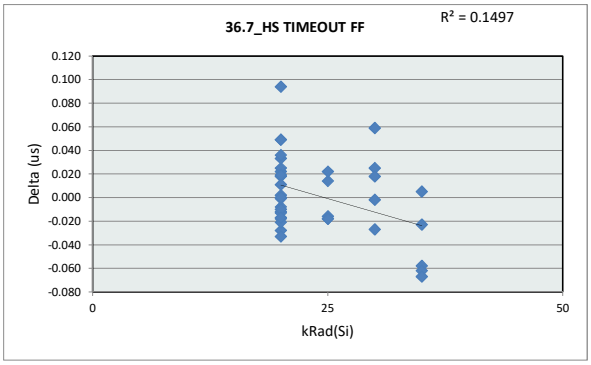


LDR TID Report
TPS7H4010-SEP

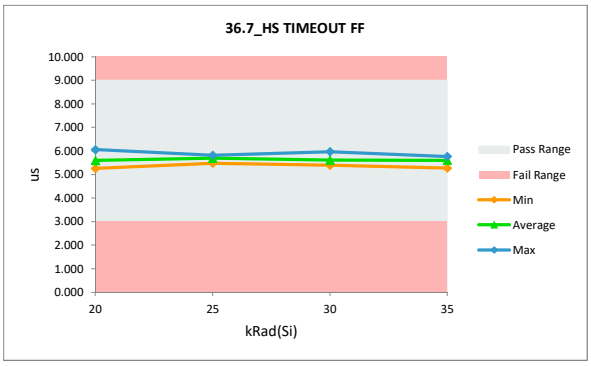
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.7_HS TIMEOUT FF	
Test Site		
Tester		
Test Number		
Unit	us	us
Max Limit	9	9
Min Limit	3	3

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	5.499	5.481	-0.018
25	2	5.821	5.805	-0.016
25	3	5.833	5.815	-0.018
25	4	5.646	5.660	0.014
25	5	5.675	5.697	0.022
20	6	5.445	5.417	-0.028
20	7	5.598	5.616	0.018
20	8	5.723	5.772	0.049
20	9	6.072	6.054	-0.018
20	10	5.255	5.254	-0.001
20	11	5.416	5.418	0.002
20	12	5.727	5.715	-0.012
20	13	5.480	5.502	0.022
20	14	5.385	5.479	0.094
20	15	5.393	5.372	-0.021
20	16	5.675	5.700	0.025
20	17	5.365	5.398	0.033
20	18	5.709	5.676	-0.033
20	19	5.798	5.790	-0.008
20	20	5.590	5.590	0.000
20	21	5.839	5.826	-0.013
20	22	5.721	5.711	-0.010
20	23	5.481	5.492	0.011
20	24	5.606	5.589	-0.017
20	25	5.600	5.619	0.019
20	26	5.530	5.566	0.036
20	27	5.465	5.514	0.049
35	28	5.683	5.688	0.005
35	29	5.799	5.741	-0.058
35	30	5.830	5.768	-0.062
35	31	5.334	5.267	-0.067
35	32	5.569	5.546	-0.023
30	33	5.369	5.394	0.025
30	34	5.766	5.739	-0.027
30	35	5.470	5.488	0.018
30	36	5.912	5.971	0.059
30	37	5.486	5.484	-0.002
	Max	6.072	6.054	0.094
	Average	5.610	5.611	0.001
	Min	5.255	5.254	-0.067
	Std Dev	0.187	0.182	0.033



	36.7_HS TIMEOUT FF			
Test Site				
Tester				
Test Number				
Max Limit	9	us		
Min Limit	3	us		
kRad(Si)	20	25	30	35
LL	3.000	3.000	3.000	3.000
Min	5.254	5.481	5.394	5.267
Average	5.594	5.692	5.615	5.602
Max	6.054	5.815	5.971	5.768
UL	9.000	9.000	9.000	9.000

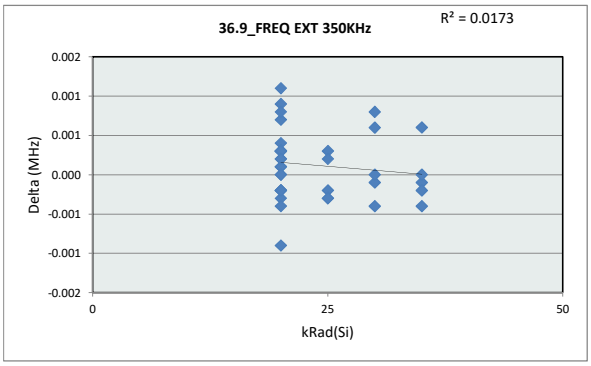


LDR TID Report
TPS7H4010-SEP

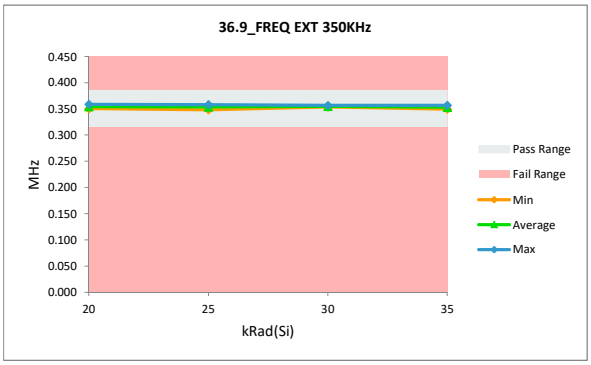
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	36.9_FREQ EXT 350KHz	
Test Site		
Tester		
Test Number		
Unit	MHz	MHz
Max Limit	0.385	0.385
Min Limit	0.315	0.315

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.350	0.350	0.000
25	2	0.358	0.358	0.000
25	3	0.356	0.357	0.000
25	4	0.349	0.348	0.000
25	5	0.355	0.354	0.000
20	6	0.350	0.350	0.000
20	7	0.354	0.354	0.000
20	8	0.357	0.358	0.001
20	9	0.354	0.354	0.000
20	10	0.356	0.357	0.000
20	11	0.352	0.351	-0.001
20	12	0.355	0.356	0.001
20	13	0.359	0.359	0.000
20	14	0.357	0.357	0.000
20	15	0.356	0.356	0.000
20	16	0.352	0.352	0.000
20	17	0.354	0.353	0.000
20	18	0.353	0.353	0.000
20	19	0.353	0.354	0.001
20	20	0.354	0.354	0.000
20	21	0.354	0.354	0.000
20	22	0.352	0.353	0.001
20	23	0.352	0.352	0.000
20	24	0.355	0.355	0.000
20	25	0.354	0.355	0.000
20	26	0.353	0.353	0.000
20	27	0.355	0.355	0.000
35	28	0.356	0.356	0.000
35	29	0.357	0.357	0.000
35	30	0.351	0.351	0.000
35	31	0.352	0.353	0.001
35	32	0.350	0.350	0.000
30	33	0.356	0.356	0.001
30	34	0.354	0.354	0.000
30	35	0.355	0.355	0.000
30	36	0.353	0.354	0.001
30	37	0.356	0.356	0.000
	Max	0.359	0.359	0.001
	Average	0.354	0.354	0.000
	Min	0.349	0.348	-0.001
	Std Dev	0.002	0.002	0.000



	36.9_FREQ EXT 350KHz			
Test Site				
Tester				
Test Number				
Max Limit	0.385	MHz		
Min Limit	0.315	MHz		
kRad(Si)	20	25	30	35
LL	0.315	0.315	0.315	0.315
Min	0.350	0.348	0.354	0.350
Average	0.354	0.353	0.355	0.353
Max	0.359	0.358	0.357	0.357
UL	0.385	0.385	0.385	0.385

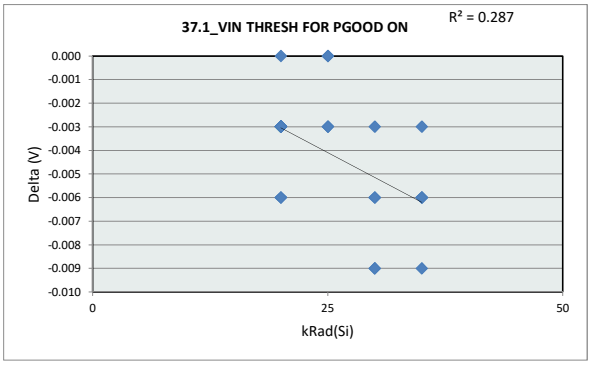


LDR TID Report
TPS7H4010-SEP

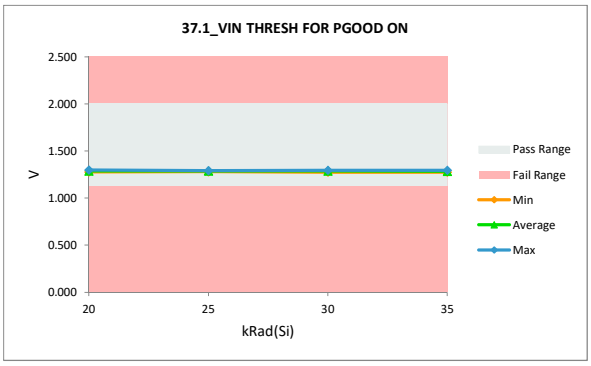
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.1_VIN THRESH FOR PGOOD O	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2	2
Min Limit	1.12	1.12

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.289	1.289	0.000
25	2	1.292	1.289	-0.003
25	3	1.289	1.286	-0.003
25	4	1.283	1.280	-0.003
25	5	1.292	1.292	0.000
20	6	1.292	1.289	-0.003
20	7	1.289	1.286	-0.003
20	8	1.301	1.298	-0.003
20	9	1.289	1.286	-0.003
20	10	1.292	1.289	-0.003
20	11	1.283	1.283	0.000
20	12	1.280	1.277	-0.003
20	13	1.292	1.289	-0.003
20	14	1.292	1.289	-0.003
20	15	1.304	1.298	-0.006
20	16	1.286	1.283	-0.003
20	17	1.286	1.283	-0.003
20	18	1.280	1.277	-0.003
20	19	1.295	1.292	-0.003
20	20	1.295	1.289	-0.006
20	21	1.292	1.289	-0.003
20	22	1.286	1.283	-0.003
20	23	1.292	1.289	-0.003
20	24	1.292	1.289	-0.003
20	25	1.292	1.289	-0.003
20	26	1.295	1.292	-0.003
20	27	1.289	1.283	-0.006
35	28	1.301	1.295	-0.006
35	29	1.283	1.280	-0.003
35	30	1.289	1.283	-0.006
35	31	1.289	1.283	-0.006
35	32	1.283	1.274	-0.009
30	33	1.298	1.292	-0.006
30	34	1.298	1.295	-0.003
30	35	1.283	1.274	-0.009
30	36	1.289	1.280	-0.009
30	37	1.298	1.292	-0.006
Max		1.304	1.298	0.000
Average		1.291	1.287	-0.004
Min		1.280	1.274	-0.009
Std Dev		0.006	0.006	0.002



	37.1_VIN THRESH FOR PGOOD			
Test Site				
Tester				
Test Number				
Max Limit	2	V		
Min Limit	1.12	V		
kRad(Si)	20	25	30	35
LL	1.120	1.120	1.120	1.120
Min	1.277	1.280	1.274	1.274
Average	1.287	1.287	1.287	1.283
Max	1.298	1.292	1.295	1.295
UL	2.000	2.000	2.000	2.000

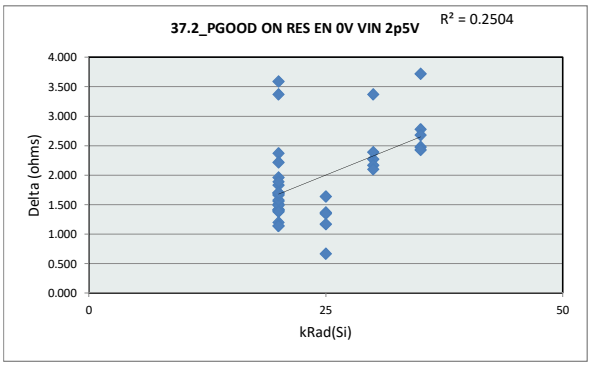


LDR TID Report
TPS7H4010-SEP

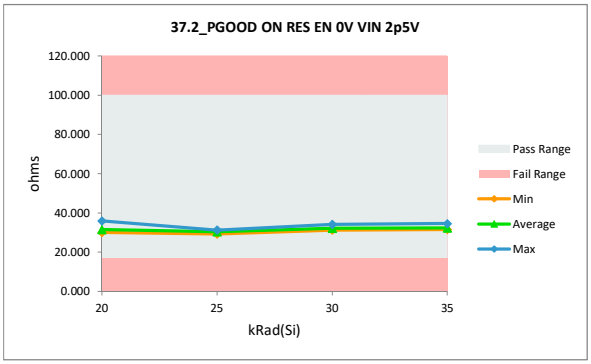
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.2_PGOOD ON RES EN 0V VIN	
Test Site		
Tester		
Test Number		
Unit	ohms	ohms
Max Limit	100	100
Min Limit	17	17

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	29.440	30.810	1.370
25	2	29.660	31.300	1.640
25	3	28.620	29.290	0.670
25	4	28.900	30.070	1.170
25	5	29.610	30.960	1.350
20	6	29.740	31.570	1.830
20	7	31.430	33.800	2.370
20	8	29.970	31.930	1.960
20	9	29.230	30.630	1.400
20	10	30.010	32.230	2.220
20	11	29.210	30.630	1.420
20	12	32.600	35.970	3.370
20	13	29.290	30.800	1.510
20	14	29.190	30.600	1.410
20	15	29.460	31.020	1.560
20	16	28.980	30.180	1.200
20	17	28.930	30.070	1.140
20	18	29.640	31.130	1.490
20	19	29.990	31.570	1.580
20	20	29.240	30.380	1.140
20	21	31.700	35.290	3.590
20	22	29.090	30.790	1.700
20	23	29.550	31.210	1.660
20	24	29.020	30.700	1.680
20	25	29.290	30.990	1.700
20	26	30.000	31.890	1.890
20	27	29.150	30.530	1.380
35	28	30.860	34.580	3.720
35	29	29.320	32.100	2.780
35	30	29.980	32.460	2.480
35	31	28.830	31.510	2.680
35	32	29.140	31.570	2.430
30	33	29.260	31.530	2.270
30	34	29.610	32.000	2.390
30	35	30.770	34.140	3.370
30	36	29.120	31.290	2.170
30	37	30.000	32.100	2.100
	Max	32.600	35.970	3.720
	Average	29.671	31.611	1.940
	Min	28.620	29.290	0.670
	Std Dev	0.843	1.461	0.732



	37.2_PGOOD ON RES EN 0V VI			
Test Site				
Tester				
Test Number				
Max Limit	100	ohms		
Min Limit	17	ohms		
kRad(Si)	20	25	30	35
LL	17.000	17.000	17.000	17.000
Min	30.070	29.290	31.290	31.510
Average	31.541	30.486	32.212	32.444
Max	35.970	31.300	34.140	34.580
UL	100.000	100.000	100.000	100.000

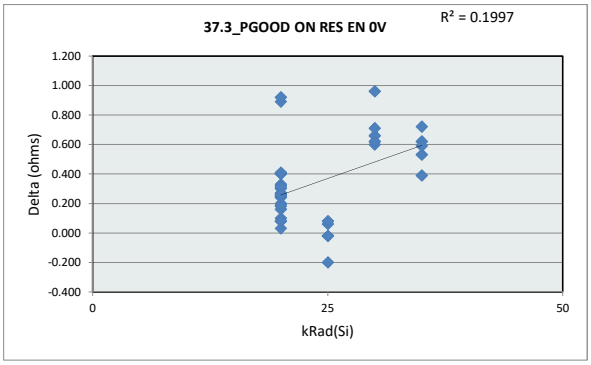


LDR TID Report
TPS7H4010-SEP

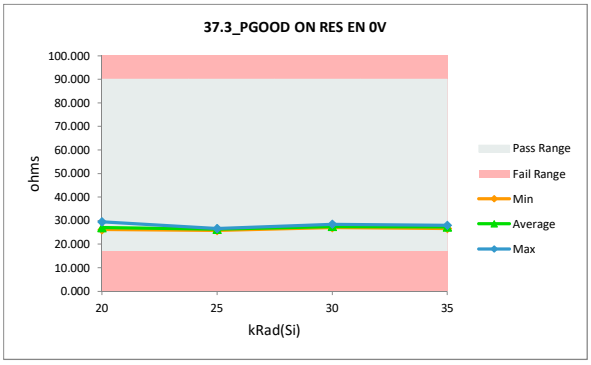
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.3_PGOOD ON RES EN 0V	
Test Site		
Tester		
Test Number		
Unit	ohms	ohms
Max Limit	90	90
Min Limit	17	17

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	26.340	26.400	0.060
25	2	26.580	26.660	0.080
25	3	26.030	25.830	-0.200
25	4	26.140	26.120	-0.020
25	5	26.640	26.620	-0.020
20	6	26.520	26.850	0.330
20	7	27.760	28.160	0.400
20	8	26.780	27.180	0.400
20	9	26.400	26.580	0.180
20	10	26.680	27.000	0.320
20	11	26.350	26.450	0.100
20	12	28.590	29.480	0.890
20	13	26.320	26.400	0.080
20	14	26.580	26.740	0.160
20	15	26.400	26.640	0.240
20	16	26.140	26.170	0.030
20	17	26.110	26.190	0.080
20	18	26.570	26.820	0.250
20	19	26.940	27.140	0.200
20	20	26.310	26.500	0.190
20	21	28.060	28.980	0.920
20	22	26.310	26.610	0.300
20	23	27.190	27.460	0.270
20	24	26.160	26.570	0.410
20	25	26.350	26.600	0.250
20	26	26.940	27.250	0.310
20	27	26.200	26.460	0.260
35	28	27.280	28.000	0.720
35	29	26.580	27.110	0.530
35	30	27.230	27.620	0.390
35	31	26.020	26.640	0.620
35	32	26.400	26.990	0.590
30	33	26.480	27.080	0.600
30	34	26.750	27.410	0.660
30	35	27.510	28.470	0.960
30	36	26.430	27.050	0.620
30	37	26.840	27.550	0.710
	Max	28.590	29.480	0.960
	Average	26.673	27.021	0.348
	Min	26.020	25.830	-0.200
	Std Dev	0.575	0.784	0.282



	37.3_PGOOD ON RES EN 0V			
Test Site				
Tester				
Test Number				
Max Limit	90	ohms		
Min Limit	17	ohms		
kRad(Si)	20	25	30	35
LL	17.000	17.000	17.000	17.000
Min	26.170	25.830	27.050	26.640
Average	27.010	26.326	27.512	27.272
Max	29.480	26.660	28.470	28.000
UL	90.000	90.000	90.000	90.000

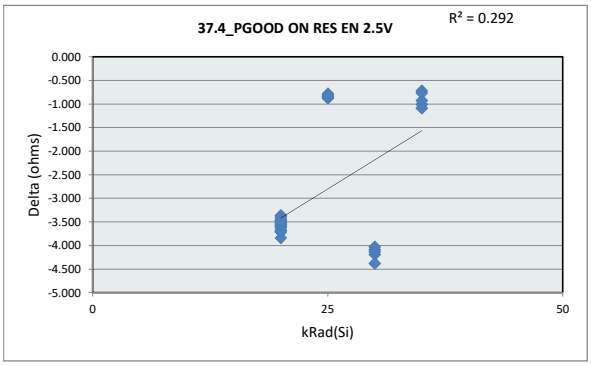


LDR TID Report
TPS7H4010-SEP

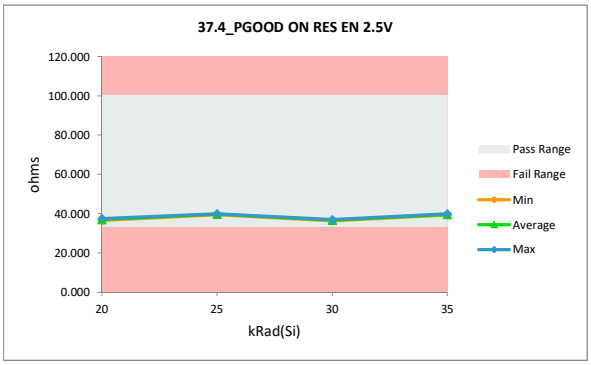
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.4_PGOOD ON RES EN 2.5V	
Test Site		
Tester		
Test Number		
Unit	ohms	ohms
Max Limit	100	100
Min Limit	33	33

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	40.600	39.720	-0.880
25	2	40.590	39.810	-0.780
25	3	40.300	39.490	-0.810
25	4	40.600	39.730	-0.870
25	5	40.760	39.920	-0.840
20	6	40.630	36.930	-3.700
20	7	41.020	37.180	-3.840
20	8	40.730	37.010	-3.720
20	9	39.920	36.450	-3.470
20	10	40.360	36.800	-3.560
20	11	40.760	37.280	-3.480
20	12	41.200	37.510	-3.690
20	13	40.390	36.720	-3.670
20	14	40.480	36.860	-3.620
20	15	40.900	37.320	-3.580
20	16	40.220	36.630	-3.590
20	17	40.280	36.880	-3.400
20	18	40.580	36.960	-3.620
20	19	40.610	37.150	-3.460
20	20	40.290	36.770	-3.520
20	21	40.940	37.240	-3.700
20	22	40.540	36.970	-3.570
20	23	40.830	37.290	-3.540
20	24	39.980	36.620	-3.360
20	25	40.320	36.850	-3.470
20	26	40.550	37.140	-3.410
20	27	40.340	36.870	-3.470
35	28	40.550	39.460	-1.090
35	29	40.290	39.280	-1.010
35	30	40.860	39.930	-0.930
35	31	40.170	39.450	-0.720
35	32	40.370	39.600	-0.770
30	33	40.670	36.480	-4.190
30	34	40.740	36.360	-4.380
30	35	41.080	36.950	-4.130
30	36	40.660	36.570	-4.090
30	37	40.680	36.650	-4.030
	Max	41.200	39.930	-0.720
	Average	40.562	37.644	-2.918
	Min	39.920	36.360	-4.380
	Std Dev	0.290	1.261	1.285



	37.4_PGOOD ON RES EN 2.5V			
Test Site				
Tester				
Test Number				
Max Limit	100	ohms		
Min Limit	33	ohms		
kRad(Si)	20	25	30	35
LL	33.000	33.000	33.000	33.000
Min	36.450	39.490	36.360	39.280
Average	36.974	39.734	36.602	39.544
Max	37.510	39.920	36.950	39.930
UL	100.000	100.000	100.000	100.000

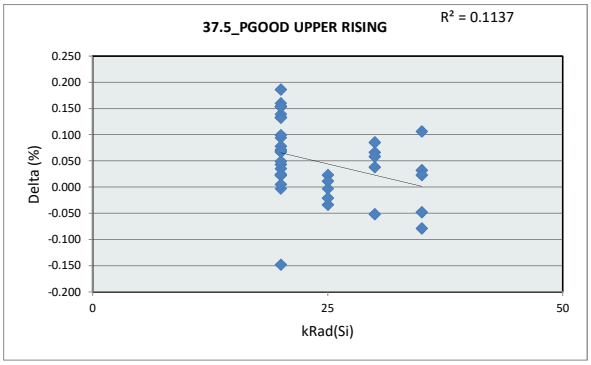


LDR TID Report
TPS7H4010-SEP

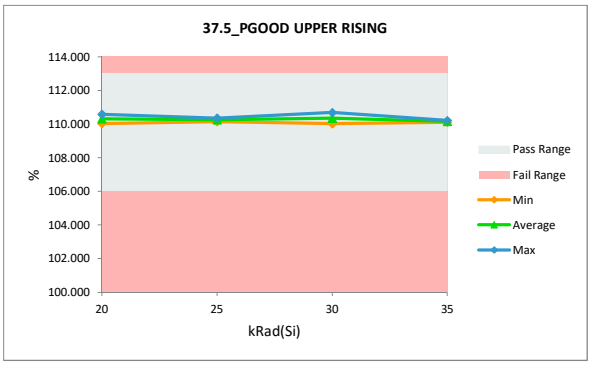
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.5_PGOOD UPPER RISING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	113	113
Min Limit	106	106

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	110.325	110.348	0.023
25	2	110.236	110.202	-0.034
25	3	110.249	110.246	-0.003
25	4	110.324	110.335	0.011
25	5	110.162	110.141	-0.021
20	6	110.343	110.410	0.067
20	7	110.195	110.266	0.071
20	8	110.368	110.390	0.022
20	9	110.316	110.449	0.133
20	10	110.179	110.214	0.035
20	11	110.024	110.163	0.139
20	12	110.495	110.573	0.078
20	13	110.102	110.170	0.068
20	14	110.247	110.341	0.094
20	15	109.999	110.022	0.023
20	16	110.168	110.165	-0.003
20	17	110.495	110.347	-0.148
20	18	110.203	110.389	0.186
20	19	110.405	110.565	0.160
20	20	110.526	110.569	0.043
20	21	110.055	110.079	0.024
20	22	110.143	110.148	0.005
20	23	110.143	110.242	0.099
20	24	110.166	110.320	0.154
20	25	110.360	110.513	0.153
20	26	110.257	110.306	0.049
20	27	110.136	110.268	0.132
35	28	110.158	110.110	-0.048
35	29	110.287	110.208	-0.079
35	30	110.060	110.092	0.032
35	31	110.099	110.205	0.106
35	32	110.116	110.139	0.023
30	33	110.069	110.017	-0.052
30	34	110.645	110.683	0.038
30	35	110.372	110.457	0.085
30	36	110.394	110.460	0.066
30	37	110.069	110.127	0.058
	Max	110.645	110.683	0.186
	Average	110.240	110.289	0.048
	Min	109.999	110.017	-0.148
	Std Dev	0.154	0.167	0.072



	37.5_PGOOD UPPER RISING			
Test Site				
Tester				
Test Number				
Max Limit	113	%		
Min Limit	106	%		
kRad(Si)	20	25	30	35
LL	106.000	106.000	106.000	106.000
Min	110.022	110.141	110.017	110.092
Average	110.314	110.254	110.349	110.151
Max	110.573	110.348	110.683	110.208
UL	113.000	113.000	113.000	113.000

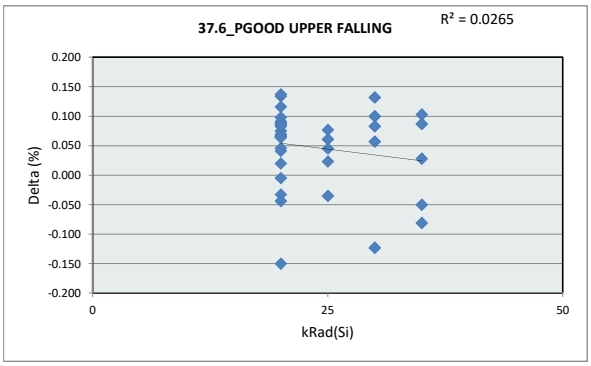


LDR TID Report
TPS7H4010-SEP

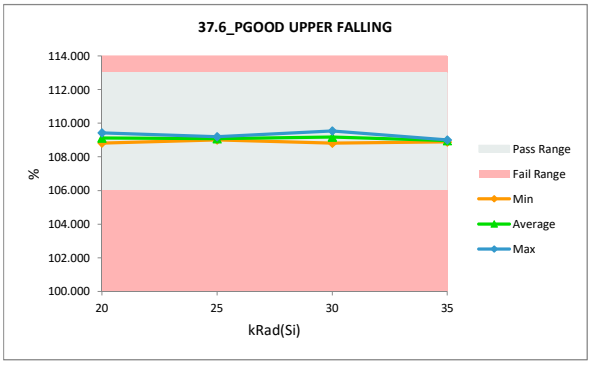
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.6_PGOOD UPPER FALLING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	113	113
Min Limit	106	106

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	109.063	109.086	0.023
25	2	109.040	109.005	-0.035
25	3	109.052	109.113	0.061
25	4	109.126	109.203	0.077
25	5	108.965	109.010	0.045
20	6	109.147	109.212	0.065
20	7	108.932	109.066	0.134
20	8	109.171	109.191	0.020
20	9	109.185	109.251	0.066
20	10	109.049	109.016	-0.033
20	11	108.893	109.030	0.137
20	12	109.232	109.307	0.075
20	13	108.907	108.971	0.064
20	14	109.049	109.140	0.091
20	15	108.870	108.826	-0.044
20	16	109.035	109.030	-0.005
20	17	109.300	109.150	-0.150
20	18	109.073	109.189	0.116
20	19	109.274	109.364	0.090
20	20	109.395	109.436	0.041
20	21	108.793	108.880	0.087
20	22	108.946	109.015	0.069
20	23	108.946	109.044	0.098
20	24	109.036	109.121	0.085
20	25	109.231	109.314	0.083
20	26	109.127	109.173	0.046
20	27	109.007	109.072	0.065
35	28	108.962	108.912	-0.050
35	29	109.090	109.009	-0.081
35	30	108.862	108.890	0.028
35	31	108.902	109.005	0.103
35	32	108.920	109.007	0.087
30	33	108.941	108.818	-0.123
30	34	109.448	109.548	0.100
30	35	109.174	109.257	0.083
30	36	109.195	109.327	0.132
30	37	108.873	108.930	0.057
	Max	109.448	109.548	0.137
	Average	109.060	109.106	0.046
	Min	108.793	108.818	-0.150
	Std Dev	0.154	0.168	0.069



	37.6_PGOOD UPPER FALLING			
Test Site				
Tester				
Test Number				
Max Limit	113	%		
Min Limit	106	%		
kRad(Si)	20	25	30	35
LL	106.000	106.000	106.000	106.000
Min	108.826	109.005	108.818	108.890
Average	109.127	109.083	109.176	108.965
Max	109.436	109.203	109.548	109.009
UL	113.000	113.000	113.000	113.000

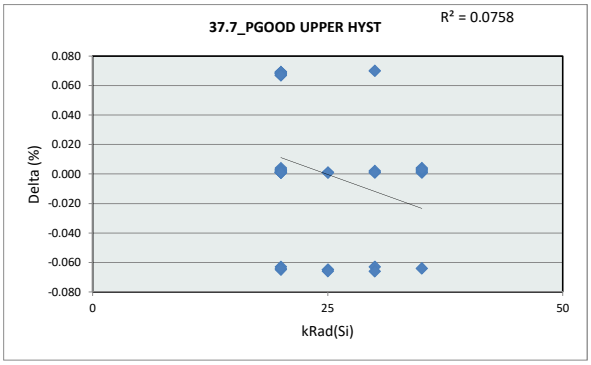


LDR TID Report
TPS7H4010-SEP

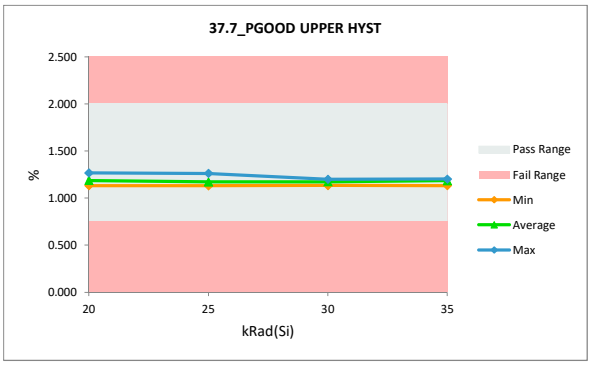
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.7_PGOOD UPPER HYST	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	2	2
Min Limit	0.75	0.75

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.261	1.262	0.001
25	2	1.196	1.197	0.001
25	3	1.197	1.132	-0.065
25	4	1.198	1.133	-0.065
25	5	1.197	1.131	-0.066
20	6	1.196	1.198	0.002
20	7	1.264	1.199	-0.065
20	8	1.198	1.199	0.001
20	9	1.130	1.198	0.068
20	10	1.130	1.198	0.068
20	11	1.131	1.132	0.001
20	12	1.263	1.266	0.003
20	13	1.195	1.199	0.004
20	14	1.198	1.201	0.003
20	15	1.129	1.196	0.067
20	16	1.132	1.134	0.002
20	17	1.195	1.197	0.002
20	18	1.131	1.200	0.069
20	19	1.131	1.200	0.069
20	20	1.131	1.132	0.001
20	21	1.262	1.199	-0.063
20	22	1.197	1.133	-0.064
20	23	1.197	1.198	0.001
20	24	1.130	1.198	0.068
20	25	1.129	1.198	0.069
20	26	1.131	1.132	0.001
20	27	1.129	1.196	0.067
35	28	1.197	1.198	0.001
35	29	1.197	1.199	0.002
35	30	1.198	1.202	0.004
35	31	1.197	1.200	0.003
35	32	1.196	1.132	-0.064
30	33	1.129	1.199	0.070
30	34	1.198	1.135	-0.063
30	35	1.198	1.200	0.002
30	36	1.199	1.133	-0.066
30	37	1.196	1.197	0.001
	Max	1.264	1.266	0.070
	Average	1.181	1.183	0.002
	Min	1.129	1.131	-0.066
	Std Dev	0.043	0.036	0.047



	37.7_PGOOD UPPER HYST			
Test Site				
Tester				
Test Number				
Max Limit	2	%		
Min Limit	0.75	%		
kRad(Si)	20	25	30	35
LL	0.750	0.750	0.750	0.750
Min	1.132	1.131	1.133	1.132
Average	1.187	1.171	1.173	1.186
Max	1.266	1.262	1.200	1.202
UL	2.000	2.000	2.000	2.000

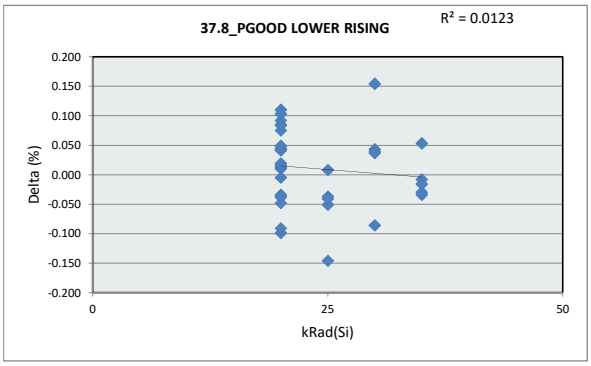


LDR TID Report
TPS7H4010-SEP

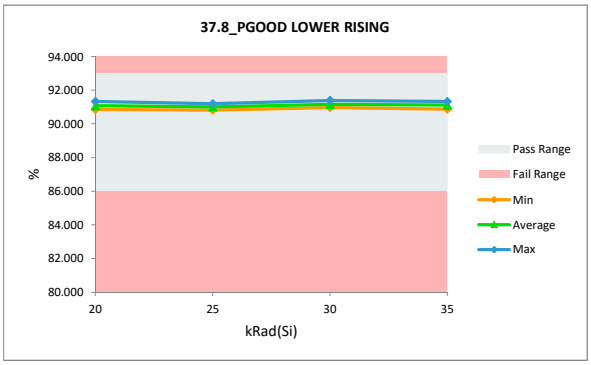
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.8_PGOOD LOWER RISING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	93	93
Min Limit	86	86

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	90.808	90.816	0.008
25	2	91.165	91.114	-0.051
25	3	91.231	91.194	-0.037
25	4	91.226	91.080	-0.146
25	5	90.882	90.841	-0.041
20	6	91.077	91.043	-0.034
20	7	90.976	90.877	-0.099
20	8	91.075	91.070	-0.005
20	9	91.032	91.142	0.110
20	10	90.962	91.046	0.084
20	11	90.866	90.914	0.048
20	12	91.015	91.056	0.041
20	13	91.109	91.119	0.010
20	14	91.284	91.328	0.044
20	15	91.068	91.087	0.019
20	16	90.985	90.947	-0.038
20	17	91.105	91.057	-0.048
20	18	91.049	91.124	0.075
20	19	91.117	91.159	0.042
20	20	91.040	91.052	0.012
20	21	91.192	91.155	-0.037
20	22	91.065	91.157	0.092
20	23	91.054	91.069	0.015
20	24	91.096	91.145	0.049
20	25	90.970	91.073	0.103
20	26	91.038	91.122	0.084
20	27	90.950	90.859	-0.091
35	28	90.879	90.871	-0.008
35	29	91.263	91.229	-0.034
35	30	91.361	91.331	-0.030
35	31	91.017	91.070	0.053
35	32	91.110	91.094	-0.016
30	33	90.949	91.103	0.154
30	34	91.084	91.123	0.039
30	35	91.278	91.192	-0.086
30	36	91.351	91.394	0.043
30	37	90.937	90.974	0.037
	Max	91.361	91.394	0.154
	Average	91.072	91.082	0.010
	Min	90.808	90.816	-0.146
	Std Dev	0.134	0.132	0.065



	37.8_PGOOD LOWER RISING			
Test Site				
Tester				
Test Number				
Max Limit	93	%		
Min Limit	86	%		
kRad(Si)	20	25	30	35
LL	86.000	86.000	86.000	86.000
Min	90.859	90.816	90.974	90.871
Average	91.073	91.009	91.157	91.119
Max	91.328	91.194	91.394	91.331
UL	93.000	93.000	93.000	93.000

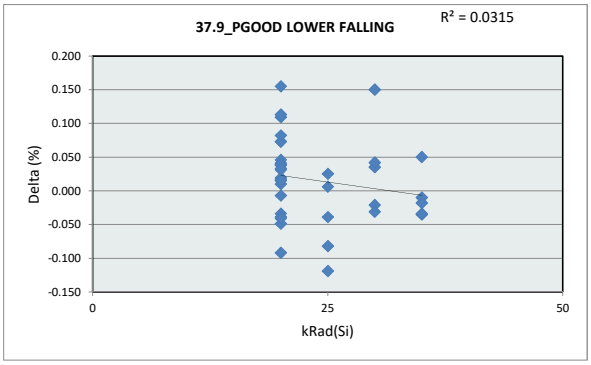


LDR TID Report
TPS7H4010-SEP

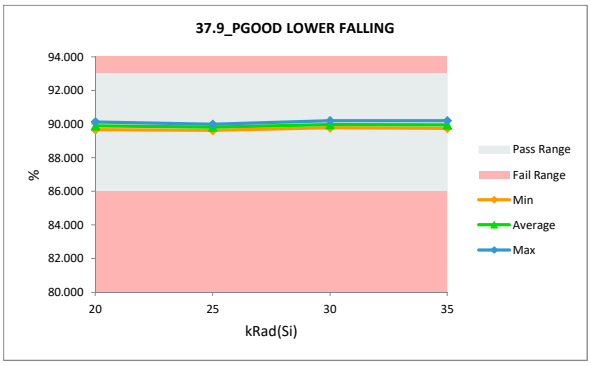
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.9_PGOOD LOWER FALLING	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	93	93
Min Limit	86	86

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	89.614	89.620	0.006
25	2	90.036	89.917	-0.119
25	3	90.034	89.995	-0.039
25	4	89.962	89.880	-0.082
25	5	89.685	89.710	0.025
20	6	89.881	89.912	0.031
20	7	89.712	89.678	-0.034
20	8	89.878	89.871	-0.007
20	9	89.768	89.877	0.109
20	10	89.832	89.848	0.016
20	11	89.735	89.781	0.046
20	12	89.752	89.790	0.038
20	13	89.914	89.987	0.073
20	14	90.086	90.127	0.041
20	15	89.938	89.957	0.019
20	16	89.852	89.813	-0.039
20	17	89.976	89.927	-0.049
20	18	89.851	89.924	0.073
20	19	89.919	89.958	0.039
20	20	89.910	89.920	0.010
20	21	89.930	89.889	-0.041
20	22	89.802	89.957	0.155
20	23	89.923	89.938	0.015
20	24	89.900	90.013	0.113
20	25	89.841	89.874	0.033
20	26	89.841	89.923	0.082
20	27	89.755	89.663	-0.092
35	28	89.749	89.739	-0.010
35	29	90.065	90.030	-0.035
35	30	90.230	90.196	-0.034
35	31	89.820	89.870	0.050
35	32	89.914	89.896	-0.018
30	33	89.754	89.904	0.150
30	34	89.953	89.988	0.035
30	35	90.013	89.992	-0.021
30	36	90.152	90.194	0.042
30	37	89.808	89.777	-0.031
Max		90.230	90.196	0.155
Average		89.886	89.901	0.015
Min		89.614	89.620	-0.119
Std Dev		0.132	0.129	0.062



	37.9_PGOOD LOWER FALLING			
Test Site				
Tester				
Test Number				
Max Limit	93	%		
Min Limit	86	%		
kRad(Si)	20	25	30	35
LL	86.000	86.000	86.000	86.000
Min	89.663	89.620	89.777	89.739
Average	89.892	89.824	89.971	89.946
Max	90.127	89.995	90.194	90.196
UL	93.000	93.000	93.000	93.000

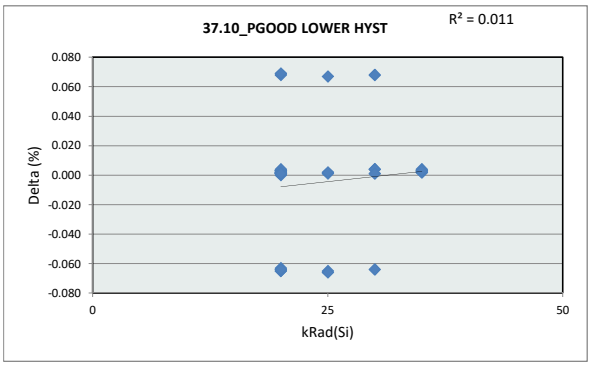


LDR TID Report
TPS7H4010-SEP

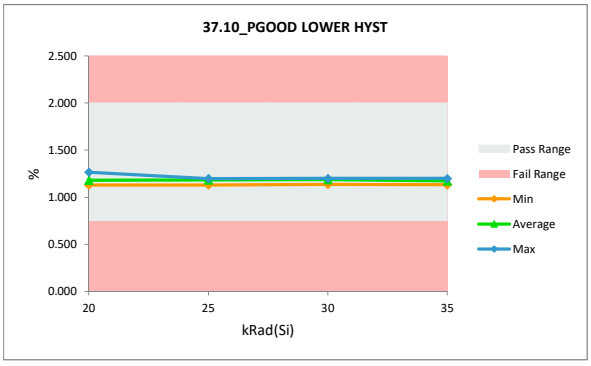
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.10_PGOOD LOWER HYST	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	2	2
Min Limit	0.75	0.75

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	1.195	1.196	0.001
25	2	1.130	1.197	0.067
25	3	1.197	1.199	0.002
25	4	1.264	1.199	-0.065
25	5	1.197	1.131	-0.066
20	6	1.196	1.131	-0.065
20	7	1.264	1.199	-0.065
20	8	1.198	1.199	0.001
20	9	1.263	1.265	0.002
20	10	1.130	1.198	0.068
20	11	1.131	1.132	0.001
20	12	1.263	1.266	0.003
20	13	1.195	1.132	-0.063
20	14	1.198	1.201	0.003
20	15	1.129	1.129	0.000
20	16	1.132	1.134	0.002
20	17	1.129	1.131	0.002
20	18	1.197	1.200	0.003
20	19	1.197	1.200	0.003
20	20	1.131	1.132	0.001
20	21	1.262	1.266	0.004
20	22	1.263	1.199	-0.064
20	23	1.131	1.132	0.001
20	24	1.196	1.132	-0.064
20	25	1.129	1.198	0.069
20	26	1.197	1.199	0.002
20	27	1.195	1.196	0.001
35	28	1.130	1.132	0.002
35	29	1.197	1.199	0.002
35	30	1.131	1.135	0.004
35	31	1.197	1.200	0.003
35	32	1.196	1.199	0.003
30	33	1.195	1.199	0.004
30	34	1.131	1.135	0.004
30	35	1.264	1.200	-0.064
30	36	1.199	1.200	0.001
30	37	1.129	1.197	0.068
	Max	1.264	1.266	0.069
	Average	1.186	1.181	-0.005
	Min	1.129	1.129	-0.066
	Std Dev	0.048	0.041	0.038



	37.10_PGOOD LOWER HYST			
Test Site				
Tester				
Test Number				
Max Limit	2	%		
Min Limit	0.75	%		
kRad(Si)	20	25	30	35
LL	0.750	0.750	0.750	0.750
Min	1.129	1.131	1.135	1.132
Average	1.181	1.184	1.186	1.173
Max	1.266	1.199	1.200	1.200
UL	2.000	2.000	2.000	2.000



LDR TID Report
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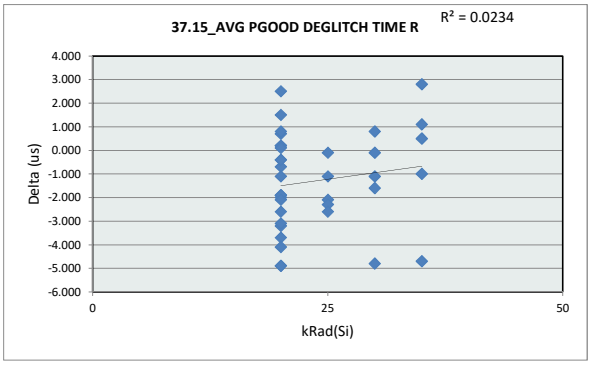
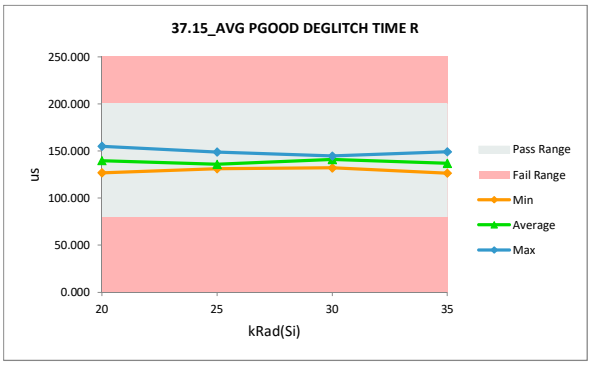
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.15_AVG PGOOD DEGLITCH TI	
Test Site		
Tester		
Test Number		
Unit	us	us
Max Limit	200	200
Min Limit	80	80

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	133.300	133.200	-0.100
25	2	135.000	132.900	-2.100
25	3	134.600	133.500	-1.100
25	4	133.400	131.100	-2.300
25	5	151.500	148.900	-2.600
20	6	132.800	133.500	0.700
20	7	145.900	141.000	-4.900
20	8	133.900	133.500	-0.400
20	9	146.000	144.000	-2.000
20	10	141.400	140.700	-0.700
20	11	143.000	140.400	-2.600
20	12	138.800	139.000	0.200
20	13	139.800	136.100	-3.700
20	14	149.000	149.200	0.200
20	15	131.700	126.800	-4.900
20	16	148.600	151.100	2.500
20	17	150.700	147.500	-3.200
20	18	143.700	144.500	0.800
20	19	142.100	138.000	-4.100
20	20	136.300	134.400	-1.900
20	21	141.300	140.900	-0.400
20	22	131.700	133.200	1.500
20	23	156.900	155.000	-1.900
20	24	136.300	136.400	0.100
20	25	137.600	136.500	-1.100
20	26	140.300	138.200	-2.100
20	27	138.400	135.300	-3.100
35	28	146.300	149.100	2.800
35	29	144.500	145.000	0.500
35	30	135.000	130.300	-4.700
35	31	125.300	126.400	1.100
35	32	134.600	133.600	-1.000
30	33	142.700	143.500	0.800
30	34	132.100	132.000	-0.100
30	35	149.400	144.600	-4.800
30	36	142.700	141.600	-1.100
30	37	144.700	143.100	-1.600
	Max	156.900	155.000	2.800
	Average	140.305	139.027	-1.278
	Min	125.300	126.400	-4.900
	Std Dev	6.892	6.941	2.038



	37.15_AVG PGOOD DEGLITCH T			
Test Site				
Tester				
Test Number				
Max Limit	200	us		
Min Limit	80	us		
kRad(Si)	20	25	30	35
LL	80.000	80.000	80.000	80.000
Min	126.800	131.100	132.000	126.400
Average	139.782	135.920	140.960	136.880
Max	155.000	148.900	144.600	149.100
UL	200.000	200.000	200.000	200.000

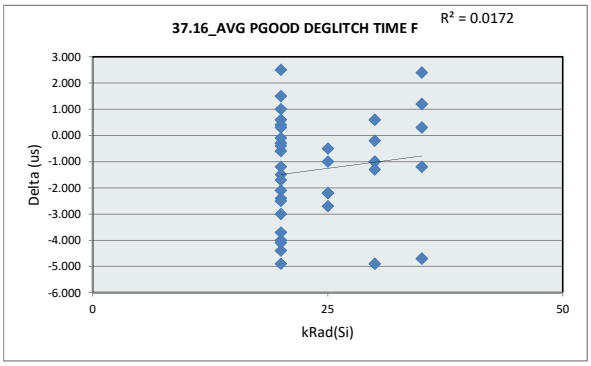


LDR TID Report
TPS7H4010-SEP

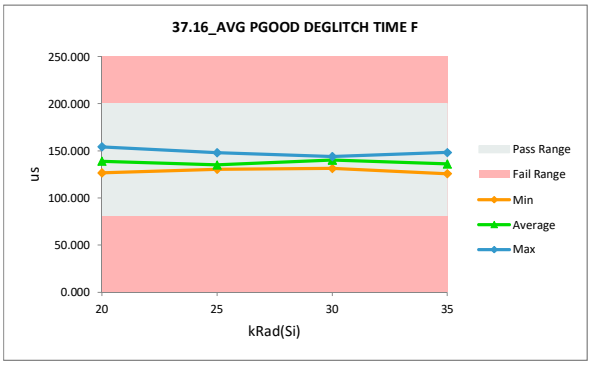
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.16_AVG PGOOD DEGLITCH TI	
Test Site		
Tester		
Test Number		
Unit	us	us
Max Limit	200	200
Min Limit	80	80

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	132.300	131.800	-0.500
25	2	134.300	132.100	-2.200
25	3	133.700	132.700	-1.000
25	4	132.600	130.400	-2.200
25	5	150.700	148.000	-2.700
20	6	131.900	132.500	0.600
20	7	145.300	140.400	-4.900
20	8	133.300	132.700	-0.600
20	9	145.200	143.100	-2.100
20	10	140.100	139.800	-0.300
20	11	142.200	139.800	-2.400
20	12	138.100	138.500	0.400
20	13	139.000	135.300	-3.700
20	14	148.300	148.600	0.300
20	15	130.900	126.500	-4.400
20	16	147.900	150.400	2.500
20	17	150.000	146.000	-4.000
20	18	142.900	143.900	1.000
20	19	141.200	137.100	-4.100
20	20	135.100	133.600	-1.500
20	21	140.600	140.200	-0.400
20	22	131.000	132.500	1.500
20	23	155.900	154.200	-1.700
20	24	135.400	135.300	-0.100
20	25	136.900	135.700	-1.200
20	26	140.000	137.500	-2.500
20	27	137.200	134.200	-3.000
35	28	145.800	148.200	2.400
35	29	143.800	144.100	0.300
35	30	134.200	129.500	-4.700
35	31	124.500	125.700	1.200
35	32	133.800	132.600	-1.200
30	33	142.000	142.600	0.600
30	34	131.400	131.200	-0.200
30	35	148.700	143.800	-4.900
30	36	141.900	140.900	-1.000
30	37	143.700	142.400	-1.300
	Max	155.900	154.200	2.500
	Average	139.508	138.211	-1.297
	Min	124.500	125.700	-4.900
	Std Dev	6.910	6.925	2.017



	37.16_AVG PGOOD DEGLITCH			
Test Site				
Tester				
Test Number				
Max Limit	200	us		
Min Limit	80	us		
kRad(Si)	20	25	30	35
LL	80.000	80.000	80.000	80.000
Min	126.500	130.400	131.200	125.700
Average	138.991	135.000	140.180	136.020
Max	154.200	148.000	143.800	148.200
UL	200.000	200.000	200.000	200.000

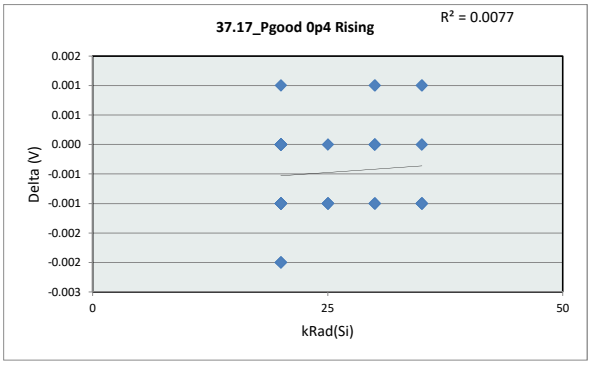


LDR TID Report
TPS7H4010-SEP

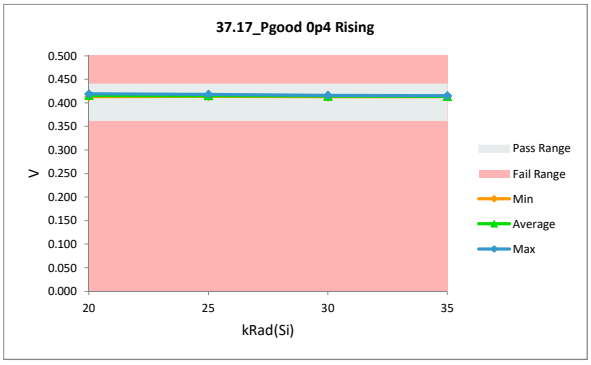
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.17_Pgood 0p4 Rising	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.44	0.44
Min Limit	0.36	0.36

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.416	0.416	0.000
25	2	0.416	0.415	-0.001
25	3	0.415	0.414	-0.001
25	4	0.419	0.418	-0.001
25	5	0.415	0.414	-0.001
20	6	0.416	0.415	-0.001
20	7	0.419	0.419	0.000
20	8	0.415	0.414	-0.001
20	9	0.418	0.418	0.000
20	10	0.416	0.415	-0.001
20	11	0.418	0.417	-0.001
20	12	0.417	0.417	0.000
20	13	0.416	0.416	0.000
20	14	0.416	0.416	0.000
20	15	0.416	0.417	0.001
20	16	0.414	0.413	-0.001
20	17	0.417	0.416	-0.001
20	18	0.417	0.416	-0.001
20	19	0.415	0.415	0.000
20	20	0.418	0.416	-0.002
20	21	0.418	0.418	0.000
20	22	0.416	0.415	-0.001
20	23	0.416	0.416	0.000
20	24	0.416	0.416	0.000
20	25	0.418	0.416	-0.002
20	26	0.416	0.416	0.000
20	27	0.417	0.417	0.000
35	28	0.414	0.413	-0.001
35	29	0.414	0.414	0.000
35	30	0.416	0.415	-0.001
35	31	0.413	0.414	0.001
35	32	0.415	0.414	-0.001
30	33	0.416	0.415	-0.001
30	34	0.414	0.413	-0.001
30	35	0.416	0.416	0.000
30	36	0.415	0.415	0.000
30	37	0.412	0.413	0.001
	Max	0.419	0.419	0.001
	Average	0.416	0.415	0.000
	Min	0.412	0.413	-0.002
	Std Dev	0.002	0.002	0.001



	37.17_Pgood 0p4 Rising			
Test Site				
Tester				
Test Number				
Max Limit	0.44	V		
Min Limit	0.36	V		
kRad(Si)	20	25	30	35
LL	0.360	0.360	0.360	0.360
Min	0.413	0.414	0.413	0.413
Average	0.416	0.415	0.414	0.414
Max	0.419	0.418	0.416	0.415
UL	0.440	0.440	0.440	0.440

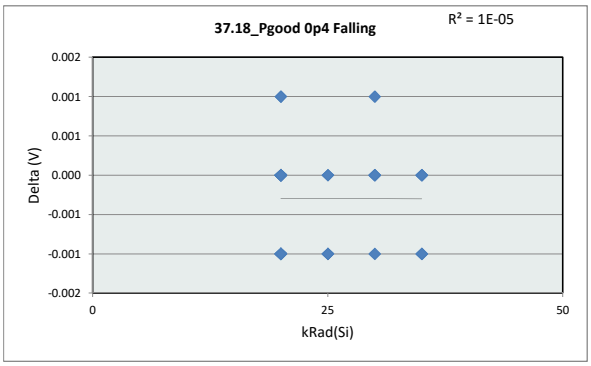


LDR TID Report
TPS7H4010-SEP

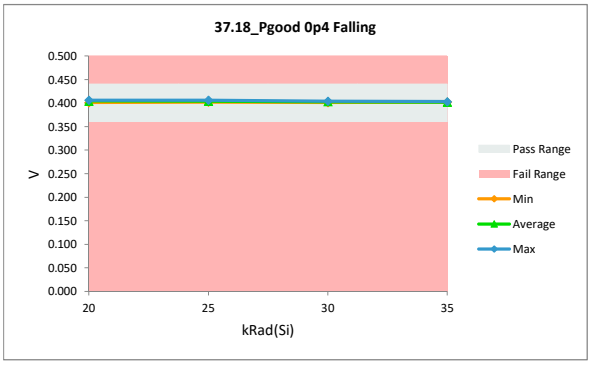
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	37.18_Pgood 0p4 Falling	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.44	0.44
Min Limit	0.36	0.36

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	0.404	0.404	0.000
25	2	0.404	0.403	-0.001
25	3	0.403	0.402	-0.001
25	4	0.407	0.406	-0.001
25	5	0.403	0.403	0.000
20	6	0.404	0.404	0.000
20	7	0.406	0.406	0.000
20	8	0.403	0.403	0.000
20	9	0.406	0.406	0.000
20	10	0.404	0.403	-0.001
20	11	0.406	0.406	0.000
20	12	0.404	0.404	0.000
20	13	0.405	0.404	-0.001
20	14	0.404	0.404	0.000
20	15	0.404	0.405	0.001
20	16	0.402	0.401	-0.001
20	17	0.405	0.404	-0.001
20	18	0.405	0.405	0.000
20	19	0.404	0.403	-0.001
20	20	0.406	0.405	-0.001
20	21	0.405	0.406	0.001
20	22	0.404	0.404	0.000
20	23	0.404	0.404	0.000
20	24	0.404	0.404	0.000
20	25	0.406	0.405	-0.001
20	26	0.405	0.404	-0.001
20	27	0.405	0.405	0.000
35	28	0.402	0.402	0.000
35	29	0.402	0.402	0.000
35	30	0.404	0.403	-0.001
35	31	0.402	0.402	0.000
35	32	0.403	0.402	-0.001
30	33	0.404	0.404	0.000
30	34	0.403	0.402	-0.001
30	35	0.404	0.404	0.000
30	36	0.403	0.403	0.000
30	37	0.400	0.401	0.001
	Max	0.407	0.406	0.001
	Average	0.404	0.404	0.000
	Min	0.400	0.401	-0.001
	Std Dev	0.001	0.001	0.001



	37.18_Pgood 0p4 Falling			
Test Site				
Tester				
Test Number				
Max Limit	0.44	V		
Min Limit	0.36	V		
kRad(Si)	20	25	30	35
LL	0.360	0.360	0.360	0.360
Min	0.401	0.402	0.401	0.402
Average	0.404	0.404	0.403	0.402
Max	0.406	0.406	0.404	0.403
UL	0.440	0.440	0.440	0.440

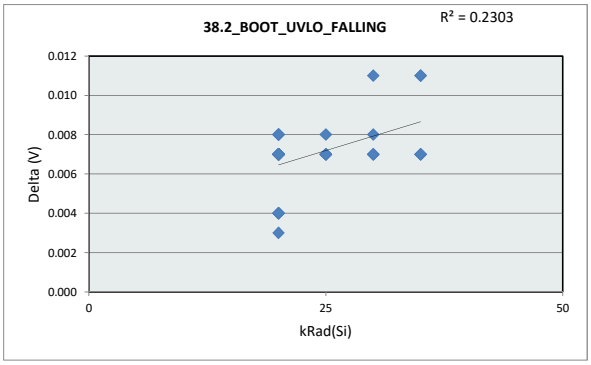


LDR TID Report
TPS7H4010-SEP

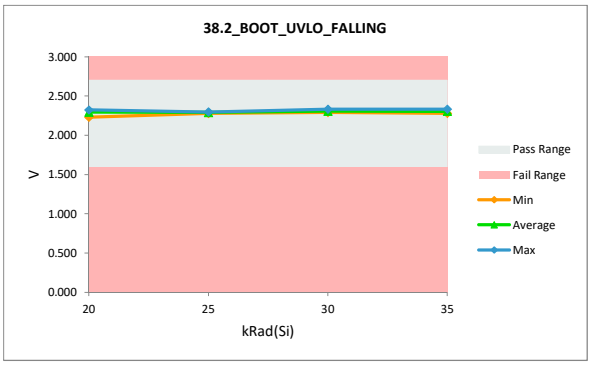
Krad(Si)	Description
20	20 KRAD BIASED
25	20 KRAD UNBIASED
30	30 KRAD BIASED
35	30 KRAD UNBIASED

	38.2_BOOT_UVLO_FALLING	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.7	2.7
Min Limit	1.6	1.6

kRad(Si)	Serial #	Pre_LDR	Post_LDR	Delta
25	1	2.283	2.290	0.007
25	2	2.279	2.286	0.007
25	3	2.286	2.294	0.008
25	4	2.272	2.279	0.007
25	5	2.290	2.297	0.007
20	6	2.294	2.301	0.007
20	7	2.247	2.254	0.007
20	8	2.308	2.312	0.004
20	9	2.294	2.301	0.007
20	10	2.315	2.319	0.004
20	11	2.315	2.322	0.007
20	12	2.221	2.229	0.008
20	13	2.304	2.312	0.008
20	14	2.301	2.308	0.007
20	15	2.286	2.294	0.008
20	16	2.308	2.312	0.004
20	17	2.304	2.312	0.008
20	18	2.265	2.272	0.007
20	19	2.283	2.290	0.007
20	20	2.290	2.297	0.007
20	21	2.254	2.261	0.007
20	22	2.290	2.297	0.007
20	23	2.279	2.286	0.007
20	24	2.290	2.297	0.007
20	25	2.304	2.308	0.004
20	26	2.312	2.315	0.003
20	27	2.283	2.290	0.007
35	28	2.312	2.319	0.007
35	29	2.322	2.333	0.011
35	30	2.283	2.290	0.007
35	31	2.297	2.304	0.007
35	32	2.268	2.279	0.011
30	33	2.290	2.297	0.007
30	34	2.301	2.308	0.007
30	35	2.279	2.290	0.011
30	36	2.326	2.333	0.007
30	37	2.304	2.312	0.008
	Max	2.326	2.333	0.011
	Average	2.290	2.297	0.007
	Min	2.221	2.229	0.003
	Std Dev	0.021	0.021	0.002



	38.2_BOOT_UVLO_FALLING			
Test Site				
Tester				
Test Number				
Max Limit	2.7	V		
Min Limit	1.6	V		
kRad(Si)	20	25	30	35
LL	1.600	1.600	1.600	1.600
Min	2.229	2.279	2.290	2.279
Average	2.295	2.289	2.308	2.305
Max	2.322	2.297	2.333	2.333
UL	2.700	2.700	2.700	2.700



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